

## ESA study



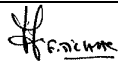
**“Test Methods, Requirements, and Guidelines for Evaluation of Radiation Sensitivity of Analog to Digital Converters (ADC), Digital to Analog Converters (DAC) and Vertical Power MOSFETs”**

# TOTAL IONIZING DOSE TEST REPORT

<b>Part Type : AD976SD/883</b>
<b>Package : GDIP4-T28</b>
<b>Description : 16-Bit, 100 kSPS / 200 kSPS BiCMOS A/D Converter</b>
<b>Manufacturer : Analog Devices</b>
<b>Date Code: 1306</b>

**ESTEC Contract N° 4000105495/12/NL/SFe dated February 27<sup>th</sup>, 2012**

**ESTEC Technical Responsible: Christian Poivey**

<b>Hirex reference:</b>	HRX/TID/1197	Issue: 02	Date:	August 11 <sup>th</sup> , 2014
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**CHANGE RECORD**

ISSUE	DATE	PAGE	DESCRIPTION OF CHANGES
01	June 05 <sup>th</sup> , 2014	All	Original Issue
02	August 11 <sup>th</sup> , 2014	9, 13 and 173	Linearity computation, parameter table and DNL functional trend plot

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**TOTAL DOSE RADIATION TEST REPORT  
on Analog Devices  
AD976SD/883  
16-Bit, 100 kSPS / 200 kSPS BiCMOS A/D Converter**

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## 1 Introduction

In the scope of the ESA study: "Test Methods, Requirements, and Guidelines for Evaluation of Radiation Sensitivity of Analog to Digital Converters (ADC), Digital to Analog Converters (DAC) and Vertical Power MOSFETs", a total dose radiation evaluation test of the Analog Devices AD976SD/883, 16-Bit, 100 kSPS / 200 kSPS BiCMOS A/D Converter has been performed with an accumulated dose of about 102 krad(Si) at a dose rate of 310 rad(Si)/hour, in response to ESTEC purchase order reference 4000105495/12/NL/SFe.

The purpose of this test was to evaluate total dose withstanding of this component, to investigate its suitability for being used in space applications. This test was conducted on samples provided by ESTEC. Test has been performed in accordance with Hirex Engineering proposal reference HRX/PRO/3624 Issue 01 dated 10/12/2012.

A complete set of electrical measurements together with graphical representation of measured parameters with respect to total dose received, are provided for all samples.

## 2 Applicable and Reference Documents

### 2.1 Applicable Documents

- Hirex Engineering proposal: HRX/PRO/3624 Issue 01 dated 10/12/2012
- Hirex Engineerin Email reference "Irradiation test plan approval for AD976SD/883" dated 02/11/2014.
- Hirex Engineering irradiation test plan for AD976SD/883: HRX/SPE/0281 Issue 01 dated 01/29/2014.
- Hirex Engineering Detail Design Document for AD976SD/883: HRX/DDD/1856 Issue 01
- Hirex Engineering Test Conditions for AD976SD/883: HRX/TC/1419 Issue 01
- ESCC Basic Specification No. 22900 issue 04.

### 2.2 Reference Documents

- Analog Devices AD976SD/883 Datasheet revision C dated 1999.
- Specification Document: SMD 5962-97564 revision B dated April 1997.

## 3 Device architecture / functional diagram / technology

The AD976A 16-bit A/D converter is considered as it can be procured to HiRel level. Maximum sampling frequency is 200KSPS. The part contains a successive approximation, switched capacitor ADC, an internal 2.5V reference and a high speed parallel interface. The ADC is factory calibrated (Resistor trimming with laser) to minimize all linearity errors.

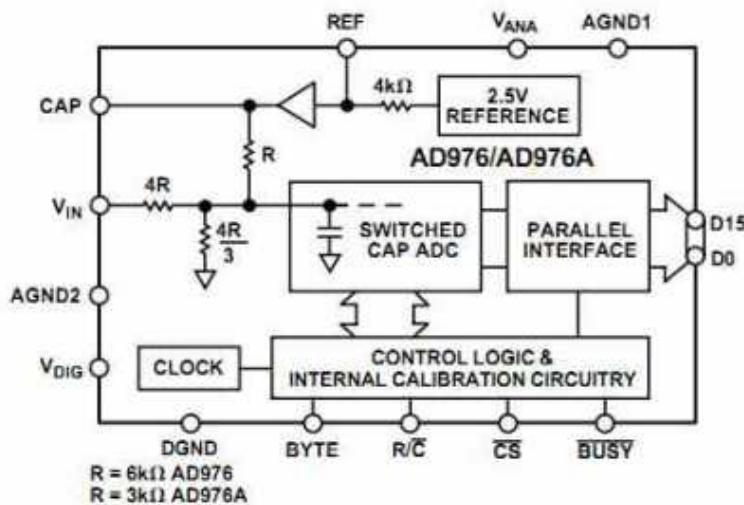


Figure 1: AD976SD/883 Block Diagram

Identification of the main blocks of the device is shown on Figure 2.

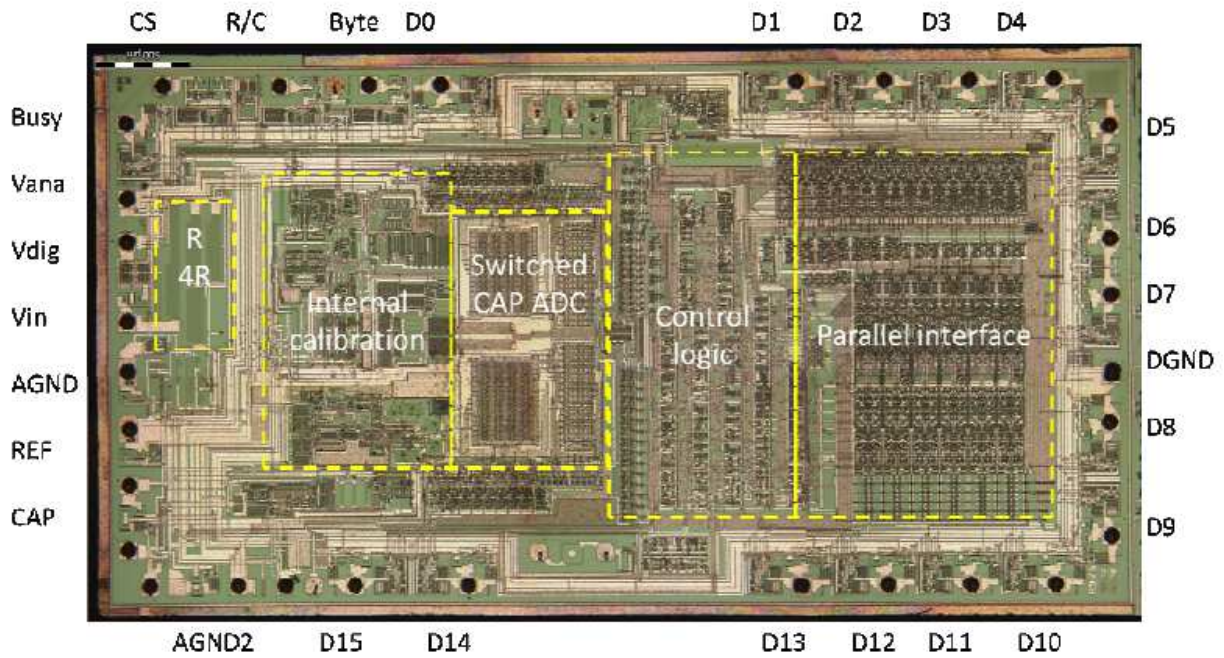


Figure 2: AD976SD/883 Die Floorplan

#### 4 Test Samples

11 samples of the AD976SD/883 device were tested (5 ON + 5 OFF + 1 control sample).

Samples were allocated into the bias conditions during exposures and annealing as provided in the following table.

Serial Number (serialized by Hirex)	Allocation
1	Control
2	Biased ON
3	Biased ON
4	Biased ON
5	Biased ON
6	Biased ON
7	Biased OFF
8	Biased OFF
9	Biased OFF
10	Biased OFF
11	Biased OFF

Identification of the AD976SD/883 is given below:

<b>Part Type:</b>	AD976SD/883	<b>Part Number:</b>	AD5962-9756401QXA
<b>Top Marking:</b>	AD5962-9756401QXA logo Q 1306 A E233220	<b>Bottom Marking:</b>	E233220 PHILIPPINES
<b>Date Code:</b>	1306	<b>Lot Number:</b>	C6X410965

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Complete traceability of the tested samples are provided on the following photos including die marking.

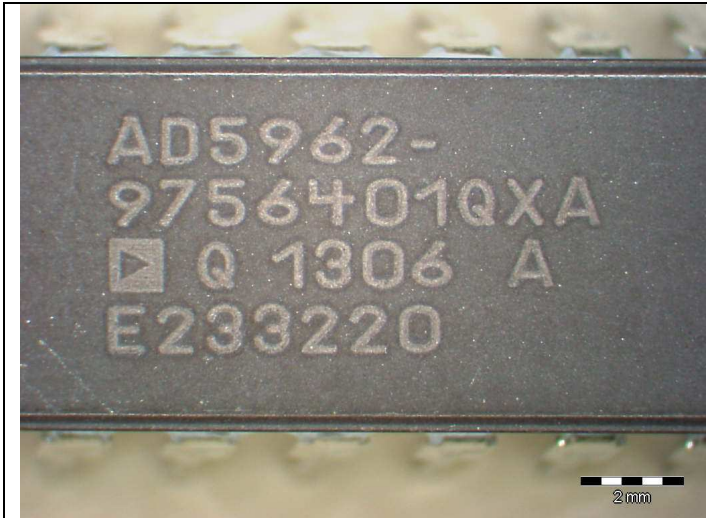


Photo 1 – Top Device Marking

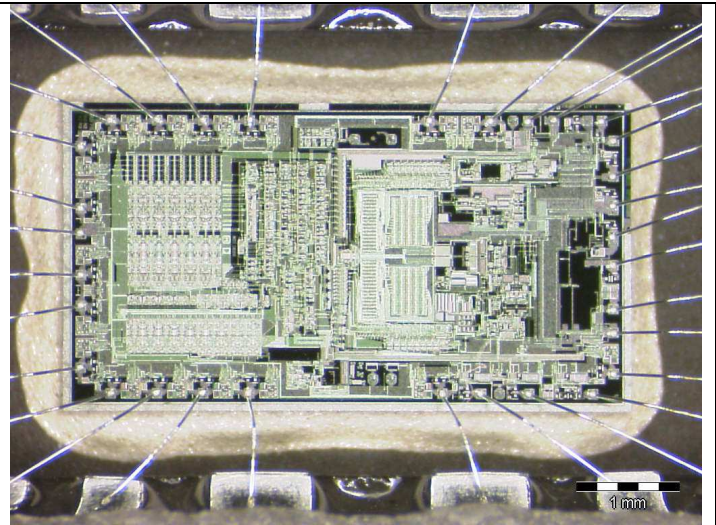


Photo 2 – Die View

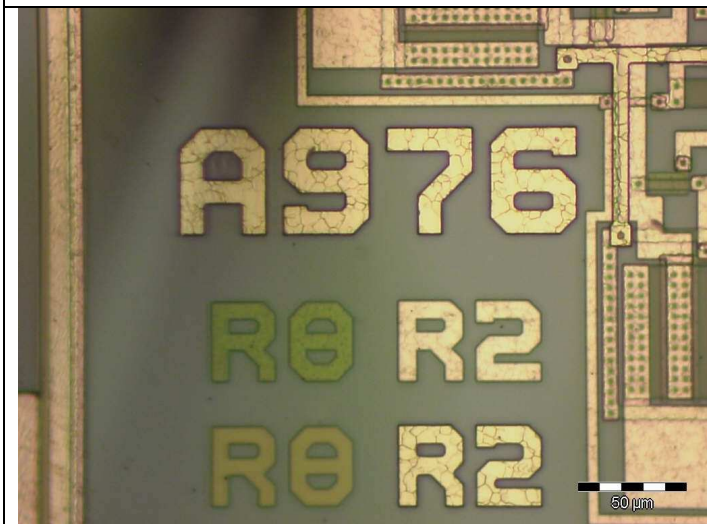


Photo 3 – Die Marking

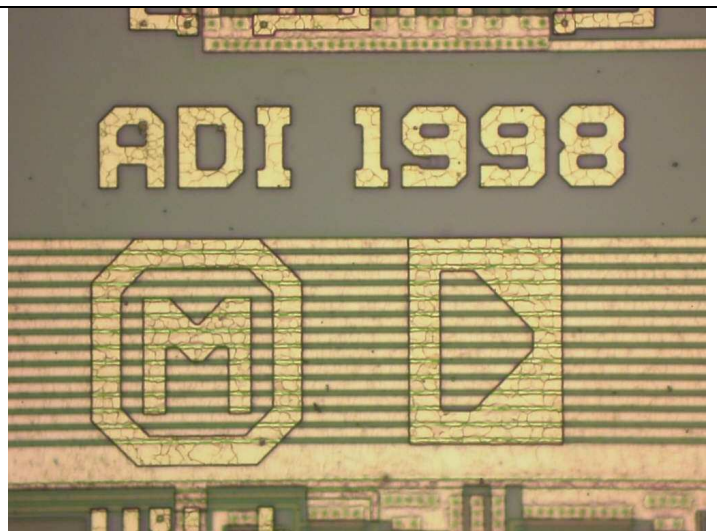


Photo 4 – Die marking

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## 5 Experimental Conditions

### 5.1 Radiation Source Dose Rate and Annealing

The dose exposures were performed at UCL in Louvain (Belgium). In this irradiation facility, a Cobalt 60 source is used with the possibility to vary the dose rate by simply adjusting the distance to the source.

During the dose exposures, devices under test have been irradiated in an ambient temperature of 24°C ±6°C.

Prior to the test campaign the dose rate at board location is controlled using the Hirex calibrated dosimeter reference: Radcal Accu-Dose.

In addition, the dose received by the devices is verified by the measurement of one Alanine pellet dosimeter placed onto the bias board.

Resulting test conditions are provided below.

Irradiation Steps Requested	Pellet dosimetry data	Dose rate	Annealing steps	Temperature
0 krad(Si)	0 krad(Si)		-	Room
10 krad(Si)	9 krad(Si)	310 rad(Si)/h	-	Room
20 krad(Si)	20.7 krad(Si)	310 rad(Si)/h	-	Room
30 krad(Si)	27.9 krad(Si)	310 rad(Si)/h	-	Room
50 krad(Si)	48.6 krad(Si)	310 rad(Si)/h	-	Room
100 krad(Si)	102.6 krad(Si)	310 rad(Si)/h	-	Room
-	-	-	24h	Room
-	-	-	+144h	Room
-	-	-	168h	100°C

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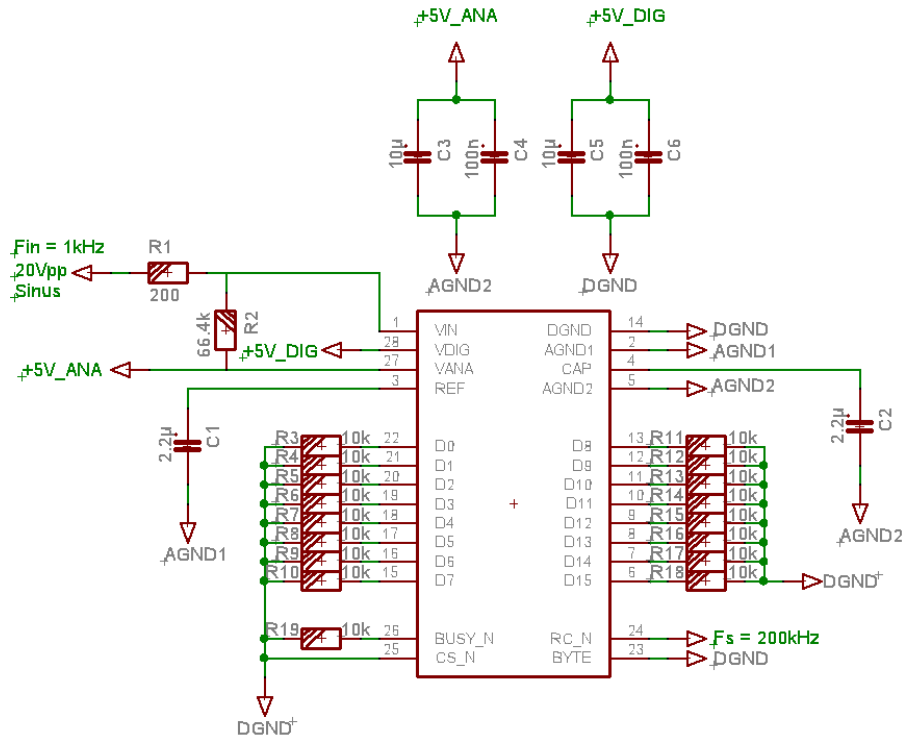
**5.2 Bias during Dose Exposures and Measurements conditions**

**5.2.1 Bias conditions**

During exposures test board allowed to bias 5 samples in accordance with the electrical circuit provided in Figure 3.

5 other samples were biased OFF with all pins connected to ground.

During annealing steps the same stress conditions were applied at room and 100°C temperatures.



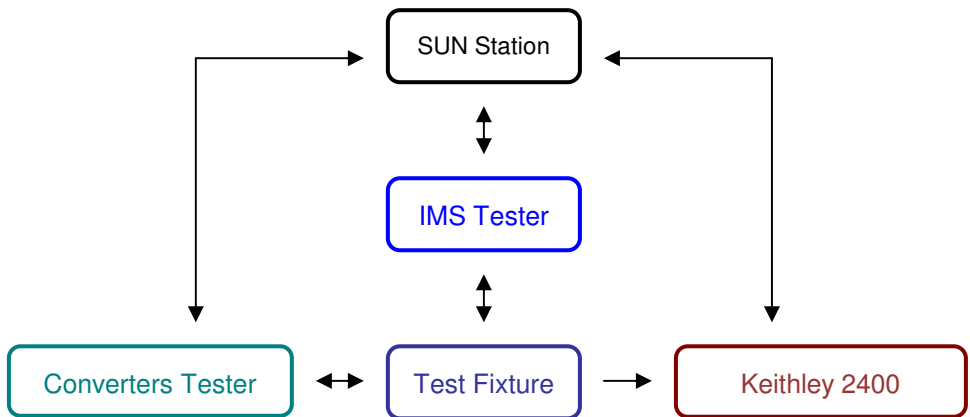
**Figure 3: Bias Conditions during Irradiation Exposures and Annealing**

**5.2.2 Electrical Measurements**

Electrical parameters test program principle for AD976SD/883 is provided in Figure 4.

A test bench including one IMS tester, one Converters Tester and one Keithley 2400 Power Supply were used to perform required measurements.

A dedicated test fixture was designed to ensure proper measurement conditions.



**Figure 4: AD976SD/883 test program principle**



5.2.3 Linearity and Dynamic Test methods description

In this paragraph the test methods used to measure the converter parameters are presented.

5.2.3.1 Linearity Test – Linear Ramp Histogram test method

A linear ramp histogram test method is used to perform linearity tests as depicted in Figure 5. The stimulus signal should be a very linear ramp waveform. It must swing slightly larger than the ADC input range, otherwise the linearity cannot be tested correctly. Its slope must be slow enough for the ADC under test to generate multiple times every code. Since histogram method is a kind of statistical method, each code had better to occur many times, for example at least 10 counts. An image of code occurrence by a ramp is shown in Figure 5. Since the input ramp overloads to the input range of the DUT, code 0 and the full-scale code ( $2^n - 1$ ) occur extremely many times than the rest of the codes. Here  $n$  denotes the number of bits.

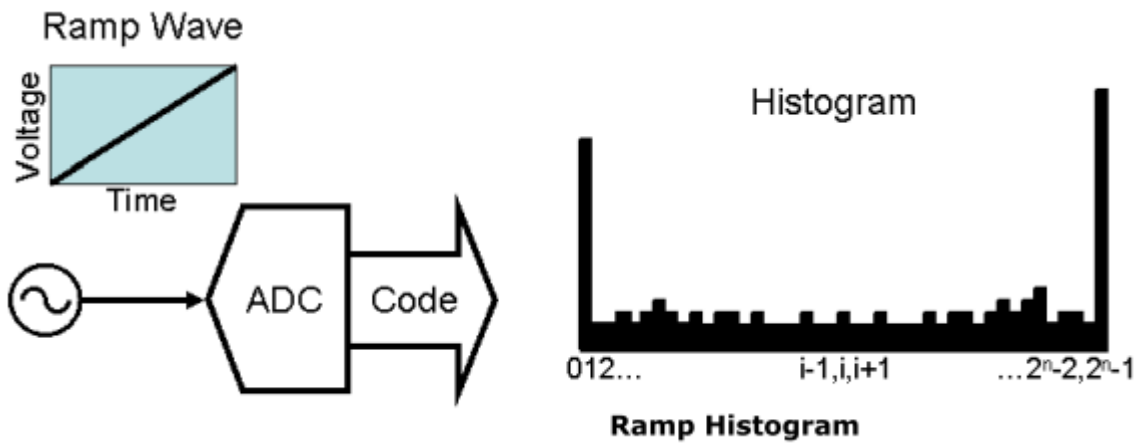


Figure 5: Linear Ramp Histogram test

A histogram by ramp signal looks as Figure 6

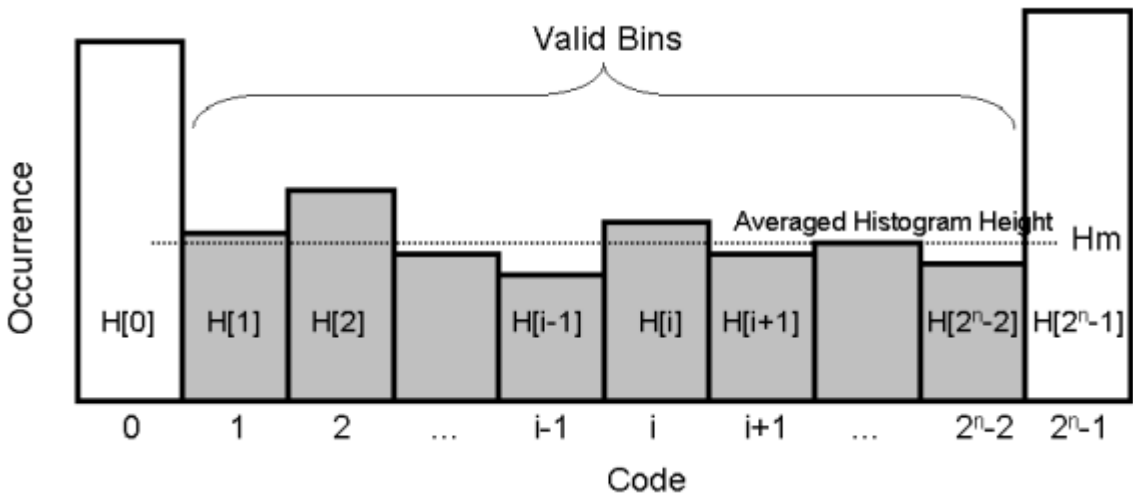


Figure 6: Ramp Histogram

The linearity is calculated as follows. Neglecting code 0 and code ( $2^n - 1$ ) counts, all the counts from code 1 through ( $2^n - 2$ ) are summed up. The average height ( $H_m$ ) of the histogram from 1 through ( $2^n - 2$ ) is calculated as below.

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$$H_m = \frac{\sum_{i=1}^{2^n-2} H[i]}{2^n - 2}$$

(1)

A bin height is proportional to its code size. The average bin height  $H_m$  corresponds to the ideal code size so that  $H_m$  is the reference of each bin. Differential linearity error  $DLE[i]$  is described using Equation (1) as below.

$$DLE[i] = \frac{H[i] - H_m}{H_m} = \frac{H[i]}{H_m} - 1 \text{ [LSB]}$$

(2)

where  $i=1,2,3, \dots, 2^n - 2$ , and  $DLE[0]=DLE[2^n - 1]=0$  perfunctory.

Integral linearity error  $ILE[i]$  is defined as Equation (3) below.

$$ILE[i] = \sum_{k=1}^i DLE[k] \text{ [LSB]}$$

(3)

where  $L_{m0} = L_0$ , and  $ILE[0]=ILE[2^n - 1]=0$  perfunctory.

Equation (3) shows that  $ILE[i]$  is derived as accumulation of  $DLE[i]$ . Equations (2) and (3) are the linearity equations by using a ramp stimulus.

### 5.2.3.2 Dynamic Tests computation

For the dynamic parameter calculations the captured sinewave must be converted to the frequency domain, using the (fast) fourrier transform.

In some situations it is not possible to capture an integer number of sinewaves. This will lead to spectral leakage. In these situations signal windowing can be useful.

From the spectrum results the following parameters can be calculated:

$$SINAD = \frac{c}{n + d} \quad ENOB = \frac{SINAD - 1.8}{6.02} \quad SNR = \frac{c}{n} \quad THD = \frac{d}{c}$$

Where:

$$c = \sqrt{\text{Re}^2_{carrier} + \text{Im}^2_{carrier}} \quad d = \sqrt{\sum_{distortion} \text{Re}^2_{dist} + \text{Im}^2_{dist}}$$

$$n = \sqrt{\sum_{noise} \text{Re}^2_{noise} + \text{Im}^2_{noise}}$$

Where “c” stands for the amplitude of the carrier bin.

The signal “d” stands for the sum of all distorsion bins and “n” for the sum of all noise bins. The position of the carrier bin is equal to the number of periods of the carrier in the captured window.

#### 5.2.3.2.1 Signal to Noise and Distorsion (SINAD) & Effective Number of Bits (ENOB)

SINAD stands for Signal to Noise and Distorsion. It is the ratio signal (or carrier) and all other spectrum bins. The Effective Number of Bits (ENOB) is calculated from the SINAD.

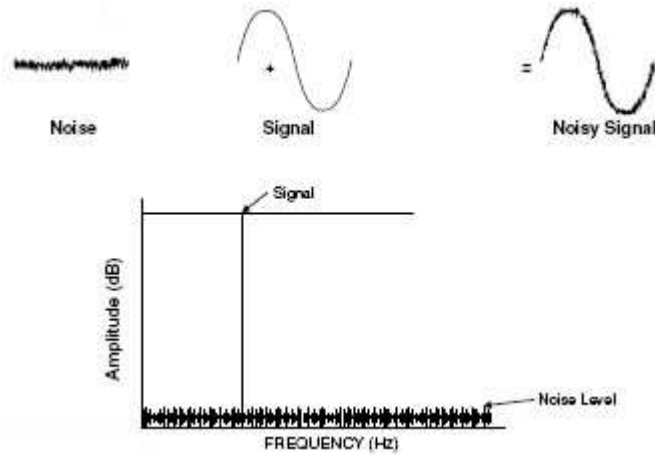
The theoretical maximum signal-to-noise-and-distorsion for a linear ADC with a full-scale sine-wave input derives from quantization noise (or resolution for a DAC) and is defined as  $20 * \log(2^{(n-1)} * \text{sqrt}(6))$ , or about  $6.02n + 1.76$  dB.

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With a perfectly linear but noisy system SINAD and SNR are interchangeable.

### 5.2.3.2.2 Signal to Noise ratio (SNR)

The Signal to Noise ratio or SNR stands for the ratio signal (or carrier) and all noise bins. Noise bins are all bins not being the carrier, a harmonic or DC.



SNR usually degrades as frequency increases because the accuracy of the comparator(s) within the ADC degrades at higher input slew rates. This loss of accuracy shows up as noise at the ADC output. In an A/D converter, noise comes from four main sources: (1) quantization noise, (2) noise generated by the converter itself, (3) application circuit noise and (4) jitter.

Quantization noise results from the quantization process, the process of assigning an output code to a range of input values.

The amplitude of the quantization noise decreases as resolution increases because the size of an LSB is smaller at higher resolutions, which reduces the maximum quantization error.

The theoretical maximum signal-to-noise ratio for a linear ADC with a full-scale sine-wave input derives from quantization noise (or resolution for a DAC) and is defined as  $20 * \log(2^{(n-1)} * \sqrt{6})$ , or about  $6.02n + 1.76$  dB. With a perfectly linear but noisy system SINAD and SNR are interchangeable.

Application circuit noise is that noise seen by the converter as a result of the way the circuit is designed and laid out. SNR increases with increasing input amplitude until the input gets close to full scale. The SNR increases at the same rate as the input signal until the input signal approaches full scale. That is, increasing the input signal amplitude by 1 dB will cause a 1 dB increase in SNR.

This is because the step size becomes a smaller part of the total signal amplitude as the the signal amplitude increases. When the input amplitude starts approaching full scale, however, the rate of increase of SNR vs. input signal decreases. SNR performance decreases at higher frequencies because the effects of jitter get worse.

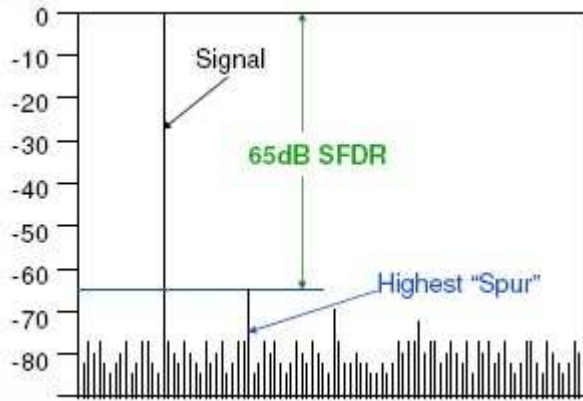
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5.2.3.2.3 Total Harmonic Distorsion (THD)

The Total Harmonic Distorsion or THD is the ratio distortion bins and signal (or carrier). Harmonics are multiples of the carrier.

5.2.3.2.4 Spurious free dynamic range (SFDR)

The spurious free dynamic range is the difference in dB between the signal and the any other signal (spurious) in the spectrum with the highest peak.



5.2.3.2.5 Peak Distorsion

The peak distorsion is the highest distorsion bin.

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Electrical parameters test conditions and limits used for performing this test are given in the following tables.

PARAMETERS	SYMBOLS	TEST CONDITIONS	MIN	MAX	UNITS
		VANA=5V, VDIG=5V, VREF=2.5V			
Logic input high Voltage	Vih			2	V
Logic input low Voltage	Vil		0.8		V
Logic Input current	ILINL	Vih=5V, Vil=0V	-10.0E-6	10.0E-6	A
Logic Input current	ILINH	Vih=5V, Vil=0V	-10.0E-6	10.0E-6	A
Logic output high voltage	VOH	IOH=0.5mA	4		V
logic output low voltage	VOL	IOL=1.6mA		0.4	V
Three state output leakage	IOLTL		-5.00E-06	5.00E-06	A
Three state output leakage	IOLTH		-5.00E-06	5.00E-06	A
Power dissipation	PD			0.1	W
Integral nonlinearity Positive	INL_Positive	All codes, fs=200ksps		2.5	LSB
Integral nonlinearity Negative	INL_Negative	All codes, fs=200ksps	-2.5		LSB
Differential nonlinearity	DNL	Go-noGo test, All codes, fs=200ksps, Minimum resolution for which "no missing codes" is guaranteed.	16 Bits		P/F
Bipolar zero error	BPZE	Code = 32767.5, Ta=+25°C, fs=200ksps	-0.01	0.01	V
Negative full scale error	AN	Code=0.5, Ta=+25°C, fs=200ksps	-0.25	0.25	%
Positive full scale error	AP	Code=65535.5, Ta=+25°C, fs=200ksps	-0.25	0.25	%
Signal-to-noise + distorsion	S/(N+D)	Fin=45KHz, fs=200ksps <b>Note 1</b>	84		dB
Total Harmonic Distorsion	THD	Fin=45KHz, fs=200ksps <b>Note 1</b>		-94	dB
Spurious free dynamic range	SFDR	Fin=45KHz, fs=200ksps	94		dB
Voltage reference output	Vref	Ta=+25°C	2.48	2.52	V
Power supply rejection	PSR	Vdig=Vana=5V □5%	-8	8	LSB
Convert pulse width	t1	<b>Note 2</b>		50.0E-9	s
Data valid after R//C low	t2	<b>Note 2</b>		4.0E-6	s
/BUSY low delay	t3	<b>Note 2</b>		100.0E-9	s
/BUSY low time	t4	<b>Note 2</b>		4.0E-6	s
Conversion time	t7	GO NOGO		4.0E-6	s
Acquisition time	t8	GO NOGO		1.0E-6	s
Bus relinquish	t9	<b>Note 2, Note 3</b>	10.0E-9	100.0E-9	s
Throughput time	t11	<b>Note 2</b>		5.0E-6	s
R//C to /CS setup	t12	<b>Note 2</b>		10.0E-9	s
Time between conversions	t13	GO NOGO, <b>Note 4</b>	5.0E-6	1.0E-3	s
Bus access and byte delay	t14	<b>Note 2, Note 5</b>	10.0E-9	100.0E-9	s

**Note 1:** Vin=-0.5dB, Fin=45 kHz, all measurement referred to a 0dB (20Vpp) input signal. THD includes first six harmonics, Bandwidth = 50 kHz.

**Note 2:** Iol=1.6mA; Ioh=500uA, Vcrossover 2.1V, Vol=0.4V, Voh=4V, Vil=0.8V, Vih=2V

**Note 3:** Measurement decomposed in t9\_DV & t9\_Z. t9\_DV: all data valid. T9\_Z: all data Z.

**Note 4:** Functionality tested at 2 extreme values of t13.

**Note 5:** Measurement decomposed in t14\_DV & t14\_Z. t14\_DV: all data valid. T14\_Z: all data Z.

**Table 1: Room Temperatures Electrical Measurements**

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## 6 Conclusion

A Total Ionizing Dose evaluation test was carried out by Hirex Engineering under ESTEC contract on the Analog Devices AD976SD/883 16-Bit, 100 kSPS / 200 kSPS BiCMOS A/D Converter in GDIP4-T28 package.

10 samples plus one control sample were used during testing. They were exposed to radiation using a dose rate of 310 rad(Si)/hour at room temperature.

A summary of the failed parameters is provided in the following table. The behavior of each parameter is recorded for both biased ON and biased OFF samples. Parameters not listed remained within specification limits all along testing.

Detail test results are presented in the following section.

Parameters	Failure Level between :		Annealing Recovery [Note 1]					Comments
			NA	No	Partial	Complete	Rebound	
<a href="#">ILINH/CS</a>	ON samples	9 & 20.7 kRad(Si)				X		
	OFF samples	No Failure	X					
VOL	ON samples	48.6 & 102.6 kRad(Si)				X		[Note 2]
	OFF samples	No Failure	X					
IOLTL	ON samples	48.6 & 102.6 kRad(Si)				X		
	OFF samples	No Failure	X					
<a href="#">INL Positive</a>	ON samples	27.9 & 48.6 kRad(Si)		X				
	OFF samples	No Failure	X					
<a href="#">INL Negative</a>	ON samples	20.7 & 27.9 kRad(Si)		X				
	OFF samples	48.6 & 102.6 kRad(Si)		X				
<a href="#">DNL</a>	ON samples	27.9 & 48.6 kRad(Si)		X				[Note 2]
	OFF samples	No Failure	X					
<a href="#">BPZE</a>	ON samples	9 & 20.7 kRad(Si)				X		
	OFF samples	No Failure	X					
<a href="#">AP</a>	ON samples	9 & 20.7 kRad(Si)		X				
	OFF samples	20.7 & 27.9 kRad(Si)				X		
<a href="#">AN</a>	ON samples	27.9 & 48.6 kRad(Si)			X			
	OFF samples	27.9 & 48.6 kRad(Si)				X		
<a href="#">SFDR</a>	ON samples	48.6 & 102.6 kRad(Si)			X			
	OFF samples	No Failure	X					
<a href="#">THD</a>	ON samples	27.9 & 48.6 kRad(Si)			X			
	OFF samples	No Failure	X					
<a href="#">SINAD</a>	ON samples	27.9 & 48.6 kRad(Si)		X				
	OFF samples	No Failure	X					

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Parameters	Failure Level between :		Annealing Recovery [Note 1]					Comments
			NA	No	Partial	Complete	Rebound	
<a href="#">T2</a>	ON samples	48.6 & 102.6 kRad(Si)				X		[Note 2]
	OFF samples	No Failure	X					
<a href="#">T8</a>	ON samples	48.6 & 102.6 kRad(Si)				X		
	OFF samples	No Failure	X					
<a href="#">T9 DV</a>	ON samples	48.6 & 102.6 kRad(Si)				X		[Note 2]
	OFF samples	No Failure	X					
<a href="#">T12</a>	ON samples	48.6 & 102.6 kRad(Si)				X		[Note 2]
	OFF samples	No Failure	X					
<a href="#">T13</a>	ON samples	48.6 & 102.6 kRad(Si)				X		
	OFF samples	No Failure	X					
<a href="#">T14 DV</a>	ON samples	48.6 & 102.6 kRad(Si)				X		[Note 2]
	OFF samples	No Failure	X					

[Note 1]: **NA** = not applicable, **No**: means no sample has recovered, **Partial**: means at least one sample has recovered, **Complete**: means all samples have recovered, **Rebound**: means rebound has been observed on at least one sample.

[Note 2]: Some or all biased ON parts, these parameters have been not measured at some irradiation steps due to device loss of functionality.

**Table 2 : Summary of parameters failure levels**

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

## 7 Test Results

Test results including tables and graphics are provided in this section for each measured parameter.

Failed values (if any) with respect to specified limits are highlighted in bold red font in the tables.

For each parameter a drift calculation table is provided that computes the drift between a given exposure step with respect to initial readings:

$$\Delta(\text{Parameter value}) = (\text{Parameter value}_{\text{POSTRAD}}) - (\text{Parameter value}_{\text{PRERAD}})$$

**Note on tables and graphics:**

In some cases, it may appear missing points in tables and graphs, this situation corresponds to a failure corresponding to a loss of functionality (Device not able to boot).



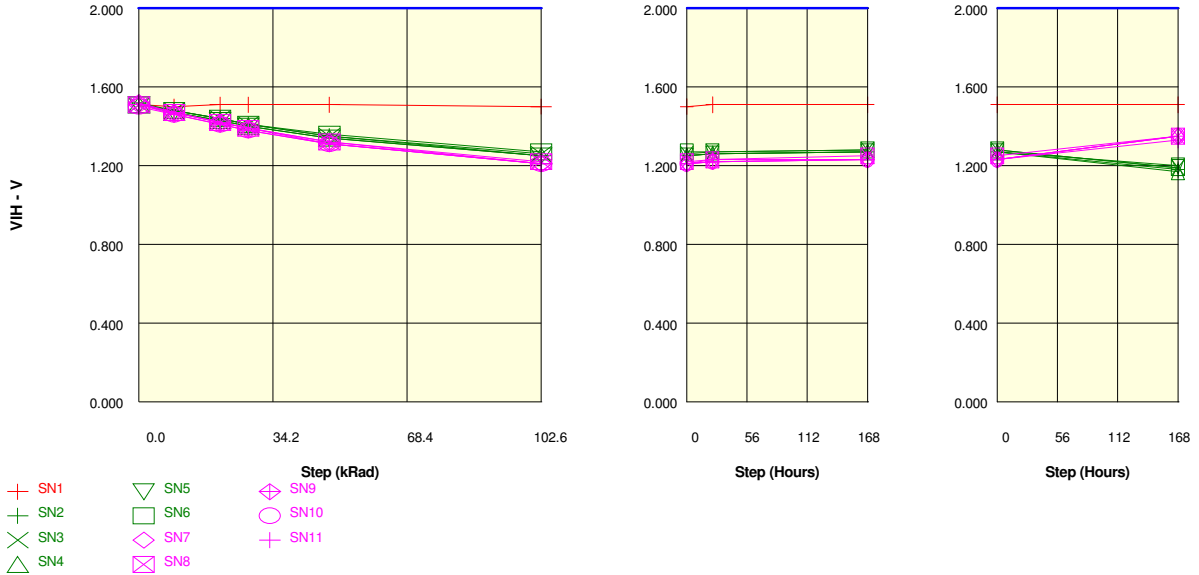
Parameter : Logic input high Voltage : VIH/CS

Test conditions :

Unit : V

Spec Limit Max : 2.000

Spec limits are represented in bold lines on the graphic.



Measurements

VIH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.510	1.500	1.510	1.510	1.510	1.500	1.510	1.510	1.510
ON samples									
SN2	1.520	1.480	1.440	1.410	1.350	1.250	1.260	1.270	1.180
SN3	1.510	1.480	1.440	1.410	1.350	1.260	1.270	1.280	1.190
SN4	1.510	1.470	1.430	1.400	1.340	1.250	1.260	1.270	1.170
SN5	1.510	1.470	1.430	1.400	1.340	1.250	1.260	1.270	1.200
SN6	1.510	1.480	1.440	1.410	1.360	1.270	1.270	1.280	1.190
Statistics									
Min	1.510	1.470	1.430	1.400	1.340	1.250	1.260	1.270	1.170
Max	1.520	1.480	1.440	1.410	1.360	1.270	1.270	1.280	1.200
Average	1.512	1.476	1.436	1.406	1.348	1.256	1.264	1.274	1.186
Sigma	0.004	0.005	0.005	0.005	0.007	0.008	0.005	0.005	0.010

Drift Calculation

VIH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-40.0E-03	-80.0E-03	-110.0E-03	-170.0E-03	-270.0E-03	-260.0E-03	-250.0E-03	-340.0E-03
SN3	-	-30.0E-03	-70.0E-03	-100.0E-03	-160.0E-03	-250.0E-03	-240.0E-03	-230.0E-03	-320.0E-03
SN4	-	-40.0E-03	-80.0E-03	-110.0E-03	-170.0E-03	-260.0E-03	-250.0E-03	-240.0E-03	-340.0E-03
SN5	-	-40.0E-03	-80.0E-03	-110.0E-03	-170.0E-03	-260.0E-03	-250.0E-03	-240.0E-03	-310.0E-03
SN6	-	-30.0E-03	-70.0E-03	-100.0E-03	-150.0E-03	-240.0E-03	-240.0E-03	-230.0E-03	-320.0E-03
Average	-	-36.0E-03	-76.0E-03	-106.0E-03	-164.0E-03	-256.0E-03	-248.0E-03	-238.0E-03	-326.0E-03
Sigma	-	4.9E-03	4.9E-03	4.9E-03	8.0E-03	10.2E-03	7.5E-03	7.5E-03	12.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT				Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices		Issue:	02

**Measurements**

VIH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.510	1.500	1.510	1.510	1.510	1.500	1.510	1.510	1.510
<b>OFF samples</b>									
SN7	1.520	1.470	1.420	1.390	1.320	1.210	1.220	1.230	1.350
SN8	1.510	1.470	1.420	1.390	1.320	1.220	1.230	1.250	1.350
SN9	1.510	1.460	1.410	1.380	1.310	1.210	1.220	1.230	1.350
SN10	1.500	1.460	1.410	1.380	1.310	1.210	1.220	1.230	1.350
SN11	1.510	1.470	1.420	1.390	1.310	1.210	1.230	1.230	1.330
<b>Statistics</b>									
Min	1.500	1.460	1.410	1.380	1.310	1.210	1.220	1.230	1.330
Max	1.520	1.470	1.420	1.390	1.320	1.220	1.230	1.250	1.350
Average	1.510	1.466	1.416	1.386	1.314	1.212	1.224	1.234	1.346
Sigma	0.006	0.005	0.005	0.005	0.005	0.004	0.005	0.008	0.008

**Drift Calculation**

VIH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-50.0E-03	-100.0E-03	-130.0E-03	-200.0E-03	-310.0E-03	-300.0E-03	-290.0E-03	-170.0E-03
SN8	-	-40.0E-03	-90.0E-03	-120.0E-03	-190.0E-03	-290.0E-03	-280.0E-03	-260.0E-03	-160.0E-03
SN9	-	-50.0E-03	-100.0E-03	-130.0E-03	-200.0E-03	-300.0E-03	-290.0E-03	-280.0E-03	-160.0E-03
SN10	-	-40.0E-03	-90.0E-03	-120.0E-03	-190.0E-03	-290.0E-03	-280.0E-03	-270.0E-03	-150.0E-03
SN11	-	-40.0E-03	-90.0E-03	-120.0E-03	-200.0E-03	-300.0E-03	-280.0E-03	-280.0E-03	-180.0E-03
Average	-	-44.0E-03	-94.0E-03	-124.0E-03	-196.0E-03	-298.0E-03	-286.0E-03	-276.0E-03	-164.0E-03
Sigma	-	4.9E-03	4.9E-03	4.9E-03	4.9E-03	7.5E-03	8.0E-03	10.2E-03	10.2E-03

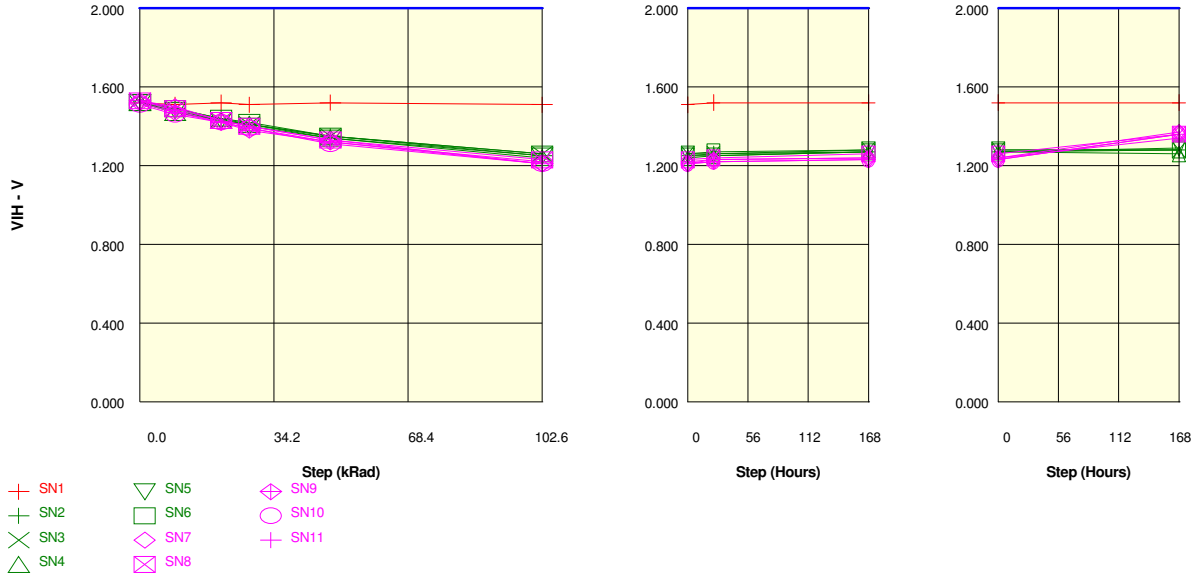
Parameter : Logic input high Voltage : VIH//C

Test conditions :

Unit : V

Spec Limit Max : 2.000

Spec limits are represented in bold lines on the graphic.



Measurements

VIHR//C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.520	1.510	1.520	1.510	1.520	1.510	1.520	1.520	1.520
ON samples									
SN2	1.530	1.490	1.440	1.410	1.350	1.250	1.260	1.270	1.280
SN3	1.530	1.490	1.430	1.410	1.350	1.260	1.260	1.280	1.280
SN4	1.520	1.470	1.430	1.410	1.340	1.240	1.250	1.270	1.260
SN5	1.520	1.480	1.430	1.400	1.340	1.250	1.250	1.270	1.290
SN6	1.520	1.490	1.440	1.420	1.350	1.260	1.270	1.280	1.280
Statistics									
Min	1.520	1.470	1.430	1.400	1.340	1.240	1.250	1.270	1.260
Max	1.530	1.490	1.440	1.420	1.350	1.260	1.270	1.280	1.290
Average	1.524	1.484	1.434	1.410	1.346	1.252	1.258	1.274	1.278
Sigma	0.005	0.008	0.005	0.006	0.005	0.007	0.007	0.005	0.010

Drift Calculation

VIHR//C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-40.0E-03	-90.0E-03	-120.0E-03	-180.0E-03	-280.0E-03	-270.0E-03	-260.0E-03	-250.0E-03
SN3	-	-40.0E-03	-100.0E-03	-120.0E-03	-180.0E-03	-270.0E-03	-270.0E-03	-250.0E-03	-250.0E-03
SN4	-	-50.0E-03	-90.0E-03	-110.0E-03	-180.0E-03	-280.0E-03	-270.0E-03	-250.0E-03	-260.0E-03
SN5	-	-40.0E-03	-90.0E-03	-120.0E-03	-180.0E-03	-270.0E-03	-270.0E-03	-250.0E-03	-230.0E-03
SN6	-	-30.0E-03	-80.0E-03	-100.0E-03	-170.0E-03	-260.0E-03	-250.0E-03	-240.0E-03	-240.0E-03
Average	-	-40.0E-03	-90.0E-03	-114.0E-03	-178.0E-03	-272.0E-03	-266.0E-03	-250.0E-03	-246.0E-03
Sigma	-	6.3E-03	6.3E-03	8.0E-03	4.0E-03	7.5E-03	8.0E-03	6.3E-03	10.2E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

VIHR/C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.520	1.510	1.520	1.510	1.520	1.510	1.520	1.520	1.520
OFF samples									
SN7	1.530	1.500	1.430	1.400	1.330	1.210	1.230	1.240	1.370
SN8	1.530	1.490	1.430	1.400	1.330	1.230	1.240	1.260	1.360
SN9	1.520	1.470	1.420	1.380	1.320	1.210	1.220	1.230	1.360
SN10	1.510	1.460	1.420	1.390	1.310	1.210	1.220	1.230	1.360
SN11	1.530	1.480	1.420	1.390	1.320	1.220	1.230	1.240	1.340
Statistics									
Min	1.510	1.460	1.420	1.380	1.310	1.210	1.220	1.230	1.340
Max	1.530	1.500	1.430	1.400	1.330	1.230	1.240	1.260	1.370
Average	1.524	1.480	1.424	1.392	1.322	1.216	1.228	1.240	1.358
Sigma	0.008	0.014	0.005	0.007	0.007	0.008	0.007	0.011	0.010

**Drift Calculation**

VIHR/C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-30.0E-03	-100.0E-03	-130.0E-03	-200.0E-03	-320.0E-03	-300.0E-03	-290.0E-03	-160.0E-03
SN8	-	-40.0E-03	-100.0E-03	-130.0E-03	-200.0E-03	-300.0E-03	-290.0E-03	-270.0E-03	-170.0E-03
SN9	-	-50.0E-03	-100.0E-03	-140.0E-03	-200.0E-03	-310.0E-03	-300.0E-03	-290.0E-03	-160.0E-03
SN10	-	-50.0E-03	-90.0E-03	-120.0E-03	-200.0E-03	-300.0E-03	-290.0E-03	-280.0E-03	-150.0E-03
SN11	-	-50.0E-03	-110.0E-03	-140.0E-03	-210.0E-03	-310.0E-03	-300.0E-03	-290.0E-03	-190.0E-03
Average	-	-44.0E-03	-100.0E-03	-132.0E-03	-202.0E-03	-308.0E-03	-296.0E-03	-284.0E-03	-166.0E-03
Sigma	-	8.0E-03	6.3E-03	7.5E-03	4.0E-03	7.5E-03	4.9E-03	8.0E-03	13.6E-03

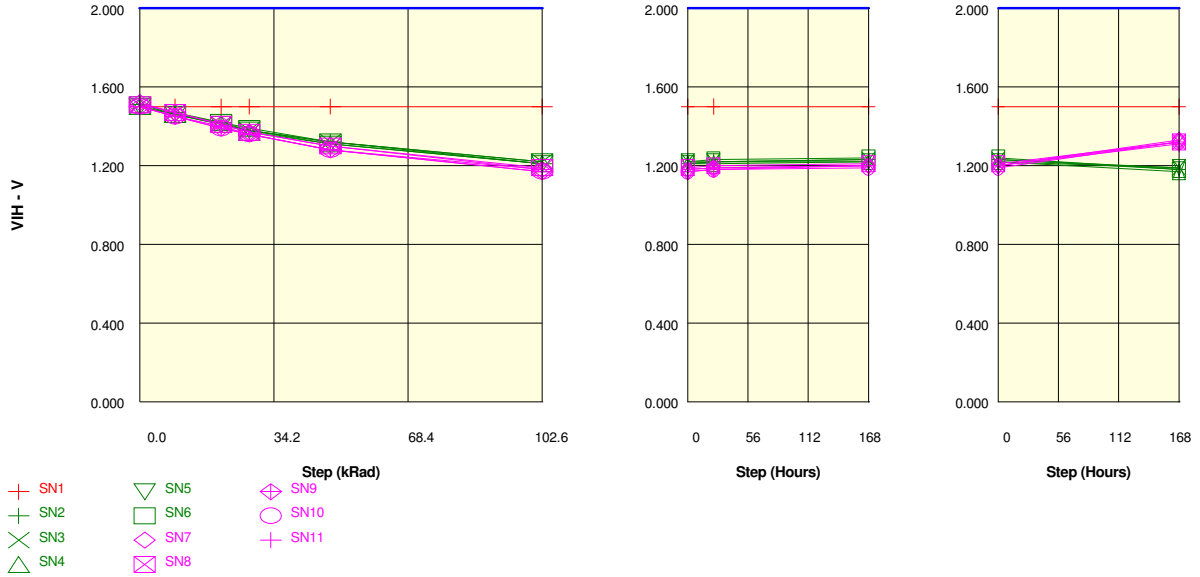
Parameter : Logic input high Voltage : VIHBYTE

Test conditions :

Unit : V

Spec Limit Max : 2.000

Spec limits are represented in bold lines on the graphic.



Measurements

VIHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.500	1.500	1.500	1.500	1.500	1.500	1.500	1.500	1.500
ON samples									
SN2	1.510	1.470	1.420	1.380	1.320	1.210	1.220	1.230	1.180
SN3	1.510	1.470	1.410	1.380	1.320	1.220	1.220	1.230	1.190
SN4	1.500	1.460	1.410	1.370	1.310	1.210	1.210	1.220	1.170
SN5	1.500	1.460	1.410	1.380	1.310	1.210	1.220	1.220	1.190
SN6	1.510	1.460	1.420	1.390	1.320	1.220	1.230	1.240	1.180
Statistics									
Min	1.500	1.460	1.410	1.370	1.310	1.210	1.210	1.220	1.170
Max	1.510	1.470	1.420	1.390	1.320	1.220	1.230	1.240	1.190
Average	1.506	1.464	1.414	1.380	1.316	1.214	1.220	1.228	1.182
Sigma	0.005	0.005	0.005	0.006	0.005	0.005	0.006	0.007	0.007

Drift Calculation

VIHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-40.0E-03	-90.0E-03	-130.0E-03	-190.0E-03	-300.0E-03	-290.0E-03	-280.0E-03	-330.0E-03
SN3	-	-40.0E-03	-100.0E-03	-130.0E-03	-190.0E-03	-290.0E-03	-290.0E-03	-280.0E-03	-320.0E-03
SN4	-	-40.0E-03	-90.0E-03	-130.0E-03	-190.0E-03	-290.0E-03	-290.0E-03	-280.0E-03	-330.0E-03
SN5	-	-40.0E-03	-90.0E-03	-120.0E-03	-190.0E-03	-290.0E-03	-280.0E-03	-280.0E-03	-310.0E-03
SN6	-	-50.0E-03	-90.0E-03	-120.0E-03	-190.0E-03	-290.0E-03	-280.0E-03	-270.0E-03	-330.0E-03
Average	-	-42.0E-03	-92.0E-03	-126.0E-03	-190.0E-03	-292.0E-03	-286.0E-03	-278.0E-03	-324.0E-03
Sigma	-	4.0E-03	4.0E-03	4.9E-03	1.7E-09	4.0E-03	4.9E-03	4.0E-03	8.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices		Issue:	02

**Measurements**

VIHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.500	1.500	1.500	1.500	1.500	1.500	1.500	1.500	1.500
<b>OFF samples</b>									
SN7	1.520	1.470	1.410	1.370	1.300	1.180	1.190	1.200	1.330
SN8	1.510	1.470	1.410	1.370	1.300	1.190	1.200	1.210	1.320
SN9	1.500	1.450	1.390	1.360	1.280	1.170	1.180	1.200	1.320
SN10	1.500	1.450	1.390	1.360	1.280	1.170	1.180	1.190	1.320
SN11	1.500	1.450	1.400	1.360	1.280	1.180	1.190	1.200	1.310
<b>Statistics</b>									
Min	1.500	1.450	1.390	1.360	1.280	1.170	1.180	1.190	1.310
Max	1.520	1.470	1.410	1.370	1.300	1.190	1.200	1.210	1.330
Average	1.506	1.458	1.400	1.364	1.288	1.178	1.188	1.200	1.320
Sigma	0.008	0.010	0.009	0.005	0.010	0.007	0.007	0.006	0.006

**Drift Calculation**

VIHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-50.0E-03	-110.0E-03	-150.0E-03	-220.0E-03	-340.0E-03	-330.0E-03	-320.0E-03	-190.0E-03
SN8	-	-40.0E-03	-100.0E-03	-140.0E-03	-210.0E-03	-320.0E-03	-310.0E-03	-300.0E-03	-190.0E-03
SN9	-	-50.0E-03	-110.0E-03	-140.0E-03	-220.0E-03	-330.0E-03	-320.0E-03	-300.0E-03	-180.0E-03
SN10	-	-50.0E-03	-110.0E-03	-140.0E-03	-220.0E-03	-330.0E-03	-320.0E-03	-310.0E-03	-180.0E-03
SN11	-	-50.0E-03	-100.0E-03	-140.0E-03	-220.0E-03	-320.0E-03	-310.0E-03	-300.0E-03	-190.0E-03
Average	-	-48.0E-03	-106.0E-03	-142.0E-03	-218.0E-03	-328.0E-03	-318.0E-03	-306.0E-03	-186.0E-03
Sigma	-	4.0E-03	4.9E-03	4.0E-03	4.0E-03	7.5E-03	7.5E-03	8.0E-03	4.9E-03

Parameter : Logic Input current : ILINL/CS

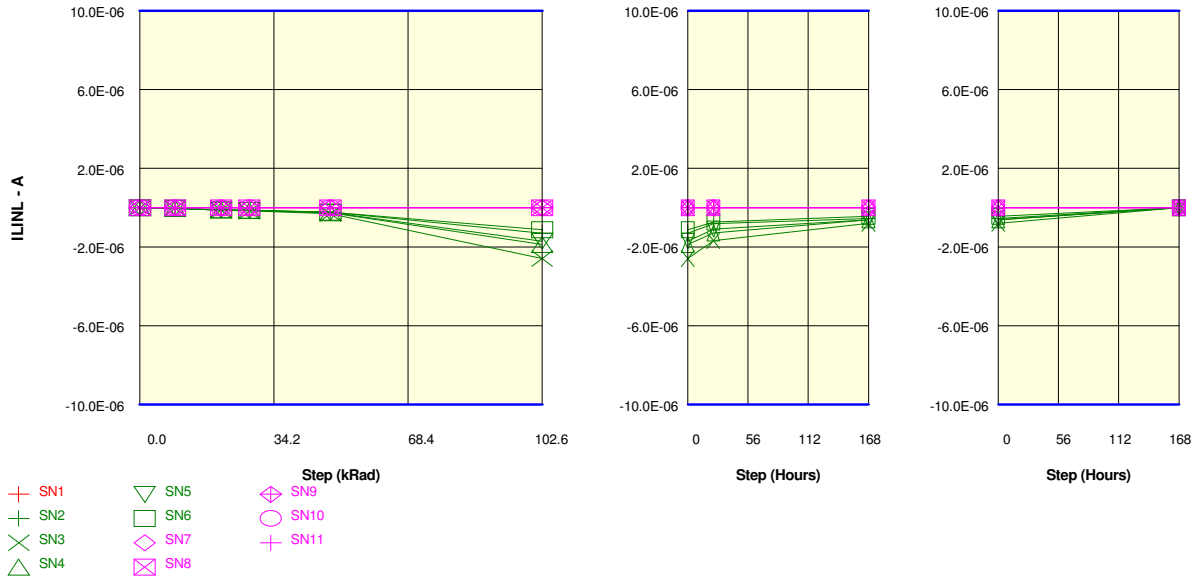
Test conditions : Vih=5V. Vil=0V

Unit : A

Spec Limit Min : -10.0E-06

Spec Limit Max : 10.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

ILINL/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-100.0E-12	-150.0E-12	-50.0E-12	-100.0E-12	-300.0E-12	-100.0E-12	-50.0E-12	-100.0E-12
ON samples									
SN2	-50.0E-12	-25.5E-09	-113.5E-09	-141.5E-09	-227.5E-09	-1.3E-06	-807.0E-09	-548.0E-09	-1.3E-09
SN3	-100.0E-12	-31.1E-09	-130.0E-09	-168.0E-09	-302.0E-09	-2.6E-06	-1.7E-06	-796.5E-09	-1.2E-09
SN4	-100.0E-12	-26.0E-09	-119.5E-09	-147.0E-09	-260.0E-09	-1.9E-06	-1.3E-06	-620.0E-09	-1.1E-09
SN5	-50.0E-12	-29.3E-09	-123.0E-09	-136.5E-09	-237.5E-09	-1.7E-06	-1.1E-06	-611.0E-09	-1.5E-09
SN6	-50.0E-12	-25.5E-09	-110.5E-09	-135.0E-09	-224.0E-09	-1.1E-06	-726.5E-09	-439.0E-09	-1.3E-09
Statistics									
Min	-100.0E-12	-31.1E-09	-130.0E-09	-168.0E-09	-302.0E-09	-2.6E-06	-1.7E-06	-796.5E-09	-1.5E-09
Max	-50.0E-12	-25.5E-09	-110.5E-09	-135.0E-09	-224.0E-09	-1.1E-06	-726.5E-09	-439.0E-09	-1.1E-09
Average	-70.0E-12	-27.5E-09	-119.3E-09	-145.6E-09	-250.2E-09	-1.7E-06	-1.1E-06	-602.9E-09	-1.3E-09
Sigma	24.5E-12	2.3E-09	6.9E-09	12.0E-09	28.8E-09	512.4E-09	343.3E-09	116.4E-09	132.7E-12

Drift Calculation

ILINL/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-25.4E-09	-113.5E-09	-141.5E-09	-227.5E-09	-1.3E-06	-807.0E-09	-548.0E-09	-1.3E-09
SN3	-	-31.0E-09	-129.9E-09	-167.9E-09	-301.9E-09	-2.6E-06	-1.7E-06	-796.4E-09	-1.1E-09
SN4	-	-25.9E-09	-119.4E-09	-146.9E-09	-259.9E-09	-1.9E-06	-1.3E-06	-619.9E-09	-1.0E-09
SN5	-	-29.3E-09	-123.0E-09	-136.5E-09	-237.5E-09	-1.7E-06	-1.1E-06	-611.0E-09	-1.5E-09
SN6	-	-25.5E-09	-110.5E-09	-135.0E-09	-224.0E-09	-1.1E-06	-726.5E-09	-439.0E-09	-1.3E-09
Average	-	-27.4E-09	-119.2E-09	-145.5E-09	-250.1E-09	-1.7E-06	-1.1E-06	-602.8E-09	-1.2E-09
Sigma	-	2.3E-09	6.9E-09	11.9E-09	28.8E-09	512.4E-09	343.3E-09	116.4E-09	153.0E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

ILINL/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-100.0E-12	-150.0E-12	-50.0E-12	-100.0E-12	-300.0E-12	-100.0E-12	-50.0E-12	-100.0E-12
OFF samples									
SN7	-100.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-150.0E-12	-300.0E-12	-150.0E-12	-150.0E-12	-50.0E-12
SN8	-150.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-150.0E-12	-250.0E-12	-150.0E-12	-150.0E-12	-100.0E-12
SN9	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-250.0E-12	-150.0E-12	-150.0E-12	-100.0E-12
SN10	-100.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-350.0E-12	-100.0E-12	-100.0E-12	0.0E+00
SN11	-100.0E-12	-150.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-250.0E-12	-150.0E-12	-150.0E-12	-150.0E-12
Statistics									
Min	-150.0E-12	-150.0E-12	-150.0E-12	-150.0E-12	-150.0E-12	-350.0E-12	-150.0E-12	-150.0E-12	-150.0E-12
Max	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-250.0E-12	-100.0E-12	-100.0E-12	0.0E+00
Average	-110.0E-12	-120.0E-12	-120.0E-12	-120.0E-12	-140.0E-12	-280.0E-12	-140.0E-12	-140.0E-12	-80.0E-12
Sigma	20.0E-12	24.5E-12	24.5E-12	24.5E-12	20.0E-12	40.0E-12	20.0E-12	20.0E-12	51.0E-12

**Drift Calculation**

ILINL/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	0.0E+00	-50.0E-12	0.0E+00	-50.0E-12	-200.0E-12	-50.0E-12	-50.0E-12	50.0E-12
SN8	-	50.0E-12	0.0E+00	50.0E-12	0.0E+00	-100.0E-12	0.0E+00	0.0E+00	50.0E-12
SN9	-	-50.0E-12	0.0E+00	0.0E+00	-50.0E-12	-150.0E-12	-50.0E-12	-50.0E-12	0.0E+00
SN10	-	0.0E+00	0.0E+00	-50.0E-12	0.0E+00	-250.0E-12	0.0E+00	0.0E+00	100.0E-12
SN11	-	-50.0E-12	0.0E+00	-50.0E-12	-50.0E-12	-150.0E-12	-50.0E-12	-50.0E-12	-50.0E-12
Average	-	-10.0E-12	-10.0E-12	-10.0E-12	-30.0E-12	-170.0E-12	-30.0E-12	-30.0E-12	30.0E-12
Sigma	-	37.4E-12	20.0E-12	37.4E-12	24.5E-12	51.0E-12	24.5E-12	24.5E-12	51.0E-12



Parameter : Logic Input current : ILINLR//C

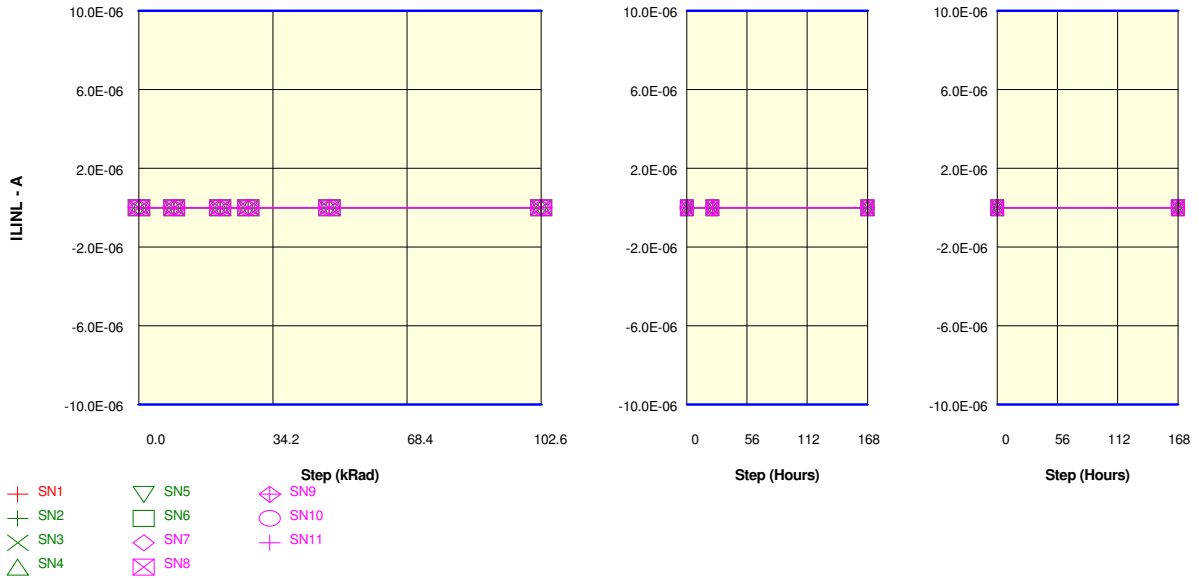
Test conditions : Vih=5V. Vil=0V

Unit : A

Spec Limit Min : -10.0E-06

Spec Limit Max : 10.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

ILINLR//C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-100.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-200.0E-12	-100.0E-12	-100.0E-12	-100.0E-12
ON samples									
SN2	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-300.0E-12	-100.0E-12	-150.0E-12	-100.0E-12
SN3	-100.0E-12	-200.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-400.0E-12	-150.0E-12	-100.0E-12	-150.0E-12
SN4	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-250.0E-12	-150.0E-12	-150.0E-12	-50.0E-12
SN5	-50.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-300.0E-12	-150.0E-12	-150.0E-12	-100.0E-12
SN6	-50.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-300.0E-12	-150.0E-12	-100.0E-12	-100.0E-12
Statistics									
Min	-100.0E-12	-200.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-400.0E-12	-150.0E-12	-150.0E-12	-150.0E-12
Max	-50.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-250.0E-12	-100.0E-12	-100.0E-12	-50.0E-12
Average	-80.0E-12	-140.0E-12	-100.0E-12	-110.0E-12	-130.0E-12	-310.0E-12	-140.0E-12	-130.0E-12	-100.0E-12
Sigma	24.5E-12	37.4E-12	0.0E+00	20.0E-12	24.5E-12	49.0E-12	20.0E-12	24.5E-12	31.6E-12

Drift Calculation

ILINLR//C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	0.0E+00	-50.0E-12	-200.0E-12	0.0E+00	-50.0E-12	0.0E+00
SN3	-	-100.0E-12	0.0E+00	-50.0E-12	-50.0E-12	-300.0E-12	-50.0E-12	0.0E+00	-50.0E-12
SN4	-	-50.0E-12	0.0E+00	0.0E+00	0.0E+00	-150.0E-12	-50.0E-12	-50.0E-12	50.0E-12
SN5	-	-100.0E-12	-50.0E-12	-50.0E-12	-50.0E-12	-250.0E-12	-100.0E-12	-100.0E-12	-50.0E-12
SN6	-	-50.0E-12	-50.0E-12	-50.0E-12	-100.0E-12	-250.0E-12	-100.0E-12	-50.0E-12	-50.0E-12
Average	-	-60.0E-12	-20.0E-12	-30.0E-12	-50.0E-12	-230.0E-12	-60.0E-12	-50.0E-12	-20.0E-12
Sigma	-	37.4E-12	24.5E-12	24.5E-12	31.6E-12	51.0E-12	37.4E-12	31.6E-12	40.0E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

ILINLR/C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-100.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-200.0E-12	-100.0E-12	-100.0E-12	-100.0E-12
OFF samples									
SN7	-100.0E-12	-100.0E-12	-50.0E-12	-150.0E-12	-150.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-100.0E-12
SN8	-50.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-200.0E-12	-100.0E-12	-100.0E-12	-100.0E-12
SN9	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-150.0E-12	-100.0E-12
SN10	-100.0E-12	-100.0E-12	-50.0E-12	-150.0E-12	-100.0E-12	-200.0E-12	-100.0E-12	-150.0E-12	-50.0E-12
SN11	-50.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-50.0E-12	-150.0E-12
Statistics									
Min	-100.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-150.0E-12	-200.0E-12	-150.0E-12	-150.0E-12	-150.0E-12
Max	-50.0E-12	-100.0E-12	-50.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-50.0E-12	-50.0E-12
Average	-80.0E-12	-100.0E-12	-100.0E-12	-120.0E-12	-110.0E-12	-160.0E-12	-110.0E-12	-120.0E-12	-100.0E-12
Sigma	24.5E-12	0.0E+00	44.7E-12	24.5E-12	20.0E-12	37.4E-12	20.0E-12	40.0E-12	31.6E-12

**Drift Calculation**

ILINLR/C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	0.0E+00	50.0E-12	-50.0E-12	-50.0E-12	0.0E+00	-50.0E-12	-50.0E-12	0.0E+00
SN8	-	-50.0E-12	-100.0E-12	-50.0E-12	-50.0E-12	-150.0E-12	-50.0E-12	-50.0E-12	-50.0E-12
SN9	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	-50.0E-12	0.0E+00	-50.0E-12	0.0E+00
SN10	-	0.0E+00	50.0E-12	-50.0E-12	0.0E+00	-100.0E-12	0.0E+00	-50.0E-12	50.0E-12
SN11	-	-50.0E-12	-100.0E-12	-50.0E-12	-50.0E-12	-100.0E-12	-50.0E-12	0.0E+00	-100.0E-12
Average	-	-20.0E-12	-20.0E-12	-40.0E-12	-30.0E-12	-80.0E-12	-30.0E-12	-40.0E-12	-20.0E-12
Sigma	-	24.5E-12	67.8E-12	20.0E-12	24.5E-12	51.0E-12	24.5E-12	20.0E-12	51.0E-12

Parameter : Logic Input current : ILINLBYTE

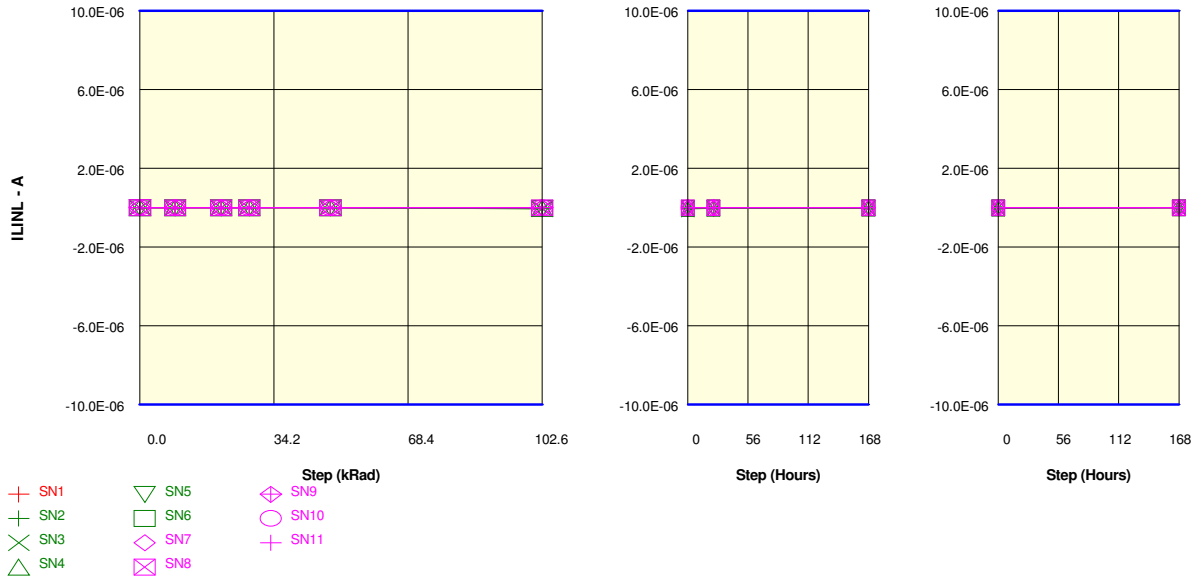
Test conditions : Vih=5V. Vil=0V

Unit : A

Spec Limit Min : -10.0E-06

Spec Limit Max : 10.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

ILINLBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	2.9E-09	3.0E-09	2.6E-09	3.0E-09	3.2E-09	3.2E-09	2.8E-09	3.2E-09	3.1E-09
ON samples									
SN2	2.8E-09	250.0E-12	-50.0E-12	-50.0E-12	-200.0E-12	-32.5E-09	-16.0E-09	-11.8E-09	-50.0E-12
SN3	3.1E-09	350.0E-12	-50.0E-12	-100.0E-12	-200.0E-12	-55.8E-09	-29.7E-09	-18.5E-09	-100.0E-12
SN4	3.2E-09	500.0E-12	-50.0E-12	-100.0E-12	-150.0E-12	-25.8E-09	-14.4E-09	-9.3E-09	-50.0E-12
SN5	3.2E-09	400.0E-12	-50.0E-12	-50.0E-12	-250.0E-12	-43.8E-09	-23.1E-09	-15.1E-09	0.0E+00
SN6	3.1E-09	450.0E-12	-50.0E-12	-150.0E-12	-250.0E-12	-30.8E-09	-16.7E-09	-10.7E-09	-100.0E-12
Statistics									
Min	2.8E-09	250.0E-12	-50.0E-12	-150.0E-12	-250.0E-12	-55.8E-09	-29.7E-09	-18.5E-09	-100.0E-12
Max	3.2E-09	500.0E-12	-50.0E-12	-50.0E-12	-150.0E-12	-25.8E-09	-14.4E-09	-9.3E-09	0.0E+00
Average	3.1E-09	390.0E-12	-50.0E-12	-90.0E-12	-210.0E-12	-37.7E-09	-20.0E-09	-13.1E-09	-60.0E-12
Sigma	146.3E-12	86.0E-12	0.0E+00	37.4E-12	37.4E-12	10.8E-09	5.7E-09	3.3E-09	37.4E-12

Drift Calculation

ILINLBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-2.6E-09	-2.9E-09	-2.9E-09	-3.0E-09	-35.3E-09	-18.8E-09	-14.6E-09	-2.9E-09
SN3	-	-2.7E-09	-3.1E-09	-3.2E-09	-3.3E-09	-58.9E-09	-32.7E-09	-21.6E-09	-3.2E-09
SN4	-	-2.7E-09	-3.3E-09	-3.3E-09	-3.4E-09	-29.0E-09	-17.6E-09	-12.5E-09	-3.3E-09
SN5	-	-2.8E-09	-3.3E-09	-3.3E-09	-3.5E-09	-47.0E-09	-26.3E-09	-18.3E-09	-3.2E-09
SN6	-	-2.6E-09	-3.1E-09	-3.2E-09	-3.3E-09	-33.8E-09	-19.8E-09	-13.7E-09	-3.2E-09
Average	-	-2.7E-09	-3.1E-09	-3.2E-09	-3.3E-09	-40.8E-09	-23.0E-09	-16.1E-09	-3.1E-09
Sigma	-	87.2E-12	146.3E-12	158.1E-12	150.3E-12	10.8E-09	5.7E-09	3.3E-09	140.0E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

ILINLBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	2.9E-09	3.0E-09	2.6E-09	3.0E-09	3.2E-09	3.2E-09	2.8E-09	3.2E-09	3.1E-09
OFF samples									
SN7	2.8E-09	350.0E-12	0.0E+00	-50.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-50.0E-12
SN8	3.2E-09	450.0E-12	0.0E+00	-50.0E-12	-50.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12
SN9	3.5E-09	450.0E-12	0.0E+00	-50.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-100.0E-12
SN10	3.0E-09	400.0E-12	-50.0E-12	-50.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-100.0E-12
SN11	3.4E-09	600.0E-12	0.0E+00	-50.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-50.0E-12
Statistics									
Min	2.8E-09	350.0E-12	-50.0E-12	-50.0E-12	-150.0E-12	-150.0E-12	-150.0E-12	-100.0E-12	-100.0E-12
Max	3.5E-09	600.0E-12	0.0E+00	-50.0E-12	-50.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-50.0E-12
Average	3.2E-09	450.0E-12	-10.0E-12	-50.0E-12	-110.0E-12	-130.0E-12	-110.0E-12	-100.0E-12	-80.0E-12
Sigma	243.7E-12	83.7E-12	20.0E-12	0.0E+00	37.4E-12	24.5E-12	20.0E-12	0.0E+00	24.5E-12

**Drift Calculation**

ILINLBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-2.5E-09	-2.8E-09	-2.9E-09	-2.9E-09	-3.0E-09	-2.9E-09	-2.9E-09	-2.9E-09
SN8	-	-2.7E-09	-3.2E-09	-3.2E-09	-3.2E-09	-3.3E-09	-3.3E-09	-3.3E-09	-3.3E-09
SN9	-	-3.0E-09	-3.5E-09	-3.5E-09	-3.6E-09	-3.6E-09	-3.6E-09	-3.6E-09	-3.6E-09
SN10	-	-2.6E-09	-3.1E-09	-3.1E-09	-3.2E-09	-3.1E-09	-3.1E-09	-3.1E-09	-3.1E-09
SN11	-	-2.8E-09	-3.4E-09	-3.5E-09	-3.6E-09	-3.6E-09	-3.5E-09	-3.5E-09	-3.5E-09
Average	-	-2.7E-09	-3.2E-09	-3.2E-09	-3.3E-09	-3.3E-09	-3.3E-09	-3.3E-09	-3.2E-09
Sigma	-	185.5E-12	237.9E-12	243.7E-12	250.2E-12	251.8E-12	244.1E-12	243.7E-12	249.8E-12

Parameter : Logic Input current : ILINH/CS

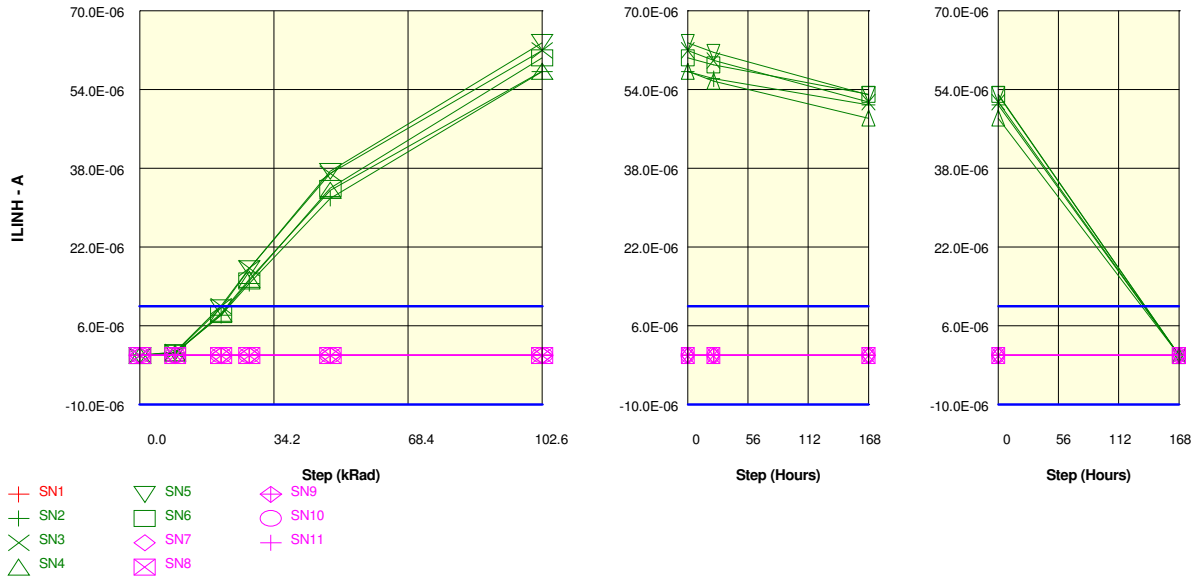
Test conditions : Vih=5V. Vil=0V

Unit : A

Spec Limit Min : -10.0E-06

Spec Limit Max : 10.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

ILINH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	500.0E-12	500.0E-12	450.0E-12	450.0E-12	350.0E-12	1.0E-09	450.0E-12	400.0E-12	500.0E-12
ON samples									
SN2	550.0E-12	478.0E-09	8.1E-06	14.6E-06	31.9E-06	57.7E-06	56.2E-06	50.9E-06	6.6E-09
SN3	500.0E-12	677.0E-09	10.0E-06	17.7E-06	37.0E-06	62.0E-06	59.9E-06	51.5E-06	6.1E-09
SN4	500.0E-12	451.5E-09	8.6E-06	15.5E-06	33.6E-06	57.7E-06	55.7E-06	48.2E-06	6.0E-09
SN5	450.0E-12	586.0E-09	9.7E-06	17.6E-06	37.4E-06	63.6E-06	61.6E-06	53.0E-06	7.9E-09
SN6	400.0E-12	447.5E-09	8.3E-06	15.1E-06	34.0E-06	60.5E-06	59.0E-06	53.1E-06	6.6E-09
Statistics									
Min	400.0E-12	447.5E-09	8.1E-06	14.6E-06	31.9E-06	57.7E-06	55.7E-06	48.2E-06	6.0E-09
Max	550.0E-12	677.0E-09	10.0E-06	17.7E-06	37.4E-06	63.6E-06	61.6E-06	53.1E-06	7.9E-09
Average	480.0E-12	528.0E-09	8.9E-06	16.1E-06	34.8E-06	60.3E-06	58.5E-06	51.3E-06	6.6E-09
Sigma	51.0E-12	89.9E-09	759.1E-09	1.3E-06	2.1E-06	2.3E-06	2.2E-06	1.8E-06	688.9E-12

Drift Calculation

ILINH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	477.5E-09	8.1E-06	14.6E-06	31.9E-06	57.6E-06	56.2E-06	50.9E-06	6.1E-09
SN3	-	676.5E-09	10.0E-06	17.7E-06	36.9E-06	61.9E-06	59.9E-06	51.4E-06	5.6E-09
SN4	-	451.0E-09	8.6E-06	15.4E-06	33.5E-06	57.7E-06	55.7E-06	48.2E-06	5.5E-09
SN5	-	585.6E-09	9.7E-06	17.6E-06	37.4E-06	63.5E-06	61.5E-06	52.9E-06	7.4E-09
SN6	-	447.1E-09	8.3E-06	15.1E-06	33.9E-06	60.4E-06	59.0E-06	53.0E-06	6.2E-09
Average	-	527.5E-09	8.9E-06	16.1E-06	34.7E-06	60.3E-06	58.5E-06	51.3E-06	6.1E-09
Sigma	-	89.9E-09	759.1E-09	1.3E-06	2.1E-06	2.3E-06	2.2E-06	1.8E-06	687.5E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

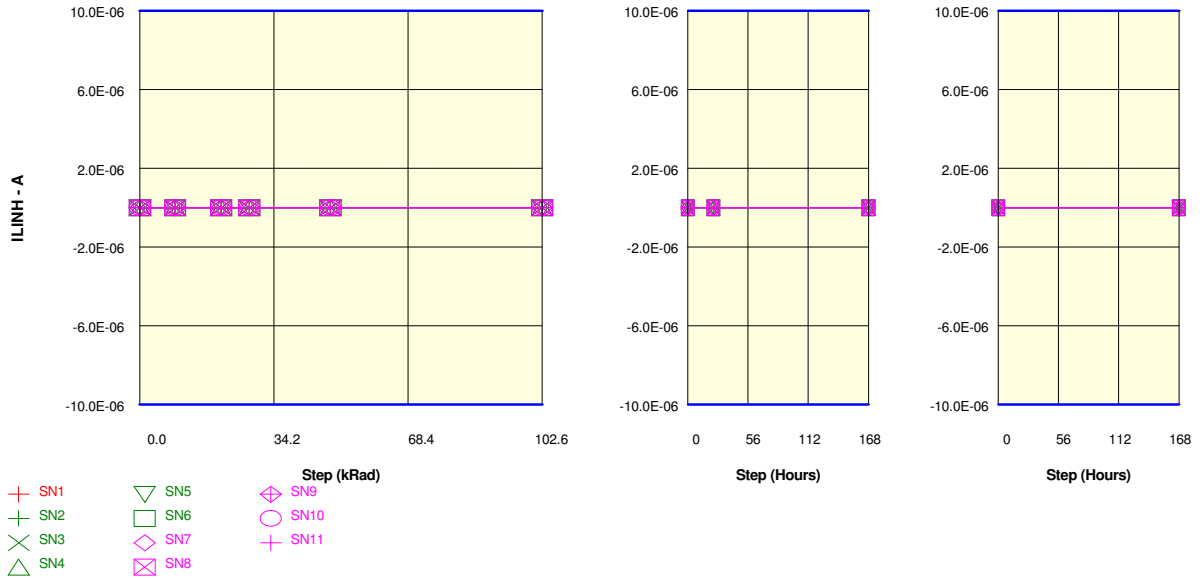
ILINH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	500.0E-12	500.0E-12	450.0E-12	450.0E-12	350.0E-12	1.0E-09	450.0E-12	400.0E-12	500.0E-12
<b>OFF samples</b>									
SN7	450.0E-12	450.0E-12	500.0E-12	500.0E-12	500.0E-12	1.1E-09	600.0E-12	550.0E-12	350.0E-12
SN8	350.0E-12	450.0E-12	450.0E-12	500.0E-12	550.0E-12	1.2E-09	600.0E-12	550.0E-12	400.0E-12
SN9	350.0E-12	500.0E-12	500.0E-12	450.0E-12	500.0E-12	1.2E-09	600.0E-12	550.0E-12	450.0E-12
SN10	450.0E-12	400.0E-12	500.0E-12	450.0E-12	550.0E-12	1.1E-09	650.0E-12	600.0E-12	350.0E-12
SN11	500.0E-12	450.0E-12	450.0E-12	450.0E-12	450.0E-12	1.1E-09	650.0E-12	700.0E-12	500.0E-12
<b>Statistics</b>									
Min	350.0E-12	400.0E-12	450.0E-12	450.0E-12	450.0E-12	1.1E-09	600.0E-12	550.0E-12	350.0E-12
Max	500.0E-12	500.0E-12	500.0E-12	500.0E-12	550.0E-12	1.2E-09	650.0E-12	700.0E-12	500.0E-12
Average	420.0E-12	450.0E-12	480.0E-12	470.0E-12	510.0E-12	1.1E-09	620.0E-12	590.0E-12	410.0E-12
Sigma	60.0E-12	31.6E-12	24.5E-12	24.5E-12	37.4E-12	40.0E-12	24.5E-12	58.3E-12	58.3E-12

**Drift Calculation**

ILINH/CS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	50.0E-12	50.0E-12	50.0E-12	650.0E-12	150.0E-12	100.0E-12	-100.0E-12
SN8	-	100.0E-12	100.0E-12	150.0E-12	200.0E-12	800.0E-12	250.0E-12	200.0E-12	50.0E-12
SN9	-	150.0E-12	150.0E-12	100.0E-12	150.0E-12	850.0E-12	250.0E-12	200.0E-12	100.0E-12
SN10	-	-50.0E-12	50.0E-12	0.0E+00	100.0E-12	650.0E-12	200.0E-12	150.0E-12	-100.0E-12
SN11	-	-50.0E-12	-50.0E-12	-50.0E-12	-50.0E-12	600.0E-12	150.0E-12	200.0E-12	0.0E+00
Average	-	30.0E-12	60.0E-12	50.0E-12	90.0E-12	710.0E-12	200.0E-12	170.0E-12	-10.0E-12
Sigma	-	81.2E-12	66.3E-12	70.7E-12	86.0E-12	97.0E-12	44.7E-12	40.0E-12	80.0E-12

Parameter : Logic Input current : ILINHR//C  
 Test conditions : Vih=5V. Vil=0V

Unit : A  
 Spec Limit Min : -10.0E-06  
 Spec Limit Max : 10.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

ILINHR//C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	300.0E-12	350.0E-12	200.0E-12	300.0E-12	300.0E-12	650.0E-12	450.0E-12	250.0E-12	350.0E-12
ON samples									
SN2	300.0E-12	450.0E-12	500.0E-12	400.0E-12	450.0E-12	1.0E-09	600.0E-12	400.0E-12	350.0E-12
SN3	350.0E-12	350.0E-12	550.0E-12	500.0E-12	350.0E-12	1.1E-09	450.0E-12	500.0E-12	400.0E-12
SN4	300.0E-12	450.0E-12	450.0E-12	450.0E-12	500.0E-12	900.0E-12	450.0E-12	500.0E-12	450.0E-12
SN5	400.0E-12	450.0E-12	450.0E-12	400.0E-12	450.0E-12	1.0E-09	500.0E-12	400.0E-12	350.0E-12
SN6	400.0E-12	450.0E-12	400.0E-12	400.0E-12	400.0E-12	1.1E-09	450.0E-12	550.0E-12	350.0E-12
Statistics									
Min	300.0E-12	350.0E-12	400.0E-12	400.0E-12	350.0E-12	900.0E-12	450.0E-12	400.0E-12	350.0E-12
Max	400.0E-12	450.0E-12	550.0E-12	500.0E-12	500.0E-12	1.1E-09	600.0E-12	550.0E-12	450.0E-12
Average	350.0E-12	430.0E-12	470.0E-12	430.0E-12	430.0E-12	1.0E-09	490.0E-12	470.0E-12	380.0E-12
Sigma	44.7E-12	40.0E-12	51.0E-12	40.0E-12	51.0E-12	74.8E-12	58.3E-12	60.0E-12	40.0E-12

Drift Calculation

ILINHR//C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	150.0E-12	200.0E-12	100.0E-12	150.0E-12	700.0E-12	300.0E-12	100.0E-12	50.0E-12
SN3	-	0.0E+00	200.0E-12	150.0E-12	0.0E+00	750.0E-12	100.0E-12	150.0E-12	50.0E-12
SN4	-	150.0E-12	150.0E-12	150.0E-12	200.0E-12	600.0E-12	150.0E-12	200.0E-12	150.0E-12
SN5	-	50.0E-12	50.0E-12	0.0E+00	50.0E-12	600.0E-12	100.0E-12	0.0E+00	-50.0E-12
SN6	-	50.0E-12	0.0E+00	0.0E+00	0.0E+00	700.0E-12	50.0E-12	150.0E-12	-50.0E-12
Average	-	80.0E-12	120.0E-12	80.0E-12	80.0E-12	670.0E-12	140.0E-12	120.0E-12	30.0E-12
Sigma	-	60.0E-12	81.2E-12	67.8E-12	81.2E-12	60.0E-12	86.0E-12	67.8E-12	74.8E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT				Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices		Issue:	02

**Measurements**

ILINHR/C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	300.0E-12	350.0E-12	200.0E-12	300.0E-12	300.0E-12	650.0E-12	450.0E-12	250.0E-12	350.0E-12
<b>OFF samples</b>									
SN7	300.0E-12	350.0E-12	300.0E-12	300.0E-12	400.0E-12	700.0E-12	400.0E-12	300.0E-12	400.0E-12
SN8	350.0E-12	350.0E-12	400.0E-12	400.0E-12	350.0E-12	800.0E-12	350.0E-12	400.0E-12	350.0E-12
SN9	250.0E-12	250.0E-12	300.0E-12	300.0E-12	400.0E-12	700.0E-12	400.0E-12	350.0E-12	300.0E-12
SN10	300.0E-12	250.0E-12	300.0E-12	300.0E-12	400.0E-12	700.0E-12	400.0E-12	400.0E-12	300.0E-12
SN11	300.0E-12	350.0E-12	300.0E-12	350.0E-12	400.0E-12	650.0E-12	350.0E-12	350.0E-12	400.0E-12
<b>Statistics</b>									
Min	250.0E-12	250.0E-12	300.0E-12	300.0E-12	350.0E-12	650.0E-12	350.0E-12	300.0E-12	300.0E-12
Max	350.0E-12	350.0E-12	400.0E-12	400.0E-12	400.0E-12	800.0E-12	400.0E-12	400.0E-12	400.0E-12
Average	300.0E-12	310.0E-12	320.0E-12	330.0E-12	390.0E-12	710.0E-12	380.0E-12	360.0E-12	350.0E-12
Sigma	31.6E-12	49.0E-12	40.0E-12	40.0E-12	20.0E-12	49.0E-12	24.5E-12	37.4E-12	44.7E-12

**Drift Calculation**

ILINHR/C	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	50.0E-12	0.0E+00	0.0E+00	100.0E-12	400.0E-12	100.0E-12	0.0E+00	100.0E-12
SN8	-	0.0E+00	50.0E-12	50.0E-12	0.0E+00	450.0E-12	0.0E+00	50.0E-12	0.0E+00
SN9	-	0.0E+00	50.0E-12	50.0E-12	150.0E-12	450.0E-12	150.0E-12	100.0E-12	50.0E-12
SN10	-	-50.0E-12	0.0E+00	0.0E+00	100.0E-12	400.0E-12	100.0E-12	100.0E-12	0.0E+00
SN11	-	50.0E-12	0.0E+00	50.0E-12	100.0E-12	350.0E-12	50.0E-12	50.0E-12	100.0E-12
Average	-	10.0E-12	20.0E-12	30.0E-12	90.0E-12	410.0E-12	80.0E-12	60.0E-12	50.0E-12
Sigma	-	37.4E-12	24.5E-12	24.5E-12	49.0E-12	37.4E-12	51.0E-12	37.4E-12	44.7E-12



Parameter : Logic Input current : ILINHBYTE

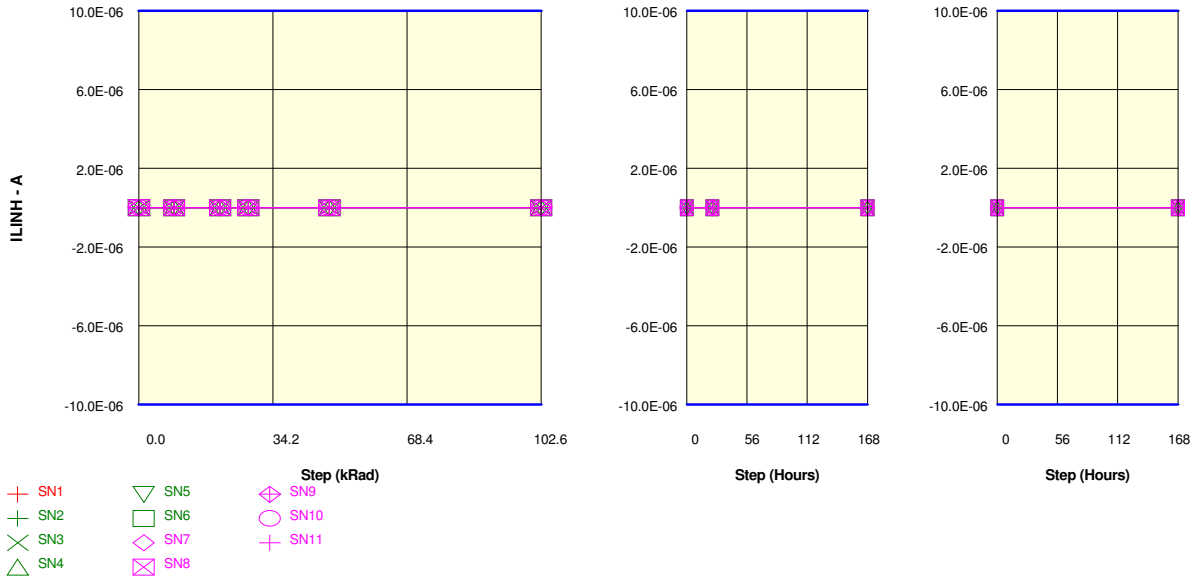
Test conditions : Vih=5V. Vil=0V

Unit : A

Spec Limit Min : -10.0E-06

Spec Limit Max : 10.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

ILINHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	3.5E-09	3.6E-09	3.2E-09	3.6E-09	3.8E-09	4.2E-09	3.4E-09	3.9E-09	3.6E-09
ON samples									
SN2	3.3E-09	700.0E-12	350.0E-12	350.0E-12	300.0E-12	700.0E-12	400.0E-12	300.0E-12	250.0E-12
SN3	3.6E-09	750.0E-12	450.0E-12	350.0E-12	350.0E-12	600.0E-12	300.0E-12	300.0E-12	250.0E-12
SN4	3.7E-09	700.0E-12	400.0E-12	350.0E-12	400.0E-12	600.0E-12	300.0E-12	400.0E-12	300.0E-12
SN5	3.8E-09	900.0E-12	350.0E-12	400.0E-12	300.0E-12	600.0E-12	400.0E-12	400.0E-12	300.0E-12
SN6	3.7E-09	900.0E-12	300.0E-12	350.0E-12	300.0E-12	700.0E-12	350.0E-12	400.0E-12	250.0E-12
Statistics									
Min	3.3E-09	700.0E-12	300.0E-12	350.0E-12	300.0E-12	600.0E-12	300.0E-12	300.0E-12	250.0E-12
Max	3.8E-09	900.0E-12	450.0E-12	400.0E-12	400.0E-12	700.0E-12	400.0E-12	400.0E-12	300.0E-12
Average	3.6E-09	790.0E-12	370.0E-12	360.0E-12	330.0E-12	640.0E-12	350.0E-12	360.0E-12	270.0E-12
Sigma	159.4E-12	91.7E-12	51.0E-12	20.0E-12	40.0E-12	49.0E-12	44.7E-12	49.0E-12	24.5E-12

Drift Calculation

ILINHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-2.6E-09	-3.0E-09	-3.0E-09	-3.0E-09	-2.6E-09	-2.9E-09	-3.0E-09	-3.1E-09
SN3	-	-2.8E-09	-3.1E-09	-3.2E-09	-3.2E-09	-3.0E-09	-3.3E-09	-3.3E-09	-3.3E-09
SN4	-	-3.0E-09	-3.3E-09	-3.4E-09	-3.3E-09	-3.1E-09	-3.4E-09	-3.3E-09	-3.4E-09
SN5	-	-2.9E-09	-3.4E-09	-3.4E-09	-3.5E-09	-3.2E-09	-3.4E-09	-3.4E-09	-3.5E-09
SN6	-	-2.8E-09	-3.4E-09	-3.3E-09	-3.4E-09	-3.0E-09	-3.3E-09	-3.3E-09	-3.4E-09
Average	-	-2.8E-09	-3.2E-09	-3.2E-09	-3.3E-09	-3.0E-09	-3.2E-09	-3.2E-09	-3.3E-09
Sigma	-	130.4E-12	169.1E-12	150.3E-12	153.0E-12	192.4E-12	177.2E-12	120.8E-12	143.5E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

ILINHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	3.5E-09	3.6E-09	3.2E-09	3.6E-09	3.8E-09	4.2E-09	3.4E-09	3.9E-09	3.6E-09
<b>OFF samples</b>									
SN7	3.5E-09	850.0E-12	300.0E-12	250.0E-12	300.0E-12	550.0E-12	250.0E-12	250.0E-12	300.0E-12
SN8	3.9E-09	900.0E-12	350.0E-12	250.0E-12	350.0E-12	550.0E-12	250.0E-12	300.0E-12	250.0E-12
SN9	4.0E-09	900.0E-12	400.0E-12	350.0E-12	400.0E-12	550.0E-12	300.0E-12	300.0E-12	250.0E-12
SN10	3.7E-09	900.0E-12	350.0E-12	400.0E-12	250.0E-12	650.0E-12	250.0E-12	250.0E-12	250.0E-12
SN11	4.0E-09	950.0E-12	300.0E-12	300.0E-12	300.0E-12	600.0E-12	350.0E-12	400.0E-12	200.0E-12
<b>Statistics</b>									
Min	3.5E-09	850.0E-12	300.0E-12	250.0E-12	250.0E-12	550.0E-12	250.0E-12	250.0E-12	200.0E-12
Max	4.0E-09	950.0E-12	400.0E-12	400.0E-12	400.0E-12	650.0E-12	350.0E-12	400.0E-12	300.0E-12
Average	3.8E-09	900.0E-12	340.0E-12	310.0E-12	320.0E-12	580.0E-12	280.0E-12	300.0E-12	250.0E-12
Sigma	197.5E-12	31.6E-12	37.4E-12	58.3E-12	51.0E-12	40.0E-12	40.0E-12	54.8E-12	31.6E-12

**Drift Calculation**

ILINHBYTE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-2.7E-09	-3.2E-09	-3.3E-09	-3.2E-09	-3.0E-09	-3.3E-09	-3.3E-09	-3.2E-09
SN8	-	-3.0E-09	-3.5E-09	-3.6E-09	-3.5E-09	-3.3E-09	-3.6E-09	-3.6E-09	-3.6E-09
SN9	-	-3.1E-09	-3.6E-09	-3.7E-09	-3.6E-09	-3.5E-09	-3.7E-09	-3.7E-09	-3.8E-09
SN10	-	-2.8E-09	-3.3E-09	-3.3E-09	-3.4E-09	-3.0E-09	-3.4E-09	-3.4E-09	-3.4E-09
SN11	-	-3.1E-09	-3.7E-09	-3.7E-09	-3.7E-09	-3.4E-09	-3.7E-09	-3.6E-09	-3.8E-09
Average	-	-2.9E-09	-3.5E-09	-3.5E-09	-3.5E-09	-3.2E-09	-3.5E-09	-3.5E-09	-3.6E-09
Sigma	-	173.2E-12	185.5E-12	198.5E-12	172.0E-12	206.4E-12	169.1E-12	158.1E-12	223.6E-12

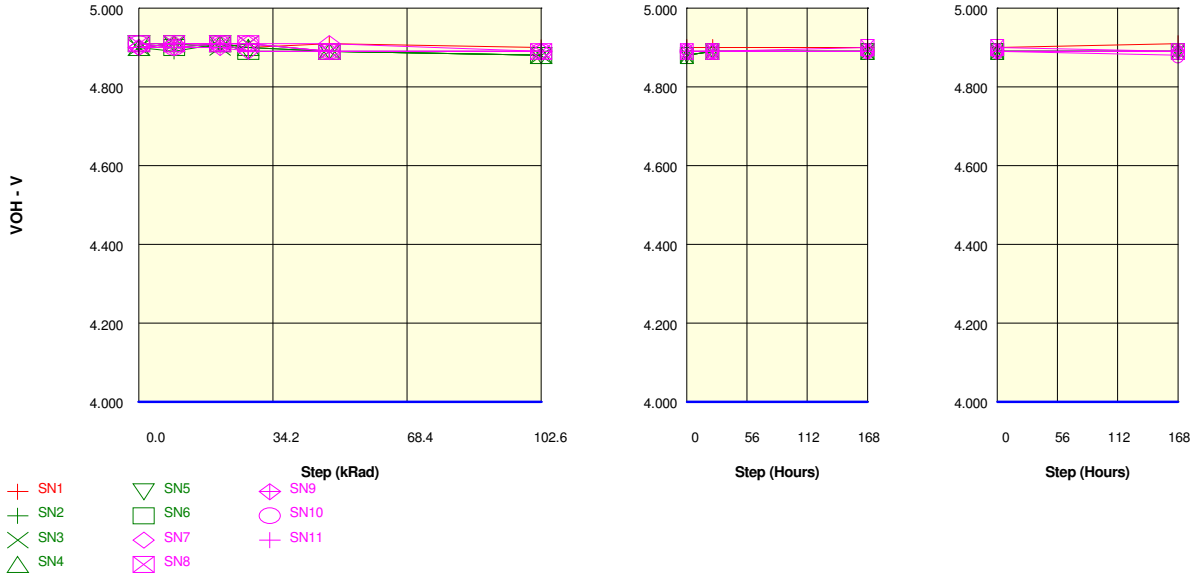
Parameter : Logic output high voltage : VOHD15

Test conditions : IOH=0.5mA

Unit : V

Spec Limit Min : 4.000

Spec limits are represented in bold lines on the graphic.



Measurements

VOHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.900	4.910	4.900	4.900	4.900	4.910
ON samples									
SN2	4.900	4.890	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.910	4.900	4.910	4.890	4.880	4.890	4.890	4.890
SN4	4.900	4.910	4.910	4.900	4.890	4.880	4.890	4.890	4.890
SN5	4.910	4.910	4.910	4.890	4.890	4.880	4.890	4.890	4.890
SN6	4.910	4.900	4.910	4.890	4.890	4.880	4.890	4.890	4.890
Statistics									
Min	4.900	4.890	4.900	4.890	4.890	4.880	4.890	4.890	4.890
Max	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
Average	4.904	4.904	4.908	4.898	4.890	4.882	4.890	4.890	4.890
Sigma	0.005	0.008	0.004	0.007	0.000	0.004	0.000	0.000	0.000

Drift Calculation

VOHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	0.0E+00	10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	0.0E+00	0.0E+00	-20.0E-03	-20.0E-03	-30.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN6	-	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-30.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
Average	-	-177.6E-18	4.0E-03	-6.0E-03	-14.0E-03	-22.0E-03	-14.0E-03	-14.0E-03	-14.0E-03
Sigma	-	8.9E-03	4.9E-03	12.0E-03	4.9E-03	7.5E-03	4.9E-03	4.9E-03	4.9E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

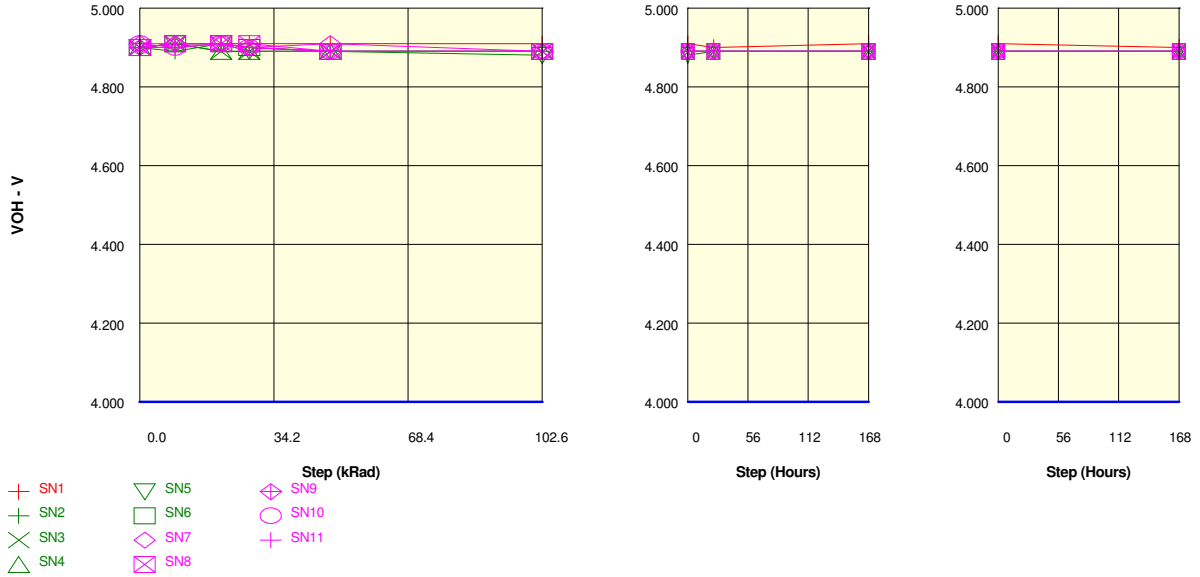
**Measurements**

VOHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.900	4.910	4.900	4.900	4.900	4.910
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
SN8	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.900	4.890
SN9	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.890	4.890
SN10	4.910	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.880
SN11	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.900	4.890
Average	4.904	4.906	4.908	4.902	4.894	4.890	4.890	4.892	4.888
Sigma	0.005	0.005	0.004	0.010	0.008	0.000	0.000	0.004	0.004

**Drift Calculation**

VOHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN8	-	0.0E+00	0.0E+00	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-20.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN10	-	-10.0E-03	0.0E+00	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-30.0E-03
SN11	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	2.0E-03	4.0E-03	-2.0E-03	-10.0E-03	-14.0E-03	-14.0E-03	-12.0E-03	-16.0E-03
Sigma	-	7.5E-03	4.9E-03	7.5E-03	11.0E-03	4.9E-03	4.9E-03	4.0E-03	8.0E-03

Parameter : Logic output high voltage : VOHD14  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
ON samples									
SN2	4.900	4.890	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890	4.890
SN4	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890	4.890
SN5	4.900	4.910	4.910	4.890	4.890	4.880	4.890	4.890	4.890
SN6	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Statistics									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.890	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.906	4.902	4.894	4.890	4.888	4.890	4.890	4.890
Sigma	0.000	0.008	0.010	0.005	0.000	0.004	0.000	0.000	0.000

**Drift Calculation**

VOHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	6.0E-03	2.0E-03	-6.0E-03	-10.0E-03	-12.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Sigma	-	8.0E-03	9.8E-03	4.9E-03	90.2E-12	4.0E-03	90.2E-12	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

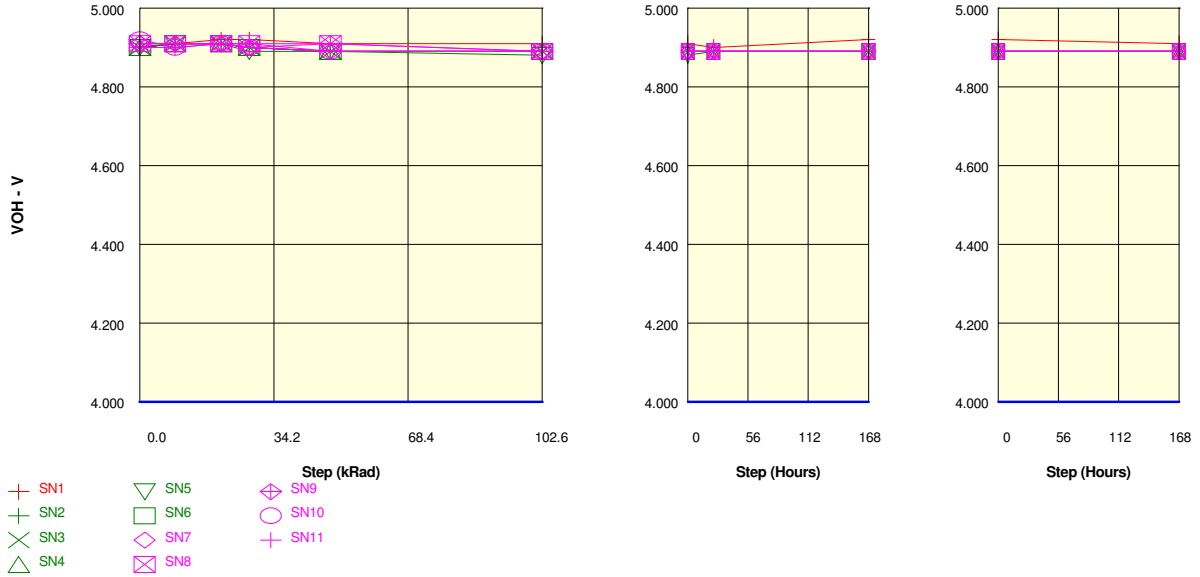
**Measurements**

VOHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.900	4.910	4.890	4.890	4.890	4.890
SN8	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN10	4.910	4.900	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN11	4.900	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890
Max	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
Average	4.904	4.906	4.910	4.900	4.894	4.890	4.890	4.890	4.890
Sigma	0.005	0.005	0.000	0.006	0.008	0.000	0.000	0.000	0.000

**Drift Calculation**

VOHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	0.0E+00	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN10	-	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN11	-	0.0E+00	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	2.0E-03	6.0E-03	-4.0E-03	-10.0E-03	-14.0E-03	-14.0E-03	-14.0E-03	-14.0E-03
Sigma	-	7.5E-03	4.9E-03	8.0E-03	11.0E-03	4.9E-03	4.9E-03	4.9E-03	4.9E-03

Parameter : Logic output high voltage : VOHD13  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.920	4.920	4.910	4.910	4.900	4.920	4.910
ON samples									
SN2	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN4	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN5	4.900	4.910	4.910	4.890	4.890	4.880	4.890	4.890	4.890
SN6	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Statistics									
Min	4.900	4.910	4.910	4.890	4.890	4.880	4.890	4.890	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.910	4.910	4.898	4.890	4.888	4.890	4.890	4.890
Sigma	0.000	0.000	0.000	0.004	0.000	0.004	0.000	0.000	0.000

**Drift Calculation**

VOHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	10.0E-03	10.0E-03	-2.0E-03	-10.0E-03	-12.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Sigma	-	127.5E-12	127.5E-12	4.0E-03	90.2E-12	4.0E-03	90.2E-12	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

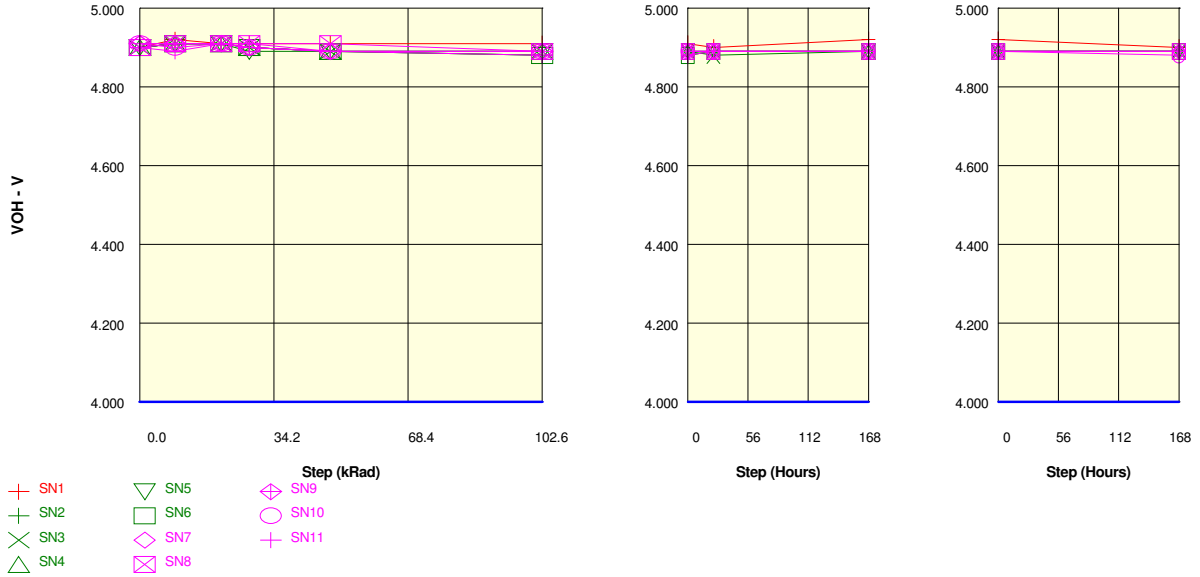
VOHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.920	4.920	4.910	4.910	4.900	4.920	4.910
<b>OFF samples</b>									
SN7	4.910	4.910	4.910	4.900	4.910	4.890	4.890	4.890	4.890
SN8	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN10	4.920	4.900	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN11	4.900	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.900	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Max	4.920	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
Average	4.910	4.906	4.910	4.904	4.898	4.890	4.890	4.890	4.890
Sigma	0.006	0.005	0.000	0.005	0.010	0.000	0.000	0.000	0.000

**Drift Calculation**

VOHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	0.0E+00	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN8	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN10	-	-20.0E-03	-10.0E-03	-20.0E-03	-30.0E-03	-30.0E-03	-30.0E-03	-30.0E-03	-30.0E-03
SN11	-	0.0E+00	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	-4.0E-03	0.0E+00	-6.0E-03	-12.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
Sigma	-	8.0E-03	6.3E-03	10.2E-03	11.7E-03	6.3E-03	6.3E-03	6.3E-03	6.3E-03



Parameter : Logic output high voltage : VOHD12  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.920	4.910	4.910	4.910	4.910	4.900	4.920	4.900
ON samples									
SN2	4.900	4.910	4.910	4.900	4.890	4.880	4.890	4.890	4.890
SN3	4.900	4.910	4.910	4.900	4.890	4.890	4.880	4.890	4.890
SN4	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN5	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN6	4.900	4.910	4.910	4.900	4.890	4.880	4.890	4.890	4.890
Statistics									
Min	4.900	4.910	4.910	4.890	4.890	4.880	4.880	4.890	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.910	4.910	4.898	4.890	4.886	4.888	4.890	4.890
Sigma	0.000	0.000	0.000	0.004	0.000	0.005	0.004	0.000	0.000

**Drift Calculation**

VOHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	10.0E-03	10.0E-03	-2.0E-03	-10.0E-03	-14.0E-03	-12.0E-03	-10.0E-03	-10.0E-03
Sigma	-	127.5E-12	127.5E-12	4.0E-03	90.2E-12	4.9E-03	4.0E-03	90.2E-12	90.2E-12

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	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.920	4.910	4.910	4.910	4.910	4.900	4.920	4.900
OFF samples									
SN7	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN8	4.900	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN10	4.910	4.900	4.910	4.900	4.890	4.890	4.890	4.890	4.880
SN11	4.900	4.890	4.910	4.910	4.890	4.880	4.890	4.890	4.890
Statistics									
Min	4.900	4.890	4.910	4.900	4.890	4.880	4.890	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
Average	4.906	4.904	4.910	4.904	4.894	4.888	4.890	4.890	4.888
Sigma	0.005	0.008	0.000	0.005	0.008	0.004	0.000	0.000	0.004

**Drift Calculation**

VOHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN10	-	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-30.0E-03
SN11	-	-10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	-2.0E-03	4.0E-03	-2.0E-03	-12.0E-03	-18.0E-03	-16.0E-03	-16.0E-03	-18.0E-03
Sigma	-	7.5E-03	4.9E-03	9.8E-03	11.7E-03	4.0E-03	4.9E-03	4.9E-03	7.5E-03

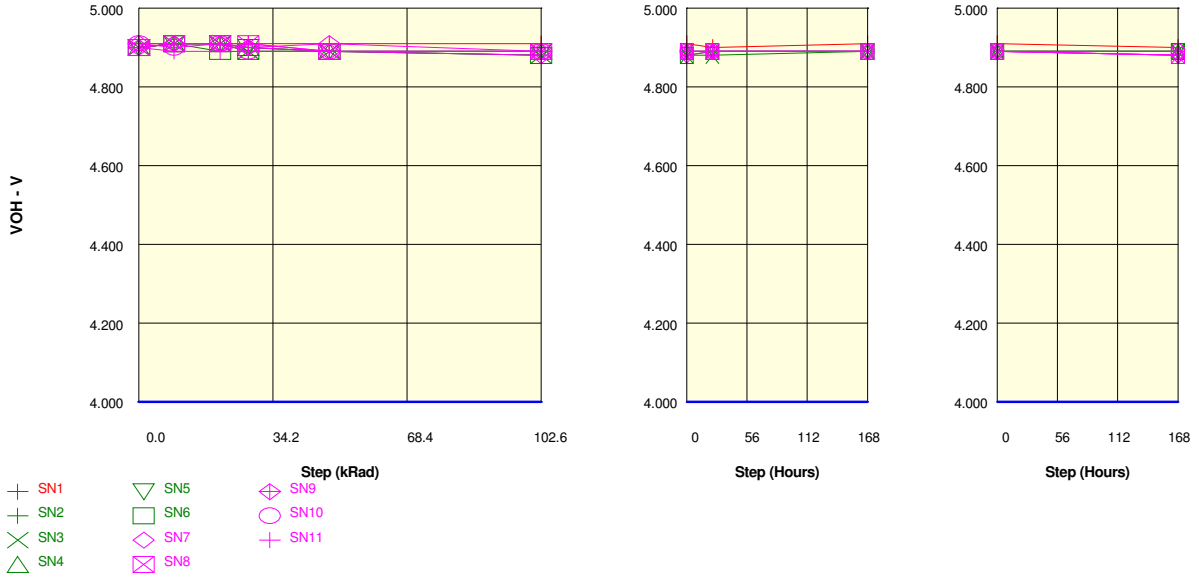
Parameter : Logic output high voltage : VOHD11

Test conditions : IOH=0.5mA

Unit : V

Spec Limit Min : 4.000

Spec limits are represented in bold lines on the graphic.



Measurements

VOHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
ON samples									
SN2	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.910	4.910	4.890	4.890	4.880	4.880	4.890	4.890
SN4	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN5	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN6	4.900	4.910	4.890	4.890	4.890	4.880	4.890	4.890	4.890
Statistics									
Min	4.900	4.910	4.890	4.890	4.890	4.880	4.880	4.890	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.910	4.906	4.894	4.890	4.886	4.888	4.890	4.890
Sigma	0.000	0.000	0.008	0.005	0.000	0.005	0.004	0.000	0.000

Drift Calculation

VOHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	10.0E-03	6.0E-03	-6.0E-03	-10.0E-03	-14.0E-03	-12.0E-03	-10.0E-03	-10.0E-03
Sigma	-	127.5E-12	8.0E-03	4.9E-03	90.2E-12	4.9E-03	4.0E-03	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

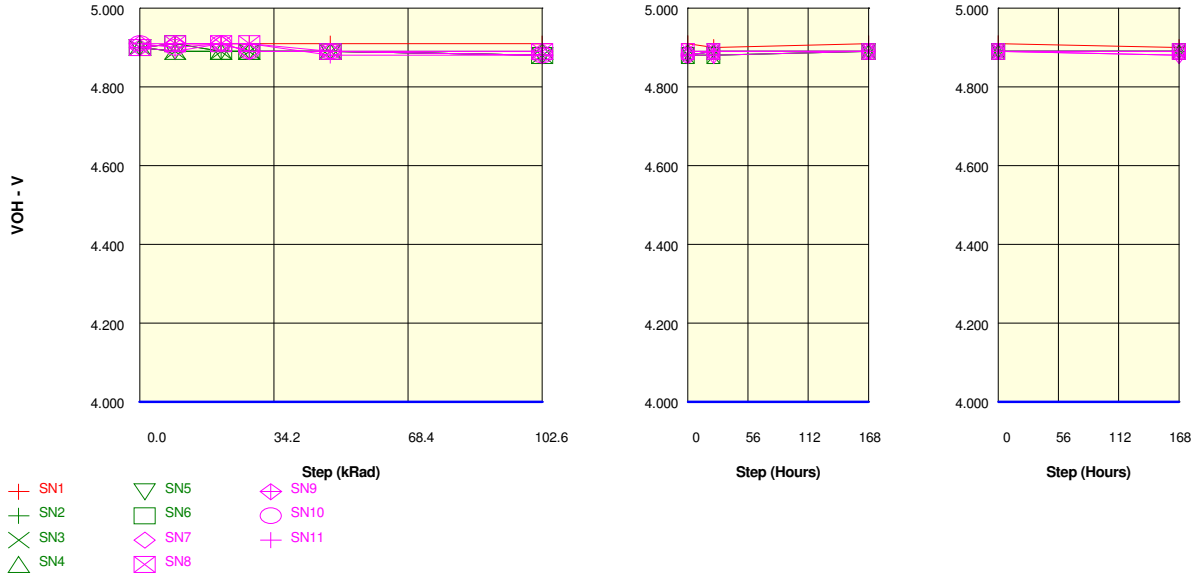
**Measurements**

VOHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.900	4.910	4.890	4.890	4.890	4.880
SN8	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.880
SN9	4.910	4.910	4.910	4.900	4.890	4.880	4.890	4.890	4.880
SN10	4.910	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN11	4.900	4.890	4.890	4.910	4.890	4.890	4.890	4.890	4.880
<b>Statistics</b>									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
Average	4.904	4.904	4.906	4.902	4.894	4.888	4.890	4.890	4.882
Sigma	0.005	0.008	0.008	0.007	0.008	0.004	0.000	0.000	0.004

**Drift Calculation**

VOHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	0.0E+00	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-30.0E-03	-20.0E-03	-20.0E-03	-30.0E-03
SN10	-	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN11	-	-10.0E-03	-10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
Average	-	-177.6E-18	2.0E-03	-2.0E-03	-10.0E-03	-16.0E-03	-14.0E-03	-14.0E-03	-22.0E-03
Sigma	-	8.9E-03	7.5E-03	11.7E-03	11.0E-03	8.0E-03	4.9E-03	4.9E-03	4.0E-03

Parameter : Logic output high voltage : VOHD10  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
<b>ON samples</b>									
SN2	4.900	4.910	4.890	4.890	4.890	4.880	4.890	4.890	4.890
SN3	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
SN4	4.900	4.890	4.890	4.890	4.890	4.890	4.890	4.890	4.890
SN5	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.890	4.890
SN6	4.900	4.910	4.890	4.890	4.890	4.880	4.880	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
Max	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.898	4.890	4.890	4.890	4.882	4.886	4.890	4.890
Sigma	0.000	0.010	0.000	0.000	0.000	0.004	0.005	0.000	0.000

**Drift Calculation**

VOHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>ON samples</b>									
SN2	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN4	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
Average	-	-2.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-18.0E-03	-14.0E-03	-10.0E-03	-10.0E-03
Sigma	-	9.8E-03	90.2E-12	90.2E-12	90.2E-12	4.0E-03	4.9E-03	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

VOHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN8	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.910	4.890	4.890	4.880	4.880	4.890	4.880
SN10	4.910	4.900	4.910	4.890	4.890	4.880	4.890	4.890	4.890
SN11	4.900	4.890	4.910	4.910	4.880	4.880	4.890	4.890	4.880
<b>Statistics</b>									
Min	4.900	4.890	4.910	4.890	4.880	4.880	4.880	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
Average	4.904	4.904	4.910	4.898	4.888	4.884	4.888	4.890	4.886
Sigma	0.005	0.008	0.000	0.010	0.004	0.005	0.004	0.000	0.005

**Drift Calculation**

VOHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	0.0E+00	-20.0E-03	-20.0E-03	-30.0E-03	-30.0E-03	-20.0E-03	-30.0E-03
SN10	-	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-30.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN11	-	-10.0E-03	10.0E-03	10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
Average	-	-177.6E-18	6.0E-03	-6.0E-03	-16.0E-03	-20.0E-03	-16.0E-03	-14.0E-03	-18.0E-03
Sigma	-	8.9E-03	4.9E-03	13.6E-03	4.9E-03	8.9E-03	8.0E-03	4.9E-03	7.5E-03

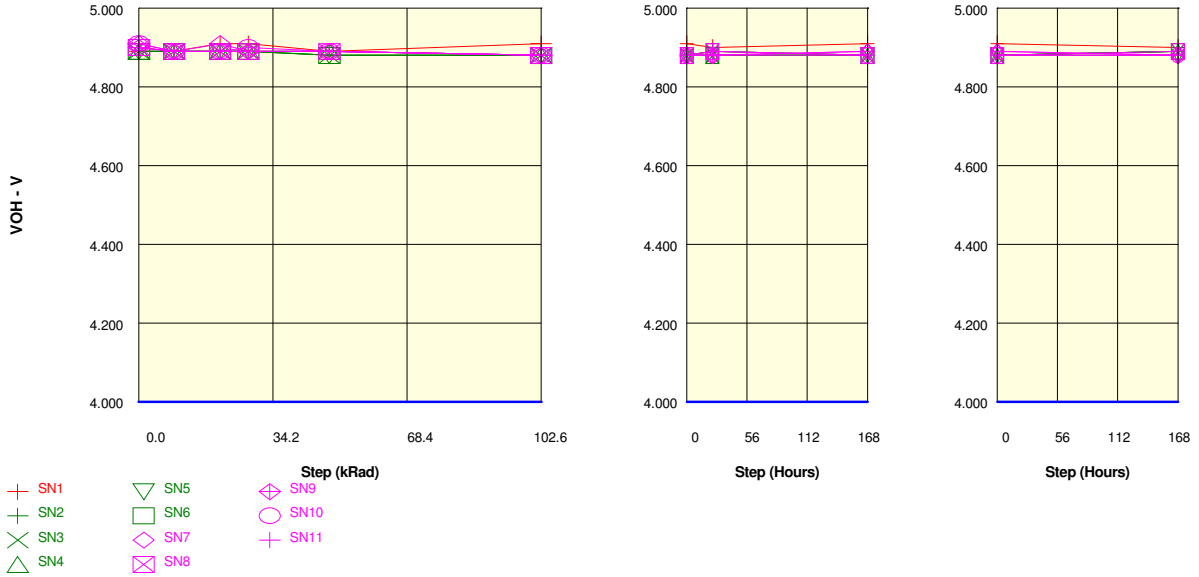
Parameter : Logic output high voltage : VOHD9

Test conditions : IOH=0.5mA

Unit : V

Spec Limit Min : 4.000

Spec limits are represented in bold lines on the graphic.



Measurements

VOHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.890	4.890	4.910	4.910	4.890	4.910	4.900	4.910	4.900
ON samples									
SN2	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.880	4.890
SN3	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.880	4.890
SN4	4.890	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.890
SN5	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.880	4.880
SN6	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.880	4.890
Statistics									
Min	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.880	4.880
Max	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.880	4.890
Average	4.892	4.890	4.890	4.890	4.884	4.880	4.884	4.880	4.888
Sigma	0.004	0.000	0.000	0.000	0.005	0.000	0.005	0.000	0.004

Drift Calculation

VOHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-20.0E-03	-10.0E-03
SN3	-	0.0E+00	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	0.0E+00
SN4	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	0.0E+00
SN5	-	0.0E+00	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	0.0E+00	-10.0E-03	-10.0E-03
SN6	-	0.0E+00	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	0.0E+00
Average	-	-2.0E-03	-2.0E-03	-2.0E-03	-8.0E-03	-12.0E-03	-8.0E-03	-12.0E-03	-4.0E-03
Sigma	-	4.0E-03	4.0E-03	4.0E-03	4.0E-03	4.0E-03	4.0E-03	4.0E-03	4.9E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.890	4.890	4.910	4.910	4.890	4.910	4.900	4.910	4.900
<b>OFF samples</b>									
SN7	4.900	4.890	4.910	4.890	4.890	4.880	4.880	4.890	4.880
SN8	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.880	4.890
SN9	4.910	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.880
SN10	4.910	4.890	4.890	4.900	4.890	4.880	4.880	4.880	4.880
SN11	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.880	4.880
<b>Statistics</b>									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.880
Max	4.910	4.890	4.910	4.900	4.890	4.880	4.890	4.890	4.890
Average	4.904	4.890	4.894	4.892	4.890	4.880	4.884	4.884	4.882
Sigma	0.005	0.000	0.008	0.004	0.000	0.000	0.005	0.005	0.004

**Drift Calculation**

VOHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-20.0E-03
SN8	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-20.0E-03	-10.0E-03
SN9	-	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-30.0E-03	-30.0E-03	-20.0E-03	-30.0E-03
SN10	-	-20.0E-03	-20.0E-03	-10.0E-03	-20.0E-03	-30.0E-03	-30.0E-03	-30.0E-03	-30.0E-03
SN11	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-20.0E-03	-20.0E-03
Average	-	-14.0E-03	-10.0E-03	-12.0E-03	-14.0E-03	-24.0E-03	-20.0E-03	-20.0E-03	-22.0E-03
Sigma	-	4.9E-03	11.0E-03	4.0E-03	4.9E-03	4.9E-03	8.9E-03	6.3E-03	7.5E-03



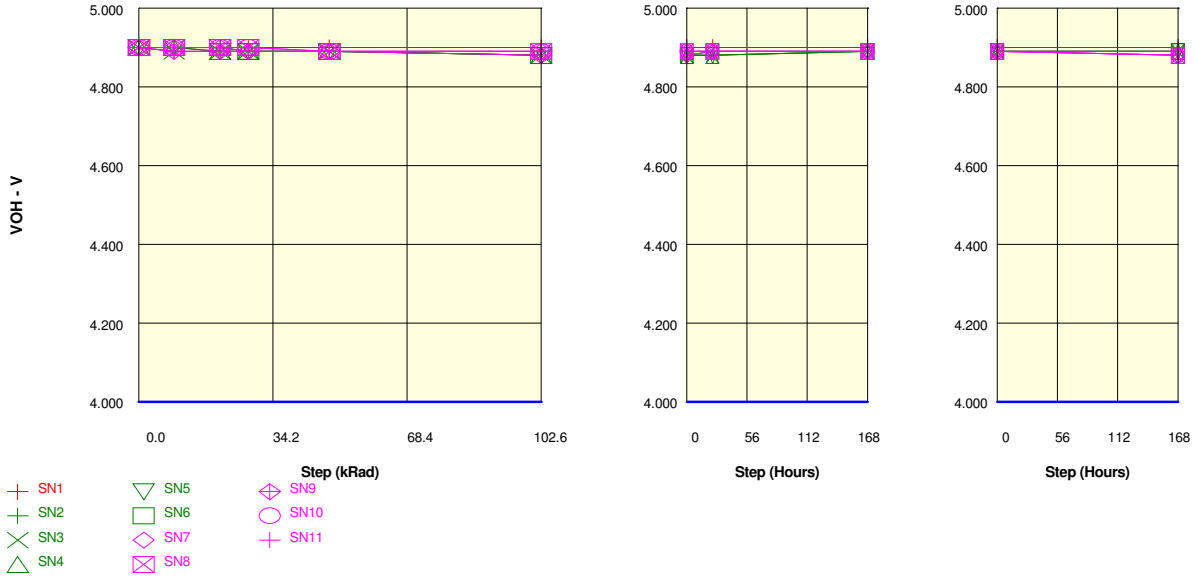
Parameter : Logic output high voltage : VOHD8

Test conditions : IOH=0.5mA

Unit : V

Spec Limit Min : 4.000

Spec limits are represented in bold lines on the graphic.



Measurements

VOHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900
ON samples									
SN2	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
SN4	4.900	4.900	4.890	4.890	4.890	4.880	4.880	4.890	4.890
SN5	4.900	4.900	4.890	4.890	4.890	4.880	4.880	4.890	4.890
SN6	4.900	4.900	4.900	4.890	4.890	4.880	4.890	4.890	4.890
Statistics									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
Max	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.898	4.894	4.890	4.890	4.882	4.884	4.890	4.890
Sigma	0.000	0.004	0.005	0.000	0.000	0.004	0.005	0.000	0.000

Drift Calculation

VOHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN4	-	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN5	-	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN6	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	-2.0E-03	-6.0E-03	-10.0E-03	-10.0E-03	-18.0E-03	-16.0E-03	-10.0E-03	-10.0E-03
Sigma	-	4.0E-03	4.9E-03	90.2E-12	90.2E-12	4.0E-03	4.9E-03	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900	4.900
<b>OFF samples</b>									
SN7	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.890	4.880
SN8	4.900	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.880
SN9	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.890	4.880
SN10	4.900	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.880
SN11	4.900	4.890	4.890	4.890	4.890	4.890	4.890	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.890	4.880
Max	4.900	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.896	4.896	4.894	4.890	4.888	4.890	4.890	4.882
Sigma	0.000	0.005	0.005	0.005	0.000	0.004	0.000	0.000	0.004

**Drift Calculation**

VOHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN8	-	0.0E+00	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN9	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN10	-	0.0E+00	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN11	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	-4.0E-03	-4.0E-03	-6.0E-03	-10.0E-03	-12.0E-03	-10.0E-03	-10.0E-03	-18.0E-03
Sigma	-	4.9E-03	4.9E-03	4.9E-03	90.2E-12	4.0E-03	90.2E-12	90.2E-12	4.0E-03

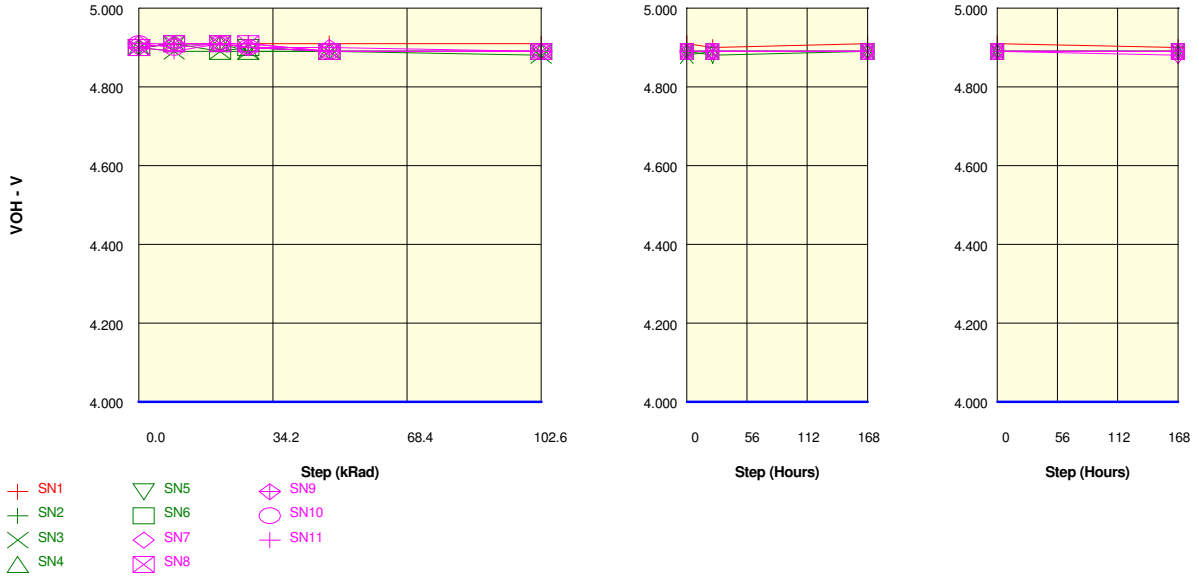
Parameter : Logic output high voltage : VOHD7

Test conditions : IOH=0.5mA

Unit : V

Spec Limit Min : 4.000

Spec limits are represented in bold lines on the graphic.



Measurements

VOHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
ON samples									
SN2	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.890	4.890	4.890	4.890	4.880	4.890	4.890	4.890
SN4	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN5	4.900	4.910	4.910	4.900	4.890	4.890	4.880	4.890	4.890
SN6	4.900	4.910	4.890	4.900	4.890	4.890	4.890	4.890	4.890
Statistics									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.906	4.902	4.896	4.890	4.888	4.888	4.890	4.890
Sigma	0.000	0.008	0.010	0.005	0.000	0.004	0.004	0.000	0.000

Drift Calculation

VOHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	-10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	6.0E-03	2.0E-03	-4.0E-03	-10.0E-03	-12.0E-03	-12.0E-03	-10.0E-03	-10.0E-03
Sigma	-	8.0E-03	9.8E-03	4.9E-03	90.2E-12	4.0E-03	4.0E-03	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
OFF samples									
SN7	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.880
SN8	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.910	4.900	4.900	4.890	4.890	4.890	4.890
SN10	4.910	4.900	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN11	4.900	4.890	4.910	4.910	4.890	4.890	4.890	4.890	4.890
Statistics									
Min	4.900	4.890	4.910	4.900	4.890	4.890	4.890	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890
Average	4.904	4.904	4.910	4.904	4.892	4.890	4.890	4.890	4.888
Sigma	0.005	0.008	0.000	0.005	0.004	0.000	0.000	0.000	0.004

**Drift Calculation**

VOHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN10	-	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN11	-	-10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	-177.6E-18	6.0E-03	0.0E+00	-12.0E-03	-14.0E-03	-14.0E-03	-14.0E-03	-16.0E-03
Sigma	-	8.9E-03	4.9E-03	8.9E-03	4.0E-03	4.9E-03	4.9E-03	4.9E-03	4.9E-03

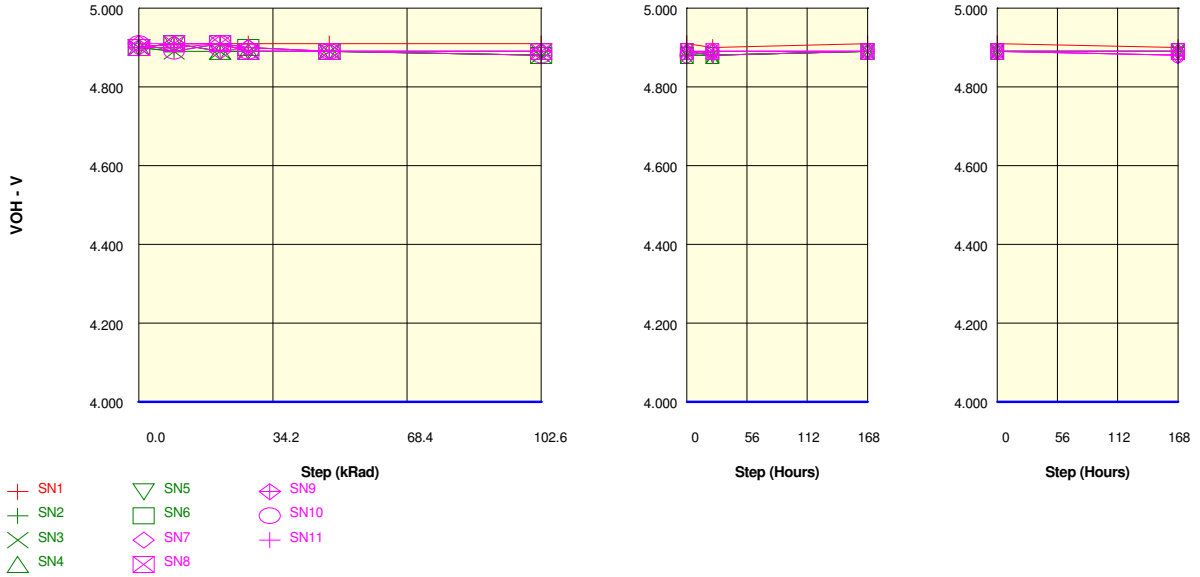
Parameter : Logic output high voltage : VOHD6

Test conditions : IOH=0.5mA

Unit : V

Spec Limit Min : 4.000

Spec limits are represented in bold lines on the graphic.



Measurements

VOHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
ON samples									
SN2	4.900	4.890	4.910	4.890	4.890	4.880	4.890	4.890	4.890
SN3	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
SN4	4.900	4.910	4.890	4.890	4.890	4.890	4.880	4.890	4.890
SN5	4.900	4.910	4.890	4.890	4.890	4.890	4.880	4.890	4.890
SN6	4.900	4.910	4.910	4.900	4.890	4.880	4.880	4.890	4.890
Statistics									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.902	4.898	4.892	4.890	4.884	4.882	4.890	4.890
Sigma	0.000	0.010	0.010	0.004	0.000	0.005	0.004	0.000	0.000

Drift Calculation

VOHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
Average	-	2.0E-03	-2.0E-03	-8.0E-03	-10.0E-03	-16.0E-03	-18.0E-03	-10.0E-03	-10.0E-03
Sigma	-	9.8E-03	9.8E-03	4.0E-03	90.2E-12	4.9E-03	4.0E-03	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

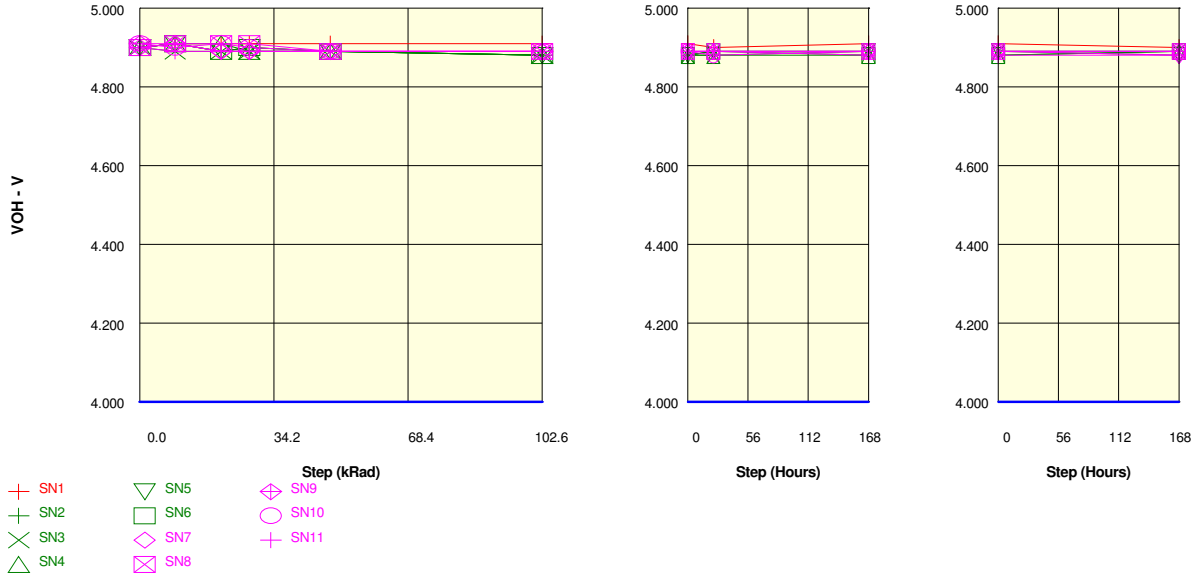
**Measurements**

VOHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
OFF samples									
SN7	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN8	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.890	4.900	4.890	4.890	4.890	4.890	4.880
SN10	4.910	4.890	4.910	4.890	4.890	4.880	4.890	4.890	4.880
SN11	4.900	4.900	4.910	4.890	4.890	4.890	4.880	4.890	4.880
Statistics									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.880
Max	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.904	4.904	4.906	4.894	4.890	4.888	4.888	4.890	4.884
Sigma	0.005	0.008	0.008	0.005	0.000	0.004	0.004	0.000	0.005

**Drift Calculation**

VOHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN8	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	-20.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-30.0E-03
SN10	-	-20.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-30.0E-03	-20.0E-03	-20.0E-03	-30.0E-03
SN11	-	0.0E+00	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-20.0E-03
Average	-	-177.6E-18	2.0E-03	-10.0E-03	-14.0E-03	-16.0E-03	-16.0E-03	-14.0E-03	-20.0E-03
Sigma	-	11.0E-03	11.7E-03	6.3E-03	4.9E-03	8.0E-03	4.9E-03	4.9E-03	8.9E-03

Parameter : Logic output high voltage : VOHD5  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
ON samples									
SN2	4.900	4.910	4.890	4.890	4.890	4.880	4.890	4.890	4.890
SN3	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.890	4.890
SN4	4.900	4.910	4.910	4.890	4.890	4.880	4.880	4.880	4.890
SN5	4.900	4.910	4.890	4.900	4.890	4.880	4.890	4.890	4.880
SN6	4.900	4.910	4.890	4.900	4.890	4.880	4.890	4.880	4.890
Statistics									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.880
Max	4.900	4.910	4.910	4.900	4.890	4.880	4.890	4.890	4.890
Average	4.900	4.906	4.894	4.894	4.890	4.880	4.886	4.886	4.888
Sigma	0.000	0.008	0.008	0.005	0.000	0.000	0.005	0.005	0.004

**Drift Calculation**

VOHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-10.0E-03
SN5	-	10.0E-03	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN6	-	10.0E-03	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-10.0E-03	-20.0E-03	-10.0E-03
Average	-	6.0E-03	-6.0E-03	-6.0E-03	-10.0E-03	-20.0E-03	-14.0E-03	-14.0E-03	-12.0E-03
Sigma	-	8.0E-03	8.0E-03	4.9E-03	90.2E-12	180.3E-12	4.9E-03	4.9E-03	4.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

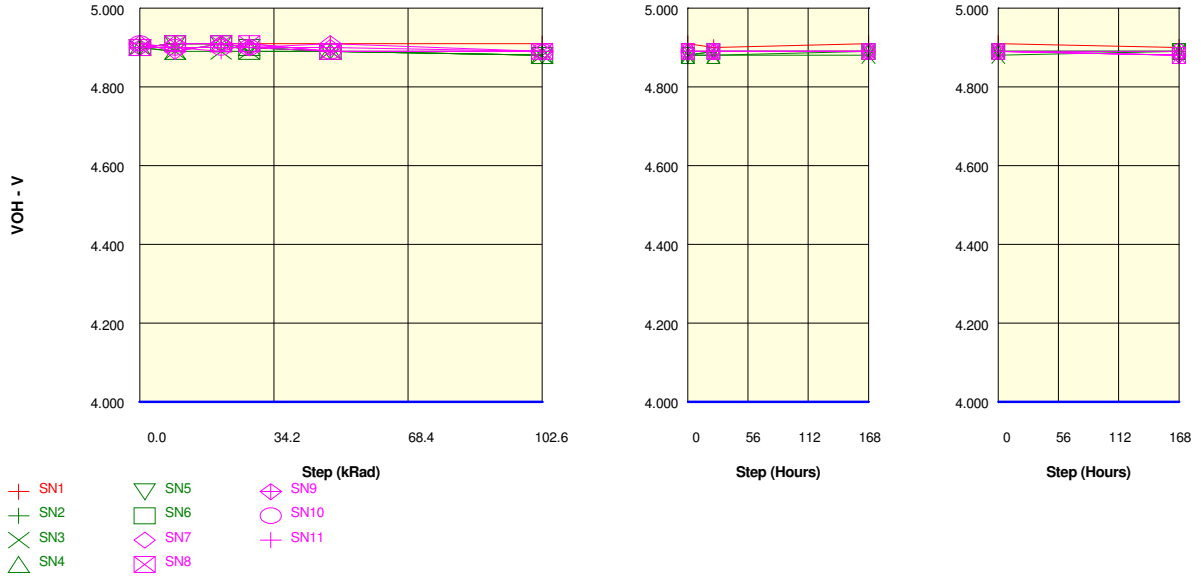
VOHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
<b>OFF samples</b>									
SN7	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890	4.880
SN8	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890	4.890
SN10	4.910	4.900	4.910	4.900	4.890	4.890	4.880	4.890	4.890
SN11	4.900	4.890	4.890	4.890	4.890	4.890	4.890	4.880	4.880
<b>Statistics</b>									
Min	4.900	4.890	4.890	4.890	4.890	4.890	4.880	4.880	4.880
Max	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
Average	4.904	4.904	4.898	4.896	4.890	4.890	4.888	4.888	4.886
Sigma	0.005	0.008	0.010	0.008	0.000	0.000	0.004	0.004	0.005

**Drift Calculation**

VOHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN10	-	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-30.0E-03	-20.0E-03	-20.0E-03
SN11	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03
Average	-	-177.6E-18	-6.0E-03	-8.0E-03	-14.0E-03	-14.0E-03	-16.0E-03	-16.0E-03	-18.0E-03
Sigma	-	8.9E-03	10.2E-03	9.8E-03	4.9E-03	4.9E-03	8.0E-03	4.9E-03	4.0E-03



Parameter : Logic output high voltage : VOHD4  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
ON samples									
SN2	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.890
SN4	4.900	4.890	4.910	4.900	4.890	4.880	4.880	4.890	4.890
SN5	4.900	4.910	4.910	4.900	4.890	4.880	4.890	4.890	4.890
SN6	4.900	4.910	4.910	4.890	4.890	4.880	4.890	4.890	4.890
Statistics									
Min	4.900	4.890	4.890	4.890	4.890	4.880	4.880	4.880	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.902	4.906	4.896	4.890	4.882	4.886	4.888	4.890
Sigma	0.000	0.010	0.008	0.005	0.000	0.004	0.005	0.004	0.000

**Drift Calculation**

VOHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-10.0E-03
SN4	-	-10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	2.0E-03	6.0E-03	-4.0E-03	-10.0E-03	-18.0E-03	-14.0E-03	-12.0E-03	-10.0E-03
Sigma	-	9.8E-03	8.0E-03	4.9E-03	90.2E-12	4.0E-03	4.9E-03	4.0E-03	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.900	4.910	4.900
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.900	4.910	4.890	4.890	4.890	4.880
SN8	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.880
SN9	4.910	4.890	4.910	4.900	4.900	4.890	4.890	4.890	4.880
SN10	4.910	4.900	4.900	4.900	4.890	4.890	4.890	4.890	4.890
SN11	4.900	4.900	4.890	4.910	4.890	4.890	4.890	4.890	4.880
<b>Statistics</b>									
Min	4.900	4.890	4.890	4.900	4.890	4.890	4.890	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
Average	4.904	4.902	4.904	4.904	4.896	4.890	4.890	4.890	4.882
Sigma	0.005	0.007	0.008	0.005	0.008	0.000	0.000	0.000	0.004

**Drift Calculation**

VOHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	0.0E+00	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
SN9	-	-20.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-30.0E-03
SN10	-	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN11	-	0.0E+00	-10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
Average	-	-2.0E-03	-177.6E-18	0.0E+00	-8.0E-03	-14.0E-03	-14.0E-03	-14.0E-03	-22.0E-03
Sigma	-	11.7E-03	8.9E-03	8.9E-03	9.8E-03	4.9E-03	4.9E-03	4.9E-03	4.0E-03

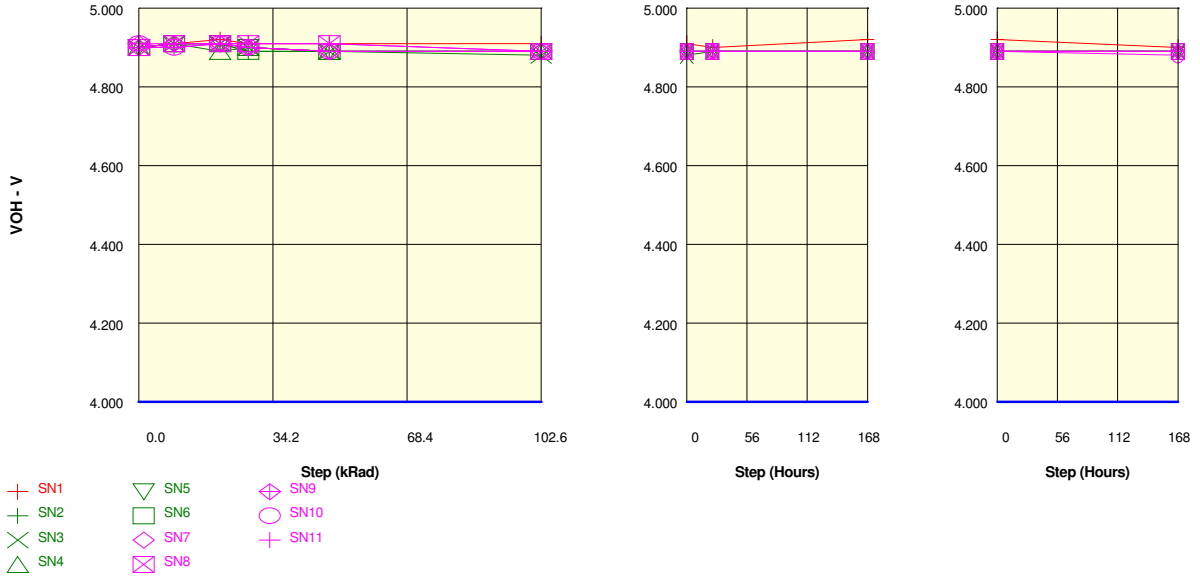
Parameter : Logic output high voltage : VOHD3

Test conditions : IOH=0.5mA

Unit : V

Spec Limit Min : 4.000

Spec limits are represented in bold lines on the graphic.



Measurements

VOHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.920	4.910	4.910	4.910	4.900	4.920	4.900
ON samples									
SN2	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN3	4.900	4.910	4.910	4.900	4.890	4.880	4.890	4.890	4.890
SN4	4.900	4.910	4.890	4.900	4.890	4.890	4.890	4.890	4.890
SN5	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN6	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.890	4.890
Statistics									
Min	4.900	4.910	4.890	4.890	4.890	4.880	4.890	4.890	4.890
Max	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Average	4.900	4.910	4.906	4.896	4.890	4.888	4.890	4.890	4.890
Sigma	0.000	0.000	0.008	0.005	0.000	0.004	0.000	0.000	0.000

Drift Calculation

VOHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN4	-	10.0E-03	-10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN6	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	10.0E-03	6.0E-03	-4.0E-03	-10.0E-03	-12.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Sigma	-	127.5E-12	8.0E-03	4.9E-03	90.2E-12	4.0E-03	90.2E-12	90.2E-12	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

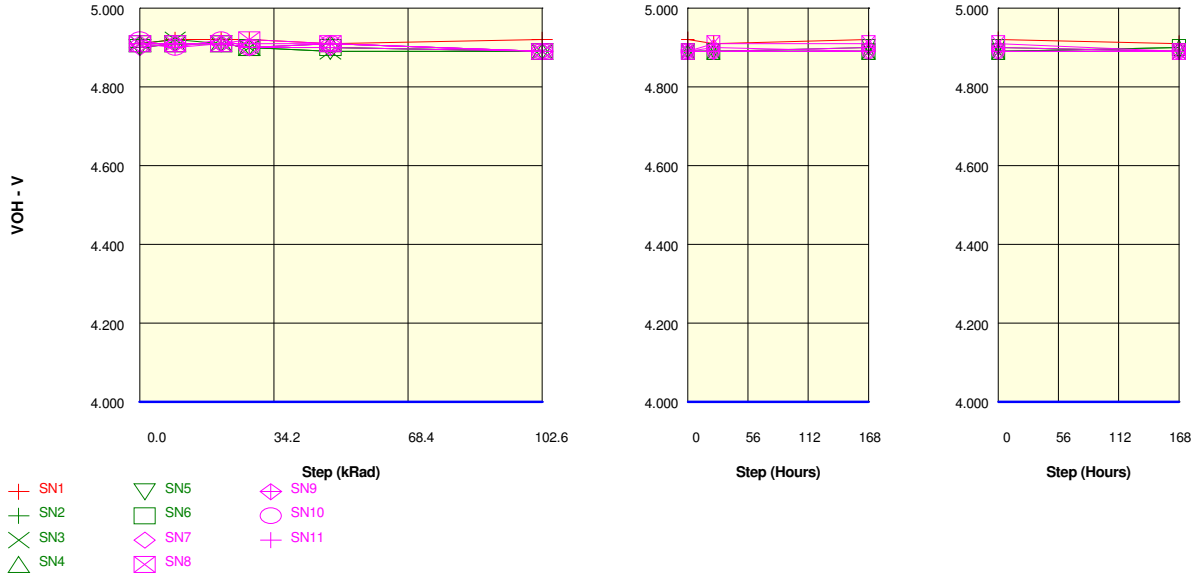
**Measurements**

VOHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.920	4.910	4.910	4.910	4.900	4.920	4.900
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN8	4.900	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN10	4.910	4.900	4.910	4.900	4.890	4.890	4.890	4.890	4.880
SN11	4.900	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.900	4.910	4.900	4.890	4.890	4.890	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
Average	4.904	4.906	4.910	4.904	4.898	4.890	4.890	4.890	4.888
Sigma	0.005	0.005	0.000	0.005	0.010	0.000	0.000	0.000	0.004

**Drift Calculation**

VOHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN10	-	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-30.0E-03
SN11	-	0.0E+00	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	2.0E-03	6.0E-03	0.0E+00	-6.0E-03	-14.0E-03	-14.0E-03	-14.0E-03	-16.0E-03
Sigma	-	7.5E-03	4.9E-03	8.9E-03	13.6E-03	4.9E-03	4.9E-03	4.9E-03	8.0E-03

Parameter : Logic output high voltage : VOHD2  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



Measurements

VOHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.920	4.920	4.920	4.910	4.920	4.910	4.920	4.910
ON samples									
SN2	4.900	4.910	4.910	4.900	4.900	4.890	4.890	4.890	4.890
SN3	4.910	4.920	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN4	4.910	4.910	4.910	4.900	4.910	4.890	4.890	4.890	4.900
SN5	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.900	4.890
SN6	4.910	4.910	4.910	4.900	4.900	4.890	4.890	4.890	4.900
Statistics									
Min	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
Max	4.910	4.920	4.910	4.900	4.910	4.890	4.890	4.900	4.900
Average	4.906	4.912	4.910	4.900	4.898	4.890	4.890	4.892	4.894
Sigma	0.005	0.004	0.000	0.000	0.007	0.000	0.000	0.004	0.005

Drift Calculation

VOHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN4	-	0.0E+00	0.0E+00	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-10.0E-03
SN5	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	0.0E+00	-10.0E-03
SN6	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-10.0E-03
Average	-	6.0E-03	4.0E-03	-6.0E-03	-8.0E-03	-16.0E-03	-16.0E-03	-14.0E-03	-12.0E-03
Sigma	-	4.9E-03	4.9E-03	4.9E-03	7.5E-03	4.9E-03	4.9E-03	8.0E-03	4.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

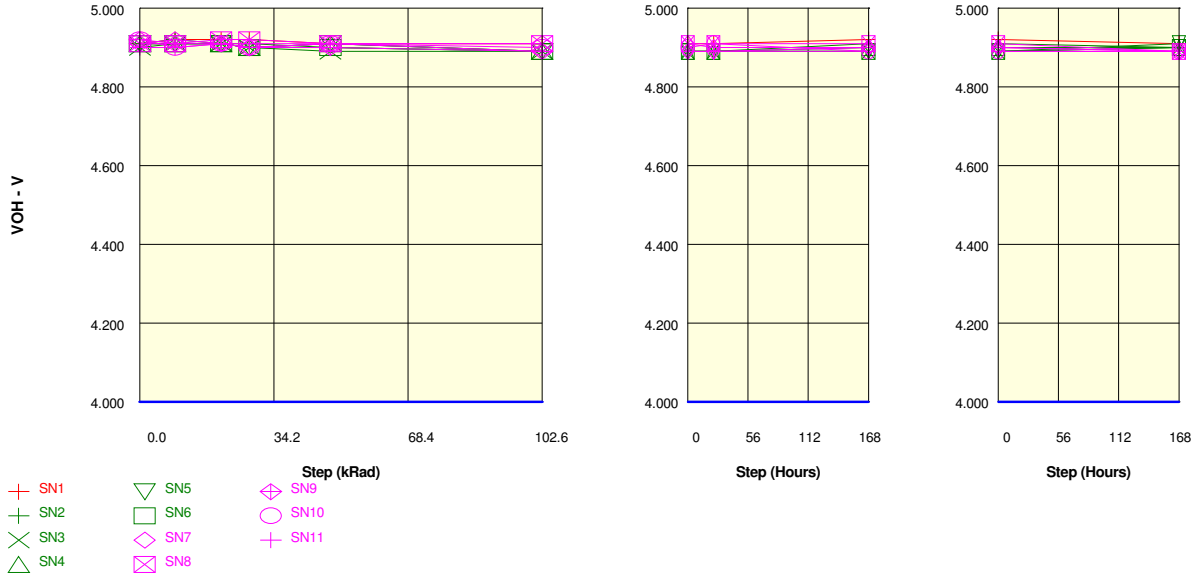
**Measurements**

VOHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.920	4.920	4.920	4.910	4.920	4.910	4.920	4.910
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.900	4.910	4.890	4.900	4.890	4.890
SN8	4.910	4.910	4.910	4.920	4.910	4.890	4.910	4.910	4.890
SN9	4.910	4.910	4.910	4.900	4.900	4.890	4.890	4.900	4.890
SN10	4.920	4.900	4.920	4.900	4.910	4.890	4.890	4.890	4.890
SN11	4.910	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.900	4.910	4.900	4.900	4.890	4.890	4.890	4.890
Max	4.920	4.910	4.920	4.920	4.910	4.890	4.910	4.910	4.890
Average	4.910	4.906	4.912	4.906	4.908	4.890	4.896	4.896	4.890
Sigma	0.006	0.005	0.004	0.008	0.004	0.000	0.008	0.008	0.000

**Drift Calculation**

VOHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	0.0E+00	10.0E-03	-10.0E-03	0.0E+00	-10.0E-03	-10.0E-03
SN8	-	0.0E+00	0.0E+00	10.0E-03	0.0E+00	-20.0E-03	0.0E+00	0.0E+00	-20.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-20.0E-03
SN10	-	-20.0E-03	0.0E+00	-20.0E-03	-10.0E-03	-30.0E-03	-30.0E-03	-30.0E-03	-30.0E-03
SN11	-	-10.0E-03	0.0E+00	0.0E+00	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
Average	-	-4.0E-03	2.0E-03	-4.0E-03	-2.0E-03	-20.0E-03	-14.0E-03	-14.0E-03	-20.0E-03
Sigma	-	10.2E-03	4.0E-03	10.2E-03	7.5E-03	6.3E-03	12.0E-03	10.2E-03	6.3E-03

Parameter : Logic output high voltage : VOHD1  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



Measurements

VOHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.920	4.920	4.920	4.910	4.910	4.910	4.920	4.910
ON samples									
SN2	4.910	4.920	4.910	4.910	4.900	4.890	4.890	4.910	4.900
SN3	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.900
SN4	4.910	4.910	4.910	4.900	4.910	4.890	4.890	4.900	4.900
SN5	4.910	4.910	4.910	4.900	4.910	4.890	4.890	4.890	4.910
SN6	4.910	4.910	4.910	4.900	4.900	4.890	4.890	4.890	4.900
Statistics									
Min	4.900	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.900
Max	4.910	4.920	4.910	4.910	4.910	4.890	4.890	4.910	4.910
Average	4.908	4.912	4.910	4.902	4.902	4.890	4.890	4.896	4.902
Sigma	0.004	0.004	0.000	0.004	0.007	0.000	0.000	0.008	0.004

Drift Calculation

VOHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	0.0E+00	-10.0E-03
SN3	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	0.0E+00
SN4	-	0.0E+00	0.0E+00	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN5	-	0.0E+00	0.0E+00	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	0.0E+00
SN6	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-10.0E-03
Average	-	4.0E-03	2.0E-03	-6.0E-03	-6.0E-03	-18.0E-03	-18.0E-03	-12.0E-03	-6.0E-03
Sigma	-	4.9E-03	4.0E-03	4.9E-03	4.9E-03	4.0E-03	4.0E-03	7.5E-03	4.9E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

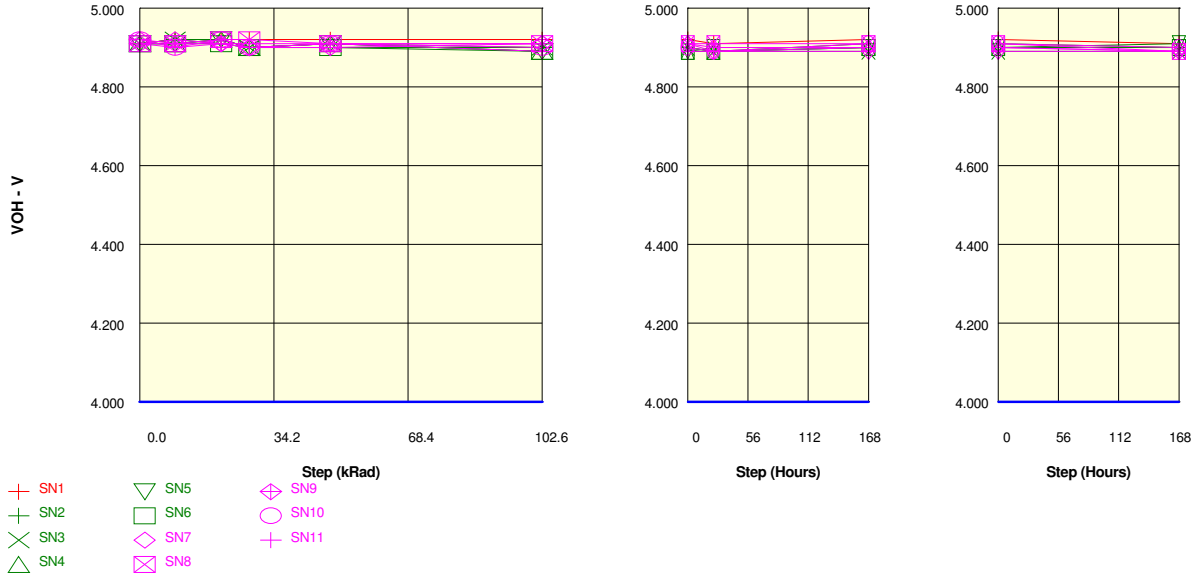
VOHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.920	4.920	4.920	4.910	4.910	4.910	4.920	4.910
<b>OFF samples</b>									
SN7	4.910	4.920	4.910	4.900	4.910	4.910	4.900	4.900	4.890
SN8	4.910	4.910	4.920	4.920	4.910	4.910	4.910	4.910	4.890
SN9	4.920	4.910	4.910	4.900	4.900	4.890	4.890	4.900	4.890
SN10	4.920	4.900	4.910	4.900	4.910	4.900	4.910	4.890	4.890
SN11	4.900	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890
<b>Statistics</b>									
Min	4.900	4.900	4.910	4.900	4.900	4.890	4.890	4.890	4.890
Max	4.920	4.920	4.920	4.920	4.910	4.910	4.910	4.910	4.890
Average	4.912	4.908	4.912	4.906	4.908	4.900	4.900	4.898	4.890
Sigma	0.007	0.007	0.004	0.008	0.004	0.009	0.009	0.007	0.000

**Drift Calculation**

VOHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	0.0E+00	-10.0E-03	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03
SN8	-	0.0E+00	10.0E-03	10.0E-03	0.0E+00	0.0E+00	0.0E+00	0.0E+00	-20.0E-03
SN9	-	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-30.0E-03	-30.0E-03	-20.0E-03	-30.0E-03
SN10	-	-20.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-20.0E-03	-10.0E-03	-30.0E-03	-30.0E-03
SN11	-	0.0E+00	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
Average	-	-4.0E-03	0.0E+00	-6.0E-03	-4.0E-03	-12.0E-03	-12.0E-03	-14.0E-03	-22.0E-03
Sigma	-	10.2E-03	8.9E-03	13.6E-03	10.2E-03	11.7E-03	9.8E-03	10.2E-03	7.5E-03



Parameter : Logic output high voltage : VOHD0  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



Measurements

VOHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.920	4.920	4.920	4.920	4.920	4.910	4.920	4.910
ON samples									
SN2	4.910	4.920	4.910	4.900	4.900	4.900	4.890	4.910	4.900
SN3	4.910	4.920	4.920	4.900	4.910	4.900	4.890	4.890	4.890
SN4	4.910	4.910	4.920	4.900	4.910	4.890	4.890	4.900	4.900
SN5	4.910	4.910	4.920	4.900	4.910	4.890	4.900	4.900	4.910
SN6	4.910	4.910	4.910	4.900	4.900	4.890	4.890	4.900	4.900
Statistics									
Min	4.910	4.910	4.910	4.900	4.900	4.890	4.890	4.890	4.890
Max	4.910	4.920	4.920	4.900	4.910	4.900	4.900	4.910	4.910
Average	4.910	4.914	4.916	4.900	4.906	4.894	4.892	4.900	4.900
Sigma	0.000	0.005	0.005	0.000	0.005	0.005	0.004	0.006	0.006

Drift Calculation

VOHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	0.0E+00	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03	0.0E+00	-10.0E-03
SN3	-	10.0E-03	10.0E-03	-10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN4	-	0.0E+00	10.0E-03	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN5	-	0.0E+00	10.0E-03	-10.0E-03	0.0E+00	-20.0E-03	-10.0E-03	-10.0E-03	0.0E+00
SN6	-	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
Average	-	4.0E-03	6.0E-03	-10.0E-03	-4.0E-03	-16.0E-03	-18.0E-03	-10.0E-03	-10.0E-03
Sigma	-	4.9E-03	4.9E-03	127.5E-12	4.9E-03	4.9E-03	4.0E-03	6.3E-03	6.3E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

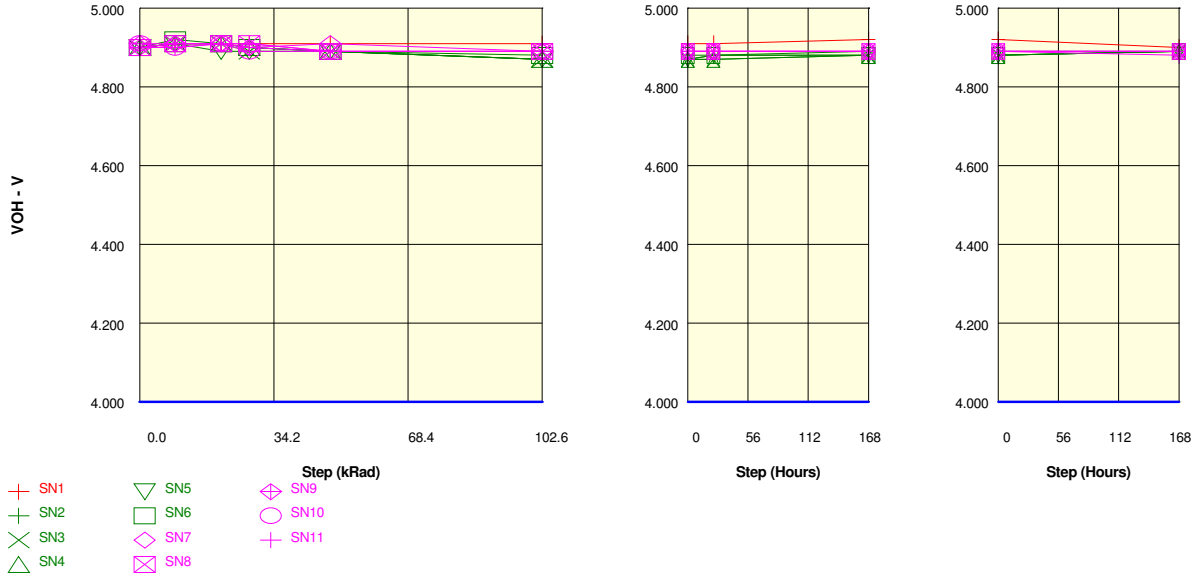
**Measurements**

VOHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.910	4.920	4.920	4.920	4.920	4.920	4.910	4.920	4.910
<b>OFF samples</b>									
SN7	4.910	4.920	4.910	4.900	4.910	4.910	4.900	4.900	4.890
SN8	4.910	4.910	4.920	4.920	4.910	4.910	4.910	4.910	4.890
SN9	4.920	4.910	4.910	4.900	4.900	4.910	4.890	4.890	4.890
SN10	4.920	4.900	4.920	4.900	4.910	4.900	4.890	4.910	4.900
SN11	4.910	4.900	4.910	4.910	4.910	4.890	4.890	4.900	4.890
<b>Statistics</b>									
Min	4.910	4.900	4.910	4.900	4.900	4.890	4.890	4.890	4.890
Max	4.920	4.920	4.920	4.920	4.910	4.910	4.910	4.910	4.900
Average	4.914	4.908	4.914	4.906	4.908	4.904	4.896	4.902	4.892
Sigma	0.005	0.007	0.005	0.008	0.004	0.008	0.008	0.007	0.004

**Drift Calculation**

VOHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	0.0E+00	-10.0E-03	0.0E+00	0.0E+00	-10.0E-03	-10.0E-03	-20.0E-03
SN8	-	0.0E+00	10.0E-03	10.0E-03	0.0E+00	0.0E+00	0.0E+00	0.0E+00	-20.0E-03
SN9	-	-10.0E-03	-10.0E-03	-20.0E-03	-20.0E-03	-10.0E-03	-30.0E-03	-30.0E-03	-30.0E-03
SN10	-	-20.0E-03	0.0E+00	-20.0E-03	-10.0E-03	-20.0E-03	-30.0E-03	-10.0E-03	-20.0E-03
SN11	-	-10.0E-03	0.0E+00	0.0E+00	0.0E+00	-20.0E-03	-20.0E-03	-10.0E-03	-20.0E-03
Average	-	-6.0E-03	0.0E+00	-8.0E-03	-6.0E-03	-10.0E-03	-18.0E-03	-12.0E-03	-22.0E-03
Sigma	-	10.2E-03	6.3E-03	11.7E-03	8.0E-03	8.9E-03	11.7E-03	9.8E-03	4.0E-03

Parameter : Logic output high voltage : VOHBUSY  
 Test conditions : IOH=0.5mA  
 Unit : V  
 Spec Limit Min : 4.000  
 Spec limits are represented in bold lines on the graphic.



Measurements

VOHBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.910	4.920	4.900
ON samples									
SN2	4.900	4.910	4.910	4.900	4.890	4.870	4.880	4.890	4.890
SN3	4.900	4.910	4.910	4.890	4.890	4.870	4.870	4.880	4.890
SN4	4.900	4.910	4.910	4.900	4.890	4.870	4.870	4.880	4.890
SN5	4.900	4.910	4.890	4.890	4.890	4.870	4.880	4.880	4.890
SN6	4.900	4.920	4.910	4.900	4.890	4.880	4.880	4.880	4.890
Statistics									
Min	4.900	4.910	4.890	4.890	4.890	4.870	4.870	4.880	4.890
Max	4.900	4.920	4.910	4.900	4.890	4.880	4.880	4.890	4.890
Average	4.900	4.912	4.906	4.896	4.890	4.872	4.876	4.882	4.890
Sigma	0.000	0.004	0.008	0.005	0.000	0.004	0.005	0.004	0.000

Drift Calculation

VOHBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-30.0E-03	-20.0E-03	-10.0E-03	-10.0E-03
SN3	-	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-30.0E-03	-30.0E-03	-20.0E-03	-10.0E-03
SN4	-	10.0E-03	10.0E-03	0.0E+00	-10.0E-03	-30.0E-03	-30.0E-03	-20.0E-03	-10.0E-03
SN5	-	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-30.0E-03	-20.0E-03	-20.0E-03	-10.0E-03
SN6	-	20.0E-03	10.0E-03	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-10.0E-03
Average	-	12.0E-03	6.0E-03	-4.0E-03	-10.0E-03	-28.0E-03	-24.0E-03	-18.0E-03	-10.0E-03
Sigma	-	4.0E-03	8.0E-03	4.9E-03	90.2E-12	4.0E-03	4.9E-03	4.0E-03	90.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOHBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.900	4.910	4.910	4.910	4.910	4.910	4.910	4.920	4.900
<b>OFF samples</b>									
SN7	4.900	4.910	4.910	4.900	4.910	4.890	4.890	4.890	4.890
SN8	4.900	4.910	4.910	4.910	4.890	4.890	4.890	4.890	4.890
SN9	4.910	4.910	4.910	4.900	4.890	4.890	4.890	4.890	4.890
SN10	4.910	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.890
SN11	4.900	4.900	4.910	4.910	4.890	4.890	4.890	4.890	4.880
<b>Statistics</b>									
Min	4.900	4.900	4.910	4.890	4.890	4.890	4.890	4.890	4.880
Max	4.910	4.910	4.910	4.910	4.910	4.890	4.890	4.890	4.890
Average	4.904	4.906	4.910	4.902	4.894	4.890	4.890	4.890	4.888
Sigma	0.005	0.005	0.000	0.007	0.008	0.000	0.000	0.000	0.004

**Drift Calculation**

VOHBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	10.0E-03	10.0E-03	0.0E+00	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN8	-	10.0E-03	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03
SN9	-	0.0E+00	0.0E+00	-10.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN10	-	-10.0E-03	0.0E+00	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03	-20.0E-03
SN11	-	0.0E+00	10.0E-03	10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-10.0E-03	-20.0E-03
Average	-	2.0E-03	6.0E-03	-2.0E-03	-10.0E-03	-14.0E-03	-14.0E-03	-14.0E-03	-16.0E-03
Sigma	-	7.5E-03	4.9E-03	11.7E-03	11.0E-03	4.9E-03	4.9E-03	4.9E-03	4.9E-03

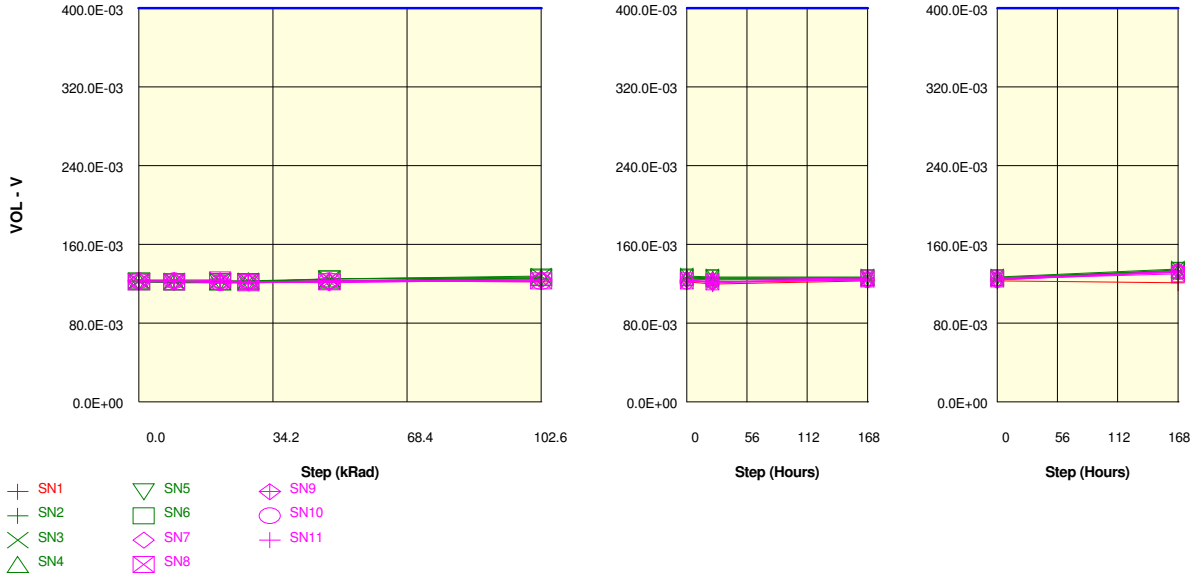
Parameter : logic output low voltage : VOLD15

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



**Measurements**

VOLD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	123.0E-03	123.0E-03	122.0E-03	121.0E-03	123.0E-03	122.0E-03	120.0E-03	123.0E-03	121.0E-03
ON samples									
SN2	122.0E-03	121.0E-03	121.0E-03	121.0E-03	123.0E-03	125.0E-03	124.0E-03	125.0E-03	133.0E-03
SN3	123.0E-03	123.0E-03	123.0E-03	123.0E-03	125.0E-03	128.0E-03	127.0E-03	127.0E-03	135.0E-03
SN4	122.0E-03	122.0E-03	122.0E-03	123.0E-03	123.0E-03	126.0E-03	125.0E-03	126.0E-03	133.0E-03
SN5	122.0E-03	122.0E-03	122.0E-03	122.0E-03	125.0E-03	126.0E-03	126.0E-03	126.0E-03	133.0E-03
SN6	123.0E-03	122.0E-03	122.0E-03	122.0E-03	125.0E-03	127.0E-03	126.0E-03	126.0E-03	134.0E-03
Statistics									
Min	122.0E-03	121.0E-03	121.0E-03	121.0E-03	123.0E-03	125.0E-03	124.0E-03	125.0E-03	133.0E-03
Max	123.0E-03	123.0E-03	123.0E-03	123.0E-03	125.0E-03	128.0E-03	127.0E-03	127.0E-03	135.0E-03
Average	122.4E-03	122.0E-03	122.0E-03	122.2E-03	124.2E-03	126.4E-03	125.6E-03	126.0E-03	133.6E-03
Sigma	489.9E-06	632.5E-06	632.5E-06	748.3E-06	979.8E-06	1.0E-03	1.0E-03	632.5E-06	800.0E-06

**Drift Calculation**

VOLD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-1.0E-03	-1.0E-03	-1.0E-03	1.0E-03	3.0E-03	2.0E-03	3.0E-03	11.0E-03
SN3	-	0.0E+00	0.0E+00	0.0E+00	2.0E-03	5.0E-03	4.0E-03	4.0E-03	12.0E-03
SN4	-	0.0E+00	0.0E+00	1.0E-03	1.0E-03	4.0E-03	3.0E-03	4.0E-03	11.0E-03
SN5	-	0.0E+00	0.0E+00	0.0E+00	3.0E-03	4.0E-03	4.0E-03	4.0E-03	11.0E-03
SN6	-	-1.0E-03	-1.0E-03	-1.0E-03	2.0E-03	4.0E-03	3.0E-03	3.0E-03	11.0E-03
Average	-	-400.0E-06	-400.0E-06	-200.0E-06	1.8E-03	4.0E-03	3.2E-03	3.6E-03	11.2E-03
Sigma	-	489.9E-06	489.9E-06	748.3E-06	748.3E-06	632.5E-06	748.3E-06	489.9E-06	400.0E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

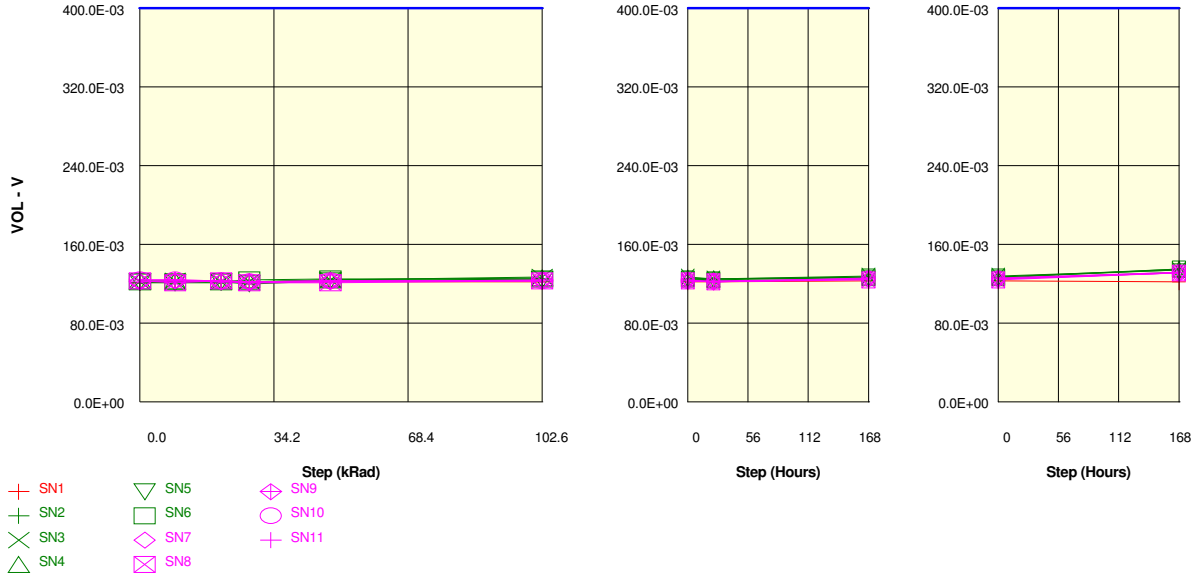
**Measurements**

VOLD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	123.0E-03	123.0E-03	122.0E-03	121.0E-03	123.0E-03	122.0E-03	120.0E-03	123.0E-03	121.0E-03
<b>OFF samples</b>									
SN7	123.0E-03	122.0E-03	122.0E-03	122.0E-03	121.0E-03	124.0E-03	122.0E-03	124.0E-03	133.0E-03
SN8	122.0E-03	122.0E-03	124.0E-03	121.0E-03	122.0E-03	123.0E-03	122.0E-03	125.0E-03	130.0E-03
SN9	122.0E-03	123.0E-03	121.0E-03	121.0E-03	122.0E-03	124.0E-03	121.0E-03	124.0E-03	133.0E-03
SN10	123.0E-03	123.0E-03	121.0E-03	122.0E-03	123.0E-03	122.0E-03	122.0E-03	124.0E-03	132.0E-03
SN11	124.0E-03	124.0E-03	124.0E-03	121.0E-03	123.0E-03	124.0E-03	124.0E-03	126.0E-03	132.0E-03
<b>Statistics</b>									
Min	122.0E-03	122.0E-03	121.0E-03	121.0E-03	121.0E-03	122.0E-03	121.0E-03	124.0E-03	130.0E-03
Max	124.0E-03	124.0E-03	124.0E-03	122.0E-03	123.0E-03	124.0E-03	124.0E-03	126.0E-03	133.0E-03
Average	122.8E-03	122.8E-03	122.4E-03	121.4E-03	122.2E-03	123.4E-03	122.2E-03	124.6E-03	132.0E-03
Sigma	748.3E-06	748.3E-06	1.4E-03	489.9E-06	748.3E-06	800.0E-06	979.8E-06	800.0E-06	1.1E-03

**Drift Calculation**

VOLD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-1.0E-03	-1.0E-03	-1.0E-03	-2.0E-03	1.0E-03	-1.0E-03	1.0E-03	10.0E-03
SN8	-	0.0E+00	2.0E-03	-1.0E-03	0.0E+00	1.0E-03	0.0E+00	3.0E-03	8.0E-03
SN9	-	1.0E-03	-1.0E-03	-1.0E-03	0.0E+00	2.0E-03	-1.0E-03	2.0E-03	11.0E-03
SN10	-	0.0E+00	-2.0E-03	-1.0E-03	0.0E+00	-1.0E-03	-1.0E-03	1.0E-03	9.0E-03
SN11	-	0.0E+00	0.0E+00	-3.0E-03	-1.0E-03	0.0E+00	0.0E+00	2.0E-03	8.0E-03
Average	-	0.0E+00	-400.0E-06	-1.4E-03	-600.0E-06	600.0E-06	-600.0E-06	1.8E-03	9.2E-03
Sigma	-	632.5E-06	1.4E-03	800.0E-06	800.0E-06	1.0E-03	489.9E-06	748.3E-06	1.2E-03

Parameter : logic output low voltage : VOLD14  
 Test conditions : IOL=1.6mA  
 Unit : V  
 Spec Limit Max : 400.0E-03  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOLD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	121.0E-03	123.0E-03	122.0E-03	122.0E-03	122.0E-03	122.0E-03	122.0E-03	123.0E-03	122.0E-03
ON samples									
SN2	121.0E-03	121.0E-03	121.0E-03	122.0E-03	123.0E-03	125.0E-03	125.0E-03	127.0E-03	134.0E-03
SN3	122.0E-03	123.0E-03	122.0E-03	122.0E-03	124.0E-03	127.0E-03	125.0E-03	128.0E-03	134.0E-03
SN4	123.0E-03	123.0E-03	123.0E-03	122.0E-03	124.0E-03	126.0E-03	125.0E-03	126.0E-03	135.0E-03
SN5	122.0E-03	121.0E-03	122.0E-03	120.0E-03	123.0E-03	124.0E-03	123.0E-03	125.0E-03	132.0E-03
SN6	122.0E-03	122.0E-03	122.0E-03	124.0E-03	125.0E-03	125.0E-03	124.0E-03	127.0E-03	135.0E-03
Statistics									
Min	121.0E-03	121.0E-03	121.0E-03	120.0E-03	123.0E-03	124.0E-03	123.0E-03	125.0E-03	132.0E-03
Max	123.0E-03	123.0E-03	123.0E-03	124.0E-03	125.0E-03	127.0E-03	125.0E-03	128.0E-03	135.0E-03
Average	122.0E-03	122.0E-03	122.0E-03	122.0E-03	123.8E-03	125.4E-03	124.4E-03	126.6E-03	134.0E-03
Sigma	632.5E-06	894.4E-06	632.5E-06	1.3E-03	748.3E-06	1.0E-03	800.0E-06	1.0E-03	1.1E-03

**Drift Calculation**

VOLD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	1.0E-03	2.0E-03	4.0E-03	4.0E-03	6.0E-03	13.0E-03
SN3	-	1.0E-03	0.0E+00	0.0E+00	2.0E-03	5.0E-03	3.0E-03	6.0E-03	12.0E-03
SN4	-	0.0E+00	0.0E+00	-1.0E-03	1.0E-03	3.0E-03	2.0E-03	3.0E-03	12.0E-03
SN5	-	-1.0E-03	0.0E+00	-2.0E-03	1.0E-03	2.0E-03	1.0E-03	3.0E-03	10.0E-03
SN6	-	0.0E+00	0.0E+00	2.0E-03	3.0E-03	3.0E-03	2.0E-03	5.0E-03	13.0E-03
Average	-	0.0E+00	0.0E+00	0.0E+00	1.8E-03	3.4E-03	2.4E-03	4.6E-03	12.0E-03
Sigma	-	632.5E-06	0.0E+00	1.4E-03	748.3E-06	1.0E-03	1.0E-03	1.4E-03	1.1E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOLD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	121.0E-03	123.0E-03	122.0E-03	122.0E-03	122.0E-03	122.0E-03	122.0E-03	123.0E-03	122.0E-03
OFF samples									
SN7	122.0E-03	123.0E-03	122.0E-03	122.0E-03	123.0E-03	123.0E-03	123.0E-03	125.0E-03	131.0E-03
SN8	123.0E-03	121.0E-03	123.0E-03	121.0E-03	121.0E-03	123.0E-03	122.0E-03	124.0E-03	131.0E-03
SN9	122.0E-03	123.0E-03	122.0E-03	121.0E-03	122.0E-03	124.0E-03	122.0E-03	125.0E-03	131.0E-03
SN10	124.0E-03	124.0E-03	123.0E-03	122.0E-03	123.0E-03	123.0E-03	122.0E-03	125.0E-03	131.0E-03
SN11	124.0E-03	124.0E-03	123.0E-03	122.0E-03	123.0E-03	123.0E-03	122.0E-03	126.0E-03	132.0E-03
Statistics									
Min	122.0E-03	121.0E-03	122.0E-03	121.0E-03	121.0E-03	123.0E-03	122.0E-03	124.0E-03	131.0E-03
Max	124.0E-03	124.0E-03	123.0E-03	122.0E-03	123.0E-03	124.0E-03	123.0E-03	126.0E-03	132.0E-03
Average	123.0E-03	123.0E-03	122.6E-03	121.6E-03	122.4E-03	123.2E-03	122.2E-03	125.0E-03	131.2E-03
Sigma	894.4E-06	1.1E-03	489.9E-06	489.9E-06	800.0E-06	400.0E-06	400.0E-06	632.5E-06	400.0E-06

**Drift Calculation**

VOLD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	1.0E-03	0.0E+00	0.0E+00	1.0E-03	1.0E-03	1.0E-03	3.0E-03	9.0E-03
SN8	-	-2.0E-03	0.0E+00	-2.0E-03	-2.0E-03	0.0E+00	-1.0E-03	1.0E-03	8.0E-03
SN9	-	1.0E-03	0.0E+00	-1.0E-03	0.0E+00	2.0E-03	0.0E+00	3.0E-03	9.0E-03
SN10	-	0.0E+00	-1.0E-03	-2.0E-03	-1.0E-03	-1.0E-03	-2.0E-03	1.0E-03	7.0E-03
SN11	-	0.0E+00	-1.0E-03	-2.0E-03	-1.0E-03	-1.0E-03	-2.0E-03	2.0E-03	8.0E-03
Average	-	0.0E+00	-400.0E-06	-1.4E-03	-600.0E-06	200.0E-06	-800.0E-06	2.0E-03	8.2E-03
Sigma	-	1.1E-03	489.9E-06	800.0E-06	1.0E-03	1.2E-03	1.2E-03	894.4E-06	748.3E-06



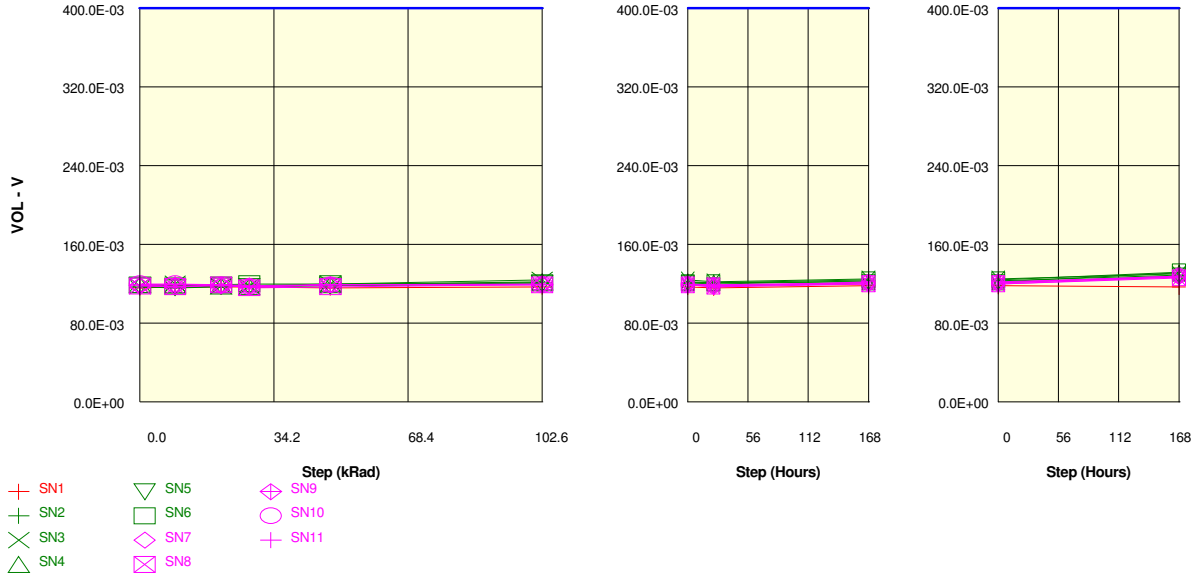
Parameter : logic output low voltage : VOLD13

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	116.0E-03	117.0E-03	117.0E-03	117.0E-03	116.0E-03	117.0E-03	116.0E-03	118.0E-03	117.0E-03
ON samples									
SN2	117.0E-03	116.0E-03	117.0E-03	118.0E-03	118.0E-03	121.0E-03	120.0E-03	123.0E-03	129.0E-03
SN3	118.0E-03	120.0E-03	118.0E-03	118.0E-03	120.0E-03	124.0E-03	122.0E-03	125.0E-03	130.0E-03
SN4	119.0E-03	119.0E-03	118.0E-03	117.0E-03	119.0E-03	122.0E-03	121.0E-03	122.0E-03	131.0E-03
SN5	118.0E-03	116.0E-03	118.0E-03	117.0E-03	118.0E-03	120.0E-03	118.0E-03	121.0E-03	128.0E-03
SN6	119.0E-03	118.0E-03	119.0E-03	120.0E-03	120.0E-03	121.0E-03	121.0E-03	124.0E-03	132.0E-03
Statistics									
Min	117.0E-03	116.0E-03	117.0E-03	117.0E-03	118.0E-03	120.0E-03	118.0E-03	121.0E-03	128.0E-03
Max	119.0E-03	120.0E-03	119.0E-03	120.0E-03	120.0E-03	124.0E-03	122.0E-03	125.0E-03	132.0E-03
Average	118.2E-03	117.8E-03	118.0E-03	118.0E-03	119.0E-03	121.6E-03	120.4E-03	123.0E-03	130.0E-03
Sigma	748.3E-06	1.6E-03	632.5E-06	1.1E-03	894.4E-06	1.4E-03	1.4E-03	1.4E-03	1.4E-03

Drift Calculation

VOLD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-1.0E-03	0.0E+00	1000.0E-06	1000.0E-06	4.0E-03	3.0E-03	6.0E-03	12.0E-03
SN3	-	2.0E-03	0.0E+00	0.0E+00	2.0E-03	6.0E-03	4.0E-03	7.0E-03	12.0E-03
SN4	-	0.0E+00	-1.0E-03	-2.0E-03	0.0E+00	3.0E-03	2.0E-03	3.0E-03	12.0E-03
SN5	-	-2.0E-03	0.0E+00	-1000.0E-06	0.0E+00	2.0E-03	0.0E+00	3.0E-03	10.0E-03
SN6	-	-1.0E-03	0.0E+00	1.0E-03	1.0E-03	2.0E-03	2.0E-03	5.0E-03	13.0E-03
Average	-	-400.0E-06	-200.0E-06	-200.0E-06	800.0E-06	3.4E-03	2.2E-03	4.8E-03	11.8E-03
Sigma	-	1.4E-03	400.0E-06	1.2E-03	748.3E-06	1.5E-03	1.3E-03	1.6E-03	979.8E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOLD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	116.0E-03	117.0E-03	117.0E-03	117.0E-03	116.0E-03	117.0E-03	116.0E-03	118.0E-03	117.0E-03
<b>OFF samples</b>									
SN7	118.0E-03	119.0E-03	119.0E-03	118.0E-03	119.0E-03	120.0E-03	119.0E-03	121.0E-03	128.0E-03
SN8	118.0E-03	117.0E-03	119.0E-03	116.0E-03	117.0E-03	119.0E-03	118.0E-03	120.0E-03	126.0E-03
SN9	118.0E-03	117.0E-03	118.0E-03	117.0E-03	119.0E-03	119.0E-03	117.0E-03	120.0E-03	127.0E-03
SN10	120.0E-03	120.0E-03	119.0E-03	117.0E-03	119.0E-03	119.0E-03	118.0E-03	121.0E-03	128.0E-03
SN11	119.0E-03	119.0E-03	119.0E-03	117.0E-03	119.0E-03	119.0E-03	117.0E-03	122.0E-03	127.0E-03
<b>Statistics</b>									
Min	118.0E-03	117.0E-03	118.0E-03	116.0E-03	117.0E-03	119.0E-03	117.0E-03	120.0E-03	126.0E-03
Max	120.0E-03	120.0E-03	119.0E-03	118.0E-03	119.0E-03	120.0E-03	119.0E-03	122.0E-03	128.0E-03
Average	118.6E-03	118.4E-03	118.8E-03	117.0E-03	118.6E-03	119.2E-03	117.8E-03	120.8E-03	127.2E-03
Sigma	800.0E-06	1.2E-03	400.0E-06	632.5E-06	800.0E-06	400.0E-06	748.3E-06	748.3E-06	748.3E-06

**Drift Calculation**

VOLD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	1.0E-03	1.0E-03	0.0E+00	1.0E-03	2.0E-03	1.0E-03	3.0E-03	10.0E-03
SN8	-	-1000.0E-06	1.0E-03	-2.0E-03	-1000.0E-06	1.0E-03	0.0E+00	2.0E-03	8.0E-03
SN9	-	-1000.0E-06	0.0E+00	-1000.0E-06	1.0E-03	1.0E-03	-1000.0E-06	2.0E-03	9.0E-03
SN10	-	0.0E+00	-1.0E-03	-3.0E-03	-1.0E-03	-1.0E-03	-2.0E-03	1.0E-03	8.0E-03
SN11	-	0.0E+00	0.0E+00	-2.0E-03	0.0E+00	0.0E+00	-2.0E-03	3.0E-03	8.0E-03
Average	-	-200.0E-06	200.0E-06	-1.6E-03	2.8E-18	600.0E-06	-800.0E-06	2.2E-03	8.6E-03
Sigma	-	748.3E-06	748.3E-06	1.0E-03	894.4E-06	1.0E-03	1.2E-03	748.3E-06	800.0E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

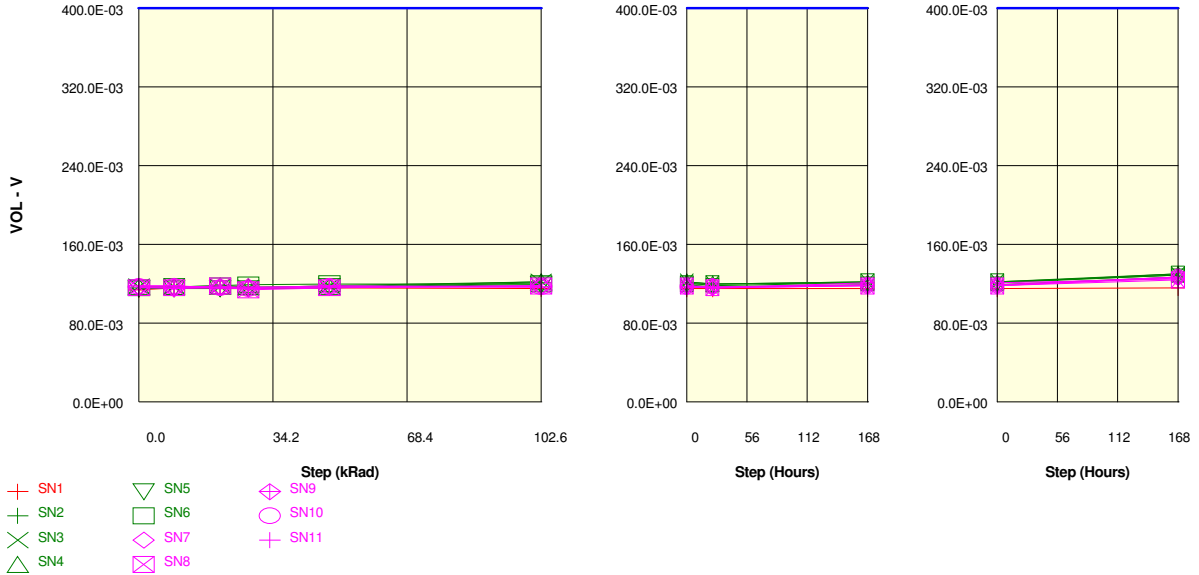
Parameter : logic output low voltage : VOLD12

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	114.0E-03	116.0E-03	115.0E-03	115.0E-03	116.0E-03	115.0E-03	115.0E-03	115.0E-03	116.0E-03
ON samples									
SN2	116.0E-03	116.0E-03	115.0E-03	116.0E-03	116.0E-03	121.0E-03	118.0E-03	121.0E-03	129.0E-03
SN3	117.0E-03	117.0E-03	117.0E-03	116.0E-03	118.0E-03	122.0E-03	120.0E-03	122.0E-03	129.0E-03
SN4	117.0E-03	117.0E-03	118.0E-03	117.0E-03	117.0E-03	122.0E-03	120.0E-03	121.0E-03	130.0E-03
SN5	115.0E-03	115.0E-03	115.0E-03	115.0E-03	117.0E-03	119.0E-03	117.0E-03	119.0E-03	127.0E-03
SN6	116.0E-03	117.0E-03	118.0E-03	119.0E-03	120.0E-03	120.0E-03	120.0E-03	122.0E-03	130.0E-03
Statistics									
Min	115.0E-03	115.0E-03	115.0E-03	115.0E-03	116.0E-03	119.0E-03	117.0E-03	119.0E-03	127.0E-03
Max	117.0E-03	117.0E-03	118.0E-03	119.0E-03	120.0E-03	122.0E-03	120.0E-03	122.0E-03	130.0E-03
Average	116.2E-03	116.4E-03	116.6E-03	116.6E-03	117.6E-03	120.8E-03	119.0E-03	121.0E-03	129.0E-03
Sigma	748.3E-06	800.0E-06	1.4E-03	1.4E-03	1.4E-03	1.2E-03	1.3E-03	1.1E-03	1.1E-03

Drift Calculation

VOLD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-1.0E-03	0.0E+00	0.0E+00	5.0E-03	2.0E-03	5.0E-03	13.0E-03
SN3	-	0.0E+00	0.0E+00	-1.0E-03	1000.0E-06	5.0E-03	3.0E-03	5.0E-03	12.0E-03
SN4	-	0.0E+00	1000.0E-06	0.0E+00	0.0E+00	5.0E-03	3.0E-03	4.0E-03	13.0E-03
SN5	-	0.0E+00	0.0E+00	0.0E+00	2.0E-03	4.0E-03	2.0E-03	4.0E-03	12.0E-03
SN6	-	1.0E-03	2.0E-03	3.0E-03	4.0E-03	4.0E-03	4.0E-03	6.0E-03	14.0E-03
Average	-	200.0E-06	400.0E-06	400.0E-06	1.4E-03	4.6E-03	2.8E-03	4.8E-03	12.8E-03
Sigma	-	400.0E-06	1.0E-03	1.4E-03	1.5E-03	489.9E-06	748.3E-06	748.3E-06	748.3E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

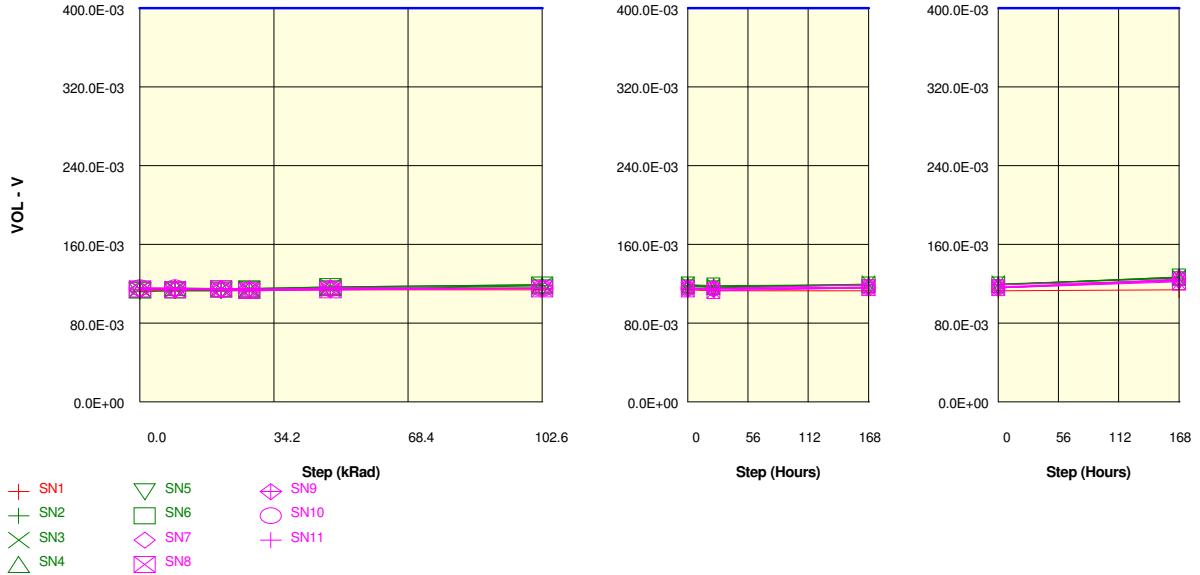
**Measurements**

VOLD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	114.0E-03	116.0E-03	115.0E-03	115.0E-03	116.0E-03	115.0E-03	115.0E-03	115.0E-03	116.0E-03
<b>OFF samples</b>									
SN7	117.0E-03	117.0E-03	117.0E-03	117.0E-03	117.0E-03	118.0E-03	117.0E-03	119.0E-03	127.0E-03
SN8	116.0E-03	116.0E-03	118.0E-03	114.0E-03	116.0E-03	118.0E-03	116.0E-03	118.0E-03	124.0E-03
SN9	117.0E-03	115.0E-03	116.0E-03	115.0E-03	117.0E-03	117.0E-03	116.0E-03	118.0E-03	126.0E-03
SN10	117.0E-03	117.0E-03	116.0E-03	115.0E-03	117.0E-03	117.0E-03	117.0E-03	118.0E-03	127.0E-03
SN11	118.0E-03	118.0E-03	116.0E-03	116.0E-03	118.0E-03	117.0E-03	116.0E-03	121.0E-03	125.0E-03
<b>Statistics</b>									
Min	116.0E-03	115.0E-03	116.0E-03	114.0E-03	116.0E-03	117.0E-03	116.0E-03	118.0E-03	124.0E-03
Max	118.0E-03	118.0E-03	118.0E-03	117.0E-03	118.0E-03	118.0E-03	117.0E-03	121.0E-03	127.0E-03
Average	117.0E-03	116.6E-03	116.6E-03	115.4E-03	117.0E-03	117.4E-03	116.4E-03	118.8E-03	125.8E-03
Sigma	632.5E-06	1.0E-03	800.0E-06	1.0E-03	632.5E-06	489.9E-06	489.9E-06	1.2E-03	1.2E-03

**Drift Calculation**

VOLD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	1000.0E-06	0.0E+00	2.0E-03	10.0E-03
SN8	-	0.0E+00	2.0E-03	-2.0E-03	0.0E+00	2.0E-03	0.0E+00	2.0E-03	8.0E-03
SN9	-	-2.0E-03	-1.0E-03	-2.0E-03	0.0E+00	0.0E+00	-1.0E-03	1000.0E-06	9.0E-03
SN10	-	0.0E+00	-1.0E-03	-2.0E-03	0.0E+00	0.0E+00	0.0E+00	1000.0E-06	10.0E-03
SN11	-	0.0E+00	-2.0E-03	-2.0E-03	0.0E+00	-1000.0E-06	-2.0E-03	3.0E-03	7.0E-03
Average	-	-400.0E-06	-400.0E-06	-1.6E-03	0.0E+00	400.0E-06	-600.0E-06	1.8E-03	8.8E-03
Sigma	-	800.0E-06	1.4E-03	800.0E-06	0.0E+00	1.0E-03	800.0E-06	748.3E-06	1.2E-03

Parameter : logic output low voltage : VOLD11  
 Test conditions : IOL=1.6mA  
 Unit : V  
 Spec Limit Max : 400.0E-03  
 Spec limits are represented in bold lines on the graphic.



Measurements

VOLD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	112.0E-03	113.0E-03	113.0E-03	113.0E-03	114.0E-03	114.0E-03	113.0E-03	113.0E-03	114.0E-03
ON samples									
SN2	114.0E-03	114.0E-03	113.0E-03	115.0E-03	114.0E-03	118.0E-03	116.0E-03	119.0E-03	126.0E-03
SN3	115.0E-03	115.0E-03	115.0E-03	115.0E-03	117.0E-03	119.0E-03	117.0E-03	120.0E-03	126.0E-03
SN4	114.0E-03	116.0E-03	115.0E-03	114.0E-03	116.0E-03	118.0E-03	117.0E-03	119.0E-03	127.0E-03
SN5	113.0E-03	113.0E-03	113.0E-03	114.0E-03	115.0E-03	116.0E-03	115.0E-03	116.0E-03	124.0E-03
SN6	114.0E-03	114.0E-03	115.0E-03	115.0E-03	117.0E-03	119.0E-03	118.0E-03	119.0E-03	127.0E-03
Statistics									
Min	113.0E-03	113.0E-03	113.0E-03	114.0E-03	114.0E-03	116.0E-03	115.0E-03	116.0E-03	124.0E-03
Max	115.0E-03	116.0E-03	115.0E-03	115.0E-03	117.0E-03	119.0E-03	118.0E-03	120.0E-03	127.0E-03
Average	114.0E-03	114.4E-03	114.2E-03	114.6E-03	115.8E-03	118.0E-03	116.6E-03	118.6E-03	126.0E-03
Sigma	632.5E-06	1.0E-03	979.8E-06	489.9E-06	1.2E-03	1.1E-03	1.0E-03	1.4E-03	1.1E-03

Drift Calculation

VOLD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-1.0E-03	1.0E-03	0.0E+00	4.0E-03	2.0E-03	5.0E-03	12.0E-03
SN3	-	0.0E+00	0.0E+00	0.0E+00	2.0E-03	4.0E-03	2.0E-03	5.0E-03	11.0E-03
SN4	-	2.0E-03	1.0E-03	0.0E+00	2.0E-03	4.0E-03	3.0E-03	5.0E-03	13.0E-03
SN5	-	0.0E+00	0.0E+00	1.0E-03	2.0E-03	3.0E-03	2.0E-03	3.0E-03	11.0E-03
SN6	-	0.0E+00	1.0E-03	1.0E-03	3.0E-03	5.0E-03	4.0E-03	5.0E-03	13.0E-03
Average	-	400.0E-06	200.0E-06	600.0E-06	1.8E-03	4.0E-03	2.6E-03	4.6E-03	12.0E-03
Sigma	-	800.0E-06	748.3E-06	489.9E-06	979.8E-06	632.5E-06	800.0E-06	800.0E-06	894.4E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
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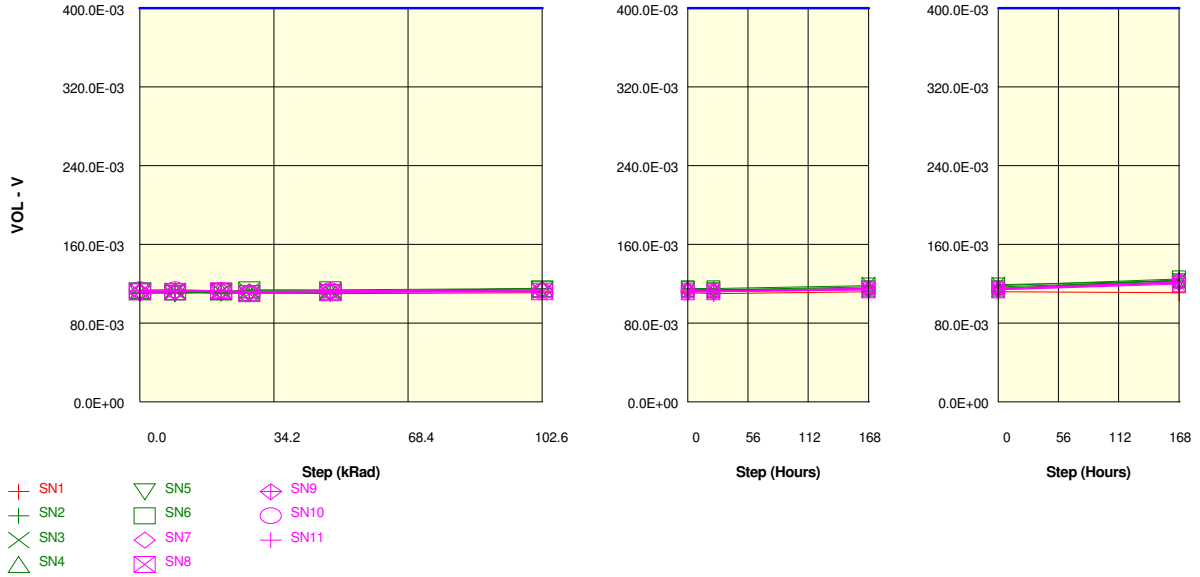
**Measurements**

VOLD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	112.0E-03	113.0E-03	113.0E-03	113.0E-03	114.0E-03	114.0E-03	113.0E-03	113.0E-03	114.0E-03
<b>OFF samples</b>									
SN7	114.0E-03	115.0E-03	115.0E-03	115.0E-03	114.0E-03	116.0E-03	115.0E-03	117.0E-03	124.0E-03
SN8	115.0E-03	114.0E-03	115.0E-03	113.0E-03	114.0E-03	115.0E-03	113.0E-03	116.0E-03	122.0E-03
SN9	114.0E-03	114.0E-03	114.0E-03	113.0E-03	116.0E-03	115.0E-03	114.0E-03	116.0E-03	123.0E-03
SN10	116.0E-03	116.0E-03	114.0E-03	113.0E-03	115.0E-03	115.0E-03	115.0E-03	116.0E-03	125.0E-03
SN11	116.0E-03	115.0E-03	115.0E-03	114.0E-03	116.0E-03	115.0E-03	115.0E-03	119.0E-03	123.0E-03
<b>Statistics</b>									
Min	114.0E-03	114.0E-03	114.0E-03	113.0E-03	114.0E-03	115.0E-03	113.0E-03	116.0E-03	122.0E-03
Max	116.0E-03	116.0E-03	115.0E-03	115.0E-03	116.0E-03	116.0E-03	115.0E-03	119.0E-03	125.0E-03
Average	115.0E-03	114.8E-03	114.6E-03	113.6E-03	115.0E-03	115.2E-03	114.4E-03	116.8E-03	123.4E-03
Sigma	894.4E-06	748.3E-06	489.9E-06	800.0E-06	894.4E-06	400.0E-06	800.0E-06	1.2E-03	1.0E-03

**Drift Calculation**

VOLD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	1.0E-03	1.0E-03	1.0E-03	0.0E+00	2.0E-03	1.0E-03	3.0E-03	10.0E-03
SN8	-	-1.0E-03	0.0E+00	-2.0E-03	-1.0E-03	0.0E+00	-2.0E-03	1.0E-03	7.0E-03
SN9	-	0.0E+00	0.0E+00	-1.0E-03	2.0E-03	1.0E-03	0.0E+00	2.0E-03	9.0E-03
SN10	-	0.0E+00	-2.0E-03	-3.0E-03	-1.0E-03	-1.0E-03	-1.0E-03	0.0E+00	9.0E-03
SN11	-	-1.0E-03	-1.0E-03	-2.0E-03	0.0E+00	-1.0E-03	-1.0E-03	3.0E-03	7.0E-03
Average	-	-200.0E-06	-400.0E-06	-1.4E-03	0.0E+00	200.0E-06	-600.0E-06	1.8E-03	8.4E-03
Sigma	-	748.3E-06	1.0E-03	1.4E-03	1.1E-03	1.2E-03	1.0E-03	1.2E-03	1.2E-03

Parameter : logic output low voltage : VOLD10  
 Test conditions : IOL=1.6mA  
 Unit : V  
 Spec Limit Max : 400.0E-03  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOLD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	110.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	111.0E-03	110.0E-03	112.0E-03	111.0E-03
ON samples									
SN2	111.0E-03	112.0E-03	110.0E-03	111.0E-03	112.0E-03	115.0E-03	114.0E-03	117.0E-03	123.0E-03
SN3	112.0E-03	113.0E-03	112.0E-03	113.0E-03	113.0E-03	114.0E-03	114.0E-03	119.0E-03	123.0E-03
SN4	112.0E-03	112.0E-03	112.0E-03	111.0E-03	112.0E-03	115.0E-03	114.0E-03	115.0E-03	124.0E-03
SN5	112.0E-03	110.0E-03	112.0E-03	110.0E-03	111.0E-03	114.0E-03	113.0E-03	115.0E-03	122.0E-03
SN6	113.0E-03	112.0E-03	112.0E-03	114.0E-03	114.0E-03	115.0E-03	115.0E-03	118.0E-03	125.0E-03
Statistics									
Min	111.0E-03	110.0E-03	110.0E-03	110.0E-03	111.0E-03	114.0E-03	113.0E-03	115.0E-03	122.0E-03
Max	113.0E-03	113.0E-03	112.0E-03	114.0E-03	114.0E-03	115.0E-03	115.0E-03	119.0E-03	125.0E-03
Average	112.0E-03	111.8E-03	111.6E-03	111.8E-03	112.4E-03	114.8E-03	114.0E-03	116.8E-03	123.4E-03
Sigma	632.5E-06	979.8E-06	800.0E-06	1.5E-03	1.0E-03	433.0E-06	707.1E-06	1.6E-03	1.0E-03

**Drift Calculation**

VOLD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	1.0E-03	-1.0E-03	0.0E+00	1.0E-03	4.0E-03	3.0E-03	6.0E-03	12.0E-03
SN3	-	1.0E-03	0.0E+00	1.0E-03	1.0E-03	-	-	7.0E-03	11.0E-03
SN4	-	0.0E+00	0.0E+00	-1.0E-03	0.0E+00	3.0E-03	2.0E-03	3.0E-03	12.0E-03
SN5	-	-2.0E-03	0.0E+00	-2.0E-03	-1.0E-03	2.0E-03	1.0E-03	3.0E-03	10.0E-03
SN6	-	-1.0E-03	-1.0E-03	1.0E-03	1.0E-03	2.0E-03	2.0E-03	5.0E-03	12.0E-03
Average	-	-200.0E-06	-400.0E-06	-200.0E-06	400.0E-06	2.8E-03	2.0E-03	4.8E-03	11.4E-03
Sigma	-	1.2E-03	489.9E-06	1.2E-03	800.0E-06	829.2E-06	707.1E-06	1.6E-03	800.0E-06

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**Measurements**

VOLD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	110.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	111.0E-03	110.0E-03	112.0E-03	111.0E-03
<b>OFF samples</b>									
SN7	111.0E-03	112.0E-03	113.0E-03	112.0E-03	113.0E-03	113.0E-03	113.0E-03	115.0E-03	121.0E-03
SN8	112.0E-03	112.0E-03	113.0E-03	110.0E-03	111.0E-03	112.0E-03	112.0E-03	114.0E-03	120.0E-03
SN9	112.0E-03	112.0E-03	113.0E-03	111.0E-03	112.0E-03	114.0E-03	112.0E-03	114.0E-03	121.0E-03
SN10	114.0E-03	114.0E-03	113.0E-03	110.0E-03	113.0E-03	112.0E-03	112.0E-03	115.0E-03	122.0E-03
SN11	113.0E-03	114.0E-03	113.0E-03	111.0E-03	113.0E-03	112.0E-03	112.0E-03	115.0E-03	121.0E-03
<b>Statistics</b>									
Min	111.0E-03	112.0E-03	113.0E-03	110.0E-03	111.0E-03	112.0E-03	112.0E-03	114.0E-03	120.0E-03
Max	114.0E-03	114.0E-03	113.0E-03	112.0E-03	113.0E-03	114.0E-03	113.0E-03	115.0E-03	122.0E-03
Average	112.4E-03	112.8E-03	113.0E-03	110.8E-03	112.4E-03	112.6E-03	112.2E-03	114.6E-03	121.0E-03
Sigma	1.0E-03	979.8E-06	2.1E-09	748.3E-06	800.0E-06	800.0E-06	400.0E-06	489.9E-06	632.5E-06

**Drift Calculation**

VOLD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	1.0E-03	2.0E-03	1.0E-03	2.0E-03	2.0E-03	2.0E-03	4.0E-03	10.0E-03
SN8	-	0.0E+00	1.0E-03	-2.0E-03	-1.0E-03	0.0E+00	0.0E+00	2.0E-03	8.0E-03
SN9	-	0.0E+00	1.0E-03	-1.0E-03	0.0E+00	2.0E-03	0.0E+00	2.0E-03	9.0E-03
SN10	-	0.0E+00	-1.0E-03	-4.0E-03	-1.0E-03	-2.0E-03	-2.0E-03	1.0E-03	8.0E-03
SN11	-	1.0E-03	0.0E+00	-2.0E-03	0.0E+00	-1.0E-03	-1.0E-03	2.0E-03	8.0E-03
Average	-	400.0E-06	600.0E-06	-1.6E-03	0.0E+00	200.0E-06	-200.0E-06	2.2E-03	8.6E-03
Sigma	-	489.9E-06	1.0E-03	1.6E-03	1.1E-03	1.6E-03	1.3E-03	979.8E-06	800.0E-06



Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

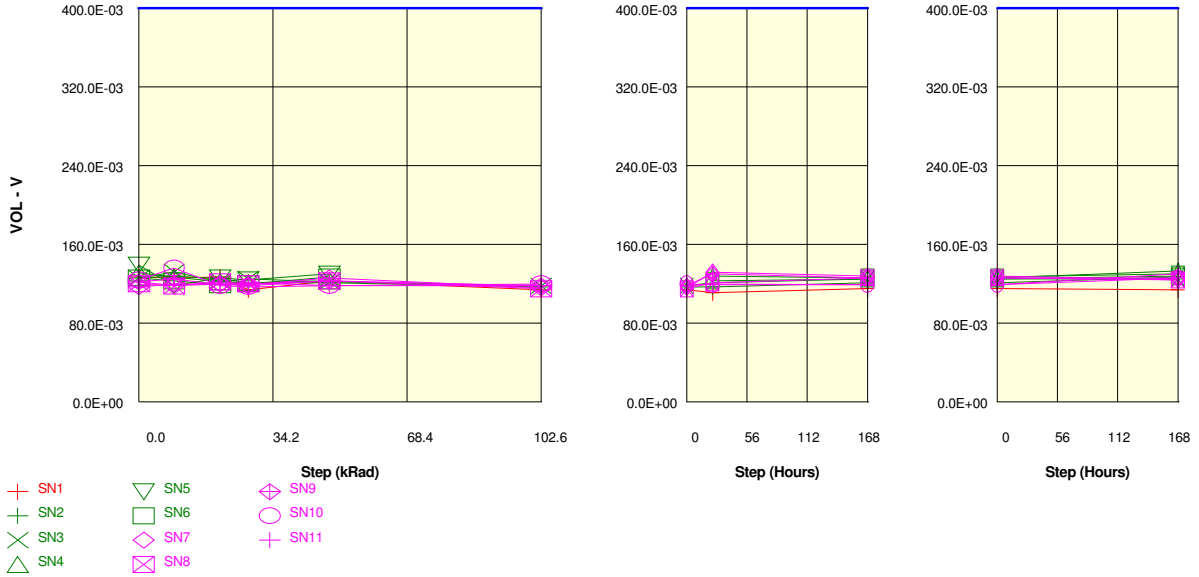
Parameter : logic output low voltage : VOLD9

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	127.0E-03	126.0E-03	127.0E-03	114.0E-03	123.0E-03	114.0E-03	111.0E-03	115.0E-03	114.0E-03
ON samples									
SN2	126.0E-03	128.0E-03	125.0E-03	121.0E-03	121.0E-03	117.0E-03	117.0E-03	121.0E-03	127.0E-03
SN3	126.0E-03	132.0E-03	122.0E-03	125.0E-03	122.0E-03	118.0E-03	121.0E-03	125.0E-03	125.0E-03
SN4	131.0E-03	127.0E-03	122.0E-03	121.0E-03	123.0E-03		128.0E-03	126.0E-03	133.0E-03
SN5	139.0E-03	118.0E-03	126.0E-03	124.0E-03	130.0E-03			127.0E-03	130.0E-03
SN6	126.0E-03	123.0E-03	119.0E-03	120.0E-03	127.0E-03		123.0E-03	125.0E-03	128.0E-03
Statistics									
Min	126.0E-03	118.0E-03	119.0E-03	120.0E-03	121.0E-03	117.0E-03	117.0E-03	121.0E-03	125.0E-03
Max	139.0E-03	132.0E-03	126.0E-03	125.0E-03	130.0E-03	118.0E-03	128.0E-03	127.0E-03	133.0E-03
Average	129.6E-03	125.6E-03	122.8E-03	122.2E-03	124.6E-03	117.5E-03	122.3E-03	124.8E-03	128.6E-03
Sigma	5.1E-03	4.8E-03	2.5E-03	1.9E-03	3.4E-03	500.0E-06	4.0E-03	2.0E-03	2.7E-03

Drift Calculation

VOLD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	2.0E-03	-1.0E-03	-5.0E-03	-5.0E-03	-9.0E-03	-9.0E-03	-5.0E-03	1.0E-03
SN3	-	6.0E-03	-4.0E-03	-1.0E-03	-4.0E-03	-8.0E-03	-5.0E-03	-1.0E-03	-1.0E-03
SN4	-	-4.0E-03	-9.0E-03	-10.0E-03	-8.0E-03		-3.0E-03	-5.0E-03	2.0E-03
SN5	-	-21.0E-03	-13.0E-03	-15.0E-03	-9.0E-03			-12.0E-03	-9.0E-03
SN6	-	-3.0E-03	-7.0E-03	-6.0E-03	1.0E-03		-3.0E-03	-1.0E-03	2.0E-03
Average	-	-4.0E-03	-6.8E-03	-7.4E-03	-5.0E-03	-8.5E-03	-5.0E-03	-4.8E-03	-1.0E-03
Sigma	-	9.2E-03	4.1E-03	4.8E-03	3.5E-03	500.0E-06	2.4E-03	4.0E-03	4.1E-03

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	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOLD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	127.0E-03	126.0E-03	127.0E-03	114.0E-03	123.0E-03	114.0E-03	111.0E-03	115.0E-03	114.0E-03
<b>OFF samples</b>									
SN7	122.0E-03	118.0E-03	120.0E-03	119.0E-03	126.0E-03	116.0E-03	132.0E-03	128.0E-03	124.0E-03
SN8	120.0E-03	118.0E-03	122.0E-03	120.0E-03	123.0E-03	115.0E-03	121.0E-03	126.0E-03	124.0E-03
SN9	117.0E-03	120.0E-03	120.0E-03	118.0E-03	123.0E-03	118.0E-03	130.0E-03	126.0E-03	126.0E-03
SN10	124.0E-03	136.0E-03	118.0E-03	117.0E-03	118.0E-03	120.0E-03	119.0E-03	119.0E-03	126.0E-03
SN11	122.0E-03	125.0E-03	119.0E-03	121.0E-03	118.0E-03	118.0E-03	120.0E-03	119.0E-03	130.0E-03
<b>Statistics</b>									
Min	117.0E-03	118.0E-03	118.0E-03	117.0E-03	118.0E-03	115.0E-03	119.0E-03	119.0E-03	124.0E-03
Max	124.0E-03	136.0E-03	122.0E-03	121.0E-03	126.0E-03	120.0E-03	132.0E-03	128.0E-03	130.0E-03
Average	121.0E-03	123.4E-03	119.8E-03	119.0E-03	121.6E-03	117.4E-03	124.4E-03	123.6E-03	126.0E-03
Sigma	2.4E-03	6.8E-03	1.3E-03	1.4E-03	3.1E-03	1.7E-03	5.5E-03	3.8E-03	2.2E-03

**Drift Calculation**

VOLD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-4.0E-03	-2.0E-03	-3.0E-03	4.0E-03	-6.0E-03	10.0E-03	6.0E-03	2.0E-03
SN8	-	-2.0E-03	2.0E-03	0.0E+00	3.0E-03	-5.0E-03	1.0E-03	6.0E-03	4.0E-03
SN9	-	3.0E-03	3.0E-03	1000.0E-06	6.0E-03	1000.0E-06	13.0E-03	9.0E-03	9.0E-03
SN10	-	12.0E-03	-6.0E-03	-7.0E-03	-6.0E-03	-4.0E-03	-5.0E-03	-5.0E-03	2.0E-03
SN11	-	3.0E-03	-3.0E-03	-1.0E-03	-4.0E-03	-4.0E-03	-2.0E-03	-3.0E-03	8.0E-03
Average	-	2.4E-03	-1.2E-03	-2.0E-03	600.0E-06	-3.6E-03	3.4E-03	2.6E-03	5.0E-03
Sigma	-	5.5E-03	3.3E-03	2.8E-03	4.7E-03	2.4E-03	6.9E-03	5.5E-03	3.0E-03

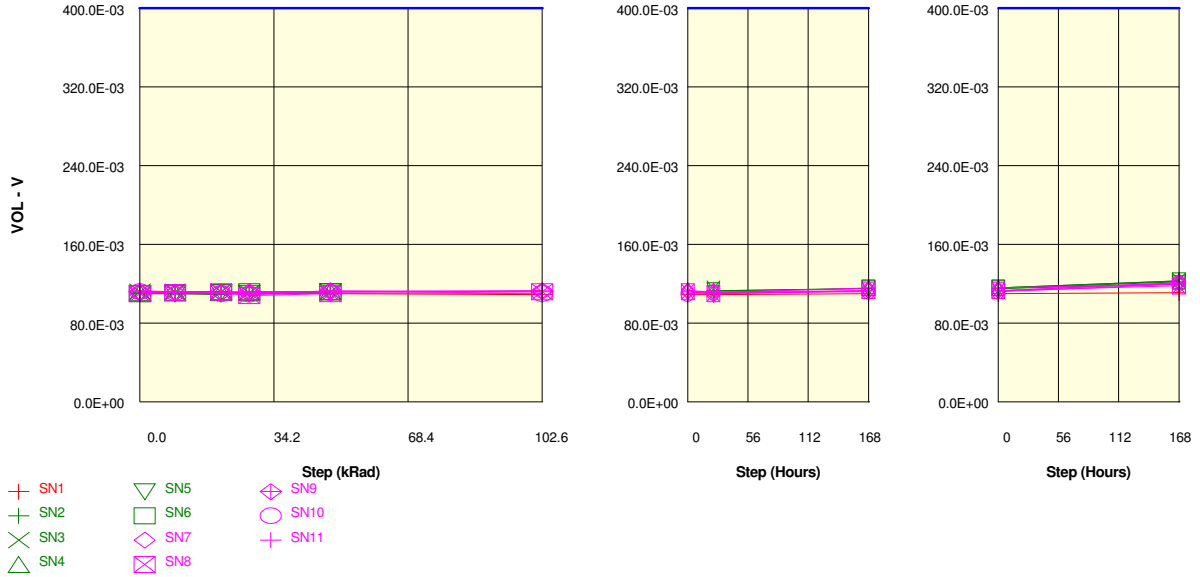
Parameter : logic output low voltage : VOLD8

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	110.0E-03	110.0E-03	110.0E-03	111.0E-03	110.0E-03	109.0E-03	109.0E-03	110.0E-03	111.0E-03
ON samples									
SN2	111.0E-03	110.0E-03	109.0E-03	111.0E-03	110.0E-03		113.0E-03	115.0E-03	122.0E-03
SN3	112.0E-03	112.0E-03	112.0E-03	111.0E-03	112.0E-03		115.0E-03		123.0E-03
SN4	111.0E-03	111.0E-03	112.0E-03	111.0E-03	112.0E-03			116.0E-03	123.0E-03
SN5	110.0E-03	110.0E-03	111.0E-03	110.0E-03	112.0E-03		113.0E-03	115.0E-03	120.0E-03
SN6	110.0E-03	111.0E-03	111.0E-03	112.0E-03	112.0E-03			116.0E-03	123.0E-03
Statistics									
Min	110.0E-03	110.0E-03	109.0E-03	110.0E-03	110.0E-03	-	113.0E-03	115.0E-03	120.0E-03
Max	112.0E-03	112.0E-03	112.0E-03	112.0E-03	112.0E-03	-	115.0E-03	116.0E-03	123.0E-03
Average	110.8E-03	110.8E-03	111.0E-03	111.0E-03	111.6E-03	-	113.7E-03	115.5E-03	122.2E-03
Sigma	748.3E-06	748.3E-06	1.1E-03	632.5E-06	800.0E-06	-	942.8E-06	500.0E-06	1.2E-03

Drift Calculation

VOLD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-1.0E-03	-2.0E-03	0.0E+00	-1.0E-03		2.0E-03	4.0E-03	11.0E-03
SN3	-	0.0E+00	0.0E+00	-1.0E-03	0.0E+00		3.0E-03		11.0E-03
SN4	-	0.0E+00	1.0E-03	0.0E+00	1.0E-03			5.0E-03	12.0E-03
SN5	-	0.0E+00	1.0E-03	0.0E+00	2.0E-03		3.0E-03	5.0E-03	10.0E-03
SN6	-	1.0E-03	1.0E-03	2.0E-03	2.0E-03			6.0E-03	13.0E-03
Average	-	0.0E+00	200.0E-06	200.0E-06	800.0E-06		2.7E-03	5.0E-03	11.4E-03
Sigma	-	632.5E-06	1.2E-03	979.8E-06	1.2E-03		471.4E-06	707.1E-06	1.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOLD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	110.0E-03	110.0E-03	110.0E-03	111.0E-03	110.0E-03	109.0E-03	109.0E-03	110.0E-03	111.0E-03
<b>OFF samples</b>									
SN7	111.0E-03	111.0E-03	111.0E-03	112.0E-03	112.0E-03	113.0E-03	112.0E-03	113.0E-03	121.0E-03
SN8	110.0E-03	111.0E-03	112.0E-03	108.0E-03	110.0E-03	112.0E-03	110.0E-03	113.0E-03	118.0E-03
SN9	112.0E-03	111.0E-03	111.0E-03	110.0E-03	113.0E-03	112.0E-03	110.0E-03	113.0E-03	121.0E-03
SN10	112.0E-03	111.0E-03	110.0E-03	109.0E-03	111.0E-03	110.0E-03	111.0E-03	112.0E-03	120.0E-03
SN11	113.0E-03	112.0E-03	111.0E-03	111.0E-03	112.0E-03	113.0E-03	111.0E-03	116.0E-03	120.0E-03
<b>Statistics</b>									
Min	110.0E-03	111.0E-03	110.0E-03	108.0E-03	110.0E-03	110.0E-03	110.0E-03	112.0E-03	118.0E-03
Max	113.0E-03	112.0E-03	112.0E-03	112.0E-03	113.0E-03	113.0E-03	112.0E-03	116.0E-03	121.0E-03
Average	111.6E-03	111.2E-03	111.0E-03	110.0E-03	111.6E-03	112.0E-03	110.8E-03	113.4E-03	120.0E-03
Sigma	1.0E-03	400.0E-06	632.5E-06	1.4E-03	1.0E-03	1.1E-03	748.3E-06	1.4E-03	1.1E-03

**Drift Calculation**

VOLD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	0.0E+00	1.0E-03	1.0E-03	2.0E-03	1.0E-03	2.0E-03	10.0E-03
SN8	-	1.0E-03	2.0E-03	-2.0E-03	0.0E+00	2.0E-03	0.0E+00	3.0E-03	8.0E-03
SN9	-	-1.0E-03	-1.0E-03	-2.0E-03	1.0E-03	0.0E+00	-2.0E-03	1.0E-03	9.0E-03
SN10	-	-1.0E-03	-2.0E-03	-3.0E-03	-1.0E-03	-2.0E-03	-1.0E-03	0.0E+00	8.0E-03
SN11	-	-1.0E-03	-2.0E-03	-2.0E-03	-1.0E-03	0.0E+00	-2.0E-03	3.0E-03	7.0E-03
Average	-	-400.0E-06	-600.0E-06	-1.6E-03	0.0E+00	400.0E-06	-800.0E-06	1.8E-03	8.4E-03
Sigma	-	800.0E-06	1.5E-03	1.4E-03	894.4E-06	1.5E-03	1.2E-03	1.2E-03	1.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

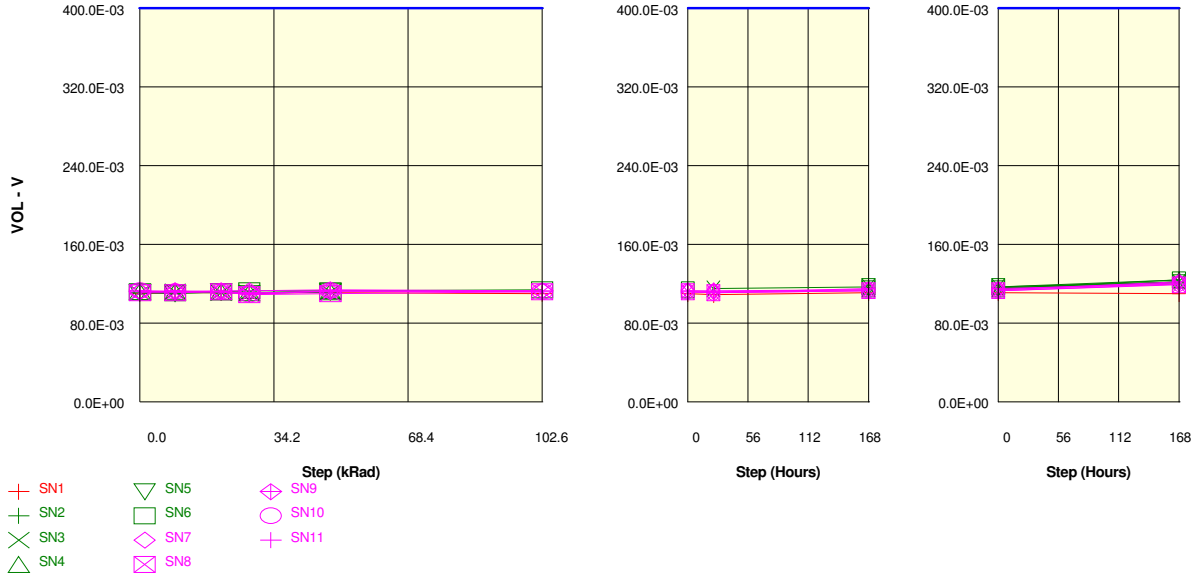
Parameter : logic output low voltage : VOLD7

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	110.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	109.0E-03	111.0E-03	110.0E-03
ON samples									
SN2	111.0E-03	111.0E-03	111.0E-03	111.0E-03	112.0E-03			116.0E-03	122.0E-03
SN3	111.0E-03	112.0E-03	111.0E-03	111.0E-03	112.0E-03		115.0E-03	117.0E-03	122.0E-03
SN4	112.0E-03	112.0E-03	112.0E-03	111.0E-03	112.0E-03			115.0E-03	124.0E-03
SN5	111.0E-03	110.0E-03	112.0E-03	110.0E-03	112.0E-03			115.0E-03	121.0E-03
SN6	112.0E-03	111.0E-03	112.0E-03	113.0E-03	113.0E-03	114.0E-03		117.0E-03	124.0E-03
Statistics									
Min	111.0E-03	110.0E-03	111.0E-03	110.0E-03	112.0E-03	114.0E-03	115.0E-03	115.0E-03	121.0E-03
Max	112.0E-03	112.0E-03	112.0E-03	113.0E-03	113.0E-03	114.0E-03	115.0E-03	117.0E-03	124.0E-03
Average	111.4E-03	111.2E-03	111.6E-03	111.2E-03	112.2E-03	114.0E-03	115.0E-03	116.0E-03	122.6E-03
Sigma	489.9E-06	748.3E-06	489.9E-06	979.8E-06	400.0E-06	0.0E+00	0.0E+00	894.4E-06	1.2E-03

Drift Calculation

VOLD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	0.0E+00	1.0E-03			5.0E-03	11.0E-03
SN3	-	1.0E-03	0.0E+00	0.0E+00	1.0E-03		4.0E-03	6.0E-03	11.0E-03
SN4	-	0.0E+00	0.0E+00	-1.0E-03	0.0E+00			3.0E-03	12.0E-03
SN5	-	-1.0E-03	1.0E-03	-1.0E-03	1.0E-03			4.0E-03	10.0E-03
SN6	-	-1.0E-03	0.0E+00	1.0E-03	1.0E-03	2.0E-03		5.0E-03	12.0E-03
Average	-	-200.0E-06	200.0E-06	-200.0E-06	800.0E-06	2.0E-03	4.0E-03	4.6E-03	11.2E-03
Sigma	-	748.3E-06	400.0E-06	748.3E-06	400.0E-06	0.0E+00	0.0E+00	1.0E-03	748.3E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197	
	AD976SD/883			Analog Devices			Issue:	02	

**Measurements**

VOLD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	110.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	109.0E-03	111.0E-03	110.0E-03
<b>OFF samples</b>									
SN7	112.0E-03	112.0E-03	113.0E-03	113.0E-03	114.0E-03	113.0E-03	113.0E-03	114.0E-03	121.0E-03
SN8	111.0E-03	111.0E-03	112.0E-03	109.0E-03	110.0E-03	112.0E-03	111.0E-03	113.0E-03	119.0E-03
SN9	112.0E-03	113.0E-03	112.0E-03	111.0E-03	112.0E-03	113.0E-03	112.0E-03	114.0E-03	122.0E-03
SN10	113.0E-03	112.0E-03	112.0E-03	109.0E-03	113.0E-03	112.0E-03	111.0E-03	113.0E-03	120.0E-03
SN11	113.0E-03	112.0E-03	112.0E-03	110.0E-03	113.0E-03	112.0E-03	111.0E-03	115.0E-03	120.0E-03
<b>Statistics</b>									
Min	111.0E-03	111.0E-03	112.0E-03	109.0E-03	110.0E-03	112.0E-03	111.0E-03	113.0E-03	119.0E-03
Max	113.0E-03	113.0E-03	113.0E-03	113.0E-03	114.0E-03	113.0E-03	113.0E-03	115.0E-03	122.0E-03
Average	112.2E-03	112.0E-03	112.2E-03	110.4E-03	112.4E-03	112.4E-03	111.6E-03	113.8E-03	120.4E-03
Sigma	748.3E-06	632.5E-06	400.0E-06	1.5E-03	1.4E-03	489.9E-06	800.0E-06	748.3E-06	1.0E-03

**Drift Calculation**

VOLD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	1.0E-03	1.0E-03	2.0E-03	1.0E-03	1.0E-03	2.0E-03	9.0E-03
SN8	-	0.0E+00	1.0E-03	-2.0E-03	-1.0E-03	1.0E-03	0.0E+00	2.0E-03	8.0E-03
SN9	-	1.0E-03	0.0E+00	-1.0E-03	0.0E+00	1.0E-03	0.0E+00	2.0E-03	10.0E-03
SN10	-	-1.0E-03	-1.0E-03	-4.0E-03	0.0E+00	-1.0E-03	-2.0E-03	0.0E+00	7.0E-03
SN11	-	-1.0E-03	-1.0E-03	-3.0E-03	0.0E+00	-1.0E-03	-2.0E-03	2.0E-03	7.0E-03
Average	-	-200.0E-06	0.0E+00	-1.8E-03	200.0E-06	200.0E-06	-600.0E-06	1.6E-03	8.2E-03
Sigma	-	748.3E-06	894.4E-06	1.7E-03	979.8E-06	979.8E-06	1.2E-03	800.0E-06	1.2E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

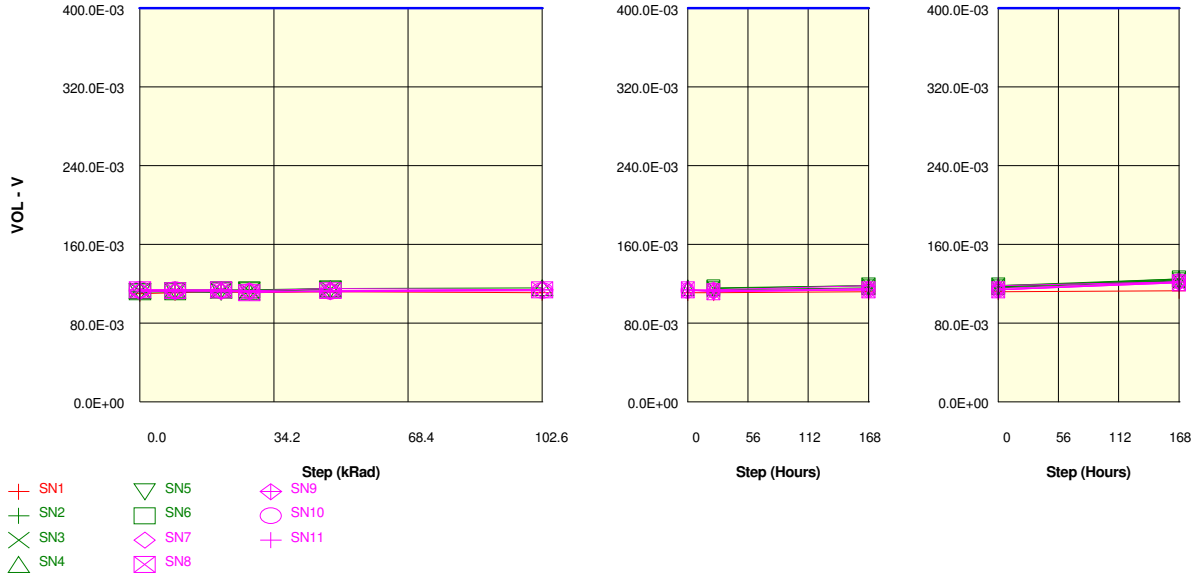
Parameter : logic output low voltage : VOLD6

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	110.0E-03	111.0E-03	112.0E-03	111.0E-03	112.0E-03	111.0E-03	111.0E-03	112.0E-03	113.0E-03
ON samples									
SN2	112.0E-03	112.0E-03	111.0E-03	113.0E-03	112.0E-03			117.0E-03	124.0E-03
SN3	113.0E-03	113.0E-03	113.0E-03	113.0E-03	115.0E-03		115.0E-03	118.0E-03	123.0E-03
SN4	113.0E-03	114.0E-03	114.0E-03	112.0E-03	115.0E-03	116.0E-03		117.0E-03	125.0E-03
SN5	112.0E-03	113.0E-03	113.0E-03	113.0E-03	114.0E-03		114.0E-03	116.0E-03	123.0E-03
SN6	112.0E-03	112.0E-03	114.0E-03	114.0E-03	115.0E-03		116.0E-03	118.0E-03	125.0E-03
Statistics									
Min	112.0E-03	112.0E-03	111.0E-03	112.0E-03	112.0E-03	116.0E-03	114.0E-03	116.0E-03	123.0E-03
Max	113.0E-03	114.0E-03	114.0E-03	114.0E-03	115.0E-03	116.0E-03	116.0E-03	118.0E-03	125.0E-03
Average	112.4E-03	112.8E-03	113.0E-03	113.0E-03	114.2E-03	116.0E-03	115.0E-03	117.2E-03	124.0E-03
Sigma	489.9E-06	748.3E-06	1.1E-03	632.5E-06	1.2E-03	0.0E+00	816.5E-06	748.3E-06	894.4E-06

Drift Calculation

VOLD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-1.0E-03	1.0E-03	0.0E+00			5.0E-03	12.0E-03
SN3	-	0.0E+00	0.0E+00	0.0E+00	2.0E-03		2.0E-03	5.0E-03	10.0E-03
SN4	-	1.0E-03	1.0E-03	-1.0E-03	2.0E-03	3.0E-03		4.0E-03	12.0E-03
SN5	-	1.0E-03	1.0E-03	1.0E-03	2.0E-03		2.0E-03	4.0E-03	11.0E-03
SN6	-	0.0E+00	2.0E-03	2.0E-03	3.0E-03		4.0E-03	6.0E-03	13.0E-03
Average	-	400.0E-06	600.0E-06	600.0E-06	1.8E-03	3.0E-03	2.7E-03	4.8E-03	11.6E-03
Sigma	-	489.9E-06	1.0E-03	1.0E-03	979.8E-06	0.0E+00	942.8E-06	748.3E-06	1.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOLD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	110.0E-03	111.0E-03	112.0E-03	111.0E-03	112.0E-03	111.0E-03	111.0E-03	112.0E-03	113.0E-03
OFF samples									
SN7	112.0E-03	113.0E-03	113.0E-03	113.0E-03	112.0E-03	114.0E-03	113.0E-03	115.0E-03	122.0E-03
SN8	114.0E-03	113.0E-03	114.0E-03	111.0E-03	113.0E-03	114.0E-03	112.0E-03	114.0E-03	121.0E-03
SN9	113.0E-03	112.0E-03	112.0E-03	112.0E-03	113.0E-03	114.0E-03	112.0E-03	114.0E-03	121.0E-03
SN10	114.0E-03	114.0E-03	113.0E-03	112.0E-03	112.0E-03	113.0E-03	113.0E-03	114.0E-03	122.0E-03
SN11	114.0E-03	114.0E-03	114.0E-03	113.0E-03	115.0E-03	114.0E-03	114.0E-03	118.0E-03	122.0E-03
Statistics									
Min	112.0E-03	112.0E-03	112.0E-03	111.0E-03	112.0E-03	113.0E-03	112.0E-03	114.0E-03	121.0E-03
Max	114.0E-03	114.0E-03	114.0E-03	113.0E-03	115.0E-03	114.0E-03	114.0E-03	118.0E-03	122.0E-03
Average	113.4E-03	113.2E-03	113.2E-03	112.2E-03	113.0E-03	113.8E-03	112.8E-03	115.0E-03	121.6E-03
Sigma	800.0E-06	748.3E-06	748.3E-06	748.3E-06	1.1E-03	400.0E-06	748.3E-06	1.5E-03	489.9E-06

**Drift Calculation**

VOLD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	1.0E-03	1.0E-03	1.0E-03	0.0E+00	2.0E-03	1.0E-03	3.0E-03	10.0E-03
SN8	-	-1.0E-03	0.0E+00	-3.0E-03	-1.0E-03	0.0E+00	-2.0E-03	0.0E+00	7.0E-03
SN9	-	-1.0E-03	-1.0E-03	-1.0E-03	0.0E+00	1.0E-03	-1.0E-03	1.0E-03	8.0E-03
SN10	-	0.0E+00	-1.0E-03	-2.0E-03	-2.0E-03	-1.0E-03	-1.0E-03	0.0E+00	8.0E-03
SN11	-	0.0E+00	0.0E+00	-1.0E-03	1.0E-03	0.0E+00	0.0E+00	4.0E-03	8.0E-03
Average	-	-200.0E-06	-200.0E-06	-1.2E-03	-400.0E-06	400.0E-06	-600.0E-06	1.6E-03	8.2E-03
Sigma	-	748.3E-06	748.3E-06	1.3E-03	1.0E-03	1.0E-03	1.0E-03	1.6E-03	979.8E-06



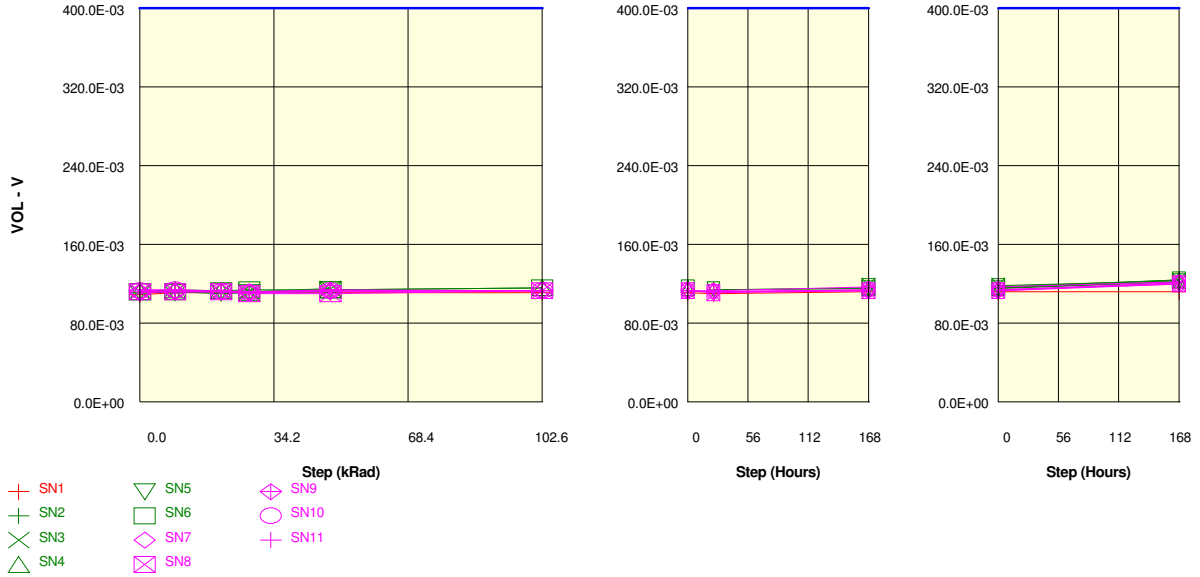
Parameter : logic output low voltage : VOLD5

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	109.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	112.0E-03	112.0E-03
ON samples									
SN2	111.0E-03	112.0E-03	110.0E-03	111.0E-03	112.0E-03		114.0E-03	116.0E-03	122.0E-03
SN3	112.0E-03	112.0E-03	112.0E-03	112.0E-03	115.0E-03			118.0E-03	123.0E-03
SN4	112.0E-03	114.0E-03	113.0E-03	111.0E-03	114.0E-03	116.0E-03		116.0E-03	124.0E-03
SN5	112.0E-03	111.0E-03	112.0E-03	111.0E-03	114.0E-03		114.0E-03	115.0E-03	122.0E-03
SN6	112.0E-03	112.0E-03	113.0E-03	114.0E-03	114.0E-03	116.0E-03		117.0E-03	124.0E-03
Statistics									
Min	111.0E-03	111.0E-03	110.0E-03	111.0E-03	112.0E-03	116.0E-03	114.0E-03	115.0E-03	122.0E-03
Max	112.0E-03	114.0E-03	113.0E-03	114.0E-03	115.0E-03	116.0E-03	114.0E-03	118.0E-03	124.0E-03
Average	111.8E-03	112.2E-03	112.0E-03	111.8E-03	113.8E-03	116.0E-03	114.0E-03	116.4E-03	123.0E-03
Sigma	400.0E-06	979.8E-06	1.1E-03	1.2E-03	979.8E-06	0.0E+00	0.0E+00	1.0E-03	894.4E-06

Drift Calculation

VOLD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	1.0E-03	-1.0E-03	0.0E+00	1.0E-03		3.0E-03	5.0E-03	11.0E-03
SN3	-	0.0E+00	0.0E+00	0.0E+00	3.0E-03			6.0E-03	11.0E-03
SN4	-	2.0E-03	1.0E-03	-1.0E-03	2.0E-03	4.0E-03		4.0E-03	12.0E-03
SN5	-	-1.0E-03	0.0E+00	-1.0E-03	2.0E-03		2.0E-03	3.0E-03	10.0E-03
SN6	-	0.0E+00	1.0E-03	2.0E-03	2.0E-03	4.0E-03		5.0E-03	12.0E-03
Average	-	400.0E-06	200.0E-06	0.0E+00	2.0E-03	4.0E-03	2.5E-03	4.6E-03	11.2E-03
Sigma	-	1.0E-03	748.3E-06	1.1E-03	632.5E-06	0.0E+00	500.0E-06	1.0E-03	748.3E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197	
	AD976SD/883			Analog Devices			Issue:	02	

**Measurements**

VOLD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	109.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	112.0E-03	112.0E-03
<b>OFF samples</b>									
SN7	111.0E-03	112.0E-03	112.0E-03	112.0E-03	113.0E-03	113.0E-03	112.0E-03	114.0E-03	121.0E-03
SN8	112.0E-03	112.0E-03	112.0E-03	110.0E-03	110.0E-03	113.0E-03	111.0E-03	113.0E-03	120.0E-03
SN9	112.0E-03	112.0E-03	112.0E-03	111.0E-03	112.0E-03	113.0E-03	112.0E-03	113.0E-03	121.0E-03
SN10	113.0E-03	114.0E-03	112.0E-03	111.0E-03	113.0E-03	113.0E-03	112.0E-03	114.0E-03	120.0E-03
SN11	114.0E-03	114.0E-03	113.0E-03	112.0E-03	114.0E-03	113.0E-03	113.0E-03	117.0E-03	122.0E-03
<b>Statistics</b>									
Min	111.0E-03	112.0E-03	112.0E-03	110.0E-03	110.0E-03	113.0E-03	111.0E-03	113.0E-03	120.0E-03
Max	114.0E-03	114.0E-03	113.0E-03	112.0E-03	114.0E-03	113.0E-03	113.0E-03	117.0E-03	122.0E-03
Average	112.4E-03	112.8E-03	112.2E-03	111.2E-03	112.4E-03	113.0E-03	112.0E-03	114.2E-03	120.8E-03
Sigma	1.0E-03	979.8E-06	400.0E-06	748.3E-06	1.4E-03	2.1E-09	632.5E-06	1.5E-03	748.3E-06

**Drift Calculation**

VOLD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	1.0E-03	1.0E-03	1.0E-03	2.0E-03	2.0E-03	1.0E-03	3.0E-03	10.0E-03
SN8	-	0.0E+00	0.0E+00	-2.0E-03	-2.0E-03	1.0E-03	-1.0E-03	1.0E-03	8.0E-03
SN9	-	0.0E+00	0.0E+00	-1.0E-03	0.0E+00	1.0E-03	0.0E+00	1.0E-03	9.0E-03
SN10	-	1.0E-03	-1.0E-03	-2.0E-03	0.0E+00	0.0E+00	-1.0E-03	1.0E-03	7.0E-03
SN11	-	0.0E+00	-1.0E-03	-2.0E-03	0.0E+00	-1.0E-03	-1.0E-03	3.0E-03	8.0E-03
Average	-	400.0E-06	-200.0E-06	-1.2E-03	0.0E+00	600.0E-06	-400.0E-06	1.8E-03	8.4E-03
Sigma	-	489.9E-06	748.3E-06	1.2E-03	1.3E-03	1.0E-03	800.0E-06	979.8E-06	1.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

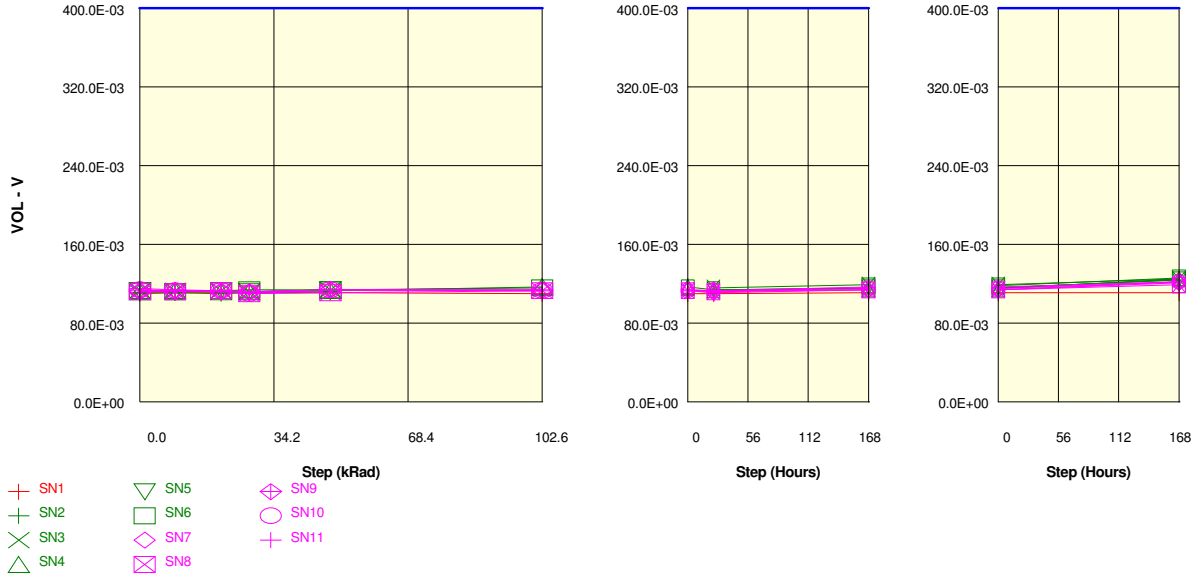
Parameter : logic output low voltage : VOLD4

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	110.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	110.0E-03	111.0E-03	111.0E-03
ON samples									
SN2	111.0E-03	111.0E-03	110.0E-03	111.0E-03	112.0E-03		113.0E-03	116.0E-03	124.0E-03
SN3	113.0E-03	113.0E-03	113.0E-03	112.0E-03	114.0E-03		116.0E-03	119.0E-03	125.0E-03
SN4	112.0E-03	113.0E-03	112.0E-03	112.0E-03	113.0E-03	117.0E-03	114.0E-03	115.0E-03	125.0E-03
SN5	113.0E-03	112.0E-03	113.0E-03	112.0E-03	114.0E-03		114.0E-03	116.0E-03	124.0E-03
SN6	113.0E-03	112.0E-03	113.0E-03	114.0E-03	114.0E-03	116.0E-03		118.0E-03	126.0E-03
Statistics									
Min	111.0E-03	111.0E-03	110.0E-03	111.0E-03	112.0E-03	116.0E-03	113.0E-03	115.0E-03	124.0E-03
Max	113.0E-03	113.0E-03	113.0E-03	114.0E-03	114.0E-03	117.0E-03	116.0E-03	119.0E-03	126.0E-03
Average	112.4E-03	112.2E-03	112.2E-03	112.2E-03	113.4E-03	116.5E-03	114.3E-03	116.8E-03	124.8E-03
Sigma	800.0E-06	748.3E-06	1.2E-03	979.8E-06	800.0E-06	500.0E-06	1.1E-03	1.5E-03	748.3E-06

Drift Calculation

VOLD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-1.0E-03	0.0E+00	1.0E-03		2.0E-03	5.0E-03	13.0E-03
SN3	-	0.0E+00	0.0E+00	-1.0E-03	1.0E-03		3.0E-03	6.0E-03	12.0E-03
SN4	-	1.0E-03	0.0E+00	0.0E+00	1.0E-03	5.0E-03	2.0E-03	3.0E-03	13.0E-03
SN5	-	-1.0E-03	0.0E+00	-1.0E-03	1.0E-03		1.0E-03	3.0E-03	11.0E-03
SN6	-	-1.0E-03	0.0E+00	1.0E-03	1.0E-03	3.0E-03		5.0E-03	13.0E-03
Average	-	-200.0E-06	-200.0E-06	-200.0E-06	1.0E-03	4.0E-03	2.0E-03	4.4E-03	12.4E-03
Sigma	-	748.3E-06	400.0E-06	748.3E-06	9.2E-12	1.0E-03	707.1E-06	1.2E-03	800.0E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

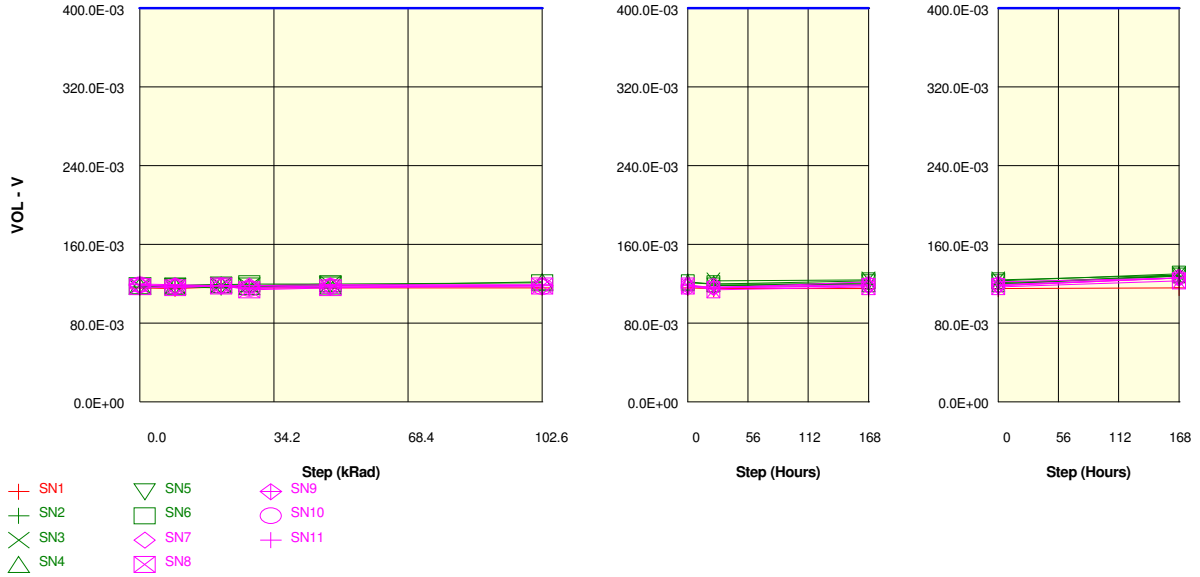
**Measurements**

VOLD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	110.0E-03	111.0E-03	111.0E-03	111.0E-03	111.0E-03	110.0E-03	110.0E-03	111.0E-03	111.0E-03
<b>OFF samples</b>									
SN7	112.0E-03	113.0E-03	113.0E-03	112.0E-03	114.0E-03	114.0E-03	113.0E-03	114.0E-03	121.0E-03
SN8	112.0E-03	112.0E-03	113.0E-03	110.0E-03	111.0E-03	113.0E-03	112.0E-03	114.0E-03	119.0E-03
SN9	113.0E-03	113.0E-03	112.0E-03	111.0E-03	114.0E-03	113.0E-03	111.0E-03	114.0E-03	122.0E-03
SN10	114.0E-03	113.0E-03	113.0E-03	110.0E-03	114.0E-03	113.0E-03	113.0E-03	115.0E-03	122.0E-03
SN11	115.0E-03	114.0E-03	113.0E-03	112.0E-03	114.0E-03	114.0E-03	113.0E-03	117.0E-03	122.0E-03
<b>Statistics</b>									
Min	112.0E-03	112.0E-03	112.0E-03	110.0E-03	111.0E-03	113.0E-03	111.0E-03	114.0E-03	119.0E-03
Max	115.0E-03	114.0E-03	113.0E-03	112.0E-03	114.0E-03	114.0E-03	113.0E-03	117.0E-03	122.0E-03
Average	113.2E-03	113.0E-03	112.8E-03	111.0E-03	113.4E-03	113.4E-03	112.4E-03	114.8E-03	121.2E-03
Sigma	1.2E-03	632.5E-06	400.0E-06	894.4E-06	1.2E-03	489.9E-06	800.0E-06	1.2E-03	1.2E-03

**Drift Calculation**

VOLD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	1.0E-03	1.0E-03	0.0E+00	2.0E-03	2.0E-03	1.0E-03	2.0E-03	9.0E-03
SN8	-	0.0E+00	1.0E-03	-2.0E-03	-1.0E-03	1.0E-03	0.0E+00	2.0E-03	7.0E-03
SN9	-	0.0E+00	-1.0E-03	-2.0E-03	1.0E-03	0.0E+00	-2.0E-03	1.0E-03	9.0E-03
SN10	-	-1.0E-03	-1.0E-03	-4.0E-03	0.0E+00	-1.0E-03	-1.0E-03	1.0E-03	8.0E-03
SN11	-	-1.0E-03	-2.0E-03	-3.0E-03	-1.0E-03	-1.0E-03	-2.0E-03	2.0E-03	7.0E-03
Average	-	-200.0E-06	-400.0E-06	-2.2E-03	200.0E-06	200.0E-06	-800.0E-06	1.6E-03	8.0E-03
Sigma	-	748.3E-06	1.2E-03	1.3E-03	1.2E-03	1.2E-03	1.2E-03	489.9E-06	894.4E-06

Parameter : logic output low voltage : VOLD3  
 Test conditions : IOL=1.6mA  
 Unit : V  
 Spec Limit Max : 400.0E-03  
 Spec limits are represented in bold lines on the graphic.



Measurements

VOLD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	116.0E-03	115.0E-03	117.0E-03	116.0E-03	116.0E-03	116.0E-03	115.0E-03	115.0E-03	116.0E-03
ON samples									
SN2	117.0E-03	117.0E-03	116.0E-03	118.0E-03	116.0E-03		118.0E-03	120.0E-03	128.0E-03
SN3	118.0E-03	118.0E-03	119.0E-03	118.0E-03	120.0E-03		123.0E-03	124.0E-03	129.0E-03
SN4	118.0E-03	118.0E-03	119.0E-03	117.0E-03	118.0E-03	122.0E-03	120.0E-03	120.0E-03	129.0E-03
SN5	118.0E-03	117.0E-03	118.0E-03	118.0E-03	119.0E-03		118.0E-03	121.0E-03	128.0E-03
SN6	118.0E-03	118.0E-03	119.0E-03	120.0E-03	120.0E-03	121.0E-03	120.0E-03	123.0E-03	130.0E-03
Statistics									
Min	117.0E-03	117.0E-03	116.0E-03	117.0E-03	116.0E-03	121.0E-03	118.0E-03	120.0E-03	128.0E-03
Max	118.0E-03	118.0E-03	119.0E-03	120.0E-03	120.0E-03	122.0E-03	123.0E-03	124.0E-03	130.0E-03
Average	117.8E-03	117.6E-03	118.2E-03	118.2E-03	118.6E-03	121.5E-03	119.8E-03	121.6E-03	128.8E-03
Sigma	400.0E-06	489.9E-06	1.2E-03	979.8E-06	1.5E-03	500.0E-06	1.8E-03	1.6E-03	748.3E-06

Drift Calculation

VOLD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-1.0E-03	1000.0E-06	-1.0E-03		1000.0E-06	3.0E-03	11.0E-03
SN3	-	0.0E+00	1.0E-03	0.0E+00	2.0E-03		5.0E-03	6.0E-03	11.0E-03
SN4	-	0.0E+00	1.0E-03	-1000.0E-06	0.0E+00	4.0E-03	2.0E-03	2.0E-03	11.0E-03
SN5	-	-1000.0E-06	0.0E+00	0.0E+00	1.0E-03		0.0E+00	3.0E-03	10.0E-03
SN6	-	0.0E+00	1.0E-03	2.0E-03	2.0E-03	3.0E-03	2.0E-03	5.0E-03	12.0E-03
Average	-	-200.0E-06	400.0E-06	400.0E-06	800.0E-06	3.5E-03	2.0E-03	3.8E-03	11.0E-03
Sigma	-	400.0E-06	800.0E-06	1.0E-03	1.2E-03	500.0E-06	1.7E-03	1.5E-03	632.5E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOLD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	116.0E-03	115.0E-03	117.0E-03	116.0E-03	116.0E-03	116.0E-03	115.0E-03	115.0E-03	116.0E-03
<b>OFF samples</b>									
SN7	118.0E-03	118.0E-03	118.0E-03	118.0E-03	117.0E-03	118.0E-03	116.0E-03	118.0E-03	126.0E-03
SN8	117.0E-03	116.0E-03	118.0E-03	114.0E-03	116.0E-03	118.0E-03	114.0E-03	117.0E-03	123.0E-03
SN9	119.0E-03	117.0E-03	118.0E-03	116.0E-03	118.0E-03	118.0E-03	116.0E-03	118.0E-03	126.0E-03
SN10	119.0E-03	117.0E-03	118.0E-03	115.0E-03	117.0E-03	117.0E-03	117.0E-03	119.0E-03	126.0E-03
SN11	120.0E-03	119.0E-03	118.0E-03	118.0E-03	119.0E-03	119.0E-03	116.0E-03	122.0E-03	126.0E-03
<b>Statistics</b>									
Min	117.0E-03	116.0E-03	118.0E-03	114.0E-03	116.0E-03	117.0E-03	114.0E-03	117.0E-03	123.0E-03
Max	120.0E-03	119.0E-03	118.0E-03	118.0E-03	119.0E-03	119.0E-03	117.0E-03	122.0E-03	126.0E-03
Average	118.6E-03	117.4E-03	118.0E-03	116.2E-03	117.4E-03	118.0E-03	115.8E-03	118.8E-03	125.4E-03
Sigma	1.0E-03	1.0E-03	1.2E-09	1.6E-03	1.0E-03	632.5E-06	979.8E-06	1.7E-03	1.2E-03

**Drift Calculation**

VOLD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	0.0E+00	0.0E+00	-1000.0E-06	0.0E+00	-2.0E-03	0.0E+00	8.0E-03
SN8	-	-1.0E-03	1000.0E-06	-3.0E-03	-1.0E-03	1000.0E-06	-3.0E-03	0.0E+00	6.0E-03
SN9	-	-2.0E-03	-1.0E-03	-3.0E-03	-1.0E-03	-1.0E-03	-3.0E-03	-1.0E-03	7.0E-03
SN10	-	-2.0E-03	-1.0E-03	-4.0E-03	-2.0E-03	-2.0E-03	-2.0E-03	0.0E+00	7.0E-03
SN11	-	-1.0E-03	-2.0E-03	-2.0E-03	-1.0E-03	-1.0E-03	-4.0E-03	2.0E-03	6.0E-03
Average	-	-1.2E-03	-600.0E-06	-2.4E-03	-1.2E-03	-600.0E-06	-2.8E-03	200.0E-06	6.8E-03
Sigma	-	748.3E-06	1.0E-03	1.4E-03	400.0E-06	1.0E-03	748.3E-06	979.8E-06	748.3E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

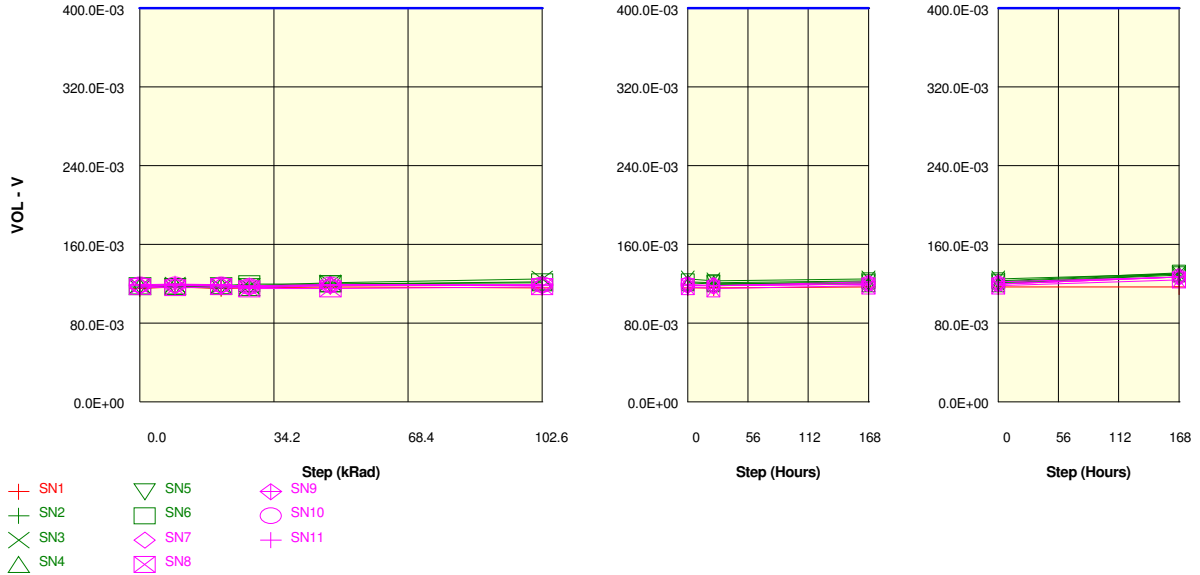
Parameter : logic output low voltage : VOLD2

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	115.0E-03	117.0E-03	115.0E-03	116.0E-03	117.0E-03	116.0E-03	116.0E-03	117.0E-03	117.0E-03
ON samples									
SN2	117.0E-03	117.0E-03	116.0E-03	118.0E-03	118.0E-03		120.0E-03	122.0E-03	130.0E-03
SN3	118.0E-03	119.0E-03	118.0E-03	118.0E-03	121.0E-03	125.0E-03	123.0E-03	125.0E-03	130.0E-03
SN4	117.0E-03	118.0E-03	118.0E-03	116.0E-03	120.0E-03	121.0E-03	120.0E-03	120.0E-03	130.0E-03
SN5	118.0E-03	117.0E-03	118.0E-03	117.0E-03	120.0E-03		120.0E-03	121.0E-03	129.0E-03
SN6	118.0E-03	117.0E-03	118.0E-03	120.0E-03	120.0E-03	122.0E-03	121.0E-03	123.0E-03	131.0E-03
Statistics									
Min	117.0E-03	117.0E-03	116.0E-03	116.0E-03	118.0E-03	121.0E-03	120.0E-03	120.0E-03	129.0E-03
Max	118.0E-03	119.0E-03	118.0E-03	120.0E-03	121.0E-03	125.0E-03	123.0E-03	125.0E-03	131.0E-03
Average	117.6E-03	117.6E-03	117.6E-03	117.8E-03	119.8E-03	122.7E-03	120.8E-03	122.2E-03	130.0E-03
Sigma	489.9E-06	800.0E-06	800.0E-06	1.3E-03	979.8E-06	1.7E-03	1.2E-03	1.7E-03	632.5E-06

Drift Calculation

VOLD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-1.0E-03	1000.0E-06	1000.0E-06		3.0E-03	5.0E-03	13.0E-03
SN3	-	1.0E-03	0.0E+00	0.0E+00	3.0E-03	7.0E-03	5.0E-03	7.0E-03	12.0E-03
SN4	-	1000.0E-06	1000.0E-06	-1.0E-03	3.0E-03	4.0E-03	3.0E-03	3.0E-03	13.0E-03
SN5	-	-1000.0E-06	0.0E+00	-1000.0E-06	2.0E-03		2.0E-03	3.0E-03	11.0E-03
SN6	-	-1000.0E-06	0.0E+00	2.0E-03	2.0E-03	4.0E-03	3.0E-03	5.0E-03	13.0E-03
Average	-	2.8E-18	-2.8E-18	200.0E-06	2.2E-03	5.0E-03	3.2E-03	4.6E-03	12.4E-03
Sigma	-	894.4E-06	632.5E-06	1.2E-03	748.3E-06	1.4E-03	979.8E-06	1.5E-03	800.0E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

VOLD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	115.0E-03	117.0E-03	115.0E-03	116.0E-03	117.0E-03	116.0E-03	116.0E-03	117.0E-03	117.0E-03
OFF samples									
SN7	117.0E-03	118.0E-03	118.0E-03	118.0E-03	119.0E-03	118.0E-03	118.0E-03	120.0E-03	127.0E-03
SN8	117.0E-03	116.0E-03	117.0E-03	115.0E-03	115.0E-03	117.0E-03	115.0E-03	118.0E-03	124.0E-03
SN9	118.0E-03	118.0E-03	118.0E-03	116.0E-03	118.0E-03	119.0E-03	118.0E-03	120.0E-03	127.0E-03
SN10	119.0E-03	119.0E-03	119.0E-03	117.0E-03	119.0E-03	119.0E-03	118.0E-03	120.0E-03	127.0E-03
SN11	119.0E-03	120.0E-03	119.0E-03	117.0E-03	119.0E-03	118.0E-03	118.0E-03	122.0E-03	127.0E-03
Statistics									
Min	117.0E-03	116.0E-03	117.0E-03	115.0E-03	115.0E-03	117.0E-03	115.0E-03	118.0E-03	124.0E-03
Max	119.0E-03	120.0E-03	119.0E-03	118.0E-03	119.0E-03	119.0E-03	118.0E-03	122.0E-03	127.0E-03
Average	118.0E-03	118.2E-03	118.2E-03	116.6E-03	118.0E-03	118.2E-03	117.4E-03	120.0E-03	126.4E-03
Sigma	894.4E-06	1.3E-03	748.3E-06	1.0E-03	1.5E-03	748.3E-06	1.2E-03	1.3E-03	1.2E-03

**Drift Calculation**

VOLD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	1000.0E-06	1000.0E-06	1000.0E-06	2.0E-03	1000.0E-06	1000.0E-06	3.0E-03	10.0E-03
SN8	-	-1.0E-03	0.0E+00	-2.0E-03	-2.0E-03	0.0E+00	-2.0E-03	1000.0E-06	7.0E-03
SN9	-	0.0E+00	0.0E+00	-2.0E-03	0.0E+00	1.0E-03	0.0E+00	2.0E-03	9.0E-03
SN10	-	0.0E+00	0.0E+00	-2.0E-03	0.0E+00	0.0E+00	-1.0E-03	1.0E-03	8.0E-03
SN11	-	1.0E-03	0.0E+00	-2.0E-03	0.0E+00	-1.0E-03	-1.0E-03	3.0E-03	8.0E-03
Average	-	200.0E-06	200.0E-06	-1.4E-03	-2.8E-18	200.0E-06	-600.0E-06	2.0E-03	8.4E-03
Sigma	-	748.3E-06	400.0E-06	1.2E-03	1.3E-03	748.3E-06	1.0E-03	894.4E-06	1.0E-03



Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

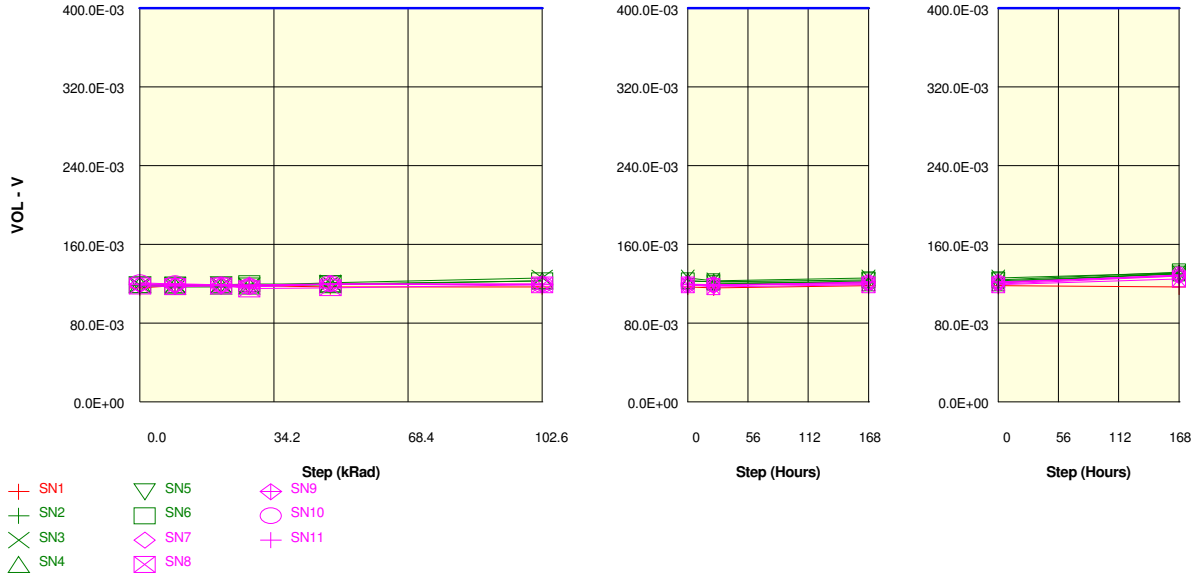
Parameter : logic output low voltage : VOLD1

Test conditions : IOL=1.6mA

Unit : V

Spec Limit Max : 400.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

VOLD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	116.0E-03	118.0E-03	118.0E-03	118.0E-03	117.0E-03	117.0E-03	116.0E-03	118.0E-03	117.0E-03
ON samples									
SN2	118.0E-03	117.0E-03	117.0E-03	119.0E-03	119.0E-03		120.0E-03	122.0E-03	130.0E-03
SN3	119.0E-03	119.0E-03	119.0E-03	118.0E-03	121.0E-03	126.0E-03	123.0E-03	126.0E-03	131.0E-03
SN4	119.0E-03	118.0E-03	118.0E-03	118.0E-03	119.0E-03	123.0E-03	122.0E-03	121.0E-03	131.0E-03
SN5	119.0E-03	118.0E-03	119.0E-03	118.0E-03	120.0E-03		120.0E-03	123.0E-03	130.0E-03
SN6	119.0E-03	119.0E-03	119.0E-03	120.0E-03	120.0E-03	123.0E-03	122.0E-03	124.0E-03	132.0E-03
Statistics									
Min	118.0E-03	117.0E-03	117.0E-03	118.0E-03	119.0E-03	123.0E-03	120.0E-03	121.0E-03	130.0E-03
Max	119.0E-03	119.0E-03	119.0E-03	120.0E-03	121.0E-03	126.0E-03	123.0E-03	126.0E-03	132.0E-03
Average	118.8E-03	118.2E-03	118.4E-03	118.6E-03	119.8E-03	124.0E-03	121.4E-03	123.2E-03	130.8E-03
Sigma	400.0E-06	748.3E-06	800.0E-06	800.0E-06	748.3E-06	1.4E-03	1.2E-03	1.7E-03	748.3E-06

Drift Calculation

VOLD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-1000.0E-06	-1000.0E-06	1.0E-03	1.0E-03		2.0E-03	4.0E-03	12.0E-03
SN3	-	0.0E+00	0.0E+00	-1.0E-03	2.0E-03	7.0E-03	4.0E-03	7.0E-03	12.0E-03
SN4	-	-1.0E-03	-1.0E-03	-1.0E-03	0.0E+00	4.0E-03	3.0E-03	2.0E-03	12.0E-03
SN5	-	-1.0E-03	0.0E+00	-1.0E-03	1.0E-03		1.0E-03	4.0E-03	11.0E-03
SN6	-	0.0E+00	0.0E+00	1.0E-03	1.0E-03	4.0E-03	3.0E-03	5.0E-03	13.0E-03
Average	-	-600.0E-06	-400.0E-06	-200.0E-06	1.0E-03	5.0E-03	2.6E-03	4.4E-03	12.0E-03
Sigma	-	489.9E-06	489.9E-06	979.8E-06	632.5E-06	1.4E-03	1.0E-03	1.6E-03	632.5E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

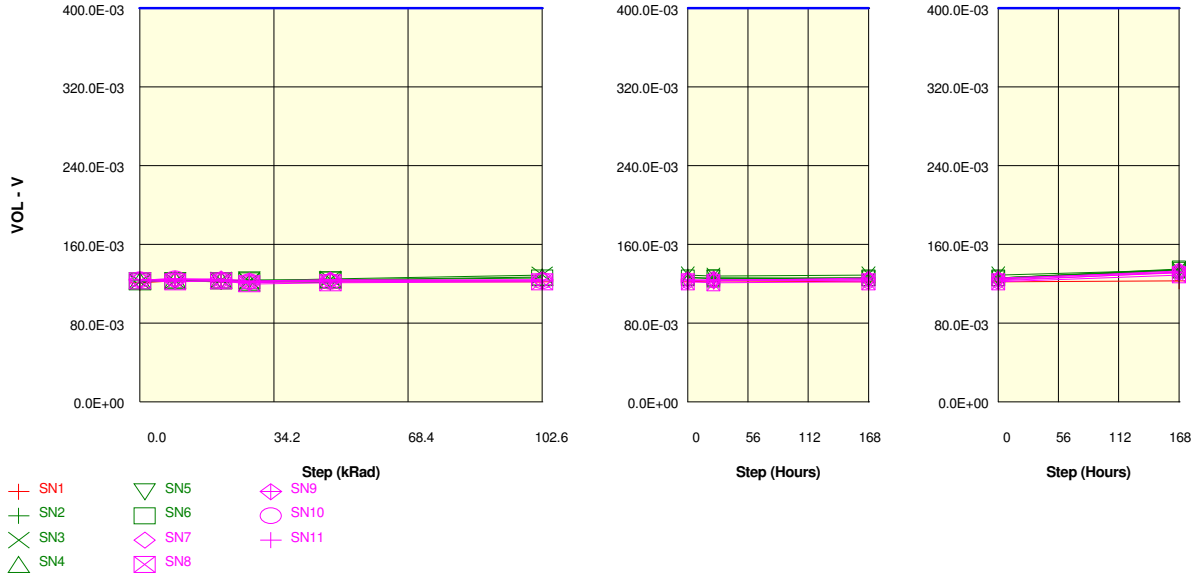
**Measurements**

VOLD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	116.0E-03	118.0E-03	118.0E-03	118.0E-03	117.0E-03	117.0E-03	116.0E-03	118.0E-03	117.0E-03
<b>OFF samples</b>									
SN7	119.0E-03	119.0E-03	119.0E-03	119.0E-03	120.0E-03	120.0E-03	119.0E-03	120.0E-03	128.0E-03
SN8	118.0E-03	117.0E-03	118.0E-03	115.0E-03	116.0E-03	119.0E-03	117.0E-03	119.0E-03	125.0E-03
SN9	119.0E-03	118.0E-03	118.0E-03	117.0E-03	120.0E-03	119.0E-03	118.0E-03	121.0E-03	129.0E-03
SN10	121.0E-03	120.0E-03	119.0E-03	117.0E-03	120.0E-03	119.0E-03	119.0E-03	121.0E-03	129.0E-03
SN11	120.0E-03	120.0E-03	119.0E-03	118.0E-03	120.0E-03	120.0E-03	118.0E-03	122.0E-03	128.0E-03
<b>Statistics</b>									
Min	118.0E-03	117.0E-03	118.0E-03	115.0E-03	116.0E-03	119.0E-03	117.0E-03	119.0E-03	125.0E-03
Max	121.0E-03	120.0E-03	119.0E-03	119.0E-03	120.0E-03	120.0E-03	119.0E-03	122.0E-03	129.0E-03
Average	119.4E-03	118.8E-03	118.6E-03	117.2E-03	119.2E-03	119.4E-03	118.2E-03	120.6E-03	127.8E-03
Sigma	1.0E-03	1.2E-03	489.9E-06	1.3E-03	1.6E-03	489.9E-06	748.3E-06	1.0E-03	1.5E-03

**Drift Calculation**

VOLD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	0.0E+00	0.0E+00	1.0E-03	1.0E-03	0.0E+00	1.0E-03	9.0E-03
SN8	-	-1000.0E-06	0.0E+00	-3.0E-03	-2.0E-03	1.0E-03	-1000.0E-06	1.0E-03	7.0E-03
SN9	-	-1.0E-03	-1.0E-03	-2.0E-03	1.0E-03	0.0E+00	-1.0E-03	2.0E-03	10.0E-03
SN10	-	-1.0E-03	-2.0E-03	-4.0E-03	-1.0E-03	-2.0E-03	-2.0E-03	0.0E+00	8.0E-03
SN11	-	0.0E+00	-1.0E-03	-2.0E-03	0.0E+00	0.0E+00	-2.0E-03	2.0E-03	8.0E-03
Average	-	-600.0E-06	-800.0E-06	-2.2E-03	-200.0E-06	0.0E+00	-1.2E-03	1.2E-03	8.4E-03
Sigma	-	489.9E-06	748.3E-06	1.3E-03	1.2E-03	1.1E-03	748.3E-06	748.3E-06	1.0E-03

Parameter : logic output low voltage : VOLD0  
 Test conditions : IOL=1.6mA  
 Unit : V  
 Spec Limit Max : 400.0E-03  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

VOLD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	121.0E-03	123.0E-03	122.0E-03	122.0E-03	122.0E-03	122.0E-03	123.0E-03	122.0E-03	123.0E-03
ON samples									
SN2	123.0E-03	123.0E-03	122.0E-03	123.0E-03	121.0E-03		125.0E-03	126.0E-03	134.0E-03
SN3	122.0E-03	123.0E-03	124.0E-03	123.0E-03	125.0E-03	129.0E-03	128.0E-03	129.0E-03	134.0E-03
SN4	123.0E-03	124.0E-03	124.0E-03	121.0E-03	124.0E-03	127.0E-03	125.0E-03	126.0E-03	134.0E-03
SN5	123.0E-03	123.0E-03	123.0E-03	124.0E-03	124.0E-03		126.0E-03	125.0E-03	134.0E-03
SN6	122.0E-03	123.0E-03	123.0E-03	123.0E-03	124.0E-03	126.0E-03	126.0E-03	126.0E-03	135.0E-03
Statistics									
Min	122.0E-03	123.0E-03	122.0E-03	121.0E-03	121.0E-03	126.0E-03	125.0E-03	125.0E-03	134.0E-03
Max	123.0E-03	124.0E-03	124.0E-03	124.0E-03	125.0E-03	129.0E-03	128.0E-03	129.0E-03	135.0E-03
Average	122.6E-03	123.2E-03	123.2E-03	122.8E-03	123.6E-03	127.3E-03	126.0E-03	126.4E-03	134.2E-03
Sigma	489.9E-06	400.0E-06	748.3E-06	979.8E-06	1.4E-03	1.2E-03	1.1E-03	1.4E-03	400.0E-06

**Drift Calculation**

VOLD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-1.0E-03	0.0E+00	-2.0E-03		2.0E-03	3.0E-03	11.0E-03
SN3	-	1.0E-03	2.0E-03	1.0E-03	3.0E-03	7.0E-03	6.0E-03	7.0E-03	12.0E-03
SN4	-	1.0E-03	1.0E-03	-2.0E-03	1.0E-03	4.0E-03	2.0E-03	3.0E-03	11.0E-03
SN5	-	0.0E+00	0.0E+00	1.0E-03	1.0E-03		3.0E-03	2.0E-03	11.0E-03
SN6	-	1.0E-03	1.0E-03	1.0E-03	2.0E-03	4.0E-03	4.0E-03	4.0E-03	13.0E-03
Average	-	600.0E-06	600.0E-06	200.0E-06	1.0E-03	5.0E-03	3.4E-03	3.8E-03	11.6E-03
Sigma	-	489.9E-06	1.0E-03	1.2E-03	1.7E-03	1.4E-03	1.5E-03	1.7E-03	800.0E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

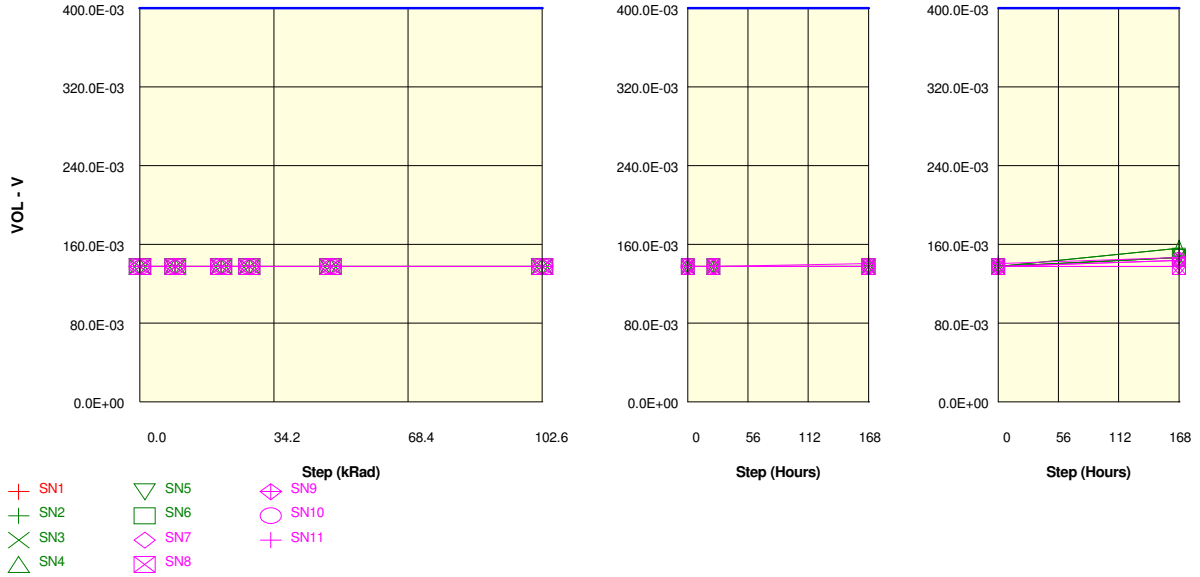
**Measurements**

VOLD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	121.0E-03	123.0E-03	122.0E-03	122.0E-03	122.0E-03	122.0E-03	123.0E-03	122.0E-03	123.0E-03
OFF samples									
SN7	124.0E-03	125.0E-03	125.0E-03	123.0E-03	124.0E-03	124.0E-03	124.0E-03	125.0E-03	133.0E-03
SN8	123.0E-03	122.0E-03	123.0E-03	120.0E-03	121.0E-03	122.0E-03	121.0E-03	122.0E-03	129.0E-03
SN9	124.0E-03	123.0E-03	123.0E-03	121.0E-03	123.0E-03	124.0E-03	123.0E-03	124.0E-03	131.0E-03
SN10	124.0E-03	125.0E-03	123.0E-03	122.0E-03	122.0E-03	123.0E-03	124.0E-03	123.0E-03	132.0E-03
SN11	124.0E-03	125.0E-03	124.0E-03	122.0E-03	124.0E-03	123.0E-03	123.0E-03	126.0E-03	132.0E-03
Statistics									
Min	123.0E-03	122.0E-03	123.0E-03	120.0E-03	121.0E-03	122.0E-03	121.0E-03	122.0E-03	129.0E-03
Max	124.0E-03	125.0E-03	125.0E-03	123.0E-03	124.0E-03	124.0E-03	124.0E-03	126.0E-03	133.0E-03
Average	123.8E-03	124.0E-03	123.6E-03	121.6E-03	122.8E-03	123.2E-03	123.0E-03	124.0E-03	131.4E-03
Sigma	400.0E-06	1.3E-03	800.0E-06	1.0E-03	1.2E-03	748.3E-06	1.1E-03	1.4E-03	1.4E-03

**Drift Calculation**

VOLD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	1.0E-03	1.0E-03	-1.0E-03	0.0E+00	0.0E+00	0.0E+00	1.0E-03	9.0E-03
SN8	-	-1.0E-03	0.0E+00	-3.0E-03	-2.0E-03	-1.0E-03	-2.0E-03	-1.0E-03	6.0E-03
SN9	-	-1.0E-03	-1.0E-03	-3.0E-03	-1.0E-03	0.0E+00	-1.0E-03	0.0E+00	7.0E-03
SN10	-	1.0E-03	-1.0E-03	-2.0E-03	-2.0E-03	-1.0E-03	0.0E+00	-1.0E-03	8.0E-03
SN11	-	1.0E-03	0.0E+00	-2.0E-03	0.0E+00	-1.0E-03	-1.0E-03	2.0E-03	8.0E-03
Average	-	200.0E-06	-200.0E-06	-2.2E-03	-1.0E-03	-600.0E-06	-800.0E-06	200.0E-06	7.6E-03
Sigma	-	979.8E-06	748.3E-06	748.3E-06	894.4E-06	489.9E-06	748.3E-06	1.2E-03	1.0E-03

Parameter : logic output low voltage : VOLBUSY  
 Test conditions : IOL=1.6mA  
 Unit : V  
 Spec Limit Max : 400.0E-03  
 Spec limits are represented in bold lines on the graphic.



Measurements

VOLBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03
ON samples									
SN2	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	156.3E-03
SN3	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	146.9E-03
SN4	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	156.3E-03
SN5	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	146.9E-03
SN6	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	146.9E-03
Statistics									
Min	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	146.9E-03
Max	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	156.3E-03
Average	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	150.6E-03
Sigma	833.0E-12	833.0E-12	833.0E-12	833.0E-12	833.0E-12	833.0E-12	833.0E-12	833.0E-12	4.6E-03

Drift Calculation

VOLBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	18.8E-03
SN3	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	9.4E-03
SN4	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	18.8E-03
SN5	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	9.4E-03
SN6	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	9.4E-03
Average	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	13.1E-03
Sigma	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	4.6E-03

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**Measurements**

VOLBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03
<b>OFF samples</b>									
SN7	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	143.8E-03
SN8	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03
SN9	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03
SN10	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	143.8E-03
SN11	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	140.6E-03	146.9E-03
<b>Statistics</b>									
Min	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03
Max	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	140.6E-03	146.9E-03
Average	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	137.5E-03	138.1E-03	141.9E-03
Sigma	833.0E-12	833.0E-12	833.0E-12	833.0E-12	833.0E-12	833.0E-12	833.0E-12	1.2E-03	3.8E-03

**Drift Calculation**

VOLBUSY	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	6.2E-03
SN8	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00
SN9	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00
SN10	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	6.2E-03
SN11	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	3.1E-03	9.4E-03
Average	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	624.0E-06	4.4E-03
Sigma	-	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	0.0E+00	1.2E-03	3.8E-03

Parameter : Three state output leakage : IOLTL-D15

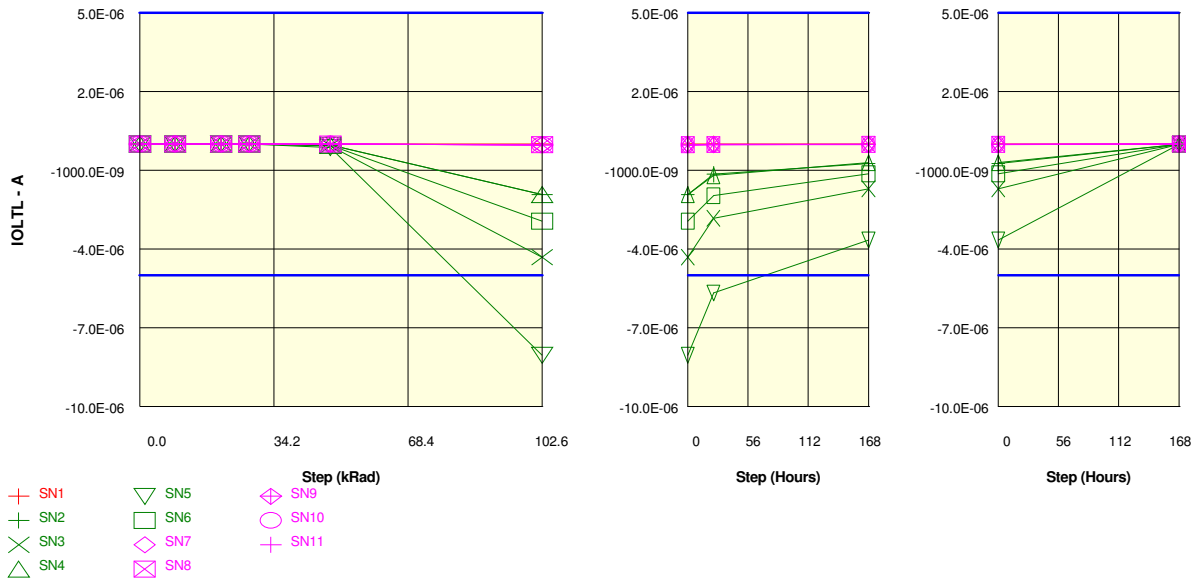
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTL-D15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-100.0E-12	-100.0E-12	-50.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-150.0E-12
ON samples									
SN2	-150.0E-12	-150.0E-12	-150.0E-12	-450.0E-12	-35.4E-09	-1.9E-06	-1.2E-06	-736.5E-09	-2.5E-09
SN3	-150.0E-12	-150.0E-12	-150.0E-12	-550.0E-12	-69.0E-09	-4.3E-06	-2.8E-06	-1.7E-06	-3.9E-09
SN4	-150.0E-12	-150.0E-12	-100.0E-12	-400.0E-12	-33.7E-09	-1.9E-06	-1.2E-06	-712.0E-09	-2.7E-09
SN5	-100.0E-12	-150.0E-12	-150.0E-12	-600.0E-12	-133.0E-09	-8.0E-06	-5.7E-06	-3.7E-06	-5.8E-09
SN6	-100.0E-12	-100.0E-12	-150.0E-12	-500.0E-12	-46.8E-09	-2.9E-06	-2.0E-06	-1.1E-06	-3.7E-09
Statistics									
Min	-150.0E-12	-150.0E-12	-150.0E-12	-600.0E-12	-133.0E-09	-8.0E-06	-5.7E-06	-3.7E-06	-5.8E-09
Max	-100.0E-12	-100.0E-12	-100.0E-12	-400.0E-12	-33.7E-09	-1.9E-06	-1.2E-06	-712.0E-09	-2.5E-09
Average	-130.0E-12	-140.0E-12	-140.0E-12	-500.0E-12	-63.6E-09	-3.8E-06	-2.6E-06	-1.6E-06	-3.7E-09
Sigma	24.5E-12	20.0E-12	20.0E-12	70.7E-12	36.9E-09	2.3E-06	1.7E-06	1.1E-06	1.2E-09

Drift Calculation

IOLTL-D15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	-300.0E-12	-35.2E-09	-1.9E-06	-1.1E-06	-736.4E-09	-2.4E-09
SN3	-	0.0E+00	0.0E+00	-400.0E-12	-68.8E-09	-4.3E-06	-2.8E-06	-1.7E-06	-3.8E-09
SN4	-	0.0E+00	50.0E-12	-250.0E-12	-33.6E-09	-1.9E-06	-1.2E-06	-711.9E-09	-2.6E-09
SN5	-	-50.0E-12	-50.0E-12	-500.0E-12	-132.9E-09	-8.0E-06	-5.7E-06	-3.7E-06	-5.7E-09
SN6	-	0.0E+00	-50.0E-12	-400.0E-12	-46.7E-09	-2.9E-06	-2.0E-06	-1.1E-06	-3.6E-09
Average	-	-10.0E-12	-10.0E-12	-370.0E-12	-63.4E-09	-3.8E-06	-2.6E-06	-1.6E-06	-3.6E-09
Sigma	-	20.0E-12	37.4E-12	87.2E-12	36.9E-09	2.3E-06	1.7E-06	1.1E-06	1.2E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT				Ref.:	HRX/TID/1197
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**Measurements**

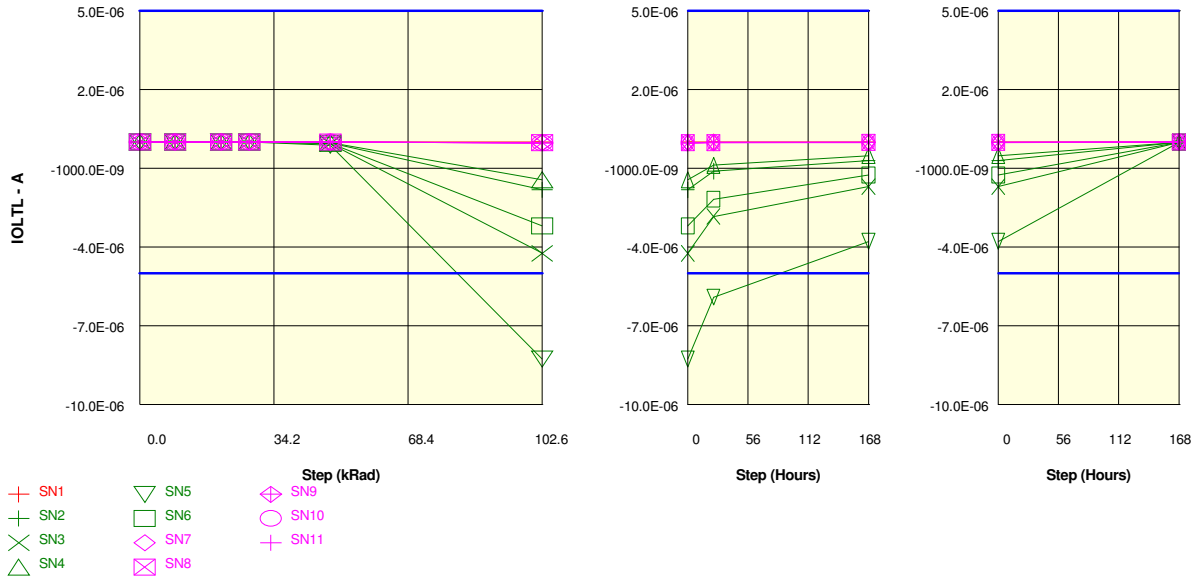
IOLTLTD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-100.0E-12	-100.0E-12	-50.0E-12	-100.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-150.0E-12
<b>OFF samples</b>									
SN7	-50.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-1.3E-09	-28.0E-09	-22.8E-09	-16.3E-09	-1.3E-09
SN8	-50.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-850.0E-12	-20.3E-09	-14.6E-09	-11.7E-09	-1.4E-09
SN9	-100.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-1.1E-09	-29.0E-09	-18.2E-09	-14.7E-09	-1.1E-09
SN10	-150.0E-12	-100.0E-12	-150.0E-12	-150.0E-12	-1.4E-09	-33.3E-09	-20.6E-09	-19.1E-09	-1.2E-09
SN11	-150.0E-12	-100.0E-12	-100.0E-12	-200.0E-12	-1.1E-09	-27.5E-09	-16.4E-09	-15.2E-09	-1.6E-09
<b>Statistics</b>									
Min	-150.0E-12	-100.0E-12	-150.0E-12	-200.0E-12	-1.4E-09	-33.3E-09	-22.8E-09	-19.1E-09	-1.6E-09
Max	-50.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	-850.0E-12	-20.3E-09	-14.6E-09	-11.7E-09	-1.1E-09
Average	-100.0E-12	-100.0E-12	-120.0E-12	-150.0E-12	-1.1E-09	-27.6E-09	-18.5E-09	-15.4E-09	-1.3E-09
Sigma	44.7E-12	0.0E+00	24.5E-12	31.6E-12	174.4E-12	4.2E-09	2.9E-09	2.4E-09	160.0E-12

**Drift Calculation**

IOLTLTD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-50.0E-12	-50.0E-12	-50.0E-12	-1.2E-09	-28.0E-09	-22.8E-09	-16.2E-09	-1.2E-09
SN8	-	-50.0E-12	-100.0E-12	-100.0E-12	-800.0E-12	-20.2E-09	-14.6E-09	-11.6E-09	-1.3E-09
SN9	-	0.0E+00	0.0E+00	-50.0E-12	-950.0E-12	-28.9E-09	-18.1E-09	-14.6E-09	-1.0E-09
SN10	-	50.0E-12	0.0E+00	0.0E+00	-1.2E-09	-33.2E-09	-20.5E-09	-19.0E-09	-1.0E-09
SN11	-	50.0E-12	50.0E-12	-50.0E-12	-900.0E-12	-27.3E-09	-16.3E-09	-15.1E-09	-1.4E-09
Average	-	-2.6E-27	-20.0E-12	-50.0E-12	-1.0E-09	-27.5E-09	-18.4E-09	-15.3E-09	-1.2E-09
Sigma	-	44.7E-12	51.0E-12	31.6E-12	162.5E-12	4.2E-09	2.9E-09	2.4E-09	160.0E-12



Parameter : Three state output leakage : IOLTLD14  
 Test conditions :  
 Unit : A  
 Spec Limit Min : -5.0E-06  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-150.0E-12	-200.0E-12	-150.0E-12	-150.0E-12	-100.0E-12	-250.0E-12	-100.0E-12	-200.0E-12	-100.0E-12
ON samples									
SN2	-150.0E-12	-100.0E-12	-150.0E-12	-450.0E-12	-30.1E-09	-1.8E-06	-1.1E-06	-711.0E-09	-2.8E-09
SN3	-150.0E-12	-100.0E-12	-150.0E-12	-450.0E-12	-59.0E-09	-4.2E-06	-2.8E-06	-1.7E-06	-4.2E-09
SN4	-100.0E-12	-100.0E-12	-150.0E-12	-350.0E-12	-25.1E-09	-1.4E-06	-885.0E-09	-518.5E-09	-2.6E-09
SN5	-150.0E-12	-150.0E-12	-200.0E-12	-450.0E-12	-121.5E-09	-8.3E-06	-5.9E-06	-3.8E-06	-5.8E-09
SN6	-100.0E-12	-100.0E-12	-100.0E-12	-450.0E-12	-48.1E-09	-3.2E-06	-2.2E-06	-1.3E-06	-3.9E-09
Statistics									
Min	-150.0E-12	-150.0E-12	-200.0E-12	-450.0E-12	-121.5E-09	-8.3E-06	-5.9E-06	-3.8E-06	-5.8E-09
Max	-100.0E-12	-100.0E-12	-100.0E-12	-350.0E-12	-25.1E-09	-1.4E-06	-885.0E-09	-518.5E-09	-2.6E-09
Average	-130.0E-12	-110.0E-12	-150.0E-12	-430.0E-12	-56.8E-09	-3.8E-06	-2.6E-06	-1.6E-06	-3.9E-09
Sigma	24.5E-12	20.0E-12	31.6E-12	40.0E-12	34.6E-09	2.4E-06	1.8E-06	1.2E-06	1.1E-09

Drift Calculation

IOLTLD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	50.0E-12	0.0E+00	-300.0E-12	-30.0E-09	-1.8E-06	-1.1E-06	-710.9E-09	-2.7E-09
SN3	-	50.0E-12	0.0E+00	-300.0E-12	-58.9E-09	-4.2E-06	-2.8E-06	-1.7E-06	-4.1E-09
SN4	-	0.0E+00	-50.0E-12	-250.0E-12	-25.0E-09	-1.4E-06	-884.9E-09	-518.4E-09	-2.5E-09
SN5	-	0.0E+00	-50.0E-12	-300.0E-12	-121.4E-09	-8.3E-06	-5.9E-06	-3.8E-06	-5.7E-09
SN6	-	0.0E+00	0.0E+00	-350.0E-12	-48.0E-09	-3.2E-06	-2.2E-06	-1.3E-06	-3.8E-09
Average	-	20.0E-12	-20.0E-12	-300.0E-12	-56.6E-09	-3.8E-06	-2.6E-06	-1.6E-06	-3.7E-09
Sigma	-	24.5E-12	24.5E-12	31.6E-12	34.6E-09	2.4E-06	1.8E-06	1.2E-06	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTLID14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-150.0E-12	-200.0E-12	-150.0E-12	-150.0E-12	-100.0E-12	-250.0E-12	-100.0E-12	-200.0E-12	-100.0E-12
<b>OFF samples</b>									
SN7	-100.0E-12	-200.0E-12	-200.0E-12	-150.0E-12	-1.3E-09	-27.5E-09	-22.2E-09	-15.8E-09	-1.2E-09
SN8	-100.0E-12	-150.0E-12	-100.0E-12	-200.0E-12	-900.0E-12	-20.9E-09	-15.1E-09	-12.2E-09	-1.3E-09
SN9	-150.0E-12	-150.0E-12	-150.0E-12	-150.0E-12	-1.1E-09	-27.0E-09	-16.9E-09	-14.0E-09	-1.2E-09
SN10	-100.0E-12	-150.0E-12	-150.0E-12	-200.0E-12	-1.4E-09	-33.9E-09	-20.9E-09	-19.8E-09	-1.2E-09
SN11	-100.0E-12	-150.0E-12	-200.0E-12	-250.0E-12	-1.1E-09	-27.3E-09	-16.2E-09	-14.9E-09	-1.5E-09
<b>Statistics</b>									
Min	-150.0E-12	-200.0E-12	-200.0E-12	-250.0E-12	-1.4E-09	-33.9E-09	-22.2E-09	-19.8E-09	-1.5E-09
Max	-100.0E-12	-150.0E-12	-100.0E-12	-150.0E-12	-900.0E-12	-20.9E-09	-15.1E-09	-12.2E-09	-1.2E-09
Average	-110.0E-12	-160.0E-12	-160.0E-12	-190.0E-12	-1.1E-09	-27.3E-09	-18.2E-09	-15.3E-09	-1.3E-09
Sigma	20.0E-12	20.0E-12	37.4E-12	37.4E-12	153.0E-12	4.1E-09	2.8E-09	2.5E-09	124.9E-12

**Drift Calculation**

IOLTLID14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-100.0E-12	-100.0E-12	-50.0E-12	-1.2E-09	-27.4E-09	-22.1E-09	-15.7E-09	-1.1E-09
SN8	-	-50.0E-12	0.0E+00	-100.0E-12	-800.0E-12	-20.8E-09	-15.0E-09	-12.1E-09	-1.2E-09
SN9	-	0.0E+00	0.0E+00	0.0E+00	-950.0E-12	-26.9E-09	-16.7E-09	-13.8E-09	-1.0E-09
SN10	-	-50.0E-12	-50.0E-12	-100.0E-12	-1.3E-09	-33.8E-09	-20.8E-09	-19.7E-09	-1.1E-09
SN11	-	-50.0E-12	-100.0E-12	-150.0E-12	-1.0E-09	-27.2E-09	-16.1E-09	-14.8E-09	-1.4E-09
Average	-	-50.0E-12	-50.0E-12	-80.0E-12	-1.0E-09	-27.2E-09	-18.1E-09	-15.2E-09	-1.2E-09
Sigma	-	31.6E-12	44.7E-12	51.0E-12	156.8E-12	4.1E-09	2.8E-09	2.5E-09	135.6E-12

Parameter : Three state output leakage : IOLTLD13

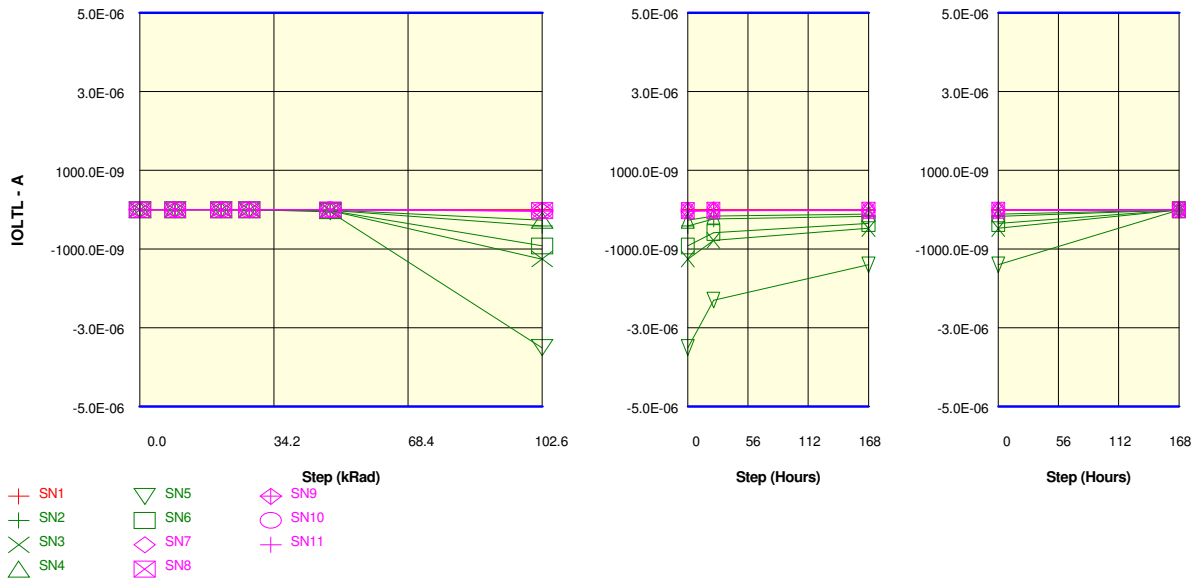
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-200.0E-12	-100.0E-12	-50.0E-12	-150.0E-12	-250.0E-12	-350.0E-12	-50.0E-12	-50.0E-12	-200.0E-12
ON samples									
SN2	-250.0E-12	-100.0E-12	-200.0E-12	-550.0E-12	-12.7E-09	-408.5E-09	-232.0E-09	-170.5E-09	-2.7E-09
SN3	-300.0E-12	-100.0E-12	-100.0E-12	-450.0E-12	-24.8E-09	-1.3E-06	-778.5E-09	-474.0E-09	-3.8E-09
SN4	-250.0E-12	-100.0E-12	-150.0E-12	-450.0E-12	-9.5E-09	-269.5E-09	-161.0E-09	-109.5E-09	-2.5E-09
SN5	-150.0E-12	-150.0E-12	-150.0E-12	-500.0E-12	-49.0E-09	-3.5E-06	-2.3E-06	-1.4E-06	-5.5E-09
SN6	-250.0E-12	-100.0E-12	-200.0E-12	-550.0E-12	-21.3E-09	-919.5E-09	-582.0E-09	-348.5E-09	-3.9E-09
Statistics									
Min	-300.0E-12	-150.0E-12	-200.0E-12	-550.0E-12	-49.0E-09	-3.5E-06	-2.3E-06	-1.4E-06	-5.5E-09
Max	-150.0E-12	-100.0E-12	-100.0E-12	-450.0E-12	-9.5E-09	-269.5E-09	-161.0E-09	-109.5E-09	-2.5E-09
Average	-240.0E-12	-110.0E-12	-160.0E-12	-500.0E-12	-23.4E-09	-1.3E-06	-809.7E-09	-500.5E-09	-3.7E-09
Sigma	49.0E-12	20.0E-12	37.4E-12	44.7E-12	13.9E-09	1.2E-06	776.3E-09	467.9E-09	1.1E-09

Drift Calculation

IOLTLD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	150.0E-12	50.0E-12	-300.0E-12	-12.4E-09	-408.3E-09	-231.8E-09	-170.3E-09	-2.5E-09
SN3	-	200.0E-12	200.0E-12	-150.0E-12	-24.5E-09	-1.3E-06	-778.2E-09	-473.7E-09	-3.5E-09
SN4	-	150.0E-12	100.0E-12	-200.0E-12	-9.3E-09	-269.3E-09	-160.8E-09	-109.3E-09	-2.2E-09
SN5	-	0.0E+00	0.0E+00	-350.0E-12	-48.9E-09	-3.5E-06	-2.3E-06	-1.4E-06	-5.3E-09
SN6	-	150.0E-12	50.0E-12	-300.0E-12	-21.1E-09	-919.3E-09	-581.8E-09	-348.3E-09	-3.6E-09
Average	-	130.0E-12	80.0E-12	-260.0E-12	-23.2E-09	-1.3E-06	-809.5E-09	-500.3E-09	-3.4E-09
Sigma	-	67.8E-12	67.8E-12	73.5E-12	14.0E-09	1.2E-06	776.4E-09	467.9E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTL13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-200.0E-12	-100.0E-12	-50.0E-12	-150.0E-12	-250.0E-12	-350.0E-12	-50.0E-12	-50.0E-12	-200.0E-12
<b>OFF samples</b>									
SN7	-250.0E-12	-100.0E-12	-150.0E-12	-250.0E-12	-1.5E-09	-25.5E-09	-20.5E-09	-14.8E-09	-1.3E-09
SN8	-250.0E-12	-100.0E-12	-100.0E-12	-250.0E-12	-950.0E-12	-20.7E-09	-14.7E-09	-11.9E-09	-1.4E-09
SN9	-250.0E-12	-200.0E-12	-150.0E-12	-200.0E-12	-1.4E-09	-28.1E-09	-17.8E-09	-14.6E-09	-1.2E-09
SN10	-250.0E-12	-100.0E-12	-100.0E-12	-250.0E-12	-1.5E-09	-33.4E-09	-20.7E-09	-19.6E-09	-1.3E-09
SN11	-200.0E-12	-100.0E-12	-150.0E-12	-200.0E-12	-1.2E-09	-28.7E-09	-17.4E-09	-15.8E-09	-1.7E-09
<b>Statistics</b>									
Min	-250.0E-12	-200.0E-12	-150.0E-12	-250.0E-12	-1.5E-09	-33.4E-09	-20.7E-09	-19.6E-09	-1.7E-09
Max	-200.0E-12	-100.0E-12	-100.0E-12	-200.0E-12	-950.0E-12	-20.7E-09	-14.7E-09	-11.9E-09	-1.2E-09
Average	-240.0E-12	-120.0E-12	-130.0E-12	-230.0E-12	-1.3E-09	-27.3E-09	-18.2E-09	-15.3E-09	-1.4E-09
Sigma	20.0E-12	40.0E-12	24.5E-12	24.5E-12	198.5E-12	4.2E-09	2.2E-09	2.5E-09	177.8E-12

**Drift Calculation**

IOLTL13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	150.0E-12	100.0E-12	0.0E+00	-1.2E-09	-25.3E-09	-20.2E-09	-14.5E-09	-1.1E-09
SN8	-	150.0E-12	150.0E-12	0.0E+00	-700.0E-12	-20.4E-09	-14.5E-09	-11.6E-09	-1.2E-09
SN9	-	50.0E-12	100.0E-12	50.0E-12	-1.1E-09	-27.9E-09	-17.5E-09	-14.4E-09	-950.0E-12
SN10	-	150.0E-12	150.0E-12	0.0E+00	-1.3E-09	-33.2E-09	-20.4E-09	-19.3E-09	-1.0E-09
SN11	-	100.0E-12	50.0E-12	0.0E+00	-1.0E-09	-28.5E-09	-17.2E-09	-15.6E-09	-1.5E-09
Average	-	120.0E-12	110.0E-12	10.0E-12	-1.1E-09	-27.0E-09	-17.9E-09	-15.1E-09	-1.1E-09
Sigma	-	40.0E-12	37.4E-12	20.0E-12	194.9E-12	4.2E-09	2.2E-09	2.5E-09	196.5E-12

Parameter : Three state output leakage : IOLTLD12

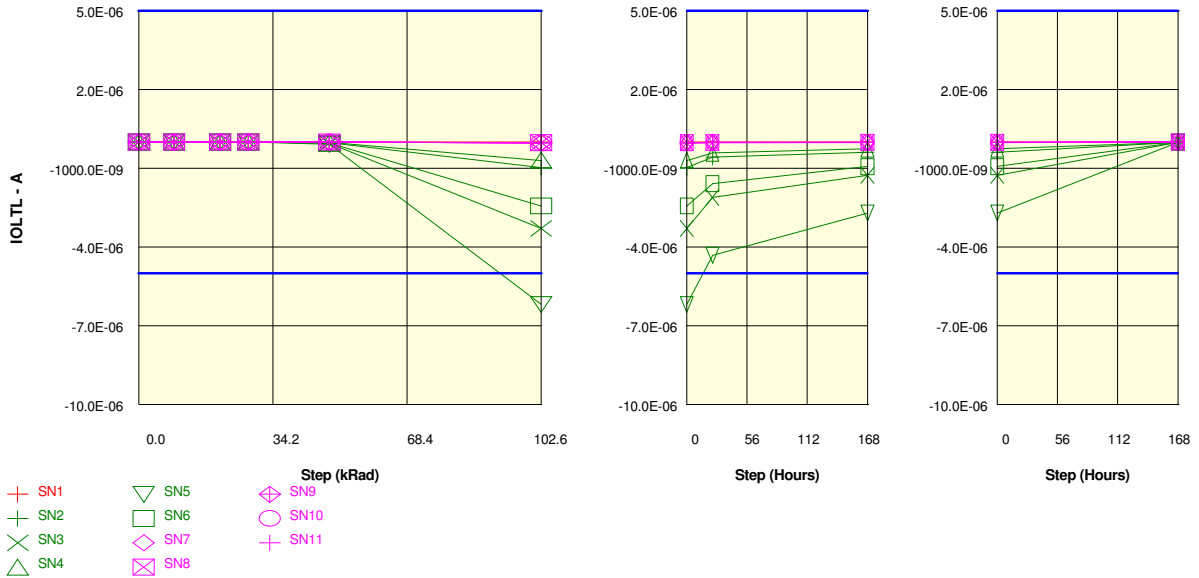
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-450.0E-12	-150.0E-12	-100.0E-12	-350.0E-12	-600.0E-12	-450.0E-12	-100.0E-12	-350.0E-12	-550.0E-12
ON samples									
SN2	-550.0E-12	-150.0E-12	-450.0E-12	-750.0E-12	-21.3E-09	-970.0E-09	-570.5E-09	-385.5E-09	-3.2E-09
SN3	-600.0E-12	-100.0E-12	-300.0E-12	-650.0E-12	-46.6E-09	-3.3E-06	-2.1E-06	-1.3E-06	-4.4E-09
SN4	-550.0E-12	-250.0E-12	-250.0E-12	-550.0E-12	-15.8E-09	-698.5E-09	-419.0E-09	-259.5E-09	-2.8E-09
SN5	-500.0E-12	-150.0E-12	-300.0E-12	-650.0E-12	-85.0E-09	<b>-6.2E-06</b>	-4.3E-06	-2.7E-06	-5.8E-09
SN6	-500.0E-12	-200.0E-12	-450.0E-12	-650.0E-12	-41.2E-09	-2.4E-06	-1.6E-06	-932.0E-09	-4.4E-09
Statistics									
Min	-600.0E-12	-250.0E-12	-450.0E-12	-750.0E-12	-85.0E-09	-6.2E-06	-4.3E-06	-2.7E-06	-5.8E-09
Max	-500.0E-12	-100.0E-12	-250.0E-12	-550.0E-12	-15.8E-09	-698.5E-09	-419.0E-09	-259.5E-09	-2.8E-09
Average	-540.0E-12	-170.0E-12	-350.0E-12	-650.0E-12	-42.0E-09	-2.7E-06	-1.8E-06	-1.1E-06	-4.1E-09
Sigma	37.4E-12	51.0E-12	83.7E-12	63.2E-12	24.5E-09	2.0E-06	1.4E-06	875.4E-09	1.1E-09

Drift Calculation

IOLTLD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	400.0E-12	100.0E-12	-200.0E-12	-20.7E-09	-969.5E-09	-570.0E-09	-385.0E-09	-2.6E-09
SN3	-	500.0E-12	300.0E-12	-50.0E-12	-46.0E-09	-3.3E-06	-2.1E-06	-1.3E-06	-3.8E-09
SN4	-	300.0E-12	300.0E-12	0.0E+00	-15.2E-09	-698.0E-09	-418.5E-09	-259.0E-09	-2.2E-09
SN5	-	350.0E-12	200.0E-12	-150.0E-12	-84.5E-09	-6.2E-06	-4.3E-06	-2.7E-06	-5.3E-09
SN6	-	300.0E-12	50.0E-12	-150.0E-12	-40.7E-09	-2.4E-06	-1.6E-06	-931.5E-09	-3.9E-09
Average	-	370.0E-12	190.0E-12	-110.0E-12	-41.4E-09	-2.7E-06	-1.8E-06	-1.1E-06	-3.6E-09
Sigma	-	74.8E-12	102.0E-12	73.5E-12	24.5E-09	2.0E-06	1.4E-06	875.5E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTL D12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-450.0E-12	-150.0E-12	-100.0E-12	-350.0E-12	-600.0E-12	-450.0E-12	-100.0E-12	-350.0E-12	-550.0E-12
<b>OFF samples</b>									
SN7	-550.0E-12	-150.0E-12	-350.0E-12	-500.0E-12	-1.9E-09	-26.3E-09	-21.1E-09	-15.5E-09	-1.6E-09
SN8	-550.0E-12	-150.0E-12	-200.0E-12	-550.0E-12	-1.3E-09	-20.2E-09	-14.2E-09	-11.6E-09	-1.7E-09
SN9	-450.0E-12	-200.0E-12	-300.0E-12	-400.0E-12	-1.7E-09	-27.7E-09	-17.2E-09	-14.1E-09	-1.5E-09
SN10	-450.0E-12	-200.0E-12	-300.0E-12	-450.0E-12	-1.9E-09	-32.2E-09	-20.0E-09	-19.4E-09	-1.4E-09
SN11	-450.0E-12	-200.0E-12	-350.0E-12	-450.0E-12	-1.6E-09	-27.1E-09	-16.3E-09	-15.1E-09	-2.0E-09
<b>Statistics</b>									
Min	-550.0E-12	-200.0E-12	-350.0E-12	-550.0E-12	-1.9E-09	-32.2E-09	-21.1E-09	-19.4E-09	-2.0E-09
Max	-450.0E-12	-150.0E-12	-200.0E-12	-400.0E-12	-1.3E-09	-20.2E-09	-14.2E-09	-11.6E-09	-1.4E-09
Average	-490.0E-12	-180.0E-12	-300.0E-12	-470.0E-12	-1.7E-09	-26.7E-09	-17.7E-09	-15.1E-09	-1.6E-09
Sigma	49.0E-12	24.5E-12	54.8E-12	51.0E-12	217.7E-12	3.8E-09	2.5E-09	2.5E-09	205.9E-12

**Drift Calculation**

IOLTL D12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	400.0E-12	200.0E-12	50.0E-12	-1.3E-09	-25.8E-09	-20.5E-09	-15.0E-09	-1.1E-09
SN8	-	400.0E-12	350.0E-12	0.0E+00	-750.0E-12	-19.6E-09	-13.7E-09	-11.1E-09	-1.2E-09
SN9	-	250.0E-12	150.0E-12	50.0E-12	-1.3E-09	-27.2E-09	-16.8E-09	-13.7E-09	-1.1E-09
SN10	-	250.0E-12	150.0E-12	0.0E+00	-1.5E-09	-31.7E-09	-19.5E-09	-19.0E-09	-950.0E-12
SN11	-	250.0E-12	100.0E-12	0.0E+00	-1.1E-09	-26.6E-09	-15.9E-09	-14.6E-09	-1.6E-09
Average	-	310.0E-12	190.0E-12	20.0E-12	-1.2E-09	-26.2E-09	-17.3E-09	-14.6E-09	-1.2E-09
Sigma	-	73.5E-12	86.0E-12	24.5E-12	237.9E-12	3.9E-09	2.5E-09	2.6E-09	209.8E-12

Parameter : Three state output leakage : IOLTLD11

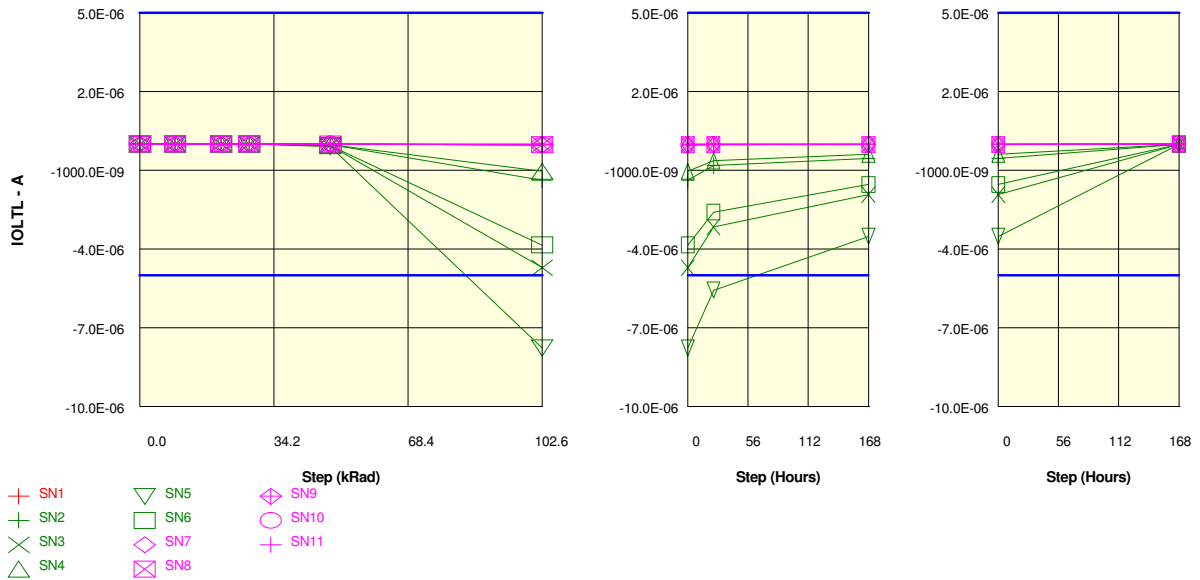
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	-50.0E-12	0.0E+00	-50.0E-12	-50.0E-12	0.0E+00	-50.0E-12	-50.0E-12	-50.0E-12	0.0E+00
ON samples									
SN2	-50.0E-12	-100.0E-12	-50.0E-12	-350.0E-12	-25.1E-09	-1.4E-06	-821.0E-09	-540.5E-09	-3.1E-09
SN3	0.0E+00	-100.0E-12	-100.0E-12	-350.0E-12	-59.2E-09	-4.7E-06	-3.2E-06	-1.9E-06	-4.6E-09
SN4	-50.0E-12	-50.0E-12	-150.0E-12	-250.0E-12	-18.4E-09	-1.0E-06	-639.0E-09	-386.5E-09	-2.6E-09
SN5	0.0E+00	0.0E+00	-100.0E-12	-350.0E-12	-96.5E-09	-7.8E-06	-5.6E-06	-3.5E-06	-5.7E-09
SN6	50.0E-12	-50.0E-12	-50.0E-12	-450.0E-12	-58.0E-09	-3.8E-06	-2.6E-06	-1.5E-06	-4.4E-09
Statistics									
Min	-50.0E-12	-100.0E-12	-150.0E-12	-450.0E-12	-96.5E-09	-7.8E-06	-5.6E-06	-3.5E-06	-5.7E-09
Max	50.0E-12	0.0E+00	-50.0E-12	-250.0E-12	-18.4E-09	-1.0E-06	-639.0E-09	-386.5E-09	-2.6E-09
Average	-10.0E-12	-60.0E-12	-90.0E-12	-350.0E-12	-51.4E-09	-3.7E-06	-2.6E-06	-1.6E-06	-4.1E-09
Sigma	37.4E-12	37.4E-12	37.4E-12	63.2E-12	28.0E-09	2.5E-06	1.8E-06	1.1E-06	1.1E-09

Drift Calculation

IOLTLD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-50.0E-12	0.0E+00	-300.0E-12	-25.1E-09	-1.4E-06	-821.0E-09	-540.5E-09	-3.1E-09
SN3	-	-100.0E-12	-100.0E-12	-350.0E-12	-59.2E-09	-4.7E-06	-3.2E-06	-1.9E-06	-4.6E-09
SN4	-	0.0E+00	-100.0E-12	-200.0E-12	-18.3E-09	-1.0E-06	-639.0E-09	-386.5E-09	-2.6E-09
SN5	-	0.0E+00	-100.0E-12	-350.0E-12	-96.5E-09	-7.8E-06	-5.6E-06	-3.5E-06	-5.7E-09
SN6	-	-100.0E-12	-100.0E-12	-500.0E-12	-58.1E-09	-3.8E-06	-2.6E-06	-1.5E-06	-4.4E-09
Average	-	-50.0E-12	-80.0E-12	-340.0E-12	-51.4E-09	-3.7E-06	-2.6E-06	-1.6E-06	-4.1E-09
Sigma	-	44.7E-12	40.0E-12	97.0E-12	28.0E-09	2.5E-06	1.8E-06	1.1E-06	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT				Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices		Issue:	02

**Measurements**

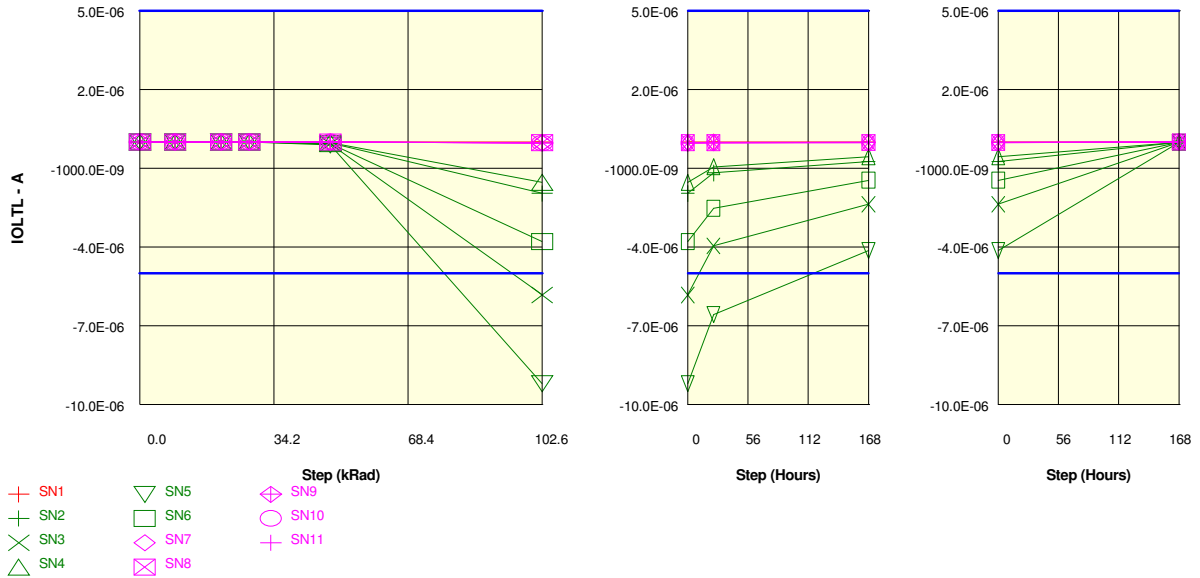
IOLTLTD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	0.0E+00	-50.0E-12	-50.0E-12	0.0E+00	-50.0E-12	-50.0E-12	-50.0E-12	0.0E+00
<b>OFF samples</b>									
SN7	-50.0E-12	-50.0E-12	-100.0E-12	-150.0E-12	-1.3E-09	-29.3E-09	-23.2E-09	-16.8E-09	-1.2E-09
SN8	-50.0E-12	0.0E+00	-50.0E-12	-100.0E-12	-900.0E-12	-23.6E-09	-16.7E-09	-13.4E-09	-1.4E-09
SN9	50.0E-12	-100.0E-12	0.0E+00	-150.0E-12	-1.1E-09	-31.2E-09	-19.5E-09	-16.3E-09	-1.2E-09
SN10	-50.0E-12	-50.0E-12	0.0E+00	-150.0E-12	-1.4E-09	-38.2E-09	-24.4E-09	-22.7E-09	-1.2E-09
SN11	-50.0E-12	-50.0E-12	-100.0E-12	-100.0E-12	-1.1E-09	-30.1E-09	-17.9E-09	-16.6E-09	-1.7E-09
<b>Statistics</b>									
Min	-50.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-1.4E-09	-38.2E-09	-24.4E-09	-22.7E-09	-1.7E-09
Max	50.0E-12	0.0E+00	0.0E+00	-100.0E-12	-900.0E-12	-23.6E-09	-16.7E-09	-13.4E-09	-1.2E-09
Average	-30.0E-12	-50.0E-12	-50.0E-12	-130.0E-12	-1.2E-09	-30.5E-09	-20.3E-09	-17.1E-09	-1.3E-09
Sigma	40.0E-12	31.6E-12	44.7E-12	24.5E-12	174.4E-12	4.7E-09	3.0E-09	3.0E-09	193.4E-12

**Drift Calculation**

IOLTLTD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	-50.0E-12	-100.0E-12	-1.3E-09	-29.3E-09	-23.2E-09	-16.8E-09	-1.1E-09
SN8	-	50.0E-12	0.0E+00	-50.0E-12	-850.0E-12	-23.5E-09	-16.7E-09	-13.3E-09	-1.4E-09
SN9	-	-150.0E-12	-50.0E-12	-200.0E-12	-1.2E-09	-31.2E-09	-19.6E-09	-16.4E-09	-1.2E-09
SN10	-	0.0E+00	50.0E-12	-100.0E-12	-1.4E-09	-38.2E-09	-24.3E-09	-22.6E-09	-1.2E-09
SN11	-	0.0E+00	-50.0E-12	-50.0E-12	-1.1E-09	-30.0E-09	-17.9E-09	-16.5E-09	-1.6E-09
Average	-	-20.0E-12	-20.0E-12	-100.0E-12	-1.1E-09	-30.4E-09	-20.3E-09	-17.1E-09	-1.3E-09
Sigma	-	67.8E-12	40.0E-12	54.8E-12	172.0E-12	4.7E-09	3.0E-09	3.0E-09	180.6E-12



Parameter : Three state output leakage : IOLTLD10  
 Test conditions :  
 Unit : A  
 Spec Limit Min : -5.0E-06  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	450.0E-12	450.0E-12	450.0E-12	450.0E-12	450.0E-12	400.0E-12	450.0E-12	500.0E-12	400.0E-12
ON samples									
SN2	500.0E-12	-50.0E-12	-100.0E-12	-300.0E-12	-30.2E-09	-2.0E-06	-1.2E-06	-751.0E-09	-4.2E-09
SN3	450.0E-12	-50.0E-12	-100.0E-12	-400.0E-12	-67.2E-09	-5.8E-06	-4.0E-06	-2.4E-06	-6.5E-09
SN4	650.0E-12	-50.0E-12	-100.0E-12	-350.0E-12	-23.6E-09	-1.5E-06	-941.5E-09	-555.5E-09	-3.5E-09
SN5	450.0E-12	-50.0E-12	-100.0E-12	-350.0E-12	-112.5E-09	-9.2E-06	-6.6E-06	-4.1E-06	-8.1E-09
SN6	600.0E-12	-50.0E-12	-50.0E-12	-450.0E-12	-58.7E-09	-3.8E-06	-2.5E-06	-1.5E-06	-5.9E-09
Statistics									
Min	450.0E-12	-50.0E-12	-100.0E-12	-450.0E-12	-112.5E-09	-9.2E-06	-6.6E-06	-4.1E-06	-8.1E-09
Max	650.0E-12	-50.0E-12	-50.0E-12	-300.0E-12	-23.6E-09	-1.5E-06	-941.5E-09	-555.5E-09	-3.5E-09
Average	530.0E-12	-50.0E-12	-90.0E-12	-370.0E-12	-58.4E-09	-4.5E-06	-3.0E-06	-1.9E-06	-5.6E-09
Sigma	81.2E-12	0.0E+00	20.0E-12	51.0E-12	31.7E-09	2.8E-06	2.1E-06	1.3E-06	1.6E-09

Drift Calculation

IOLTLD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-550.0E-12	-600.0E-12	-800.0E-12	-30.7E-09	-2.0E-06	-1.2E-06	-751.5E-09	-4.7E-09
SN3	-	-500.0E-12	-550.0E-12	-850.0E-12	-67.6E-09	-5.8E-06	-4.0E-06	-2.4E-06	-7.0E-09
SN4	-	-700.0E-12	-750.0E-12	-1.0E-09	-24.2E-09	-1.5E-06	-942.2E-09	-556.2E-09	-4.1E-09
SN5	-	-500.0E-12	-550.0E-12	-800.0E-12	-113.0E-09	-9.2E-06	-6.6E-06	-4.1E-06	-8.5E-09
SN6	-	-650.0E-12	-650.0E-12	-1.1E-09	-59.3E-09	-3.8E-06	-2.5E-06	-1.5E-06	-6.5E-09
Average	-	-580.0E-12	-620.0E-12	-900.0E-12	-59.0E-09	-4.5E-06	-3.0E-06	-1.9E-06	-6.2E-09
Sigma	-	81.2E-12	74.8E-12	104.9E-12	31.6E-09	2.8E-06	2.1E-06	1.3E-06	1.6E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTLTD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	450.0E-12	450.0E-12	450.0E-12	450.0E-12	450.0E-12	400.0E-12	450.0E-12	500.0E-12	400.0E-12
OFF samples									
SN7	400.0E-12	-50.0E-12	-100.0E-12	-150.0E-12	-1.5E-09	-33.8E-09	-26.6E-09	-19.4E-09	-1.4E-09
SN8	500.0E-12	-50.0E-12	-100.0E-12	-100.0E-12	-1.0E-09	-23.5E-09	-16.6E-09	-13.4E-09	-1.5E-09
SN9	650.0E-12	-50.0E-12	-100.0E-12	-100.0E-12	-1.3E-09	-32.9E-09	-20.9E-09	-17.1E-09	-1.3E-09
SN10	500.0E-12	-50.0E-12	-100.0E-12	-200.0E-12	-1.6E-09	-40.3E-09	-25.4E-09	-23.7E-09	-1.4E-09
SN11	600.0E-12	-50.0E-12	-100.0E-12	-100.0E-12	-1.2E-09	-32.1E-09	-19.2E-09	-17.7E-09	-1.8E-09
Statistics									
Min	400.0E-12	-50.0E-12	-100.0E-12	-200.0E-12	-1.6E-09	-40.3E-09	-26.6E-09	-23.7E-09	-1.8E-09
Max	650.0E-12	-50.0E-12	-100.0E-12	-100.0E-12	-1.0E-09	-23.5E-09	-16.6E-09	-13.4E-09	-1.3E-09
Average	530.0E-12	-50.0E-12	-100.0E-12	-130.0E-12	-1.3E-09	-32.5E-09	-21.7E-09	-18.2E-09	-1.5E-09
Sigma	87.2E-12	0.0E+00	0.0E+00	40.0E-12	199.0E-12	5.4E-09	3.8E-09	3.4E-09	187.1E-12

**Drift Calculation**

IOLTLTD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-450.0E-12	-500.0E-12	-550.0E-12	-1.9E-09	-34.2E-09	-27.0E-09	-19.8E-09	-1.8E-09
SN8	-	-550.0E-12	-600.0E-12	-600.0E-12	-1.5E-09	-24.0E-09	-17.1E-09	-13.9E-09	-2.0E-09
SN9	-	-700.0E-12	-750.0E-12	-750.0E-12	-1.9E-09	-33.5E-09	-21.5E-09	-17.8E-09	-1.9E-09
SN10	-	-550.0E-12	-600.0E-12	-700.0E-12	-2.1E-09	-40.8E-09	-25.9E-09	-24.2E-09	-1.9E-09
SN11	-	-650.0E-12	-700.0E-12	-700.0E-12	-1.8E-09	-32.7E-09	-19.8E-09	-18.3E-09	-2.4E-09
Average	-	-580.0E-12	-630.0E-12	-660.0E-12	-1.8E-09	-33.0E-09	-22.2E-09	-18.8E-09	-2.0E-09
Sigma	-	87.2E-12	87.2E-12	73.5E-12	182.8E-12	5.4E-09	3.7E-09	3.3E-09	220.5E-12

Parameter : Three state output leakage : IOLTL D9

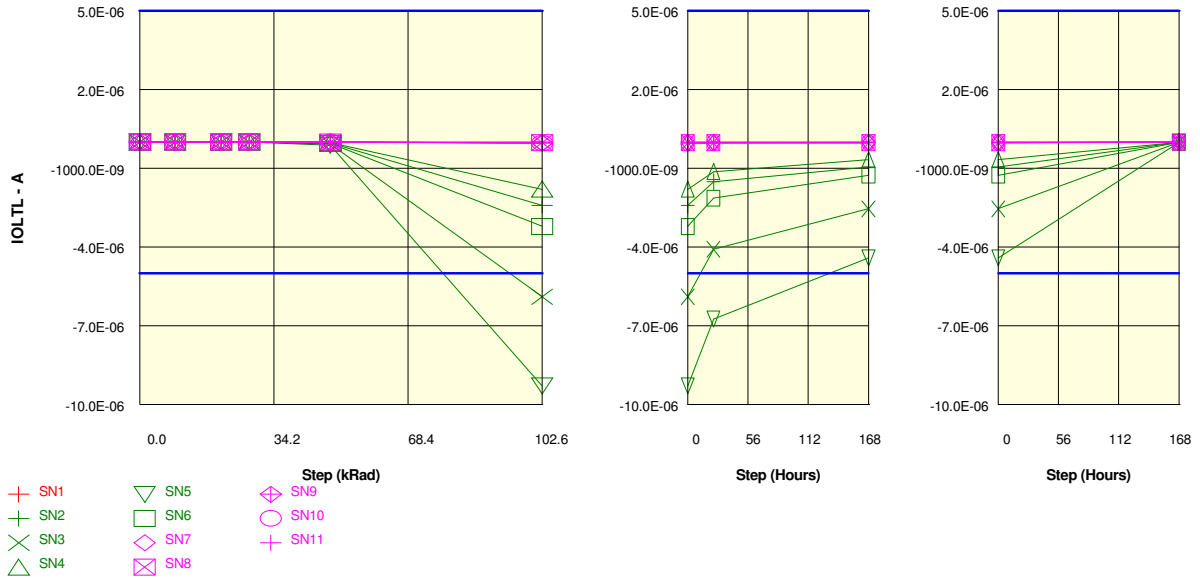
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTL D9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	50.0E-12	550.0E-12	350.0E-12	350.0E-12	450.0E-12	550.0E-12	450.0E-12	450.0E-12	450.0E-12
ON samples									
SN2	500.0E-12	-350.0E-12	-450.0E-12	-700.0E-12	-32.1E-09	-2.4E-06	-1.5E-06	-953.5E-09	-4.3E-09
SN3	100.0E-12	-250.0E-12	-450.0E-12	-850.0E-12	-73.0E-09	<b>-5.9E-06</b>	-4.1E-06	-2.5E-06	-6.3E-09
SN4	700.0E-12	-200.0E-12	-400.0E-12	-800.0E-12	-25.5E-09	-1.8E-06	-1.1E-06	-665.5E-09	-4.1E-09
SN5	500.0E-12	-300.0E-12	-400.0E-12	-800.0E-12	-118.0E-09	<b>-9.3E-06</b>	<b>-6.7E-06</b>	-4.4E-06	-7.9E-09
SN6	650.0E-12	-250.0E-12	-400.0E-12	-850.0E-12	-48.0E-09	-3.2E-06	-2.1E-06	-1.3E-06	-5.6E-09
Statistics									
Min	100.0E-12	-350.0E-12	-450.0E-12	-850.0E-12	-118.0E-09	-9.3E-06	-6.7E-06	-4.4E-06	-7.9E-09
Max	700.0E-12	-200.0E-12	-400.0E-12	-700.0E-12	-25.5E-09	-1.8E-06	-1.1E-06	-665.5E-09	-4.1E-09
Average	490.0E-12	-270.0E-12	-420.0E-12	-800.0E-12	-59.3E-09	-4.5E-06	-3.1E-06	-2.0E-06	-5.6E-09
Sigma	210.7E-12	51.0E-12	24.5E-12	54.8E-12	33.6E-09	2.8E-06	2.1E-06	1.4E-06	1.4E-09

Drift Calculation

IOLTL D9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-850.0E-12	-950.0E-12	-1.2E-09	-32.6E-09	-2.4E-06	-1.5E-06	-954.0E-09	-4.8E-09
SN3	-	-350.0E-12	-550.0E-12	-950.0E-12	-73.1E-09	-5.9E-06	-4.1E-06	-2.5E-06	-6.4E-09
SN4	-	-900.0E-12	-1.1E-09	-1.5E-09	-26.2E-09	-1.8E-06	-1.1E-06	-666.2E-09	-4.8E-09
SN5	-	-800.0E-12	-900.0E-12	-1.3E-09	-118.5E-09	-9.3E-06	-6.7E-06	-4.4E-06	-8.4E-09
SN6	-	-900.0E-12	-1.1E-09	-1.5E-09	-48.6E-09	-3.2E-06	-2.1E-06	-1.3E-06	-6.2E-09
Average	-	-760.0E-12	-910.0E-12	-1.3E-09	-59.8E-09	-4.5E-06	-3.1E-06	-2.0E-06	-6.1E-09
Sigma	-	208.3E-12	193.4E-12	205.9E-12	33.5E-09	2.8E-06	2.1E-06	1.4E-06	1.3E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

IOLTLID9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	50.0E-12	550.0E-12	350.0E-12	350.0E-12	450.0E-12	550.0E-12	450.0E-12	450.0E-12	450.0E-12
<b>OFF samples</b>									
SN7	250.0E-12	-300.0E-12	-450.0E-12	-650.0E-12	-2.0E-09	-36.2E-09	-28.7E-09	-20.8E-09	-1.8E-09
SN8	500.0E-12	-250.0E-12	-400.0E-12	-500.0E-12	-1.4E-09	-26.4E-09	-19.1E-09	-16.0E-09	-2.0E-09
SN9	700.0E-12	-150.0E-12	-450.0E-12	-400.0E-12	-1.7E-09	-35.0E-09	-22.8E-09	-19.2E-09	-1.8E-09
SN10	650.0E-12	-200.0E-12	-400.0E-12	-600.0E-12	-1.9E-09	-44.9E-09	-27.9E-09	-26.9E-09	-2.0E-09
SN11	700.0E-12	-200.0E-12	-400.0E-12	-650.0E-12	-1.8E-09	-33.0E-09	-20.9E-09	-19.2E-09	-2.4E-09
<b>Statistics</b>									
Min	250.0E-12	-300.0E-12	-450.0E-12	-650.0E-12	-2.0E-09	-44.9E-09	-28.7E-09	-26.9E-09	-2.4E-09
Max	700.0E-12	-150.0E-12	-400.0E-12	-400.0E-12	-1.4E-09	-26.4E-09	-19.1E-09	-16.0E-09	-1.8E-09
Average	560.0E-12	-220.0E-12	-420.0E-12	-560.0E-12	-1.7E-09	-35.1E-09	-23.9E-09	-20.4E-09	-2.0E-09
Sigma	171.5E-12	51.0E-12	24.5E-12	97.0E-12	193.4E-12	6.0E-09	3.8E-09	3.6E-09	201.5E-12

**Drift Calculation**

IOLTLID9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-550.0E-12	-700.0E-12	-900.0E-12	-2.2E-09	-36.5E-09	-29.0E-09	-21.0E-09	-2.1E-09
SN8	-	-750.0E-12	-900.0E-12	-1.0E-09	-1.9E-09	-26.9E-09	-19.6E-09	-16.5E-09	-2.5E-09
SN9	-	-850.0E-12	-1.2E-09	-1.1E-09	-2.4E-09	-35.7E-09	-23.5E-09	-19.9E-09	-2.5E-09
SN10	-	-850.0E-12	-1.1E-09	-1.3E-09	-2.6E-09	-45.6E-09	-28.6E-09	-27.5E-09	-2.6E-09
SN11	-	-900.0E-12	-1.1E-09	-1.4E-09	-2.5E-09	-33.7E-09	-21.6E-09	-19.9E-09	-3.1E-09
Average	-	-780.0E-12	-980.0E-12	-1.1E-09	-2.3E-09	-35.6E-09	-24.4E-09	-21.0E-09	-2.5E-09
Sigma	-	124.9E-12	163.1E-12	163.1E-12	230.2E-12	6.0E-09	3.7E-09	3.6E-09	320.3E-12

Parameter : Three state output leakage : IOLTL D8

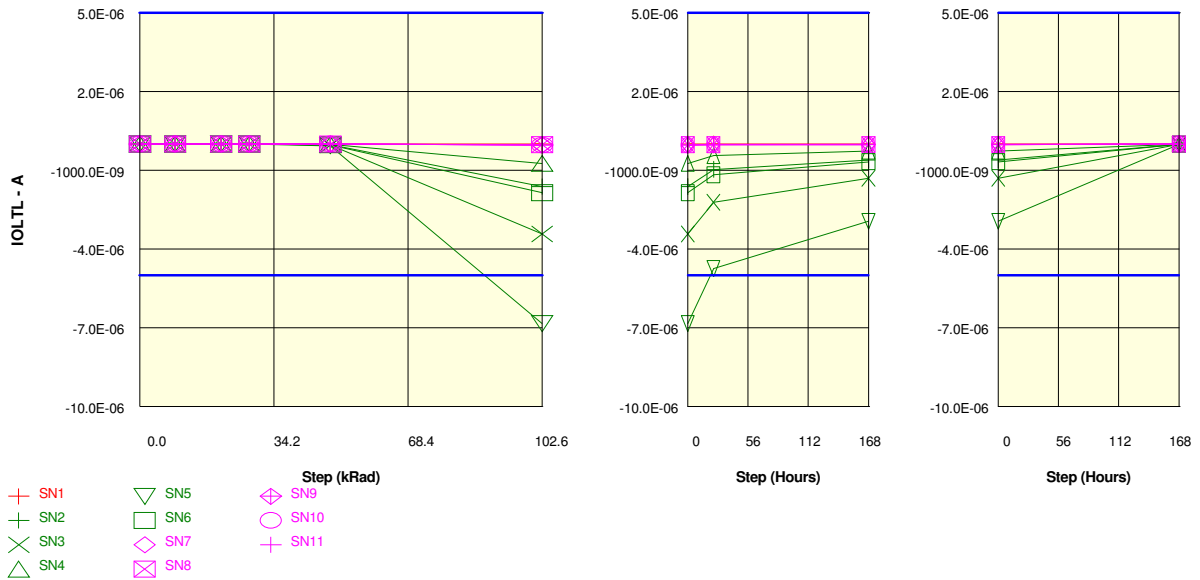
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTL D8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-1.2E-09	-450.0E-12	-600.0E-12	-800.0E-12	-550.0E-12	-600.0E-12	-850.0E-12	-850.0E-12	-650.0E-12
ON samples									
SN2	-550.0E-12	-650.0E-12	-750.0E-12	-1.0E-09	-21.5E-09	-1.6E-06	-965.0E-09	-607.5E-09	-4.3E-09
SN3	-950.0E-12	-450.0E-12	-850.0E-12	-1.2E-09	-37.1E-09	-3.4E-06	-2.2E-06	-1.3E-06	-5.8E-09
SN4	-550.0E-12	-450.0E-12	-850.0E-12	-950.0E-12	-13.6E-09	-736.0E-09	-440.0E-09	-268.0E-09	-3.9E-09
SN5	-500.0E-12	-450.0E-12	-650.0E-12	-1.0E-09	-66.7E-09	<b>-6.8E-06</b>	-4.7E-06	-2.9E-06	-6.7E-09
SN6	-550.0E-12	-450.0E-12	-650.0E-12	-1.2E-09	-29.0E-09	-1.9E-06	-1.2E-06	-675.5E-09	-5.2E-09
Statistics									
Min	-950.0E-12	-650.0E-12	-850.0E-12	-1.2E-09	-66.7E-09	-6.8E-06	-4.7E-06	-2.9E-06	-6.7E-09
Max	-500.0E-12	-450.0E-12	-650.0E-12	-950.0E-12	-13.6E-09	-736.0E-09	-440.0E-09	-268.0E-09	-3.9E-09
Average	-620.0E-12	-490.0E-12	-750.0E-12	-1.1E-09	-33.6E-09	-2.9E-06	-1.9E-06	-1.2E-06	-5.2E-09
Sigma	166.1E-12	80.0E-12	89.4E-12	83.7E-12	18.3E-09	2.2E-06	1.5E-06	951.3E-09	1.0E-09

Drift Calculation

IOLTL D8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-100.0E-12	-200.0E-12	-450.0E-12	-20.9E-09	-1.6E-06	-964.5E-09	-607.0E-09	-3.7E-09
SN3	-	500.0E-12	100.0E-12	-200.0E-12	-36.2E-09	-3.4E-06	-2.2E-06	-1.3E-06	-4.9E-09
SN4	-	100.0E-12	-300.0E-12	-400.0E-12	-13.0E-09	-735.5E-09	-439.5E-09	-267.5E-09	-3.3E-09
SN5	-	50.0E-12	-150.0E-12	-500.0E-12	-66.2E-09	-6.8E-06	-4.7E-06	-2.9E-06	-6.2E-09
SN6	-	100.0E-12	-100.0E-12	-600.0E-12	-28.5E-09	-1.8E-06	-1.2E-06	-675.0E-09	-4.7E-09
Average	-	130.0E-12	-130.0E-12	-430.0E-12	-32.9E-09	-2.9E-06	-1.9E-06	-1.2E-06	-4.5E-09
Sigma	-	199.0E-12	132.7E-12	132.7E-12	18.3E-09	2.2E-06	1.5E-06	951.3E-09	1.0E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTLDB	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-1.2E-09	-450.0E-12	-600.0E-12	-800.0E-12	-550.0E-12	-600.0E-12	-850.0E-12	-850.0E-12	-650.0E-12
<b>OFF samples</b>									
SN7	-650.0E-12	-550.0E-12	-950.0E-12	-1.3E-09	-2.2E-09	-31.6E-09	-25.9E-09	-18.7E-09	-1.9E-09
SN8	-750.0E-12	-450.0E-12	-750.0E-12	-750.0E-12	-1.5E-09	-22.5E-09	-16.1E-09	-14.7E-09	-1.9E-09
SN9	-600.0E-12	-400.0E-12	-700.0E-12	-700.0E-12	-2.0E-09	-32.7E-09	-21.1E-09	-18.6E-09	-2.0E-09
SN10	-600.0E-12	-400.0E-12	-700.0E-12	-1.0E-09	-2.0E-09	-39.2E-09	-24.8E-09	-23.9E-09	-2.1E-09
SN11	-300.0E-12	-450.0E-12	-750.0E-12	-850.0E-12	-2.1E-09	-28.7E-09	-18.3E-09	-17.2E-09	-2.5E-09
<b>Statistics</b>									
Min	-750.0E-12	-550.0E-12	-950.0E-12	-1.3E-09	-2.2E-09	-39.2E-09	-25.9E-09	-23.9E-09	-2.5E-09
Max	-300.0E-12	-400.0E-12	-700.0E-12	-700.0E-12	-1.5E-09	-22.5E-09	-16.1E-09	-14.7E-09	-1.9E-09
Average	-580.0E-12	-450.0E-12	-770.0E-12	-910.0E-12	-1.9E-09	-30.9E-09	-21.2E-09	-18.6E-09	-2.1E-09
Sigma	150.3E-12	54.8E-12	92.7E-12	198.5E-12	254.2E-12	5.4E-09	3.7E-09	3.0E-09	208.3E-12

**Drift Calculation**

IOLTLDB	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	100.0E-12	-300.0E-12	-600.0E-12	-1.6E-09	-30.9E-09	-25.2E-09	-18.0E-09	-1.3E-09
SN8	-	300.0E-12	0.0E+00	0.0E+00	-700.0E-12	-21.8E-09	-15.3E-09	-14.0E-09	-1.2E-09
SN9	-	200.0E-12	-100.0E-12	-100.0E-12	-1.4E-09	-32.1E-09	-20.5E-09	-18.0E-09	-1.4E-09
SN10	-	200.0E-12	-100.0E-12	-400.0E-12	-1.4E-09	-38.6E-09	-24.2E-09	-23.3E-09	-1.5E-09
SN11	-	-150.0E-12	-450.0E-12	-550.0E-12	-1.8E-09	-28.4E-09	-18.0E-09	-16.9E-09	-2.2E-09
Average	-	130.0E-12	-190.0E-12	-330.0E-12	-1.4E-09	-30.3E-09	-20.6E-09	-18.0E-09	-1.5E-09
Sigma	-	153.6E-12	162.5E-12	240.0E-12	353.6E-12	5.4E-09	3.7E-09	3.0E-09	354.4E-12

Parameter : Three state output leakage : IOLTL D7

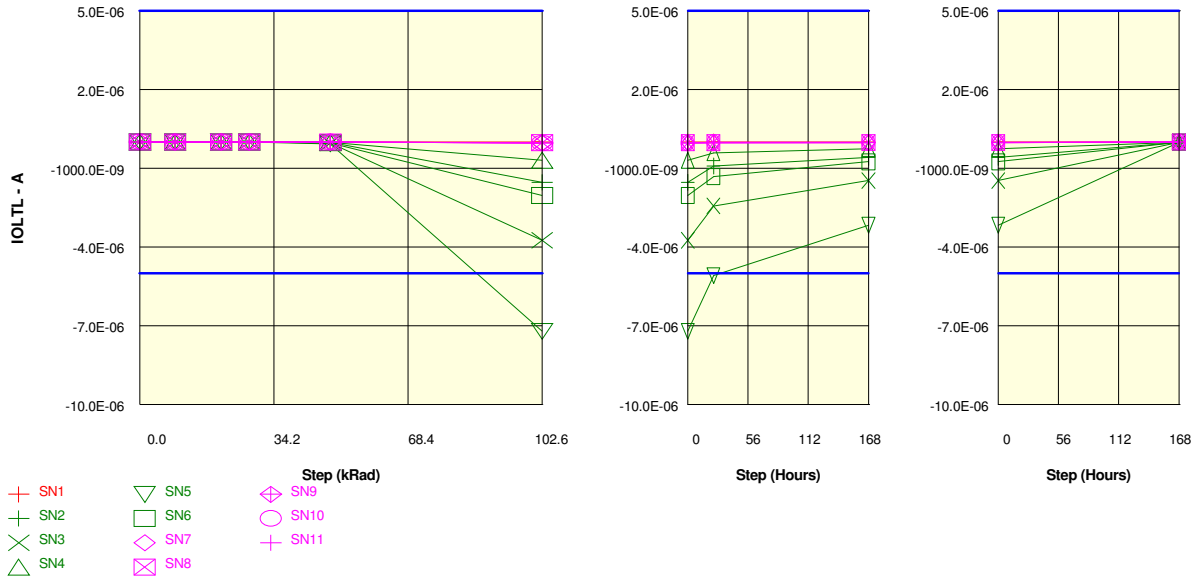
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTL D7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	3.0E-09	3.2E-09	2.8E-09	3.2E-09	3.2E-09	3.0E-09	2.8E-09	3.5E-09	3.2E-09
ON samples									
SN2	3.0E-09	250.0E-12	-200.0E-12	-400.0E-12	-17.3E-09	-1.5E-06	-914.0E-09	-583.5E-09	-3.7E-09
SN3	3.2E-09	450.0E-12	0.0E+00	-300.0E-12	-36.0E-09	-3.7E-06	-2.4E-06	-1.5E-06	-5.2E-09
SN4	3.4E-09	400.0E-12	-50.0E-12	-300.0E-12	-10.6E-09	-693.0E-09	-406.0E-09	-248.0E-09	-2.8E-09
SN5	3.4E-09	400.0E-12	0.0E+00	-200.0E-12	-65.6E-09	-7.2E-06	-5.1E-06	-3.2E-06	-6.5E-09
SN6	3.4E-09	400.0E-12	-50.0E-12	-350.0E-12	-26.9E-09	-2.0E-06	-1.3E-06	-749.0E-09	-4.3E-09
Statistics									
Min	3.0E-09	250.0E-12	-200.0E-12	-400.0E-12	-65.6E-09	-7.2E-06	-5.1E-06	-3.2E-06	-6.5E-09
Max	3.4E-09	450.0E-12	0.0E+00	-200.0E-12	-10.6E-09	-693.0E-09	-406.0E-09	-248.0E-09	-2.8E-09
Average	3.2E-09	380.0E-12	-60.0E-12	-310.0E-12	-31.3E-09	-3.0E-06	-2.0E-06	-1.2E-06	-4.5E-09
Sigma	168.5E-12	67.8E-12	73.5E-12	66.3E-12	19.2E-09	2.3E-06	1.7E-06	1.0E-06	1.3E-09

Drift Calculation

IOLTL D7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-2.7E-09	-3.2E-09	-3.4E-09	-20.2E-09	-1.5E-06	-917.0E-09	-586.5E-09	-6.6E-09
SN3	-	-2.7E-09	-3.2E-09	-3.5E-09	-39.1E-09	-3.7E-06	-2.4E-06	-1.5E-06	-8.3E-09
SN4	-	-3.0E-09	-3.5E-09	-3.7E-09	-14.0E-09	-696.4E-09	-409.4E-09	-251.4E-09	-6.2E-09
SN5	-	-3.0E-09	-3.4E-09	-3.6E-09	-69.0E-09	-7.2E-06	-5.1E-06	-3.2E-06	-9.8E-09
SN6	-	-3.0E-09	-3.4E-09	-3.7E-09	-30.2E-09	-2.0E-06	-1.3E-06	-752.4E-09	-7.7E-09
Average	-	-2.9E-09	-3.3E-09	-3.6E-09	-34.5E-09	-3.0E-06	-2.0E-06	-1.2E-06	-7.7E-09
Sigma	-	131.9E-12	126.5E-12	137.8E-12	19.2E-09	2.3E-06	1.7E-06	1.0E-06	1.3E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	3.0E-09	3.2E-09	2.8E-09	3.2E-09	3.2E-09	3.0E-09	2.8E-09	3.5E-09	3.2E-09
<b>OFF samples</b>									
SN7	3.3E-09	600.0E-12	-50.0E-12	-50.0E-12	-1.4E-09	-34.1E-09	-27.6E-09	-20.0E-09	-1.4E-09
SN8	3.6E-09	650.0E-12	-50.0E-12	0.0E+00	-750.0E-12	-23.3E-09	-16.7E-09	-13.5E-09	-1.4E-09
SN9	3.7E-09	550.0E-12	50.0E-12	-100.0E-12	-1.1E-09	-35.6E-09	-22.8E-09	-18.8E-09	-1.5E-09
SN10	3.5E-09	550.0E-12	-150.0E-12	-100.0E-12	-1.3E-09	-38.1E-09	-24.3E-09	-22.7E-09	-1.5E-09
SN11	3.8E-09	650.0E-12	-50.0E-12	-350.0E-12	-1.0E-09	-28.0E-09	-16.9E-09	-15.9E-09	-1.7E-09
<b>Statistics</b>									
Min	3.3E-09	550.0E-12	-150.0E-12	-350.0E-12	-1.4E-09	-38.1E-09	-27.6E-09	-22.7E-09	-1.7E-09
Max	3.8E-09	650.0E-12	50.0E-12	0.0E+00	-750.0E-12	-23.3E-09	-16.7E-09	-13.5E-09	-1.4E-09
Average	3.5E-09	600.0E-12	-50.0E-12	-120.0E-12	-1.1E-09	-31.8E-09	-21.6E-09	-18.2E-09	-1.5E-09
Sigma	174.4E-12	44.7E-12	63.2E-12	120.8E-12	216.8E-12	5.4E-09	4.3E-09	3.2E-09	120.8E-12

**Drift Calculation**

IOLTD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-2.7E-09	-3.3E-09	-3.3E-09	-4.6E-09	-37.3E-09	-30.9E-09	-23.3E-09	-4.6E-09
SN8	-	-3.0E-09	-3.7E-09	-3.6E-09	-4.4E-09	-26.9E-09	-20.3E-09	-17.1E-09	-5.0E-09
SN9	-	-3.1E-09	-3.6E-09	-3.8E-09	-4.8E-09	-39.2E-09	-26.4E-09	-22.5E-09	-5.2E-09
SN10	-	-2.9E-09	-3.6E-09	-3.6E-09	-4.8E-09	-41.5E-09	-27.8E-09	-26.2E-09	-4.9E-09
SN11	-	-3.1E-09	-3.8E-09	-4.1E-09	-4.8E-09	-31.7E-09	-20.6E-09	-19.6E-09	-5.5E-09
Average	-	-2.9E-09	-3.6E-09	-3.7E-09	-4.6E-09	-35.3E-09	-25.2E-09	-21.7E-09	-5.0E-09
Sigma	-	165.5E-12	162.5E-12	263.4E-12	156.2E-12	5.3E-09	4.1E-09	3.1E-09	280.4E-12



Parameter : Three state output leakage : IOLTL D6

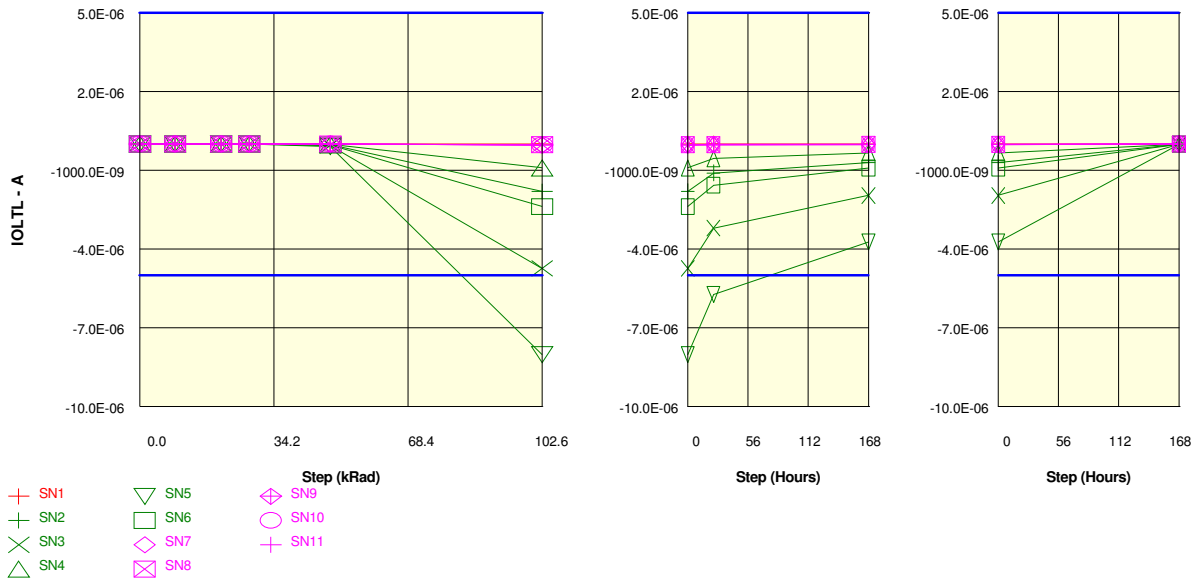
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTL D6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	3.5E-09	3.5E-09	3.0E-09	3.6E-09	3.6E-09	3.2E-09	3.3E-09	3.9E-09	3.6E-09
ON samples									
SN2	3.4E-09	300.0E-12	-200.0E-12	-400.0E-12	-21.9E-09	-1.8E-06	-1.1E-06	-708.5E-09	-4.0E-09
SN3	3.9E-09	600.0E-12	-50.0E-12	-450.0E-12	-51.9E-09	-4.7E-06	-3.2E-06	-2.0E-06	-5.9E-09
SN4	3.9E-09	300.0E-12	-50.0E-12	-400.0E-12	-14.2E-09	-907.0E-09	-553.5E-09	-335.5E-09	-3.3E-09
SN5	4.0E-09	500.0E-12	-50.0E-12	-300.0E-12	-97.5E-09	-8.0E-06	-5.7E-06	-3.7E-06	-7.2E-09
SN6	4.2E-09	350.0E-12	-50.0E-12	-350.0E-12	-32.8E-09	-2.4E-06	-1.6E-06	-913.5E-09	-4.6E-09
Statistics									
Min	3.4E-09	300.0E-12	-200.0E-12	-450.0E-12	-97.5E-09	-8.0E-06	-5.7E-06	-3.7E-06	-7.2E-09
Max	4.2E-09	600.0E-12	-50.0E-12	-300.0E-12	-14.2E-09	-907.0E-09	-553.5E-09	-335.5E-09	-3.3E-09
Average	3.9E-09	410.0E-12	-80.0E-12	-380.0E-12	-43.6E-09	-3.6E-06	-2.4E-06	-1.5E-06	-5.0E-09
Sigma	260.0E-12	120.0E-12	60.0E-12	51.0E-12	29.8E-09	2.6E-06	1.9E-06	1.2E-06	1.4E-09

Drift Calculation

IOLTL D6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-3.1E-09	-3.6E-09	-3.8E-09	-25.3E-09	-1.8E-06	-1.1E-06	-711.9E-09	-7.4E-09
SN3	-	-3.3E-09	-4.0E-09	-4.4E-09	-55.8E-09	-4.7E-06	-3.2E-06	-2.0E-06	-9.8E-09
SN4	-	-3.6E-09	-4.0E-09	-4.3E-09	-18.1E-09	-910.9E-09	-557.4E-09	-339.4E-09	-7.2E-09
SN5	-	-3.5E-09	-4.0E-09	-4.3E-09	-101.5E-09	-8.0E-06	-5.7E-06	-3.7E-06	-11.1E-09
SN6	-	-3.9E-09	-4.3E-09	-4.6E-09	-37.0E-09	-2.4E-06	-1.6E-06	-917.7E-09	-8.8E-09
Average	-	-3.5E-09	-4.0E-09	-4.3E-09	-47.5E-09	-3.6E-06	-2.4E-06	-1.5E-06	-8.8E-09
Sigma	-	255.7E-12	207.4E-12	247.0E-12	29.8E-09	2.6E-06	1.9E-06	1.2E-06	1.5E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTL D6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	3.5E-09	3.5E-09	3.0E-09	3.6E-09	3.6E-09	3.2E-09	3.3E-09	3.9E-09	3.6E-09
<b>OFF samples</b>									
SN7	3.8E-09	750.0E-12	0.0E+00	0.0E+00	-1.5E-09	-33.8E-09	-27.3E-09	-19.5E-09	-1.4E-09
SN8	4.2E-09	800.0E-12	0.0E+00	0.0E+00	-700.0E-12	-21.1E-09	-15.2E-09	-12.3E-09	-1.3E-09
SN9	4.0E-09	650.0E-12	-50.0E-12	-50.0E-12	-950.0E-12	-32.4E-09	-20.9E-09	-17.4E-09	-1.4E-09
SN10	4.1E-09	600.0E-12	-250.0E-12	-100.0E-12	-1.2E-09	-36.4E-09	-22.7E-09	-21.8E-09	-1.4E-09
SN11	4.4E-09	850.0E-12	-50.0E-12	-350.0E-12	-1.0E-09	-29.2E-09	-17.8E-09	-16.4E-09	-1.8E-09
<b>Statistics</b>									
Min	3.8E-09	600.0E-12	-250.0E-12	-350.0E-12	-1.5E-09	-36.4E-09	-27.3E-09	-21.8E-09	-1.8E-09
Max	4.4E-09	850.0E-12	0.0E+00	0.0E+00	-700.0E-12	-21.1E-09	-15.2E-09	-12.3E-09	-1.3E-09
Average	4.1E-09	730.0E-12	-70.0E-12	-100.0E-12	-1.1E-09	-30.6E-09	-20.8E-09	-17.5E-09	-1.4E-09
Sigma	196.5E-12	92.7E-12	92.7E-12	130.4E-12	263.4E-12	5.3E-09	4.1E-09	3.2E-09	169.1E-12

**Drift Calculation**

IOLTL D6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-3.1E-09	-3.8E-09	-3.8E-09	-5.3E-09	-37.6E-09	-31.1E-09	-23.3E-09	-5.2E-09
SN8	-	-3.4E-09	-4.2E-09	-4.2E-09	-4.9E-09	-25.3E-09	-19.4E-09	-16.4E-09	-5.4E-09
SN9	-	-3.4E-09	-4.1E-09	-4.1E-09	-5.0E-09	-36.4E-09	-24.9E-09	-21.4E-09	-5.4E-09
SN10	-	-3.5E-09	-4.3E-09	-4.2E-09	-5.2E-09	-40.4E-09	-26.8E-09	-25.8E-09	-5.4E-09
SN11	-	-3.6E-09	-4.5E-09	-4.8E-09	-5.4E-09	-33.6E-09	-22.2E-09	-20.8E-09	-6.2E-09
Average	-	-3.4E-09	-4.2E-09	-4.2E-09	-5.1E-09	-34.6E-09	-24.9E-09	-21.5E-09	-5.5E-09
Sigma	-	167.3E-12	221.4E-12	312.4E-12	208.3E-12	5.2E-09	4.0E-09	3.1E-09	329.2E-12

Parameter : Three state output leakage : IOLTL D5

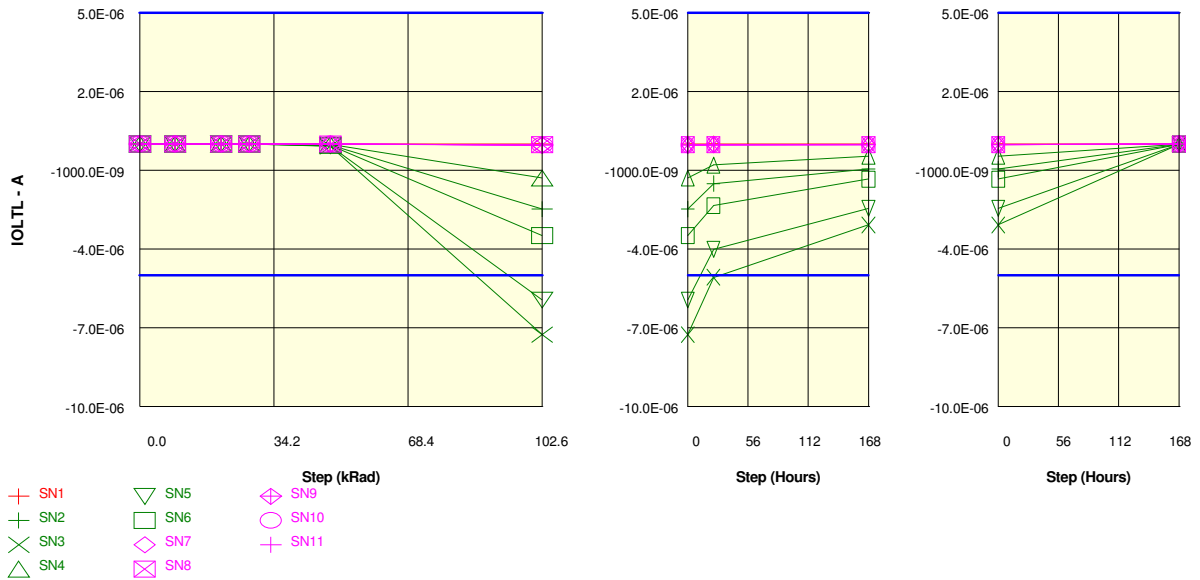
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



IOLTL D5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	900.0E-12	850.0E-12	800.0E-12	950.0E-12	950.0E-12	350.0E-12	800.0E-12	1.0E-09	900.0E-12
<b>ON samples</b>									
SN2	950.0E-12	-150.0E-12	-250.0E-12	-450.0E-12	-29.6E-09	-2.5E-06	-1.5E-06	-953.5E-09	-4.1E-09
SN3	850.0E-12	-150.0E-12	-200.0E-12	-450.0E-12	-79.1E-09	<b>-7.3E-06</b>	<b>-5.1E-06</b>	-3.1E-06	-5.4E-09
SN4	1.1E-09	-250.0E-12	-250.0E-12	-400.0E-12	-16.6E-09	-1.3E-06	-797.0E-09	-463.0E-09	-3.1E-09
SN5	950.0E-12	-200.0E-12	-250.0E-12	-450.0E-12	-67.2E-09	<b>-5.9E-06</b>	-4.0E-06	-2.5E-06	-6.5E-09
SN6	1.0E-09	-100.0E-12	-200.0E-12	-450.0E-12	-43.9E-09	-3.5E-06	-2.3E-06	-1.3E-06	-4.4E-09
<b>Statistics</b>									
Min	850.0E-12	-250.0E-12	-250.0E-12	-450.0E-12	-79.1E-09	-7.3E-06	-5.1E-06	-3.1E-06	-6.5E-09
Max	1.1E-09	-100.0E-12	-200.0E-12	-400.0E-12	-16.6E-09	-1.3E-06	-797.0E-09	-463.0E-09	-3.1E-09
Average	960.0E-12	-170.0E-12	-230.0E-12	-440.0E-12	-47.3E-09	-4.1E-06	-2.7E-06	-1.7E-06	-4.7E-09
Sigma	66.3E-12	51.0E-12	24.5E-12	20.0E-12	23.1E-09	2.2E-06	1.6E-06	965.8E-09	1.2E-09

IOLTL D5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>ON samples</b>									
SN2	-	-1.1E-09	-1.2E-09	-1.4E-09	-30.5E-09	-2.5E-06	-1.5E-06	-954.5E-09	-5.0E-09
SN3	-	-1.0E-09	-1.1E-09	-1.3E-09	-80.0E-09	-7.3E-06	-5.1E-06	-3.1E-06	-6.2E-09
SN4	-	-1.3E-09	-1.3E-09	-1.5E-09	-17.6E-09	-1.3E-06	-798.1E-09	-464.1E-09	-4.1E-09
SN5	-	-1.2E-09	-1.2E-09	-1.4E-09	-68.2E-09	-5.9E-06	-4.0E-06	-2.5E-06	-7.4E-09
SN6	-	-1.1E-09	-1.2E-09	-1.5E-09	-44.9E-09	-3.5E-06	-2.3E-06	-1.3E-06	-5.4E-09
Average	-	-1.1E-09	-1.2E-09	-1.4E-09	-48.2E-09	-4.1E-06	-2.7E-06	-1.7E-06	-5.6E-09
Sigma	-	98.0E-12	80.0E-12	54.8E-12	23.1E-09	2.2E-06	1.6E-06	965.7E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTLDS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	900.0E-12	850.0E-12	800.0E-12	950.0E-12	950.0E-12	350.0E-12	800.0E-12	1.0E-09	900.0E-12
<b>OFF samples</b>									
SN7	800.0E-12	-200.0E-12	-250.0E-12	-300.0E-12	-1.5E-09	-36.3E-09	-29.1E-09	-20.8E-09	-1.8E-09
SN8	1.0E-09	-100.0E-12	-250.0E-12	-300.0E-12	-1.2E-09	-26.5E-09	-18.6E-09	-15.4E-09	-1.8E-09
SN9	1.3E-09	-100.0E-12	-250.0E-12	-300.0E-12	-1.5E-09	-39.4E-09	-25.5E-09	-20.6E-09	-1.8E-09
SN10	1.0E-09	-150.0E-12	-200.0E-12	-300.0E-12	-1.7E-09	-42.8E-09	-27.3E-09	-25.2E-09	-1.8E-09
SN11	1.0E-09	-150.0E-12	-250.0E-12	-300.0E-12	-1.4E-09	-36.0E-09	-21.8E-09	-20.1E-09	-2.2E-09
<b>Statistics</b>									
Min	800.0E-12	-200.0E-12	-250.0E-12	-300.0E-12	-1.7E-09	-42.8E-09	-29.1E-09	-25.2E-09	-2.2E-09
Max	1.3E-09	-100.0E-12	-200.0E-12	-300.0E-12	-1.2E-09	-26.5E-09	-18.6E-09	-15.4E-09	-1.8E-09
Average	1.0E-09	-140.0E-12	-240.0E-12	-300.0E-12	-1.4E-09	-36.2E-09	-24.4E-09	-20.4E-09	-1.8E-09
Sigma	142.8E-12	37.4E-12	20.0E-12	0.0E+00	166.1E-12	5.4E-09	3.8E-09	3.1E-09	180.0E-12

**Drift Calculation**

IOLTLDS	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-1.0E-09	-1.1E-09	-1.1E-09	-2.3E-09	-37.1E-09	-29.9E-09	-21.6E-09	-2.6E-09
SN8	-	-1.1E-09	-1.3E-09	-1.3E-09	-2.2E-09	-27.5E-09	-19.6E-09	-16.4E-09	-2.8E-09
SN9	-	-1.4E-09	-1.5E-09	-1.6E-09	-2.7E-09	-40.6E-09	-26.7E-09	-21.8E-09	-3.0E-09
SN10	-	-1.2E-09	-1.2E-09	-1.3E-09	-2.7E-09	-43.8E-09	-28.3E-09	-26.2E-09	-2.8E-09
SN11	-	-1.2E-09	-1.3E-09	-1.3E-09	-2.4E-09	-37.0E-09	-22.8E-09	-21.1E-09	-3.2E-09
Average	-	-1.2E-09	-1.3E-09	-1.3E-09	-2.4E-09	-37.2E-09	-25.4E-09	-21.4E-09	-2.9E-09
Sigma	-	114.0E-12	144.9E-12	142.8E-12	211.2E-12	5.5E-09	3.8E-09	3.1E-09	225.8E-12

Parameter : Three state output leakage : IOLTL D4

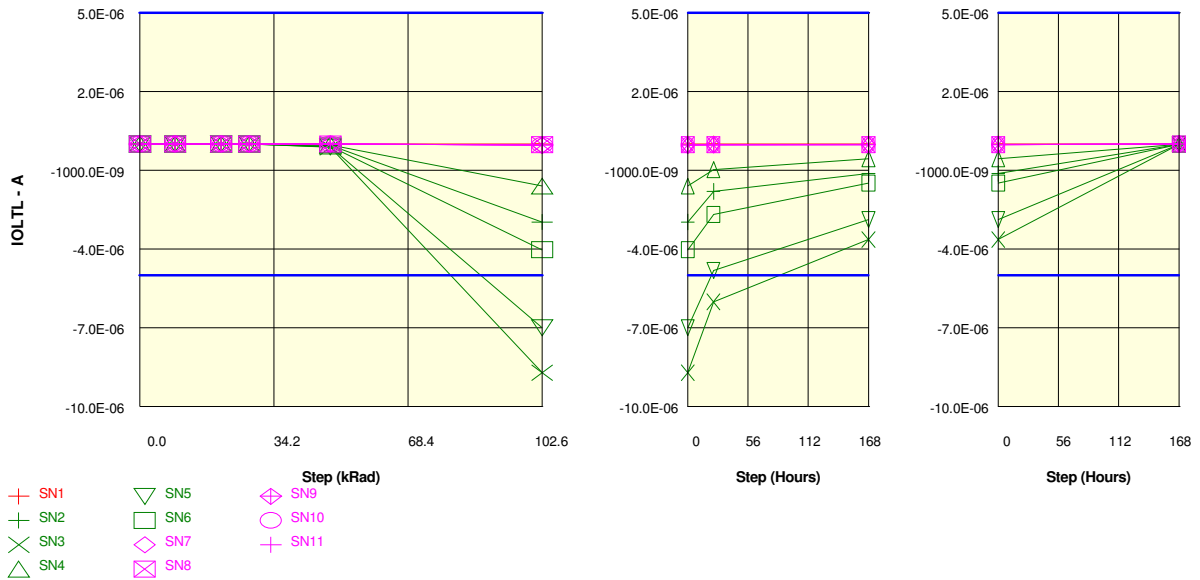
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements									
IOLTL D4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	450.0E-12	350.0E-12	350.0E-12	350.0E-12	450.0E-12	-350.0E-12	300.0E-12	450.0E-12	350.0E-12
ON samples									
SN2	500.0E-12	-350.0E-12	-350.0E-12	-650.0E-12	-46.1E-09	-3.0E-06	-1.8E-06	-1.1E-06	-5.0E-09
SN3	450.0E-12	-350.0E-12	-300.0E-12	-600.0E-12	-119.5E-09	<b>-8.7E-06</b>	<b>-6.0E-06</b>	-3.6E-06	-6.6E-09
SN4	550.0E-12	-250.0E-12	-300.0E-12	-500.0E-12	-26.5E-09	-1.6E-06	-970.0E-09	-561.5E-09	-3.8E-09
SN5	400.0E-12	-300.0E-12	-300.0E-12	-700.0E-12	-110.0E-09	<b>-7.0E-06</b>	-4.8E-06	-2.9E-06	-7.8E-09
SN6	450.0E-12	-300.0E-12	-300.0E-12	-700.0E-12	-74.6E-09	-4.0E-06	-2.7E-06	-1.5E-06	-5.9E-09
Statistics									
Min	400.0E-12	-350.0E-12	-350.0E-12	-700.0E-12	-119.5E-09	-8.7E-06	-6.0E-06	-3.6E-06	-7.8E-09
Max	550.0E-12	-250.0E-12	-300.0E-12	-500.0E-12	-26.5E-09	-1.6E-06	-970.0E-09	-561.5E-09	-3.8E-09
Average	470.0E-12	-310.0E-12	-310.0E-12	-630.0E-12	-75.3E-09	-4.9E-06	-3.3E-06	-1.9E-06	-5.8E-09
Sigma	51.0E-12	37.4E-12	20.0E-12	74.8E-12	35.8E-09	2.6E-06	1.9E-06	1.1E-06	1.4E-09

Drift Calculation									
IOLTL D4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-850.0E-12	-850.0E-12	-1.2E-09	-46.6E-09	-3.0E-06	-1.8E-06	-1.1E-06	-5.5E-09
SN3	-	-800.0E-12	-750.0E-12	-1.1E-09	-120.0E-09	-8.7E-06	-6.0E-06	-3.6E-06	-7.1E-09
SN4	-	-800.0E-12	-850.0E-12	-1.1E-09	-27.1E-09	-1.6E-06	-970.6E-09	-562.1E-09	-4.3E-09
SN5	-	-700.0E-12	-700.0E-12	-1.1E-09	-110.4E-09	-7.0E-06	-4.8E-06	-2.9E-06	-8.2E-09
SN6	-	-750.0E-12	-750.0E-12	-1.2E-09	-75.0E-09	-4.0E-06	-2.7E-06	-1.5E-06	-6.4E-09
Average	-	-780.0E-12	-780.0E-12	-1.1E-09	-75.8E-09	-4.9E-06	-3.3E-06	-1.9E-06	-6.3E-09
Sigma	-	51.0E-12	60.0E-12	44.7E-12	35.7E-09	2.6E-06	1.9E-06	1.1E-06	1.3E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTL4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	450.0E-12	350.0E-12	350.0E-12	350.0E-12	450.0E-12	-350.0E-12	300.0E-12	450.0E-12	350.0E-12
<b>OFF samples</b>									
SN7	350.0E-12	-300.0E-12	-350.0E-12	-400.0E-12	-1.8E-09	-40.0E-09	-31.0E-09	-22.4E-09	-1.8E-09
SN8	400.0E-12	-300.0E-12	-300.0E-12	-350.0E-12	-1.3E-09	-26.9E-09	-19.0E-09	-15.2E-09	-2.0E-09
SN9	650.0E-12	-200.0E-12	-350.0E-12	-400.0E-12	-1.6E-09	-40.1E-09	-25.4E-09	-20.8E-09	-1.9E-09
SN10	450.0E-12	-250.0E-12	-350.0E-12	-400.0E-12	-1.8E-09	-41.2E-09	-25.6E-09	-24.6E-09	-1.8E-09
SN11	450.0E-12	-250.0E-12	-300.0E-12	-450.0E-12	-1.4E-09	-39.0E-09	-20.2E-09	-18.6E-09	-2.2E-09
<b>Statistics</b>									
Min	350.0E-12	-300.0E-12	-350.0E-12	-450.0E-12	-1.8E-09	-41.2E-09	-31.0E-09	-24.6E-09	-2.2E-09
Max	650.0E-12	-200.0E-12	-300.0E-12	-350.0E-12	-1.3E-09	-26.9E-09	-19.0E-09	-15.2E-09	-1.8E-09
Average	460.0E-12	-260.0E-12	-330.0E-12	-400.0E-12	-1.6E-09	-37.4E-09	-24.2E-09	-20.3E-09	-1.9E-09
Sigma	102.0E-12	37.4E-12	24.5E-12	31.6E-12	216.8E-12	5.3E-09	4.3E-09	3.2E-09	131.9E-12

**Drift Calculation**

IOLTL4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-650.0E-12	-700.0E-12	-750.0E-12	-2.2E-09	-40.3E-09	-31.4E-09	-22.7E-09	-2.2E-09
SN8	-	-700.0E-12	-700.0E-12	-750.0E-12	-1.7E-09	-27.3E-09	-19.4E-09	-15.6E-09	-2.4E-09
SN9	-	-850.0E-12	-1.0E-09	-1.1E-09	-2.3E-09	-40.7E-09	-26.1E-09	-21.4E-09	-2.5E-09
SN10	-	-700.0E-12	-800.0E-12	-850.0E-12	-2.2E-09	-41.7E-09	-26.1E-09	-25.0E-09	-2.3E-09
SN11	-	-700.0E-12	-750.0E-12	-900.0E-12	-1.8E-09	-39.5E-09	-20.6E-09	-19.1E-09	-2.6E-09
Average	-	-720.0E-12	-790.0E-12	-860.0E-12	-2.0E-09	-37.9E-09	-24.7E-09	-20.8E-09	-2.4E-09
Sigma	-	67.8E-12	111.4E-12	111.4E-12	239.6E-12	5.4E-09	4.3E-09	3.2E-09	163.1E-12

Parameter : Three state output leakage : IOLTLD3

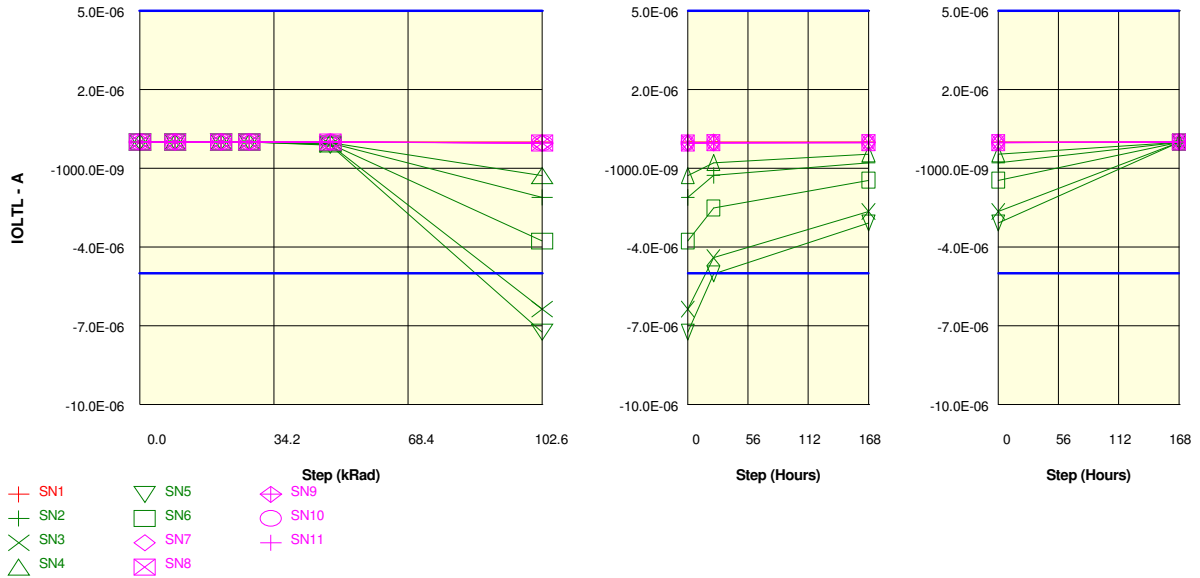
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



**Measurements**

IOLTLD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	100.0E-12	0.0E+00	50.0E-12	0.0E+00	50.0E-12	0.0E+00	50.0E-12	50.0E-12	50.0E-12
<b>ON samples</b>									
SN2	100.0E-12	-50.0E-12	-100.0E-12	-300.0E-12	-35.4E-09	-2.1E-06	-1.3E-06	-790.0E-09	-4.2E-09
SN3	50.0E-12	-150.0E-12	-100.0E-12	-400.0E-12	-97.5E-09	<b>-6.4E-06</b>	-4.4E-06	-2.6E-06	-5.2E-09
SN4	100.0E-12	-50.0E-12	-50.0E-12	-350.0E-12	-23.8E-09	-1.3E-06	-783.5E-09	-456.0E-09	-3.3E-09
SN5	100.0E-12	-100.0E-12	0.0E+00	-400.0E-12	-118.0E-09	<b>-7.2E-06</b>	<b>-5.0E-06</b>	-3.1E-06	-6.3E-09
SN6	50.0E-12	-100.0E-12	-100.0E-12	-450.0E-12	-70.4E-09	-3.8E-06	-2.5E-06	-1.5E-06	-4.6E-09
<b>Statistics</b>									
Min	50.0E-12	-150.0E-12	-100.0E-12	-450.0E-12	-118.0E-09	-7.2E-06	-5.0E-06	-3.1E-06	-6.3E-09
Max	100.0E-12	-50.0E-12	0.0E+00	-300.0E-12	-23.8E-09	-1.3E-06	-783.5E-09	-456.0E-09	-3.3E-09
Average	80.0E-12	-90.0E-12	-70.0E-12	-380.0E-12	-69.0E-09	-4.2E-06	-2.8E-06	-1.7E-06	-4.7E-09
Sigma	24.5E-12	37.4E-12	40.0E-12	51.0E-12	35.8E-09	2.3E-06	1.7E-06	1.0E-06	1.0E-09

**Drift Calculation**

IOLTLD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>ON samples</b>									
SN2	-	-150.0E-12	-200.0E-12	-400.0E-12	-35.5E-09	-2.1E-06	-1.3E-06	-790.1E-09	-4.3E-09
SN3	-	-200.0E-12	-150.0E-12	-450.0E-12	-97.6E-09	-6.4E-06	-4.4E-06	-2.6E-06	-5.3E-09
SN4	-	-150.0E-12	-150.0E-12	-450.0E-12	-23.9E-09	-1.3E-06	-783.6E-09	-456.1E-09	-3.4E-09
SN5	-	-200.0E-12	-100.0E-12	-500.0E-12	-118.1E-09	-7.2E-06	-5.0E-06	-3.1E-06	-6.4E-09
SN6	-	-150.0E-12	-150.0E-12	-500.0E-12	-70.4E-09	-3.8E-06	-2.5E-06	-1.5E-06	-4.7E-09
Average	-	-170.0E-12	-150.0E-12	-460.0E-12	-69.1E-09	-4.2E-06	-2.8E-06	-1.7E-06	-4.8E-09
Sigma	-	24.5E-12	31.6E-12	37.4E-12	35.7E-09	2.3E-06	1.7E-06	1.0E-06	997.8E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTL D3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	100.0E-12	0.0E+00	50.0E-12	0.0E+00	50.0E-12	0.0E+00	50.0E-12	50.0E-12	50.0E-12
<b>OFF samples</b>									
SN7	50.0E-12	-100.0E-12	-50.0E-12	-150.0E-12	-1.6E-09	-44.1E-09	-35.7E-09	-25.6E-09	-1.7E-09
SN8	50.0E-12	-50.0E-12	0.0E+00	-150.0E-12	-1.1E-09	-31.1E-09	-22.3E-09	-17.5E-09	-1.7E-09
SN9	150.0E-12	-100.0E-12	0.0E+00	-100.0E-12	-1.2E-09	-34.3E-09	-21.6E-09	-17.8E-09	-1.3E-09
SN10	100.0E-12	-100.0E-12	-50.0E-12	-150.0E-12	-1.6E-09	-41.4E-09	-26.9E-09	-25.2E-09	-1.4E-09
SN11	100.0E-12	-50.0E-12	-100.0E-12	-200.0E-12	-1.2E-09	-34.2E-09	-20.4E-09	-19.0E-09	-1.8E-09
<b>Statistics</b>									
Min	50.0E-12	-100.0E-12	-100.0E-12	-200.0E-12	-1.6E-09	-44.1E-09	-35.7E-09	-25.6E-09	-1.8E-09
Max	150.0E-12	-50.0E-12	0.0E+00	-100.0E-12	-1.1E-09	-31.1E-09	-20.4E-09	-17.5E-09	-1.3E-09
Average	90.0E-12	-80.0E-12	-40.0E-12	-150.0E-12	-1.3E-09	-37.0E-09	-25.4E-09	-21.0E-09	-1.6E-09
Sigma	37.4E-12	24.5E-12	37.4E-12	31.6E-12	211.2E-12	4.9E-09	5.6E-09	3.6E-09	203.5E-12

**Drift Calculation**

IOLTL D3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-150.0E-12	-100.0E-12	-200.0E-12	-1.7E-09	-44.2E-09	-35.8E-09	-25.7E-09	-1.7E-09
SN8	-	-100.0E-12	-50.0E-12	-200.0E-12	-1.2E-09	-31.2E-09	-22.3E-09	-17.6E-09	-1.8E-09
SN9	-	-250.0E-12	-150.0E-12	-250.0E-12	-1.4E-09	-34.5E-09	-21.8E-09	-17.9E-09	-1.4E-09
SN10	-	-200.0E-12	-150.0E-12	-250.0E-12	-1.7E-09	-41.5E-09	-27.0E-09	-25.3E-09	-1.5E-09
SN11	-	-150.0E-12	-200.0E-12	-300.0E-12	-1.3E-09	-34.3E-09	-20.5E-09	-19.1E-09	-1.9E-09
Average	-	-170.0E-12	-130.0E-12	-240.0E-12	-1.4E-09	-37.1E-09	-25.4E-09	-21.1E-09	-1.7E-09
Sigma	-	51.0E-12	51.0E-12	37.4E-12	205.9E-12	4.9E-09	5.6E-09	3.6E-09	178.9E-12



Parameter : Three state output leakage : IOLTLD2

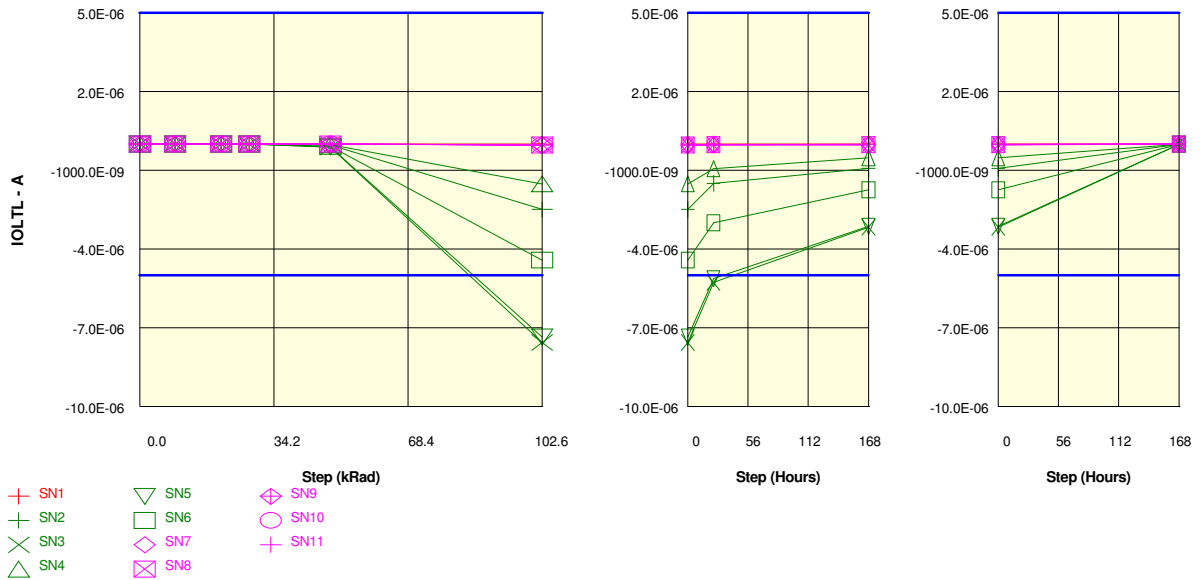
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-50.0E-12	0.0E+00	50.0E-12	0.0E+00	-150.0E-12	-50.0E-12	-50.0E-12	0.0E+00
ON samples									
SN2	50.0E-12	-150.0E-12	-100.0E-12	-300.0E-12	-40.5E-09	-2.5E-06	-1.5E-06	-924.0E-09	-4.0E-09
SN3	-50.0E-12	-150.0E-12	-150.0E-12	-500.0E-12	-122.0E-09	<b>-7.6E-06</b>	<b>-5.3E-06</b>	-3.2E-06	-5.2E-09
SN4	0.0E+00	-100.0E-12	-100.0E-12	-300.0E-12	-25.5E-09	-1.5E-06	-934.0E-09	-523.5E-09	-3.1E-09
SN5	0.0E+00	-150.0E-12	-150.0E-12	-450.0E-12	-109.0E-09	<b>-7.4E-06</b>	<b>-5.1E-06</b>	-3.1E-06	-6.1E-09
SN6	50.0E-12	-100.0E-12	-150.0E-12	-450.0E-12	-82.0E-09	-4.4E-06	-3.0E-06	-1.7E-06	-4.4E-09
Statistics									
Min	-50.0E-12	-150.0E-12	-150.0E-12	-500.0E-12	-122.0E-09	-7.6E-06	-5.3E-06	-3.2E-06	-6.1E-09
Max	50.0E-12	-100.0E-12	-100.0E-12	-300.0E-12	-25.5E-09	-1.5E-06	-934.0E-09	-523.5E-09	-3.1E-09
Average	10.0E-12	-130.0E-12	-130.0E-12	-400.0E-12	-75.8E-09	-4.7E-06	-3.2E-06	-1.9E-06	-4.5E-09
Sigma	37.4E-12	24.5E-12	24.5E-12	83.7E-12	37.6E-09	2.5E-06	1.8E-06	1.1E-06	1.0E-09

Drift Calculation

IOLTLD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-200.0E-12	-150.0E-12	-350.0E-12	-40.5E-09	-2.5E-06	-1.5E-06	-924.1E-09	-4.0E-09
SN3	-	-100.0E-12	-100.0E-12	-450.0E-12	-122.0E-09	-7.6E-06	-5.3E-06	-3.2E-06	-5.1E-09
SN4	-	-100.0E-12	-100.0E-12	-300.0E-12	-25.5E-09	-1.5E-06	-934.0E-09	-523.5E-09	-3.1E-09
SN5	-	-150.0E-12	-150.0E-12	-450.0E-12	-109.0E-09	-7.4E-06	-5.1E-06	-3.1E-06	-6.1E-09
SN6	-	-150.0E-12	-200.0E-12	-500.0E-12	-82.0E-09	-4.4E-06	-3.0E-06	-1.7E-06	-4.4E-09
Average	-	-140.0E-12	-140.0E-12	-410.0E-12	-75.8E-09	-4.7E-06	-3.2E-06	-1.9E-06	-4.5E-09
Sigma	-	37.4E-12	37.4E-12	73.5E-12	37.6E-09	2.5E-06	1.8E-06	1.1E-06	1.0E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTL2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-50.0E-12	0.0E+00	50.0E-12	0.0E+00	-150.0E-12	-50.0E-12	-50.0E-12	0.0E+00
<b>OFF samples</b>									
SN7	0.0E+00	-100.0E-12	-150.0E-12	-250.0E-12	-1.7E-09	-45.7E-09	-36.5E-09	-26.0E-09	-1.7E-09
SN8	-50.0E-12	-100.0E-12	-100.0E-12	-150.0E-12	-1.2E-09	-31.2E-09	-22.3E-09	-17.9E-09	-1.8E-09
SN9	50.0E-12	-100.0E-12	-100.0E-12	-200.0E-12	-1.3E-09	-34.2E-09	-22.0E-09	-17.8E-09	-1.4E-09
SN10	0.0E+00	-50.0E-12	-150.0E-12	-200.0E-12	-1.6E-09	-40.4E-09	-25.7E-09	-24.0E-09	-1.4E-09
SN11	50.0E-12	-50.0E-12	-100.0E-12	-250.0E-12	-1.2E-09	-34.9E-09	-21.1E-09	-19.5E-09	-1.9E-09
<b>Statistics</b>									
Min	-50.0E-12	-100.0E-12	-150.0E-12	-250.0E-12	-1.7E-09	-45.7E-09	-36.5E-09	-26.0E-09	-1.9E-09
Max	50.0E-12	-50.0E-12	-100.0E-12	-150.0E-12	-1.2E-09	-31.2E-09	-21.1E-09	-17.8E-09	-1.4E-09
Average	10.0E-12	-80.0E-12	-120.0E-12	-210.0E-12	-1.4E-09	-37.3E-09	-25.5E-09	-21.0E-09	-1.6E-09
Sigma	37.4E-12	24.5E-12	24.5E-12	37.4E-12	201.5E-12	5.1E-09	5.7E-09	3.4E-09	203.5E-12

**Drift Calculation**

IOLTL2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-100.0E-12	-150.0E-12	-250.0E-12	-1.7E-09	-45.7E-09	-36.5E-09	-26.0E-09	-1.7E-09
SN8	-	-50.0E-12	-50.0E-12	-100.0E-12	-1.2E-09	-31.2E-09	-22.2E-09	-17.8E-09	-1.8E-09
SN9	-	-150.0E-12	-150.0E-12	-250.0E-12	-1.3E-09	-34.3E-09	-22.1E-09	-17.9E-09	-1.4E-09
SN10	-	-50.0E-12	-150.0E-12	-200.0E-12	-1.6E-09	-40.4E-09	-25.7E-09	-24.0E-09	-1.4E-09
SN11	-	-100.0E-12	-150.0E-12	-300.0E-12	-1.3E-09	-35.0E-09	-21.2E-09	-19.6E-09	-1.9E-09
Average	-	-90.0E-12	-130.0E-12	-220.0E-12	-1.4E-09	-37.3E-09	-25.5E-09	-21.0E-09	-1.6E-09
Sigma	-	37.4E-12	40.0E-12	67.8E-12	198.5E-12	5.1E-09	5.7E-09	3.4E-09	196.5E-12

Parameter : Three state output leakage : IOLTLD1

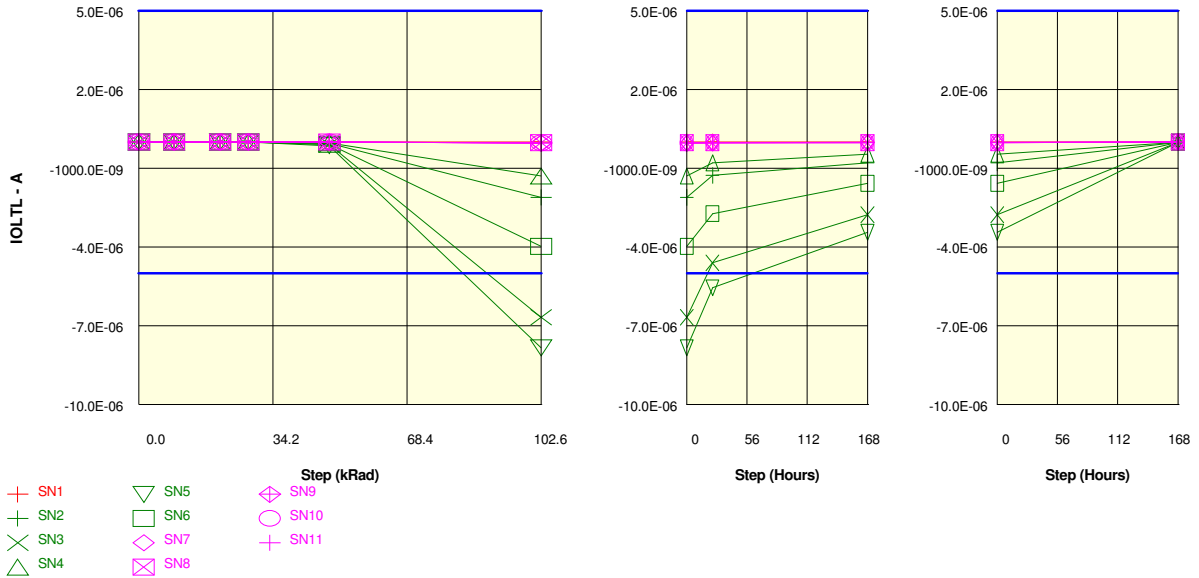
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	0.0E+00	-50.0E-12	-100.0E-12	0.0E+00	0.0E+00	-150.0E-12	-50.0E-12	-50.0E-12	0.0E+00
ON samples									
SN2	50.0E-12	-100.0E-12	-150.0E-12	-450.0E-12	-42.3E-09	-2.1E-06	-1.3E-06	-788.0E-09	-3.7E-09
SN3	0.0E+00	-200.0E-12	-150.0E-12	-450.0E-12	-94.7E-09	-6.7E-06	-4.6E-06	-2.8E-06	-5.0E-09
SN4	0.0E+00	-150.0E-12	-100.0E-12	-350.0E-12	-26.3E-09	-1.3E-06	-793.0E-09	-457.5E-09	-3.1E-09
SN5	0.0E+00	-100.0E-12	-100.0E-12	-450.0E-12	-138.0E-09	-7.8E-06	-5.6E-06	-3.4E-06	-6.0E-09
SN6	50.0E-12	-150.0E-12	-150.0E-12	-650.0E-12	-83.6E-09	-4.0E-06	-2.7E-06	-1.6E-06	-4.6E-09
Statistics									
Min	0.0E+00	-200.0E-12	-150.0E-12	-650.0E-12	-138.0E-09	-7.8E-06	-5.6E-06	-3.4E-06	-6.0E-09
Max	50.0E-12	-100.0E-12	-100.0E-12	-350.0E-12	-26.3E-09	-1.3E-06	-793.0E-09	-457.5E-09	-3.1E-09
Average	20.0E-12	-140.0E-12	-130.0E-12	-470.0E-12	-77.0E-09	-4.4E-06	-3.0E-06	-1.8E-06	-4.5E-09
Sigma	24.5E-12	37.4E-12	24.5E-12	98.0E-12	39.6E-09	2.5E-06	1.8E-06	1.1E-06	1.0E-09

Drift Calculation

IOLTLD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-150.0E-12	-200.0E-12	-500.0E-12	-42.3E-09	-2.1E-06	-1.3E-06	-788.1E-09	-3.8E-09
SN3	-	-200.0E-12	-150.0E-12	-450.0E-12	-94.7E-09	-6.7E-06	-4.6E-06	-2.8E-06	-5.0E-09
SN4	-	-150.0E-12	-100.0E-12	-350.0E-12	-26.3E-09	-1.3E-06	-793.0E-09	-457.5E-09	-3.1E-09
SN5	-	-100.0E-12	-100.0E-12	-450.0E-12	-138.0E-09	-7.8E-06	-5.6E-06	-3.4E-06	-6.0E-09
SN6	-	-200.0E-12	-200.0E-12	-700.0E-12	-83.7E-09	-4.0E-06	-2.7E-06	-1.6E-06	-4.6E-09
Average	-	-160.0E-12	-150.0E-12	-490.0E-12	-77.0E-09	-4.4E-06	-3.0E-06	-1.8E-06	-4.5E-09
Sigma	-	37.4E-12	44.7E-12	115.8E-12	39.6E-09	2.5E-06	1.8E-06	1.1E-06	998.3E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTL D1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	0.0E+00	-50.0E-12	-100.0E-12	0.0E+00	0.0E+00	-150.0E-12	-50.0E-12	-50.0E-12	0.0E+00
<b>OFF samples</b>									
SN7	0.0E+00	-100.0E-12	-150.0E-12	-150.0E-12	-1.6E-09	-40.2E-09	-32.7E-09	-23.1E-09	-1.6E-09
SN8	0.0E+00	-100.0E-12	-150.0E-12	-200.0E-12	-1.2E-09	-27.6E-09	-19.9E-09	-15.8E-09	-1.6E-09
SN9	-50.0E-12	-150.0E-12	-100.0E-12	-150.0E-12	-1.2E-09	-32.0E-09	-19.8E-09	-16.4E-09	-1.2E-09
SN10	-50.0E-12	-100.0E-12	-100.0E-12	-200.0E-12	-1.5E-09	-36.5E-09	-22.4E-09	-21.8E-09	-1.3E-09
SN11	50.0E-12	-100.0E-12	0.0E+00	-100.0E-12	-1.3E-09	-35.5E-09	-21.3E-09	-19.2E-09	-1.8E-09
<b>Statistics</b>									
Min	-50.0E-12	-150.0E-12	-150.0E-12	-200.0E-12	-1.6E-09	-40.2E-09	-32.7E-09	-23.1E-09	-1.8E-09
Max	50.0E-12	-100.0E-12	0.0E+00	-100.0E-12	-1.2E-09	-27.6E-09	-19.8E-09	-15.8E-09	-1.2E-09
Average	-10.0E-12	-110.0E-12	-100.0E-12	-160.0E-12	-1.3E-09	-34.4E-09	-23.2E-09	-19.3E-09	-1.5E-09
Sigma	37.4E-12	20.0E-12	54.8E-12	37.4E-12	153.6E-12	4.3E-09	4.8E-09	2.9E-09	215.4E-12

**Drift Calculation**

IOLTL D1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-100.0E-12	-150.0E-12	-150.0E-12	-1.6E-09	-40.2E-09	-32.7E-09	-23.1E-09	-1.6E-09
SN8	-	-100.0E-12	-150.0E-12	-200.0E-12	-1.2E-09	-27.6E-09	-19.9E-09	-15.8E-09	-1.6E-09
SN9	-	-100.0E-12	-50.0E-12	-100.0E-12	-1.2E-09	-32.0E-09	-19.8E-09	-16.4E-09	-1.2E-09
SN10	-	-50.0E-12	-50.0E-12	-150.0E-12	-1.4E-09	-36.5E-09	-22.4E-09	-21.8E-09	-1.3E-09
SN11	-	-150.0E-12	-50.0E-12	-150.0E-12	-1.3E-09	-35.5E-09	-21.3E-09	-19.3E-09	-1.9E-09
Average	-	-100.0E-12	-90.0E-12	-150.0E-12	-1.3E-09	-34.3E-09	-23.2E-09	-19.2E-09	-1.5E-09
Sigma	-	31.6E-12	49.0E-12	31.6E-12	153.0E-12	4.3E-09	4.8E-09	2.9E-09	252.2E-12

Parameter : Three state output leakage : IOLTLD0

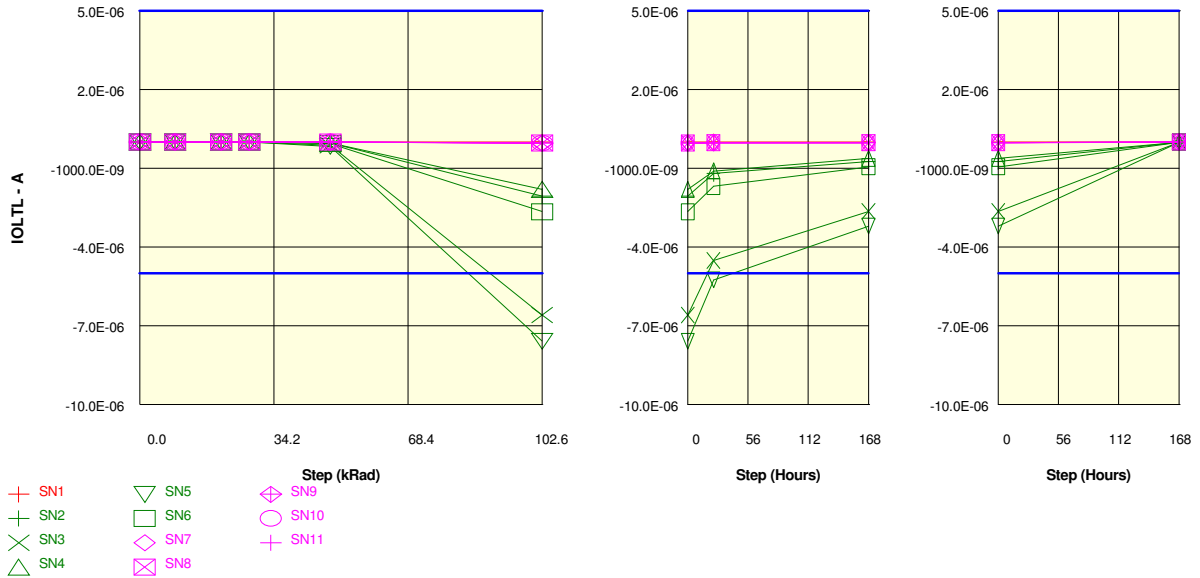
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTLD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-50.0E-12	-350.0E-12	-150.0E-12	-150.0E-12	0.0E+00
ON samples									
SN2	-50.0E-12	-100.0E-12	-200.0E-12	-600.0E-12	-40.7E-09	-2.1E-06	-1.2E-06	-746.5E-09	-3.5E-09
SN3	-50.0E-12	-100.0E-12	-150.0E-12	-650.0E-12	-120.5E-09	-6.6E-06	-4.5E-06	-2.6E-06	-4.2E-09
SN4	50.0E-12	-150.0E-12	-150.0E-12	-550.0E-12	-37.7E-09	-1.8E-06	-1.1E-06	-618.0E-09	-3.1E-09
SN5	-50.0E-12	-200.0E-12	-150.0E-12	-850.0E-12	-164.5E-09	-7.6E-06	-5.3E-06	-3.2E-06	-5.4E-09
SN6	0.0E+00	-200.0E-12	-200.0E-12	-600.0E-12	-54.2E-09	-2.7E-06	-1.7E-06	-941.5E-09	-3.5E-09
Statistics									
Min	-50.0E-12	-200.0E-12	-200.0E-12	-850.0E-12	-164.5E-09	-7.6E-06	-5.3E-06	-3.2E-06	-5.4E-09
Max	50.0E-12	-100.0E-12	-150.0E-12	-550.0E-12	-37.7E-09	-1.8E-06	-1.1E-06	-618.0E-09	-3.1E-09
Average	-20.0E-12	-150.0E-12	-170.0E-12	-650.0E-12	-83.5E-09	-4.1E-06	-2.7E-06	-1.6E-06	-3.9E-09
Sigma	40.0E-12	44.7E-12	24.5E-12	104.9E-12	50.4E-09	2.4E-06	1.8E-06	1.1E-06	824.3E-12

Drift Calculation

IOLTLD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-50.0E-12	-150.0E-12	-550.0E-12	-40.6E-09	-2.1E-06	-1.2E-06	-746.5E-09	-3.5E-09
SN3	-	-50.0E-12	-100.0E-12	-600.0E-12	-120.5E-09	-6.6E-06	-4.5E-06	-2.6E-06	-4.1E-09
SN4	-	-200.0E-12	-200.0E-12	-600.0E-12	-37.8E-09	-1.8E-06	-1.1E-06	-618.1E-09	-3.1E-09
SN5	-	-150.0E-12	-100.0E-12	-800.0E-12	-164.5E-09	-7.6E-06	-5.2E-06	-3.2E-06	-5.4E-09
SN6	-	-200.0E-12	-200.0E-12	-600.0E-12	-54.2E-09	-2.7E-06	-1.7E-06	-941.5E-09	-3.5E-09
Average	-	-130.0E-12	-150.0E-12	-630.0E-12	-83.5E-09	-4.1E-06	-2.7E-06	-1.6E-06	-3.9E-09
Sigma	-	67.8E-12	44.7E-12	87.2E-12	50.4E-09	2.4E-06	1.8E-06	1.1E-06	798.4E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

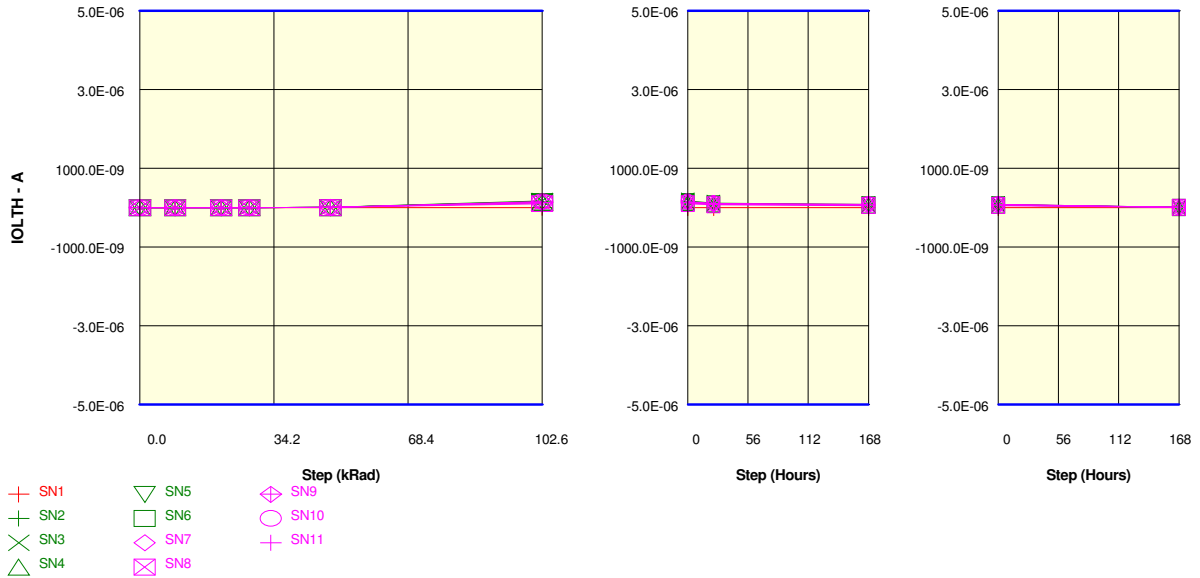
**Measurements**

IOLTLDO	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-50.0E-12	-150.0E-12	-100.0E-12	-100.0E-12	-50.0E-12	-350.0E-12	-150.0E-12	-150.0E-12	0.0E+00
<b>OFF samples</b>									
SN7	0.0E+00	-150.0E-12	-250.0E-12	-250.0E-12	-1.7E-09	-42.5E-09	-34.2E-09	-24.4E-09	-1.6E-09
SN8	-50.0E-12	-150.0E-12	-100.0E-12	-250.0E-12	-1.3E-09	-32.7E-09	-23.6E-09	-18.8E-09	-1.7E-09
SN9	50.0E-12	-150.0E-12	-100.0E-12	-250.0E-12	-1.4E-09	-37.5E-09	-23.8E-09	-19.4E-09	-1.4E-09
SN10	-50.0E-12	-150.0E-12	-100.0E-12	-300.0E-12	-1.9E-09	-45.1E-09	-28.2E-09	-26.3E-09	-1.6E-09
SN11	0.0E+00	-100.0E-12	-100.0E-12	-250.0E-12	-1.4E-09	-34.4E-09	-20.9E-09	-19.2E-09	-1.8E-09
<b>Statistics</b>									
Min	-50.0E-12	-150.0E-12	-250.0E-12	-300.0E-12	-1.9E-09	-45.1E-09	-34.2E-09	-26.3E-09	-1.8E-09
Max	50.0E-12	-100.0E-12	-100.0E-12	-250.0E-12	-1.3E-09	-32.7E-09	-20.9E-09	-18.8E-09	-1.4E-09
Average	-10.0E-12	-140.0E-12	-130.0E-12	-260.0E-12	-1.5E-09	-38.4E-09	-26.1E-09	-21.6E-09	-1.6E-09
Sigma	37.4E-12	20.0E-12	60.0E-12	20.0E-12	231.5E-12	4.7E-09	4.7E-09	3.1E-09	122.5E-12

**Drift Calculation**

IOLTLDO	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-150.0E-12	-250.0E-12	-250.0E-12	-1.7E-09	-42.5E-09	-34.2E-09	-24.4E-09	-1.6E-09
SN8	-	-100.0E-12	-50.0E-12	-200.0E-12	-1.3E-09	-32.6E-09	-23.5E-09	-18.8E-09	-1.7E-09
SN9	-	-200.0E-12	-150.0E-12	-300.0E-12	-1.5E-09	-37.5E-09	-23.8E-09	-19.4E-09	-1.5E-09
SN10	-	-100.0E-12	-50.0E-12	-250.0E-12	-1.9E-09	-45.0E-09	-28.1E-09	-26.3E-09	-1.5E-09
SN11	-	-100.0E-12	-100.0E-12	-250.0E-12	-1.4E-09	-34.4E-09	-20.9E-09	-19.2E-09	-1.8E-09
Average	-	-130.0E-12	-120.0E-12	-250.0E-12	-1.5E-09	-38.4E-09	-26.1E-09	-21.6E-09	-1.6E-09
Sigma	-	40.0E-12	74.8E-12	31.6E-12	222.7E-12	4.7E-09	4.7E-09	3.1E-09	106.8E-12

Parameter : Three state output leakage : IOLTHD15  
 Test conditions :  
 Unit : A  
 Spec Limit Min : -5.0E-06  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	400.0E-12	400.0E-12	250.0E-12	400.0E-12	350.0E-12	950.0E-12	400.0E-12	450.0E-12	350.0E-12
ON samples									
SN2	400.0E-12	400.0E-12	400.0E-12	700.0E-12	5.1E-09	148.0E-09	96.0E-09	74.8E-09	5.1E-09
SN3	350.0E-12	300.0E-12	450.0E-12	650.0E-12	5.7E-09	173.0E-09	117.0E-09	81.4E-09	6.7E-09
SN4	350.0E-12	400.0E-12	450.0E-12	650.0E-12	5.1E-09	138.0E-09	94.5E-09	66.7E-09	5.2E-09
SN5	300.0E-12	400.0E-12	450.0E-12	700.0E-12	5.4E-09	154.5E-09	103.5E-09	75.2E-09	7.8E-09
SN6	450.0E-12	400.0E-12	450.0E-12	700.0E-12	5.0E-09	133.5E-09	90.2E-09	63.1E-09	6.0E-09
Statistics									
Min	300.0E-12	300.0E-12	400.0E-12	650.0E-12	5.0E-09	133.5E-09	90.2E-09	63.1E-09	5.1E-09
Max	450.0E-12	400.0E-12	450.0E-12	700.0E-12	5.7E-09	173.0E-09	117.0E-09	81.4E-09	7.8E-09
Average	370.0E-12	380.0E-12	440.0E-12	680.0E-12	5.3E-09	149.4E-09	100.2E-09	72.2E-09	6.1E-09
Sigma	51.0E-12	40.0E-12	20.0E-12	24.5E-12	253.0E-12	13.9E-09	9.4E-09	6.5E-09	1.0E-09

Drift Calculation

IOLTHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	300.0E-12	4.7E-09	147.6E-09	95.6E-09	74.4E-09	4.7E-09
SN3	-	-50.0E-12	100.0E-12	300.0E-12	5.4E-09	172.7E-09	116.7E-09	81.0E-09	6.3E-09
SN4	-	50.0E-12	100.0E-12	300.0E-12	4.8E-09	137.7E-09	94.1E-09	66.3E-09	4.8E-09
SN5	-	100.0E-12	150.0E-12	400.0E-12	5.1E-09	154.2E-09	103.2E-09	74.9E-09	7.5E-09
SN6	-	-50.0E-12	0.0E+00	250.0E-12	4.6E-09	133.1E-09	89.8E-09	62.7E-09	5.6E-09
Average	-	10.0E-12	70.0E-12	310.0E-12	4.9E-09	149.0E-09	99.9E-09	71.8E-09	5.8E-09
Sigma	-	58.3E-12	60.0E-12	49.0E-12	285.7E-12	13.9E-09	9.5E-09	6.5E-09	1.0E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

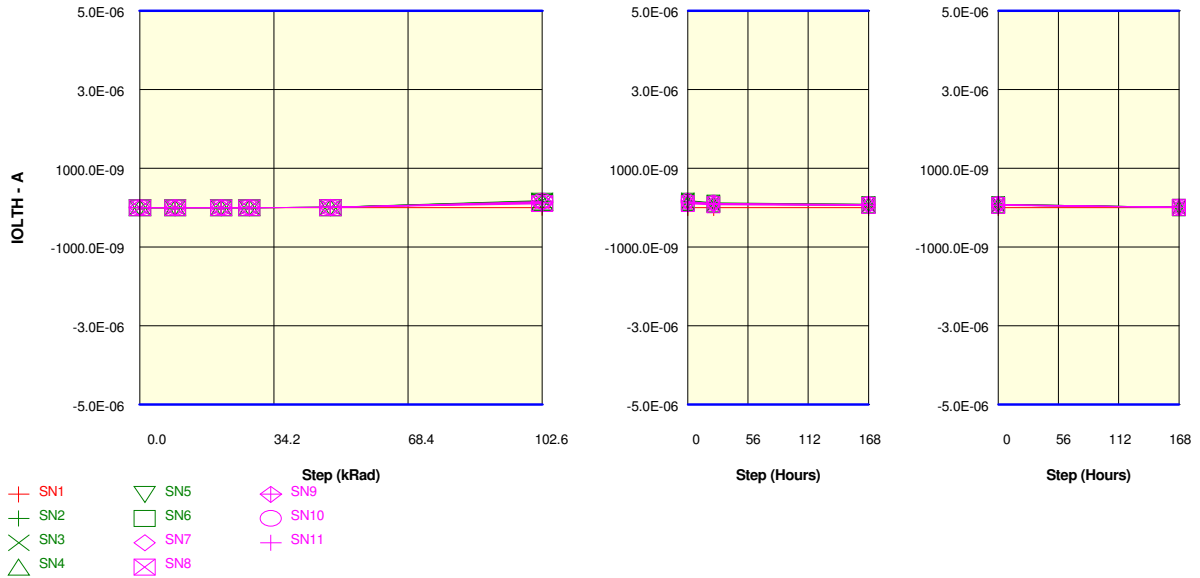
IOLTHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	400.0E-12	400.0E-12	250.0E-12	400.0E-12	350.0E-12	950.0E-12	400.0E-12	450.0E-12	350.0E-12
OFF samples									
SN7	350.0E-12	400.0E-12	450.0E-12	700.0E-12	5.0E-09	144.0E-09	103.5E-09	78.1E-09	6.1E-09
SN8	400.0E-12	400.0E-12	400.0E-12	650.0E-12	3.9E-09	103.0E-09	74.4E-09	55.8E-09	7.1E-09
SN9	500.0E-12	350.0E-12	400.0E-12	700.0E-12	4.8E-09	132.0E-09	94.1E-09	71.4E-09	6.5E-09
SN10	500.0E-12	300.0E-12	450.0E-12	700.0E-12	5.5E-09	153.5E-09	108.5E-09	84.5E-09	6.9E-09
SN11	300.0E-12	450.0E-12	450.0E-12	600.0E-12	4.6E-09	128.5E-09	86.3E-09	74.6E-09	8.8E-09
Statistics									
Min	300.0E-12	300.0E-12	400.0E-12	600.0E-12	3.9E-09	103.0E-09	74.4E-09	55.8E-09	6.1E-09
Max	500.0E-12	450.0E-12	450.0E-12	700.0E-12	5.5E-09	153.5E-09	108.5E-09	84.5E-09	8.8E-09
Average	410.0E-12	380.0E-12	430.0E-12	670.0E-12	4.7E-09	132.2E-09	93.3E-09	72.9E-09	7.1E-09
Sigma	80.0E-12	51.0E-12	24.5E-12	40.0E-12	522.1E-12	17.1E-09	12.2E-09	9.6E-09	926.1E-12

**Drift Calculation**

IOLTHD15	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	50.0E-12	100.0E-12	350.0E-12	4.6E-09	143.7E-09	103.2E-09	77.8E-09	5.8E-09
SN8	-	0.0E+00	0.0E+00	250.0E-12	3.5E-09	102.6E-09	74.0E-09	55.4E-09	6.7E-09
SN9	-	-150.0E-12	-100.0E-12	200.0E-12	4.3E-09	131.5E-09	93.6E-09	70.9E-09	6.0E-09
SN10	-	-200.0E-12	-50.0E-12	200.0E-12	5.0E-09	153.0E-09	108.0E-09	84.0E-09	6.4E-09
SN11	-	150.0E-12	150.0E-12	300.0E-12	4.3E-09	128.2E-09	86.0E-09	74.3E-09	8.5E-09
Average	-	-30.0E-12	20.0E-12	260.0E-12	4.3E-09	131.8E-09	92.9E-09	72.4E-09	6.7E-09
Sigma	-	128.8E-12	92.7E-12	58.3E-12	496.6E-12	17.1E-09	12.2E-09	9.6E-09	971.4E-12



Parameter : Three state output leakage : IOLTHD14  
 Test conditions :  
 Unit : A  
 Spec Limit Min : -5.0E-06  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	550.0E-12	500.0E-12	500.0E-12	550.0E-12	600.0E-12	1.3E-09	500.0E-12	500.0E-12	600.0E-12
ON samples									
SN2	550.0E-12	500.0E-12	600.0E-12	800.0E-12	5.4E-09	161.5E-09	104.0E-09	80.7E-09	5.2E-09
SN3	500.0E-12	500.0E-12	600.0E-12	850.0E-12	6.1E-09	178.0E-09	120.5E-09	82.4E-09	6.6E-09
SN4	500.0E-12	500.0E-12	700.0E-12	900.0E-12	5.1E-09	134.5E-09	92.7E-09	64.7E-09	4.9E-09
SN5	550.0E-12	550.0E-12	600.0E-12	900.0E-12	5.7E-09	166.5E-09	112.0E-09	79.7E-09	7.7E-09
SN6	450.0E-12	450.0E-12	650.0E-12	850.0E-12	4.8E-09	135.0E-09	92.3E-09	63.7E-09	5.7E-09
Statistics									
Min	450.0E-12	450.0E-12	600.0E-12	800.0E-12	4.8E-09	134.5E-09	92.3E-09	63.7E-09	4.9E-09
Max	550.0E-12	550.0E-12	700.0E-12	900.0E-12	6.1E-09	178.0E-09	120.5E-09	82.4E-09	7.7E-09
Average	510.0E-12	500.0E-12	630.0E-12	860.0E-12	5.4E-09	155.1E-09	104.3E-09	74.2E-09	6.0E-09
Sigma	37.4E-12	31.6E-12	40.0E-12	37.4E-12	455.4E-12	17.5E-09	11.0E-09	8.2E-09	1.0E-09

Drift Calculation

IOLTHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-50.0E-12	50.0E-12	250.0E-12	4.8E-09	161.0E-09	103.5E-09	80.1E-09	4.7E-09
SN3	-	0.0E+00	100.0E-12	350.0E-12	5.6E-09	177.5E-09	120.0E-09	81.9E-09	6.1E-09
SN4	-	0.0E+00	200.0E-12	400.0E-12	4.6E-09	134.0E-09	92.2E-09	64.2E-09	4.4E-09
SN5	-	0.0E+00	50.0E-12	350.0E-12	5.1E-09	166.0E-09	111.5E-09	79.1E-09	7.1E-09
SN6	-	0.0E+00	200.0E-12	400.0E-12	4.4E-09	134.6E-09	91.8E-09	63.3E-09	5.3E-09
Average	-	-10.0E-12	120.0E-12	350.0E-12	4.9E-09	154.6E-09	103.8E-09	73.7E-09	5.5E-09
Sigma	-	20.0E-12	67.8E-12	54.8E-12	438.9E-12	17.4E-09	11.0E-09	8.2E-09	991.5E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

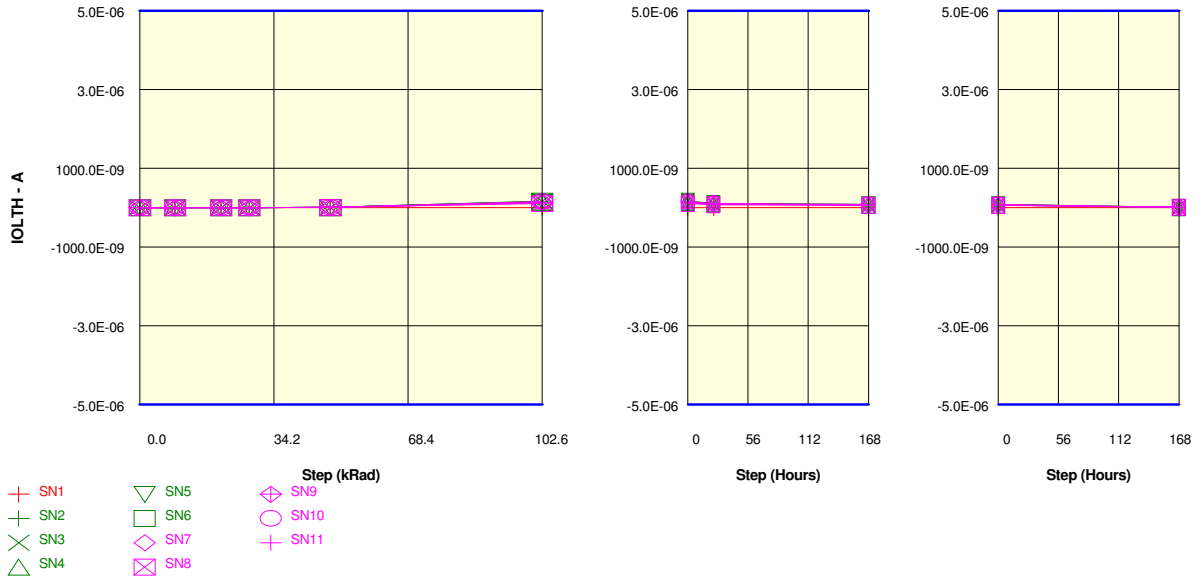
**Measurements**

IOLTHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	550.0E-12	550.0E-12	500.0E-12	550.0E-12	600.0E-12	1.3E-09	500.0E-12	500.0E-12	600.0E-12
<b>OFF samples</b>									
SN7	500.0E-12	550.0E-12	700.0E-12	900.0E-12	5.1E-09	141.5E-09	102.5E-09	76.7E-09	6.3E-09
SN8	500.0E-12	600.0E-12	600.0E-12	800.0E-12	3.9E-09	103.0E-09	74.3E-09	56.6E-09	7.3E-09
SN9	600.0E-12	500.0E-12	550.0E-12	850.0E-12	4.8E-09	125.5E-09	89.5E-09	68.1E-09	6.5E-09
SN10	600.0E-12	500.0E-12	600.0E-12	1.0E-09	5.7E-09	159.5E-09	113.0E-09	87.7E-09	7.1E-09
SN11	500.0E-12	550.0E-12	600.0E-12	800.0E-12	4.7E-09	122.0E-09	82.7E-09	70.8E-09	8.5E-09
<b>Statistics</b>									
Min	500.0E-12	500.0E-12	550.0E-12	800.0E-12	3.9E-09	103.0E-09	74.3E-09	56.6E-09	6.3E-09
Max	600.0E-12	600.0E-12	700.0E-12	1.0E-09	5.7E-09	159.5E-09	113.0E-09	87.7E-09	8.5E-09
Average	540.0E-12	540.0E-12	610.0E-12	870.0E-12	4.8E-09	130.3E-09	92.4E-09	71.9E-09	7.1E-09
Sigma	49.0E-12	37.4E-12	49.0E-12	74.8E-12	569.2E-12	19.1E-09	13.9E-09	10.2E-09	790.8E-12

**Drift Calculation**

IOLTHD14	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	50.0E-12	200.0E-12	400.0E-12	4.6E-09	141.0E-09	102.0E-09	76.2E-09	5.8E-09
SN8	-	100.0E-12	100.0E-12	300.0E-12	3.4E-09	102.5E-09	73.8E-09	56.1E-09	6.8E-09
SN9	-	-100.0E-12	-50.0E-12	250.0E-12	4.2E-09	124.9E-09	88.9E-09	67.5E-09	5.9E-09
SN10	-	-100.0E-12	0.0E+00	400.0E-12	5.1E-09	158.9E-09	112.4E-09	87.1E-09	6.5E-09
SN11	-	50.0E-12	100.0E-12	300.0E-12	4.2E-09	121.5E-09	82.2E-09	70.3E-09	8.0E-09
Average	-	-20.7E-27	70.0E-12	330.0E-12	4.3E-09	129.8E-09	91.8E-09	71.4E-09	6.6E-09
Sigma	-	83.7E-12	87.2E-12	60.0E-12	542.6E-12	19.0E-09	13.8E-09	10.2E-09	809.1E-12

Parameter : Three state output leakage : IOLTHD13  
 Test conditions :  
 Unit : A  
 Spec Limit Min : -5.0E-06  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	500.0E-12	300.0E-12	300.0E-12	400.0E-12	400.0E-12	1.2E-09	350.0E-12	400.0E-12	500.0E-12
ON samples									
SN2	400.0E-12	300.0E-12	400.0E-12	700.0E-12	5.4E-09	146.5E-09	94.0E-09	73.5E-09	4.9E-09
SN3	650.0E-12	250.0E-12	500.0E-12	750.0E-12	5.8E-09	163.0E-09	111.0E-09	77.4E-09	5.9E-09
SN4	550.0E-12	250.0E-12	350.0E-12	700.0E-12	5.4E-09	142.5E-09	99.5E-09	68.5E-09	4.6E-09
SN5	450.0E-12	300.0E-12	450.0E-12	650.0E-12	5.8E-09	165.0E-09	109.5E-09	78.0E-09	7.4E-09
SN6	600.0E-12	300.0E-12	350.0E-12	700.0E-12	5.1E-09	134.5E-09	90.8E-09	63.0E-09	5.4E-09
Statistics									
Min	400.0E-12	250.0E-12	350.0E-12	650.0E-12	5.1E-09	134.5E-09	90.8E-09	63.0E-09	4.6E-09
Max	650.0E-12	300.0E-12	500.0E-12	750.0E-12	5.8E-09	165.0E-09	111.0E-09	78.0E-09	7.4E-09
Average	530.0E-12	280.0E-12	410.0E-12	700.0E-12	5.5E-09	150.3E-09	101.0E-09	72.1E-09	5.6E-09
Sigma	92.7E-12	24.5E-12	58.3E-12	31.6E-12	273.1E-12	11.9E-09	8.1E-09	5.7E-09	978.1E-12

Drift Calculation

IOLTHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-100.0E-12	0.0E+00	300.0E-12	5.0E-09	146.1E-09	93.6E-09	73.1E-09	4.5E-09
SN3	-	-400.0E-12	-150.0E-12	100.0E-12	5.1E-09	162.4E-09	110.4E-09	76.8E-09	5.3E-09
SN4	-	-300.0E-12	-200.0E-12	150.0E-12	4.9E-09	142.0E-09	99.0E-09	67.9E-09	4.0E-09
SN5	-	-150.0E-12	0.0E+00	200.0E-12	5.4E-09	164.6E-09	109.1E-09	77.6E-09	6.9E-09
SN6	-	-300.0E-12	-250.0E-12	100.0E-12	4.5E-09	133.9E-09	90.2E-09	62.4E-09	4.8E-09
Average	-	-250.0E-12	-120.0E-12	170.0E-12	5.0E-09	149.8E-09	100.4E-09	71.5E-09	5.1E-09
Sigma	-	109.5E-12	103.0E-12	74.8E-12	298.3E-12	11.9E-09	8.1E-09	5.7E-09	992.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

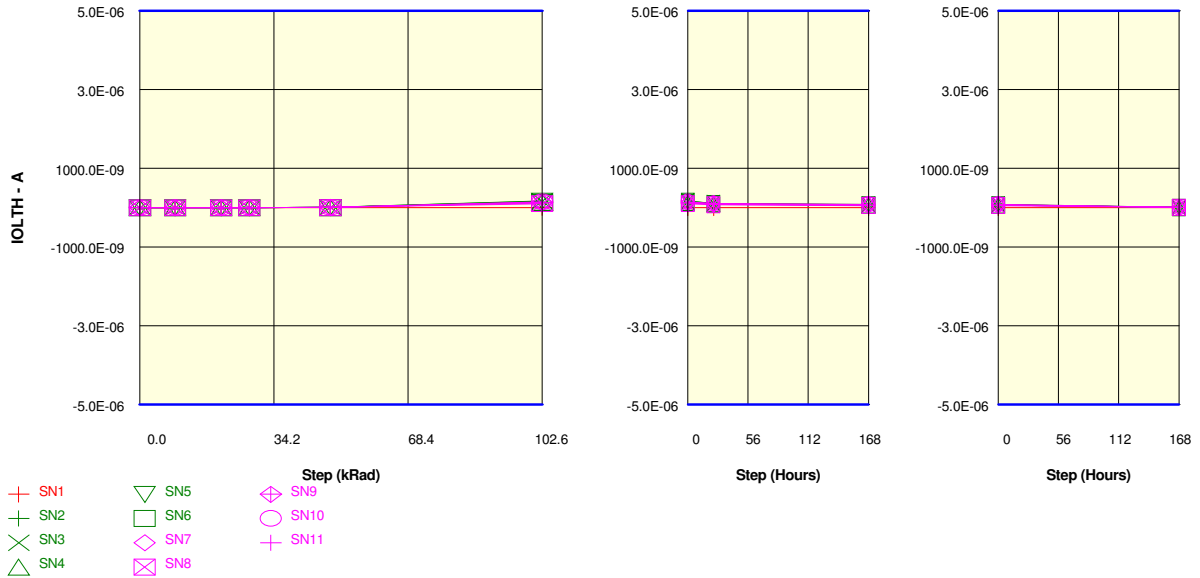
**Measurements**

IOLTHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	500.0E-12	300.0E-12	300.0E-12	400.0E-12	400.0E-12	1.2E-09	350.0E-12	400.0E-12	500.0E-12
<b>OFF samples</b>									
SN7	450.0E-12	200.0E-12	400.0E-12	600.0E-12	4.9E-09	132.5E-09	95.0E-09	71.5E-09	5.7E-09
SN8	450.0E-12	300.0E-12	350.0E-12	600.0E-12	4.1E-09	105.0E-09	75.3E-09	57.2E-09	7.0E-09
SN9	450.0E-12	300.0E-12	450.0E-12	600.0E-12	4.9E-09	129.0E-09	91.8E-09	70.0E-09	6.0E-09
SN10	600.0E-12	350.0E-12	450.0E-12	650.0E-12	5.4E-09	154.5E-09	109.0E-09	84.8E-09	6.2E-09
SN11	400.0E-12	400.0E-12	350.0E-12	550.0E-12	4.6E-09	128.5E-09	86.6E-09	74.8E-09	8.5E-09
<b>Statistics</b>									
Min	400.0E-12	200.0E-12	350.0E-12	550.0E-12	4.1E-09	105.0E-09	75.3E-09	57.2E-09	5.7E-09
Max	600.0E-12	400.0E-12	450.0E-12	650.0E-12	5.4E-09	154.5E-09	109.0E-09	84.8E-09	8.5E-09
Average	470.0E-12	310.0E-12	400.0E-12	600.0E-12	4.8E-09	129.9E-09	91.5E-09	71.6E-09	6.7E-09
Sigma	67.8E-12	66.3E-12	44.7E-12	31.6E-12	428.3E-12	15.7E-09	11.0E-09	8.9E-09	995.5E-12

**Drift Calculation**

IOLTHD13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-250.0E-12	-50.0E-12	150.0E-12	4.5E-09	132.1E-09	94.6E-09	71.0E-09	5.2E-09
SN8	-	-150.0E-12	-100.0E-12	150.0E-12	3.7E-09	104.6E-09	74.9E-09	56.7E-09	6.5E-09
SN9	-	-150.0E-12	0.0E+00	150.0E-12	4.4E-09	128.6E-09	91.4E-09	69.6E-09	5.6E-09
SN10	-	-250.0E-12	-150.0E-12	50.0E-12	4.8E-09	153.9E-09	108.4E-09	84.2E-09	5.6E-09
SN11	-	0.0E+00	-50.0E-12	150.0E-12	4.2E-09	128.1E-09	86.2E-09	74.4E-09	8.1E-09
Average	-	-160.0E-12	-70.0E-12	130.0E-12	4.3E-09	129.4E-09	91.1E-09	71.2E-09	6.2E-09
Sigma	-	91.7E-12	51.0E-12	40.0E-12	381.3E-12	15.7E-09	11.0E-09	8.9E-09	1.0E-09

Parameter : Three state output leakage : IOLTHD12  
 Test conditions :  
 Unit : A  
 Spec Limit Min : -5.0E-06  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.1E-09	400.0E-12	450.0E-12	700.0E-12	800.0E-12	1.5E-09	300.0E-12	600.0E-12	1.0E-09
ON samples									
SN2	600.0E-12	400.0E-12	450.0E-12	650.0E-12	5.6E-09	143.0E-09	91.9E-09	72.2E-09	5.3E-09
SN3	1.3E-09	450.0E-12	650.0E-12	900.0E-12	6.4E-09	168.0E-09	114.0E-09	79.3E-09	6.4E-09
SN4	900.0E-12	450.0E-12	500.0E-12	900.0E-12	5.8E-09	139.5E-09	97.5E-09	67.3E-09	5.0E-09
SN5	800.0E-12	400.0E-12	550.0E-12	750.0E-12	5.9E-09	161.5E-09	108.0E-09	77.0E-09	7.5E-09
SN6	900.0E-12	400.0E-12	500.0E-12	900.0E-12	5.6E-09	130.5E-09	88.8E-09	61.9E-09	5.4E-09
Statistics									
Min	600.0E-12	400.0E-12	450.0E-12	650.0E-12	5.6E-09	130.5E-09	88.8E-09	61.9E-09	5.0E-09
Max	1.3E-09	450.0E-12	650.0E-12	900.0E-12	6.4E-09	168.0E-09	114.0E-09	79.3E-09	7.5E-09
Average	890.0E-12	420.0E-12	530.0E-12	820.0E-12	5.8E-09	148.5E-09	100.0E-09	71.5E-09	5.9E-09
Sigma	210.7E-12	24.5E-12	67.8E-12	103.0E-12	305.6E-12	14.0E-09	9.6E-09	6.3E-09	914.1E-12

Drift Calculation

IOLTHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-200.0E-12	-150.0E-12	50.0E-12	5.0E-09	142.4E-09	91.3E-09	71.6E-09	4.7E-09
SN3	-	-800.0E-12	-600.0E-12	-350.0E-12	5.2E-09	166.8E-09	112.8E-09	78.1E-09	5.1E-09
SN4	-	-450.0E-12	-400.0E-12	0.0E+00	4.9E-09	138.6E-09	96.6E-09	66.4E-09	4.1E-09
SN5	-	-400.0E-12	-250.0E-12	-50.0E-12	5.1E-09	160.7E-09	107.2E-09	76.2E-09	6.7E-09
SN6	-	-500.0E-12	-400.0E-12	0.0E+00	4.7E-09	129.6E-09	87.9E-09	61.0E-09	4.5E-09
Average	-	-470.0E-12	-360.0E-12	-70.0E-12	5.0E-09	147.6E-09	99.2E-09	70.7E-09	5.0E-09
Sigma	-	193.9E-12	153.0E-12	143.5E-12	164.3E-12	13.9E-09	9.4E-09	6.3E-09	895.2E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.1E-09	400.0E-12	450.0E-12	700.0E-12	800.0E-12	1.5E-09	300.0E-12	600.0E-12	1.0E-09
OFF samples									
SN7	900.0E-12	350.0E-12	500.0E-12	800.0E-12	5.5E-09	136.0E-09	98.0E-09	73.2E-09	6.1E-09
SN8	800.0E-12	400.0E-12	500.0E-12	900.0E-12	4.3E-09	102.0E-09	72.7E-09	55.5E-09	7.7E-09
SN9	900.0E-12	350.0E-12	500.0E-12	1.1E-09	5.3E-09	128.0E-09	90.2E-09	69.4E-09	6.2E-09
SN10	950.0E-12	400.0E-12	450.0E-12	950.0E-12	5.8E-09	147.5E-09	104.0E-09	81.2E-09	6.6E-09
SN11	850.0E-12	350.0E-12	600.0E-12	850.0E-12	4.9E-09	121.5E-09	82.1E-09	71.3E-09	8.7E-09
Statistics									
Min	800.0E-12	350.0E-12	450.0E-12	800.0E-12	4.3E-09	102.0E-09	72.7E-09	55.5E-09	6.1E-09
Max	950.0E-12	400.0E-12	600.0E-12	1.1E-09	5.8E-09	147.5E-09	104.0E-09	81.2E-09	8.7E-09
Average	880.0E-12	370.0E-12	510.0E-12	910.0E-12	5.2E-09	127.0E-09	89.4E-09	70.1E-09	7.0E-09
Sigma	51.0E-12	24.5E-12	49.0E-12	86.0E-12	507.9E-12	15.2E-09	11.1E-09	8.4E-09	997.2E-12

**Drift Calculation**

IOLTHD12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-550.0E-12	-400.0E-12	-100.0E-12	4.6E-09	135.1E-09	97.1E-09	72.3E-09	5.2E-09
SN8	-	-400.0E-12	-300.0E-12	100.0E-12	3.5E-09	101.2E-09	71.9E-09	54.7E-09	6.9E-09
SN9	-	-550.0E-12	-400.0E-12	150.0E-12	4.4E-09	127.1E-09	89.3E-09	68.5E-09	5.3E-09
SN10	-	-550.0E-12	-500.0E-12	0.0E+00	4.8E-09	146.6E-09	103.1E-09	80.3E-09	5.6E-09
SN11	-	-500.0E-12	-250.0E-12	0.0E+00	4.1E-09	120.7E-09	81.2E-09	70.5E-09	7.8E-09
Average	-	-510.0E-12	-370.0E-12	30.0E-12	4.3E-09	126.1E-09	88.5E-09	69.2E-09	6.1E-09
Sigma	-	58.3E-12	87.2E-12	87.2E-12	457.8E-12	15.2E-09	11.1E-09	8.3E-09	1.0E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

Parameter : Three state output leakage : IOLTHD11

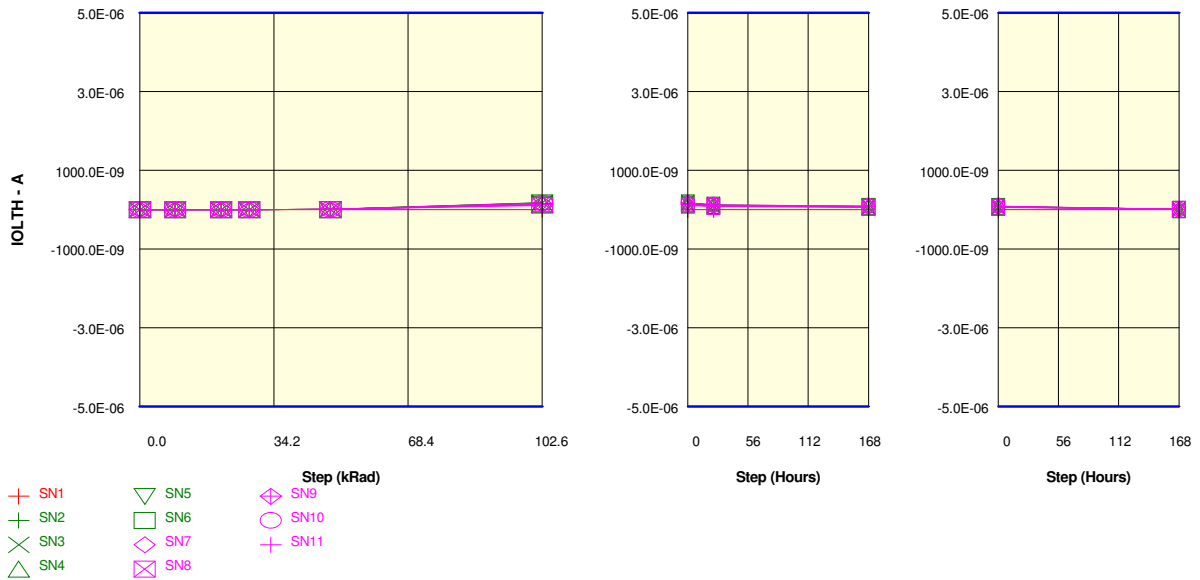
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	150.0E-12	150.0E-12	100.0E-12	200.0E-12	150.0E-12	450.0E-12	250.0E-12	200.0E-12	150.0E-12
ON samples									
SN2	200.0E-12	150.0E-12	150.0E-12	500.0E-12	5.1E-09	157.5E-09	102.5E-09	79.7E-09	4.7E-09
SN3	150.0E-12	200.0E-12	250.0E-12	500.0E-12	5.7E-09	178.5E-09	121.5E-09	84.6E-09	6.5E-09
SN4	200.0E-12	250.0E-12	150.0E-12	500.0E-12	5.2E-09	146.5E-09	102.5E-09	72.4E-09	4.4E-09
SN5	200.0E-12	200.0E-12	250.0E-12	450.0E-12	5.5E-09	171.0E-09	115.0E-09	82.3E-09	7.3E-09
SN6	100.0E-12	150.0E-12	250.0E-12	450.0E-12	4.9E-09	139.0E-09	94.0E-09	65.4E-09	5.4E-09
Statistics									
Min	100.0E-12	150.0E-12	150.0E-12	450.0E-12	4.9E-09	139.0E-09	94.0E-09	65.4E-09	4.4E-09
Max	200.0E-12	250.0E-12	250.0E-12	500.0E-12	5.7E-09	178.5E-09	121.5E-09	84.6E-09	7.3E-09
Average	170.0E-12	190.0E-12	210.0E-12	480.0E-12	5.3E-09	158.5E-09	107.1E-09	76.9E-09	5.6E-09
Sigma	40.0E-12	37.4E-12	49.0E-12	24.5E-12	263.4E-12	14.7E-09	9.8E-09	7.0E-09	1.1E-09

Drift Calculation

IOLTHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-50.0E-12	-50.0E-12	300.0E-12	4.9E-09	157.3E-09	102.3E-09	79.5E-09	4.5E-09
SN3	-	50.0E-12	100.0E-12	350.0E-12	5.5E-09	178.4E-09	121.4E-09	84.4E-09	6.4E-09
SN4	-	50.0E-12	-50.0E-12	300.0E-12	5.0E-09	146.3E-09	102.3E-09	72.2E-09	4.2E-09
SN5	-	0.0E+00	50.0E-12	250.0E-12	5.3E-09	170.8E-09	114.8E-09	82.1E-09	7.1E-09
SN6	-	50.0E-12	150.0E-12	350.0E-12	4.8E-09	138.9E-09	93.9E-09	65.3E-09	5.3E-09
Average	-	20.0E-12	40.0E-12	310.0E-12	5.1E-09	158.3E-09	106.9E-09	76.7E-09	5.5E-09
Sigma	-	40.0E-12	80.0E-12	37.4E-12	253.8E-12	14.7E-09	9.8E-09	7.0E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

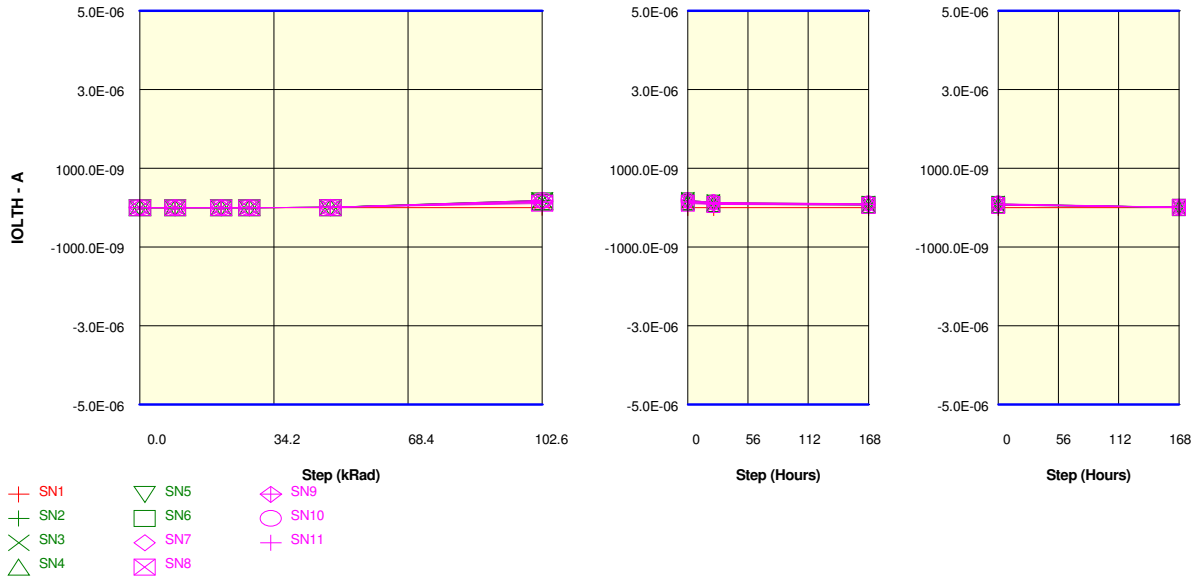
IOLTHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	150.0E-12	150.0E-12	100.0E-12	200.0E-12	150.0E-12	450.0E-12	250.0E-12	200.0E-12	150.0E-12
<b>OFF samples</b>									
SN7	200.0E-12	150.0E-12	200.0E-12	450.0E-12	4.9E-09	141.0E-09	104.5E-09	79.5E-09	5.8E-09
SN8	200.0E-12	150.0E-12	150.0E-12	350.0E-12	4.1E-09	111.5E-09	81.0E-09	61.2E-09	7.3E-09
SN9	250.0E-12	200.0E-12	250.0E-12	400.0E-12	4.6E-09	134.5E-09	96.5E-09	74.9E-09	6.3E-09
SN10	200.0E-12	150.0E-12	250.0E-12	500.0E-12	5.2E-09	168.0E-09	119.5E-09	93.0E-09	6.6E-09
SN11	200.0E-12	150.0E-12	200.0E-12	450.0E-12	4.4E-09	124.0E-09	84.8E-09	73.7E-09	8.7E-09
<b>Statistics</b>									
Min	200.0E-12	150.0E-12	150.0E-12	350.0E-12	4.1E-09	111.5E-09	81.0E-09	61.2E-09	5.8E-09
Max	250.0E-12	200.0E-12	250.0E-12	500.0E-12	5.2E-09	168.0E-09	119.5E-09	93.0E-09	8.7E-09
Average	210.0E-12	160.0E-12	210.0E-12	430.0E-12	4.6E-09	135.8E-09	97.3E-09	76.4E-09	6.9E-09
Sigma	20.0E-12	20.0E-12	37.4E-12	51.0E-12	390.6E-12	18.9E-09	13.9E-09	10.2E-09	1.0E-09

**Drift Calculation**

IOLTHD11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-50.0E-12	0.0E+00	250.0E-12	4.7E-09	140.8E-09	104.3E-09	79.3E-09	5.6E-09
SN8	-	-50.0E-12	-50.0E-12	150.0E-12	3.9E-09	111.3E-09	80.8E-09	61.0E-09	7.1E-09
SN9	-	-50.0E-12	0.0E+00	150.0E-12	4.4E-09	134.3E-09	96.3E-09	74.7E-09	6.0E-09
SN10	-	-50.0E-12	50.0E-12	300.0E-12	5.0E-09	167.8E-09	119.3E-09	92.8E-09	6.4E-09
SN11	-	-50.0E-12	0.0E+00	250.0E-12	4.2E-09	123.8E-09	84.6E-09	73.5E-09	8.5E-09
Average	-	-50.0E-12	0.0E+00	220.0E-12	4.4E-09	135.6E-09	97.1E-09	76.2E-09	6.7E-09
Sigma	-	909.7E-21	31.6E-12	60.0E-12	391.7E-12	18.9E-09	13.9E-09	10.2E-09	1.0E-09



Parameter : Three state output leakage : IOLTHD10  
 Test conditions :  
 Unit : A  
 Spec Limit Min : -5.0E-06  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	800.0E-12	750.0E-12	650.0E-12	850.0E-12	800.0E-12	1.1E-09	850.0E-12	800.0E-12	750.0E-12
ON samples									
SN2	850.0E-12	300.0E-12	250.0E-12	600.0E-12	5.6E-09	179.5E-09	117.5E-09	90.8E-09	5.7E-09
SN3	750.0E-12	250.0E-12	300.0E-12	600.0E-12	6.1E-09	191.5E-09	130.5E-09	91.6E-09	7.5E-09
SN4	900.0E-12	350.0E-12	350.0E-12	600.0E-12	5.3E-09	155.0E-09	109.0E-09	75.5E-09	5.0E-09
SN5	850.0E-12	300.0E-12	250.0E-12	500.0E-12	5.8E-09	174.0E-09	117.0E-09	84.5E-09	8.5E-09
SN6	1.0E-09	300.0E-12	350.0E-12	550.0E-12	4.7E-09	133.5E-09	91.3E-09	64.1E-09	6.1E-09
Statistics									
Min	750.0E-12	250.0E-12	250.0E-12	500.0E-12	4.7E-09	133.5E-09	91.3E-09	64.1E-09	5.0E-09
Max	1.0E-09	350.0E-12	350.0E-12	600.0E-12	6.1E-09	191.5E-09	130.5E-09	91.6E-09	8.5E-09
Average	870.0E-12	300.0E-12	300.0E-12	570.0E-12	5.5E-09	166.7E-09	113.1E-09	81.3E-09	6.5E-09
Sigma	81.2E-12	31.6E-12	44.7E-12	40.0E-12	463.2E-12	20.4E-09	12.9E-09	10.4E-09	1.3E-09

Drift Calculation

IOLTHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-550.0E-12	-600.0E-12	-250.0E-12	4.7E-09	178.7E-09	116.7E-09	89.9E-09	4.8E-09
SN3	-	-500.0E-12	-450.0E-12	-150.0E-12	5.3E-09	190.8E-09	129.8E-09	90.8E-09	6.7E-09
SN4	-	-550.0E-12	-550.0E-12	-300.0E-12	4.4E-09	154.1E-09	108.1E-09	74.6E-09	4.1E-09
SN5	-	-550.0E-12	-600.0E-12	-350.0E-12	5.0E-09	173.2E-09	116.2E-09	83.6E-09	7.6E-09
SN6	-	-700.0E-12	-650.0E-12	-450.0E-12	3.7E-09	132.5E-09	90.3E-09	63.1E-09	5.1E-09
Average	-	-570.0E-12	-570.0E-12	-300.0E-12	4.6E-09	165.8E-09	112.2E-09	80.4E-09	5.7E-09
Sigma	-	67.8E-12	67.8E-12	100.0E-12	542.6E-12	20.4E-09	13.0E-09	10.4E-09	1.3E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	800.0E-12	750.0E-12	650.0E-12	850.0E-12	800.0E-12	1.1E-09	850.0E-12	800.0E-12	750.0E-12
OFF samples									
SN7	600.0E-12	250.0E-12	300.0E-12	550.0E-12	5.5E-09	165.0E-09	119.5E-09	86.7E-09	7.0E-09
SN8	700.0E-12	250.0E-12	300.0E-12	450.0E-12	4.2E-09	113.5E-09	82.2E-09	62.5E-09	7.9E-09
SN9	1.0E-09	250.0E-12	300.0E-12	500.0E-12	5.2E-09	149.5E-09	108.0E-09	82.1E-09	7.2E-09
SN10	950.0E-12	300.0E-12	250.0E-12	550.0E-12	5.8E-09	183.5E-09	131.0E-09	103.0E-09	7.9E-09
SN11	800.0E-12	300.0E-12	300.0E-12	500.0E-12	4.8E-09	141.5E-09	97.0E-09	83.7E-09	10.0E-09
Statistics									
Min	600.0E-12	250.0E-12	250.0E-12	450.0E-12	4.2E-09	113.5E-09	82.2E-09	62.5E-09	7.0E-09
Max	1.0E-09	300.0E-12	300.0E-12	550.0E-12	5.8E-09	183.5E-09	131.0E-09	103.0E-09	10.0E-09
Average	810.0E-12	270.0E-12	290.0E-12	510.0E-12	5.1E-09	150.6E-09	107.5E-09	83.6E-09	8.0E-09
Sigma	149.7E-12	24.5E-12	20.0E-12	37.4E-12	553.5E-12	23.5E-09	17.0E-09	12.9E-09	1.1E-09

**Drift Calculation**

IOLTHD10	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-350.0E-12	-300.0E-12	-50.0E-12	4.9E-09	164.4E-09	118.9E-09	86.1E-09	6.4E-09
SN8	-	-450.0E-12	-400.0E-12	-250.0E-12	3.5E-09	112.8E-09	81.5E-09	61.8E-09	7.2E-09
SN9	-	-750.0E-12	-700.0E-12	-500.0E-12	4.2E-09	148.5E-09	107.0E-09	81.1E-09	6.2E-09
SN10	-	-650.0E-12	-700.0E-12	-400.0E-12	4.8E-09	182.6E-09	130.1E-09	102.1E-09	7.0E-09
SN11	-	-500.0E-12	-500.0E-12	-300.0E-12	4.0E-09	140.7E-09	96.2E-09	82.9E-09	9.2E-09
Average	-	-540.0E-12	-520.0E-12	-300.0E-12	4.3E-09	149.8E-09	106.7E-09	82.8E-09	7.2E-09
Sigma	-	142.8E-12	160.0E-12	151.7E-12	524.4E-12	23.4E-09	17.0E-09	12.8E-09	1.1E-09

Parameter : Three state output leakage : IOLTHD9

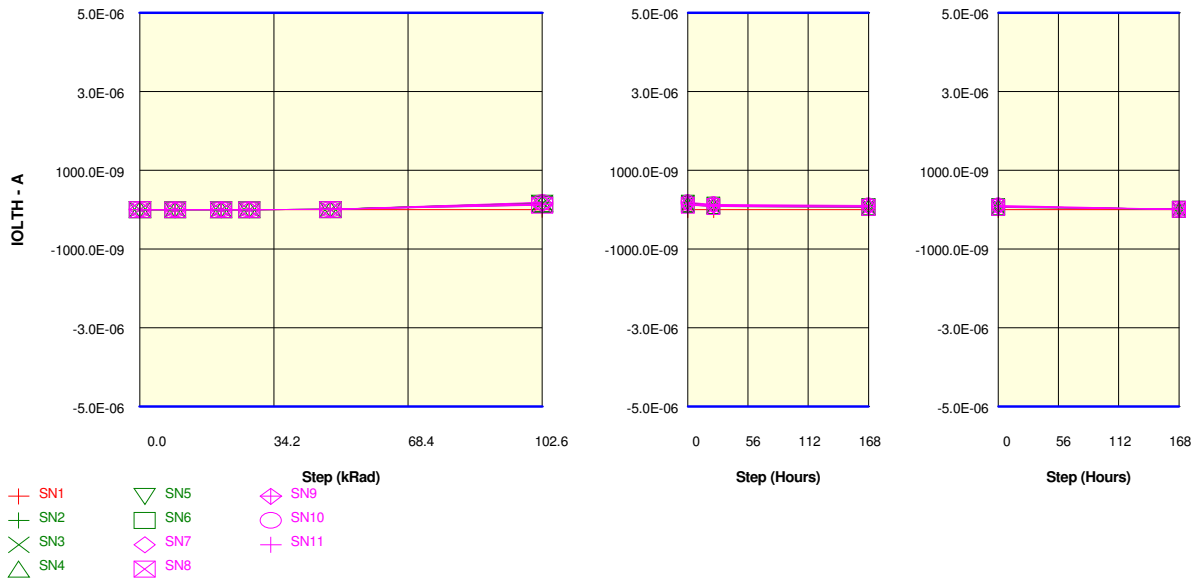
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	2.1E-09	1.8E-09	1.7E-09	2.1E-09	2.1E-09	2.1E-09	1.7E-09	2.1E-09	2.2E-09
ON samples									
SN2	2.1E-09	850.0E-12	900.0E-12	1.3E-09	6.0E-09	170.5E-09	110.0E-09	86.1E-09	6.6E-09
SN3	2.2E-09	800.0E-12	1.0E-09	1.3E-09	6.5E-09	169.0E-09	118.0E-09	81.5E-09	8.5E-09
SN4	2.6E-09	800.0E-12	850.0E-12	1.4E-09	6.0E-09	154.0E-09	108.0E-09	74.5E-09	6.4E-09
SN5	2.3E-09	750.0E-12	1.0E-09	1.4E-09	6.8E-09	163.5E-09	112.0E-09	79.7E-09	9.6E-09
SN6	2.3E-09	850.0E-12	900.0E-12	1.3E-09	5.4E-09	129.0E-09	85.5E-09	60.3E-09	6.9E-09
Statistics									
Min	2.1E-09	750.0E-12	850.0E-12	1.3E-09	5.4E-09	129.0E-09	85.5E-09	60.3E-09	6.4E-09
Max	2.6E-09	850.0E-12	1.0E-09	1.4E-09	6.8E-09	170.5E-09	118.0E-09	86.1E-09	9.6E-09
Average	2.3E-09	810.0E-12	930.0E-12	1.3E-09	6.1E-09	157.2E-09	106.7E-09	76.4E-09	7.6E-09
Sigma	156.8E-12	37.4E-12	60.0E-12	60.0E-12	469.7E-12	15.2E-09	11.1E-09	8.9E-09	1.2E-09

Drift Calculation

IOLTHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-1.3E-09	-1.2E-09	-800.0E-12	3.9E-09	168.4E-09	107.9E-09	84.0E-09	4.5E-09
SN3	-	-1.4E-09	-1.2E-09	-850.0E-12	4.4E-09	166.9E-09	115.9E-09	79.4E-09	6.3E-09
SN4	-	-1.8E-09	-1.7E-09	-1.2E-09	3.4E-09	151.5E-09	105.5E-09	72.0E-09	3.9E-09
SN5	-	-1.5E-09	-1.3E-09	-850.0E-12	4.5E-09	161.3E-09	109.8E-09	77.5E-09	7.4E-09
SN6	-	-1.5E-09	-1.4E-09	-1.1E-09	3.1E-09	126.7E-09	83.2E-09	58.0E-09	4.6E-09
Average	-	-1.5E-09	-1.3E-09	-940.0E-12	3.9E-09	154.9E-09	104.4E-09	74.2E-09	5.3E-09
Sigma	-	168.5E-12	198.5E-12	135.6E-12	536.7E-12	15.3E-09	11.2E-09	9.0E-09	1.3E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	2.1E-09	1.8E-09	1.7E-09	2.1E-09	2.1E-09	2.1E-09	1.7E-09	2.1E-09	2.2E-09
<b>OFF samples</b>									
SN7	2.2E-09	800.0E-12	1.0E-09	1.4E-09	6.1E-09	160.5E-09	117.5E-09	84.1E-09	8.3E-09
SN8	2.4E-09	750.0E-12	950.0E-12	1.1E-09	5.1E-09	114.5E-09	82.1E-09	62.7E-09	9.1E-09
SN9	2.4E-09	850.0E-12	1.0E-09	1.3E-09	5.8E-09	145.0E-09	105.5E-09	79.4E-09	8.8E-09
SN10	2.3E-09	850.0E-12	1.2E-09	1.3E-09	6.8E-09	185.0E-09	133.0E-09	106.0E-09	9.5E-09
SN11	2.5E-09	800.0E-12	850.0E-12	1.2E-09	5.4E-09	131.0E-09	87.6E-09	76.7E-09	10.5E-09
<b>Statistics</b>									
Min	2.2E-09	750.0E-12	850.0E-12	1.1E-09	5.1E-09	114.5E-09	82.1E-09	62.7E-09	8.3E-09
Max	2.5E-09	850.0E-12	1.2E-09	1.4E-09	6.8E-09	185.0E-09	133.0E-09	106.0E-09	10.5E-09
Average	2.3E-09	810.0E-12	1.0E-09	1.2E-09	5.8E-09	147.2E-09	105.1E-09	81.8E-09	9.2E-09
Sigma	106.8E-12	37.4E-12	114.0E-12	97.0E-12	609.4E-12	24.3E-09	18.8E-09	14.1E-09	741.9E-12

**Drift Calculation**

IOLTHD9	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-1.4E-09	-1.2E-09	-800.0E-12	4.0E-09	158.4E-09	115.4E-09	82.0E-09	6.2E-09
SN8	-	-1.7E-09	-1.5E-09	-1.3E-09	2.7E-09	112.1E-09	79.7E-09	60.3E-09	6.7E-09
SN9	-	-1.6E-09	-1.4E-09	-1.1E-09	3.4E-09	142.6E-09	103.1E-09	77.0E-09	6.4E-09
SN10	-	-1.5E-09	-1.1E-09	-1.0E-09	4.5E-09	182.7E-09	130.7E-09	103.7E-09	7.2E-09
SN11	-	-1.7E-09	-1.6E-09	-1.3E-09	2.9E-09	128.6E-09	85.2E-09	74.3E-09	8.1E-09
Average	-	-1.5E-09	-1.3E-09	-1.1E-09	3.5E-09	144.9E-09	102.8E-09	79.4E-09	6.9E-09
Sigma	-	116.6E-12	188.1E-12	189.7E-12	678.7E-12	24.3E-09	18.9E-09	14.1E-09	673.1E-12

Parameter : Three state output leakage : IOLTHD8

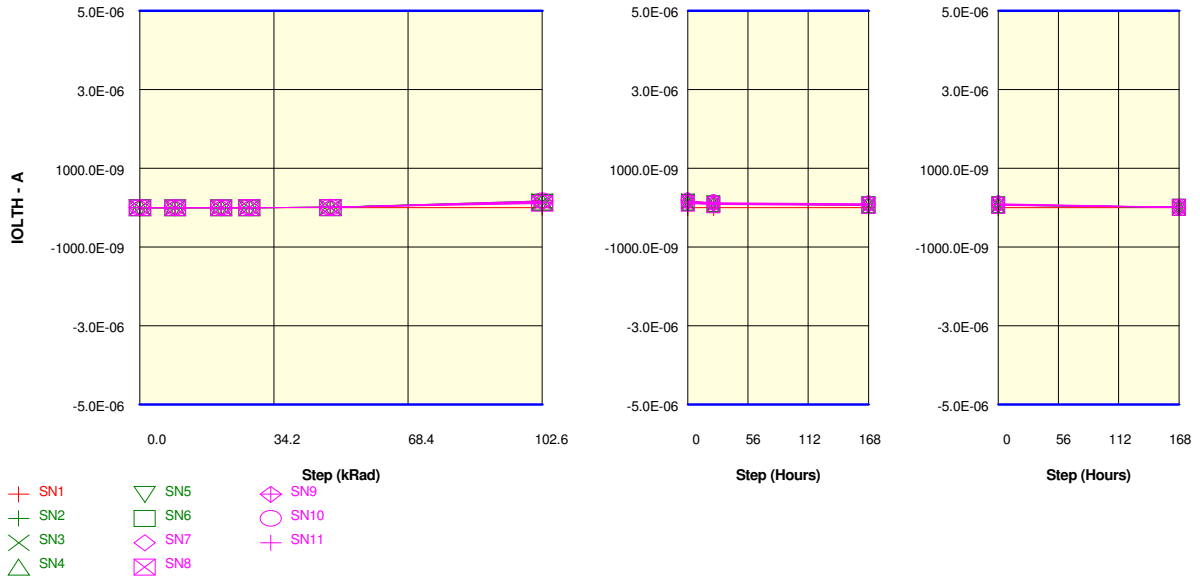
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.5E-09	950.0E-12	1.1E-09	1.6E-09	1.5E-09	1.3E-09	1.1E-09	1.1E-09	2.0E-09
ON samples									
SN2	1.7E-09	900.0E-12	1.3E-09	1.4E-09	6.4E-09	171.0E-09	111.0E-09	87.8E-09	7.4E-09
SN3	1.8E-09	900.0E-12	1.1E-09	1.8E-09	6.5E-09	156.0E-09	110.0E-09	76.1E-09	8.4E-09
SN4	1.6E-09	950.0E-12	950.0E-12	1.9E-09	5.9E-09	140.5E-09	101.0E-09	69.6E-09	6.5E-09
SN5	1.5E-09	950.0E-12	1.1E-09	1.4E-09	6.8E-09	143.5E-09	100.0E-09	71.6E-09	9.4E-09
SN6	1.7E-09	750.0E-12	1.2E-09	1.3E-09	5.7E-09	136.0E-09	90.5E-09	64.8E-09	7.4E-09
Statistics									
Min	1.5E-09	750.0E-12	950.0E-12	1.3E-09	5.7E-09	136.0E-09	90.5E-09	64.8E-09	6.5E-09
Max	1.8E-09	950.0E-12	1.3E-09	1.9E-09	6.8E-09	171.0E-09	111.0E-09	87.8E-09	9.4E-09
Average	1.7E-09	890.0E-12	1.1E-09	1.5E-09	6.2E-09	149.4E-09	102.5E-09	74.0E-09	7.8E-09
Sigma	100.0E-12	73.5E-12	120.8E-12	259.6E-12	425.9E-12	12.7E-09	7.5E-09	7.8E-09	992.8E-12

Drift Calculation

IOLTHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-750.0E-12	-350.0E-12	-300.0E-12	4.8E-09	169.4E-09	109.4E-09	86.2E-09	5.8E-09
SN3	-	-900.0E-12	-700.0E-12	0.0E+00	4.7E-09	154.2E-09	108.2E-09	74.3E-09	6.6E-09
SN4	-	-650.0E-12	-650.0E-12	300.0E-12	4.3E-09	138.9E-09	99.4E-09	68.0E-09	4.9E-09
SN5	-	-550.0E-12	-450.0E-12	-100.0E-12	5.3E-09	142.0E-09	98.5E-09	70.1E-09	7.9E-09
SN6	-	-950.0E-12	-500.0E-12	-450.0E-12	4.0E-09	134.3E-09	88.8E-09	63.1E-09	5.7E-09
Average	-	-760.0E-12	-530.0E-12	-110.0E-12	4.6E-09	147.8E-09	100.9E-09	72.3E-09	6.2E-09
Sigma	-	149.7E-12	128.8E-12	257.7E-12	462.0E-12	12.7E-09	7.5E-09	7.8E-09	1.0E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.5E-09	950.0E-12	1.1E-09	1.6E-09	1.5E-09	1.3E-09	1.1E-09	1.1E-09	2.0E-09
<b>OFF samples</b>									
SN7	1.6E-09	800.0E-12	1.5E-09	1.7E-09	6.0E-09	154.5E-09	115.5E-09	83.9E-09	8.7E-09
SN8	1.5E-09	850.0E-12	1.4E-09	1.6E-09	4.9E-09	111.0E-09	78.6E-09	60.1E-09	9.1E-09
SN9	1.7E-09	900.0E-12	1.2E-09	1.8E-09	5.8E-09	145.5E-09	105.5E-09	80.2E-09	9.6E-09
SN10	1.7E-09	850.0E-12	1.3E-09	1.7E-09	7.2E-09	176.0E-09	129.0E-09	102.0E-09	9.9E-09
SN11	2.0E-09	750.0E-12	1.3E-09	1.3E-09	5.6E-09	126.5E-09	84.5E-09	74.6E-09	10.2E-09
<b>Statistics</b>									
Min	1.5E-09	750.0E-12	1.2E-09	1.3E-09	4.9E-09	111.0E-09	78.6E-09	60.1E-09	8.7E-09
Max	2.0E-09	900.0E-12	1.5E-09	1.8E-09	7.2E-09	176.0E-09	129.0E-09	102.0E-09	10.2E-09
Average	1.7E-09	830.0E-12	1.3E-09	1.6E-09	5.9E-09	142.7E-09	102.6E-09	80.1E-09	9.5E-09
Sigma	168.5E-12	51.0E-12	92.7E-12	187.1E-12	765.9E-12	22.5E-09	18.8E-09	13.6E-09	562.7E-12

**Drift Calculation**

IOLTHD8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-800.0E-12	-150.0E-12	100.0E-12	4.4E-09	152.9E-09	113.9E-09	82.3E-09	7.1E-09
SN8	-	-650.0E-12	-100.0E-12	100.0E-12	3.4E-09	109.5E-09	77.1E-09	58.6E-09	7.6E-09
SN9	-	-800.0E-12	-500.0E-12	100.0E-12	4.1E-09	143.8E-09	103.8E-09	78.5E-09	7.9E-09
SN10	-	-800.0E-12	-350.0E-12	0.0E+00	5.6E-09	174.4E-09	127.4E-09	100.4E-09	8.3E-09
SN11	-	-1.3E-09	-750.0E-12	-750.0E-12	3.6E-09	124.5E-09	82.5E-09	72.6E-09	8.2E-09
Average	-	-860.0E-12	-370.0E-12	-90.0E-12	4.2E-09	141.0E-09	100.9E-09	78.4E-09	7.8E-09
Sigma	-	203.5E-12	237.9E-12	332.3E-12	776.8E-12	22.5E-09	18.9E-09	13.6E-09	446.5E-12

Parameter : Three state output leakage : IOLTHD7

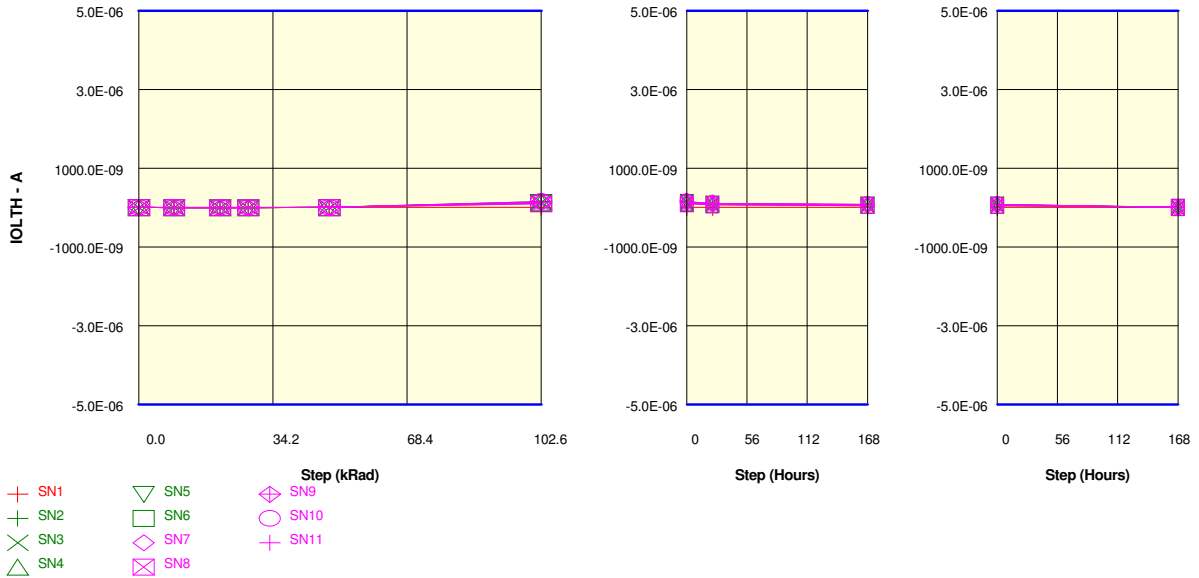
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.3E-09	4.4E-09	4.2E-09	4.6E-09	4.7E-09	5.3E-09	4.3E-09	4.9E-09	4.7E-09
ON samples									
SN2	4.3E-09	1.3E-09	850.0E-12	1.1E-09	5.3E-09	155.5E-09	103.0E-09	80.9E-09	6.3E-09
SN3	4.5E-09	1.4E-09	850.0E-12	1.1E-09	5.4E-09	142.5E-09	100.0E-09	72.6E-09	7.2E-09
SN4	5.0E-09	1.5E-09	850.0E-12	1.2E-09	5.2E-09	133.0E-09	95.0E-09	67.2E-09	5.8E-09
SN5	4.8E-09	1.4E-09	800.0E-12	1.1E-09	5.4E-09	134.5E-09	91.0E-09	67.9E-09	8.7E-09
SN6	4.8E-09	1.6E-09	850.0E-12	950.0E-12	4.5E-09	109.5E-09	75.7E-09	54.3E-09	6.1E-09
Statistics									
Min	4.3E-09	1.3E-09	800.0E-12	950.0E-12	4.5E-09	109.5E-09	75.7E-09	54.3E-09	5.8E-09
Max	5.0E-09	1.6E-09	850.0E-12	1.2E-09	5.4E-09	155.5E-09	103.0E-09	80.9E-09	8.7E-09
Average	4.6E-09	1.4E-09	840.0E-12	1.1E-09	5.1E-09	135.0E-09	92.9E-09	68.6E-09	6.8E-09
Sigma	248.2E-12	103.0E-12	20.0E-12	81.2E-12	326.5E-12	15.0E-09	9.6E-09	8.6E-09	1.0E-09

Drift Calculation

IOLTHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-3.0E-09	-3.4E-09	-3.2E-09	1.0E-09	151.3E-09	98.8E-09	76.6E-09	2.1E-09
SN3	-	-3.1E-09	-3.6E-09	-3.4E-09	900.0E-12	138.1E-09	95.6E-09	68.1E-09	2.8E-09
SN4	-	-3.5E-09	-4.1E-09	-3.8E-09	200.0E-12	128.1E-09	90.1E-09	62.2E-09	800.0E-12
SN5	-	-3.4E-09	-4.0E-09	-3.7E-09	650.0E-12	129.8E-09	86.3E-09	63.2E-09	3.9E-09
SN6	-	-3.2E-09	-3.9E-09	-3.8E-09	-250.0E-12	104.8E-09	71.0E-09	49.6E-09	1.4E-09
Average	-	-3.2E-09	-3.8E-09	-3.6E-09	500.0E-12	130.4E-09	88.3E-09	63.9E-09	2.2E-09
Sigma	-	193.4E-12	253.8E-12	247.8E-12	465.8E-12	15.2E-09	9.7E-09	8.8E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.3E-09	4.4E-09	4.2E-09	4.6E-09	4.7E-09	5.3E-09	4.3E-09	4.9E-09	4.7E-09
<b>OFF samples</b>									
SN7	4.7E-09	1.3E-09	900.0E-12	1.1E-09	4.7E-09	141.0E-09	106.5E-09	79.5E-09	7.3E-09
SN8	5.2E-09	1.6E-09	900.0E-12	1.0E-09	4.0E-09	97.5E-09	73.0E-09	53.7E-09	7.8E-09
SN9	5.1E-09	1.6E-09	850.0E-12	1.0E-09	5.0E-09	137.0E-09	103.0E-09	76.9E-09	8.4E-09
SN10	4.8E-09	1.4E-09	900.0E-12	1.1E-09	5.3E-09	158.5E-09	113.0E-09	87.0E-09	8.7E-09
SN11	5.2E-09	1.6E-09	850.0E-12	900.0E-12	4.6E-09	123.5E-09	84.4E-09	70.4E-09	9.7E-09
<b>Statistics</b>									
Min	4.7E-09	1.3E-09	850.0E-12	900.0E-12	4.0E-09	97.5E-09	73.0E-09	53.7E-09	7.3E-09
Max	5.2E-09	1.6E-09	900.0E-12	1.1E-09	5.3E-09	158.5E-09	113.0E-09	87.0E-09	9.7E-09
Average	5.0E-09	1.5E-09	880.0E-12	1.0E-09	4.7E-09	131.5E-09	96.0E-09	73.5E-09	8.3E-09
Sigma	201.0E-12	128.8E-12	24.5E-12	74.8E-12	438.6E-12	20.3E-09	14.9E-09	11.2E-09	818.8E-12

**Drift Calculation**

IOLTHD7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-3.4E-09	-3.8E-09	-3.6E-09	50.0E-12	136.4E-09	101.9E-09	74.9E-09	2.6E-09
SN8	-	-3.6E-09	-4.3E-09	-4.2E-09	-1.2E-09	92.4E-09	67.8E-09	48.6E-09	2.6E-09
SN9	-	-3.5E-09	-4.2E-09	-4.1E-09	-50.0E-12	132.0E-09	98.0E-09	71.9E-09	3.4E-09
SN10	-	-3.5E-09	-3.9E-09	-3.7E-09	500.0E-12	153.7E-09	108.2E-09	82.2E-09	3.9E-09
SN11	-	-3.6E-09	-4.3E-09	-4.3E-09	-600.0E-12	118.4E-09	79.2E-09	65.2E-09	4.5E-09
Average	-	-3.5E-09	-4.1E-09	-3.9E-09	-250.0E-12	126.5E-09	91.0E-09	68.5E-09	3.4E-09
Sigma	-	87.2E-12	215.9E-12	269.1E-12	570.1E-12	20.5E-09	15.1E-09	11.4E-09	733.9E-12



Parameter : Three state output leakage : IOLTHD6

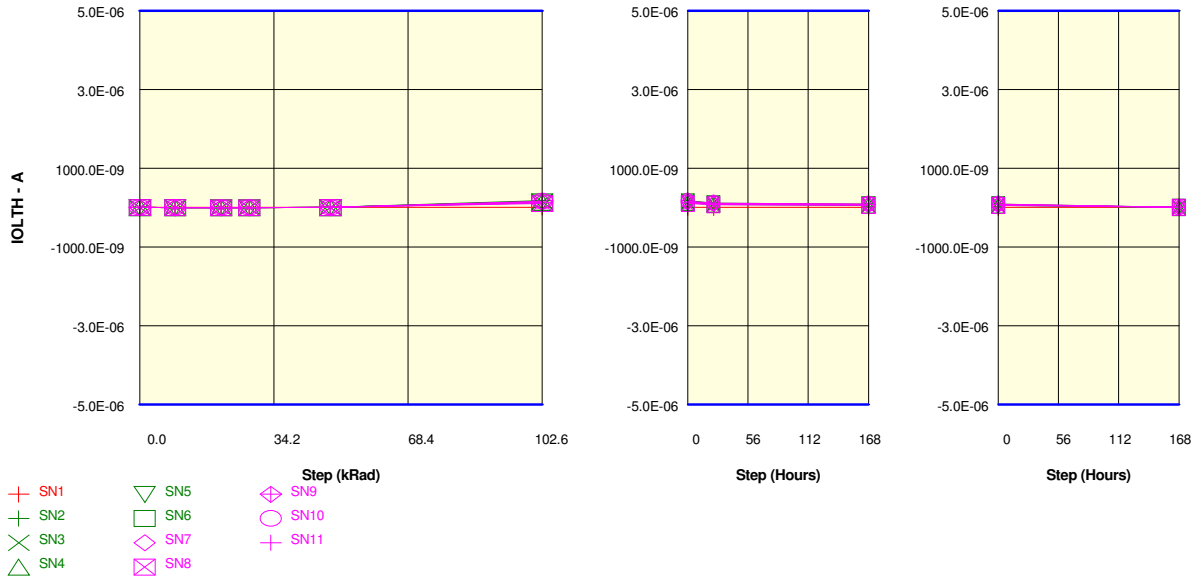
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.9E-09	5.2E-09	4.8E-09	5.5E-09	5.4E-09	6.0E-09	5.2E-09	5.7E-09	5.3E-09
ON samples									
SN2	4.9E-09	1.8E-09	1.1E-09	1.4E-09	6.2E-09	178.0E-09	115.0E-09	89.3E-09	6.6E-09
SN3	5.5E-09	2.0E-09	1.1E-09	1.3E-09	5.9E-09	154.0E-09	106.0E-09	75.6E-09	8.0E-09
SN4	5.6E-09	1.9E-09	1.2E-09	1.4E-09	5.3E-09	135.5E-09	95.0E-09	65.6E-09	5.7E-09
SN5	5.7E-09	2.0E-09	1.3E-09	1.5E-09	6.1E-09	151.5E-09	101.5E-09	73.6E-09	9.1E-09
SN6	5.8E-09	2.2E-09	1.3E-09	1.3E-09	5.3E-09	121.0E-09	82.2E-09	57.6E-09	7.0E-09
Statistics									
Min	4.9E-09	1.8E-09	1.1E-09	1.3E-09	5.3E-09	121.0E-09	82.2E-09	57.6E-09	5.7E-09
Max	5.8E-09	2.2E-09	1.3E-09	1.5E-09	6.2E-09	178.0E-09	115.0E-09	89.3E-09	9.1E-09
Average	5.5E-09	2.0E-09	1.2E-09	1.4E-09	5.7E-09	148.0E-09	99.9E-09	72.3E-09	7.3E-09
Sigma	314.0E-12	132.7E-12	80.0E-12	70.7E-12	400.7E-12	19.1E-09	11.0E-09	10.6E-09	1.2E-09

Drift Calculation

IOLTHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-3.1E-09	-3.8E-09	-3.5E-09	1.3E-09	173.1E-09	110.1E-09	84.4E-09	1.7E-09
SN3	-	-3.5E-09	-4.4E-09	-4.2E-09	450.0E-12	148.6E-09	100.6E-09	70.2E-09	2.6E-09
SN4	-	-3.7E-09	-4.4E-09	-4.2E-09	-300.0E-12	130.0E-09	89.5E-09	60.0E-09	150.0E-12
SN5	-	-3.7E-09	-4.5E-09	-4.3E-09	400.0E-12	145.8E-09	95.8E-09	67.9E-09	3.4E-09
SN6	-	-3.6E-09	-4.5E-09	-4.6E-09	-550.0E-12	115.2E-09	76.4E-09	51.8E-09	1.2E-09
Average	-	-3.5E-09	-4.3E-09	-4.1E-09	250.0E-12	142.5E-09	94.5E-09	66.8E-09	1.8E-09
Sigma	-	215.4E-12	251.8E-12	344.4E-12	633.2E-12	19.4E-09	11.3E-09	10.9E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	4.9E-09	5.2E-09	4.8E-09	5.5E-09	5.4E-09	6.0E-09	5.2E-09	5.7E-09	5.3E-09
<b>OFF samples</b>									
SN7	5.5E-09	2.0E-09	1.3E-09	1.6E-09	5.5E-09	148.5E-09	110.0E-09	79.9E-09	7.7E-09
SN8	6.1E-09	1.8E-09	1.1E-09	1.5E-09	4.5E-09	105.5E-09	75.7E-09	57.4E-09	8.4E-09
SN9	5.7E-09	2.3E-09	1.2E-09	1.3E-09	5.3E-09	144.0E-09	104.0E-09	80.1E-09	8.9E-09
SN10	5.8E-09	2.0E-09	1.3E-09	1.4E-09	5.8E-09	163.5E-09	116.5E-09	92.5E-09	9.1E-09
SN11	6.1E-09	2.1E-09	1.3E-09	1.3E-09	5.1E-09	128.5E-09	84.2E-09	76.0E-09	10.7E-09
<b>Statistics</b>									
Min	5.5E-09	1.8E-09	1.1E-09	1.3E-09	4.5E-09	105.5E-09	75.7E-09	57.4E-09	7.7E-09
Max	6.1E-09	2.3E-09	1.3E-09	1.6E-09	5.8E-09	163.5E-09	116.5E-09	92.5E-09	10.7E-09
Average	5.8E-09	2.0E-09	1.2E-09	1.4E-09	5.2E-09	138.0E-09	98.1E-09	77.2E-09	8.9E-09
Sigma	239.6E-12	163.1E-12	92.7E-12	120.0E-12	417.9E-12	19.7E-09	15.6E-09	11.3E-09	982.1E-12

**Drift Calculation**

IOLTHD6	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-3.5E-09	-4.2E-09	-3.9E-09	0.0E+00	143.1E-09	104.6E-09	74.5E-09	2.3E-09
SN8	-	-4.3E-09	-5.0E-09	-4.6E-09	-1.6E-09	99.5E-09	69.6E-09	51.4E-09	2.3E-09
SN9	-	-3.5E-09	-4.5E-09	-4.4E-09	-400.0E-12	138.3E-09	98.3E-09	74.4E-09	3.2E-09
SN10	-	-3.8E-09	-4.5E-09	-4.4E-09	0.0E+00	167.8E-09	110.8E-09	86.8E-09	3.3E-09
SN11	-	-4.0E-09	-4.9E-09	-4.8E-09	-1.0E-09	122.4E-09	78.1E-09	69.9E-09	4.6E-09
Average	-	-3.8E-09	-4.6E-09	-4.4E-09	-590.0E-12	132.2E-09	92.3E-09	71.4E-09	3.1E-09
Sigma	-	327.7E-12	302.3E-12	311.4E-12	603.7E-12	19.9E-09	15.8E-09	11.5E-09	838.2E-12

Parameter : Three state output leakage : IOLTHD5

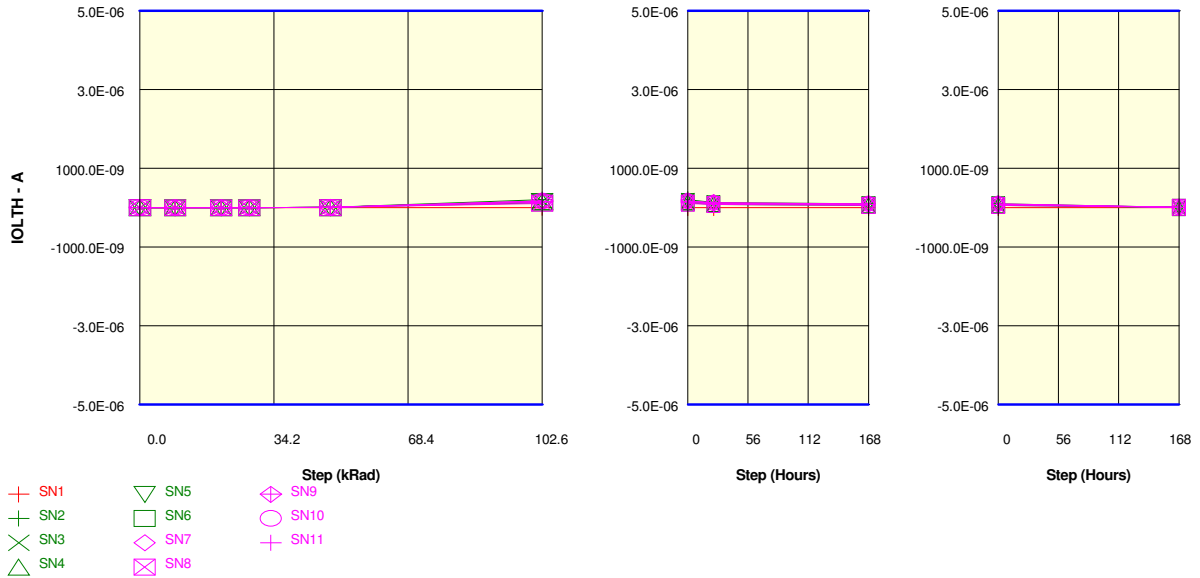
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	1.5E-09	1.7E-09	1.4E-09	1.7E-09	1.7E-09	2.4E-09	1.5E-09	1.8E-09	1.7E-09
ON samples									
SN2	1.6E-09	650.0E-12	400.0E-12	700.0E-12	5.9E-09	208.0E-09	133.0E-09	102.0E-09	6.7E-09
SN3	1.5E-09	600.0E-12	400.0E-12	750.0E-12	5.4E-09	161.5E-09	110.5E-09	77.3E-09	7.2E-09
SN4	1.7E-09	550.0E-12	400.0E-12	750.0E-12	5.2E-09	154.5E-09	107.5E-09	74.2E-09	5.3E-09
SN5	1.6E-09	500.0E-12	400.0E-12	700.0E-12	5.6E-09	158.5E-09	106.0E-09	75.3E-09	8.9E-09
SN6	1.7E-09	550.0E-12	450.0E-12	650.0E-12	4.6E-09	123.0E-09	84.1E-09	58.9E-09	6.1E-09
Statistics									
Min	1.5E-09	500.0E-12	400.0E-12	650.0E-12	4.6E-09	123.0E-09	84.1E-09	58.9E-09	5.3E-09
Max	1.7E-09	650.0E-12	450.0E-12	750.0E-12	5.9E-09	208.0E-09	133.0E-09	102.0E-09	8.9E-09
Average	1.6E-09	570.0E-12	410.0E-12	710.0E-12	5.3E-09	161.1E-09	108.2E-09	77.5E-09	6.8E-09
Sigma	73.5E-12	51.0E-12	20.0E-12	37.4E-12	432.9E-12	27.2E-09	15.5E-09	13.9E-09	1.2E-09

Drift Calculation

IOLTHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-950.0E-12	-1.2E-09	-900.0E-12	4.3E-09	206.4E-09	131.4E-09	100.4E-09	5.1E-09
SN3	-	-850.0E-12	-1.1E-09	-700.0E-12	3.9E-09	160.1E-09	109.1E-09	75.9E-09	5.8E-09
SN4	-	-1.1E-09	-1.3E-09	-900.0E-12	3.5E-09	152.9E-09	105.9E-09	72.6E-09	3.7E-09
SN5	-	-1.1E-09	-1.2E-09	-900.0E-12	4.0E-09	156.9E-09	104.4E-09	73.7E-09	7.3E-09
SN6	-	-1.1E-09	-1.2E-09	-1.0E-09	3.0E-09	121.4E-09	82.5E-09	57.2E-09	4.4E-09
Average	-	-1.0E-09	-1.2E-09	-880.0E-12	3.7E-09	159.5E-09	106.6E-09	75.9E-09	5.2E-09
Sigma	-	103.0E-12	67.8E-12	98.0E-12	461.1E-12	27.2E-09	15.6E-09	13.9E-09	1.2E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.5E-09	1.7E-09	1.4E-09	1.7E-09	1.7E-09	2.4E-09	1.5E-09	1.8E-09	1.7E-09
<b>OFF samples</b>									
SN7	1.5E-09	600.0E-12	400.0E-12	700.0E-12	5.5E-09	173.0E-09	129.0E-09	98.0E-09	7.8E-09
SN8	1.6E-09	650.0E-12	500.0E-12	600.0E-12	4.1E-09	113.5E-09	84.3E-09	61.4E-09	8.2E-09
SN9	1.9E-09	550.0E-12	500.0E-12	600.0E-12	5.3E-09	155.0E-09	115.0E-09	85.1E-09	8.3E-09
SN10	1.6E-09	600.0E-12	450.0E-12	700.0E-12	5.3E-09	168.0E-09	120.0E-09	92.1E-09	8.1E-09
SN11	1.7E-09	600.0E-12	350.0E-12	650.0E-12	4.8E-09	139.0E-09	91.4E-09	78.8E-09	10.3E-09
<b>Statistics</b>									
Min	1.5E-09	550.0E-12	350.0E-12	600.0E-12	4.1E-09	113.5E-09	84.3E-09	61.4E-09	7.8E-09
Max	1.9E-09	650.0E-12	500.0E-12	700.0E-12	5.5E-09	173.0E-09	129.0E-09	98.0E-09	10.3E-09
Average	1.6E-09	600.0E-12	440.0E-12	650.0E-12	5.0E-09	149.7E-09	107.9E-09	83.1E-09	8.5E-09
Sigma	115.8E-12	31.6E-12	58.3E-12	44.7E-12	494.6E-12	21.6E-09	17.2E-09	12.6E-09	887.7E-12

**Drift Calculation**

IOLTHD5	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-900.0E-12	-1.1E-09	-800.0E-12	4.0E-09	171.5E-09	127.5E-09	96.5E-09	6.3E-09
SN8	-	-950.0E-12	-1.1E-09	-1.0E-09	2.5E-09	111.9E-09	82.7E-09	59.8E-09	6.6E-09
SN9	-	-1.3E-09	-1.4E-09	-1.3E-09	3.4E-09	153.2E-09	113.2E-09	83.2E-09	6.4E-09
SN10	-	-1.0E-09	-1.2E-09	-900.0E-12	3.7E-09	166.4E-09	118.4E-09	90.5E-09	6.5E-09
SN11	-	-1.1E-09	-1.3E-09	-1.0E-09	3.2E-09	137.4E-09	89.7E-09	77.1E-09	8.6E-09
Average	-	-1.0E-09	-1.2E-09	-990.0E-12	3.3E-09	148.1E-09	106.3E-09	81.4E-09	6.9E-09
Sigma	-	139.3E-12	104.9E-12	149.7E-12	505.4E-12	21.6E-09	17.2E-09	12.6E-09	873.7E-12

Parameter : Three state output leakage : IOLTHD4

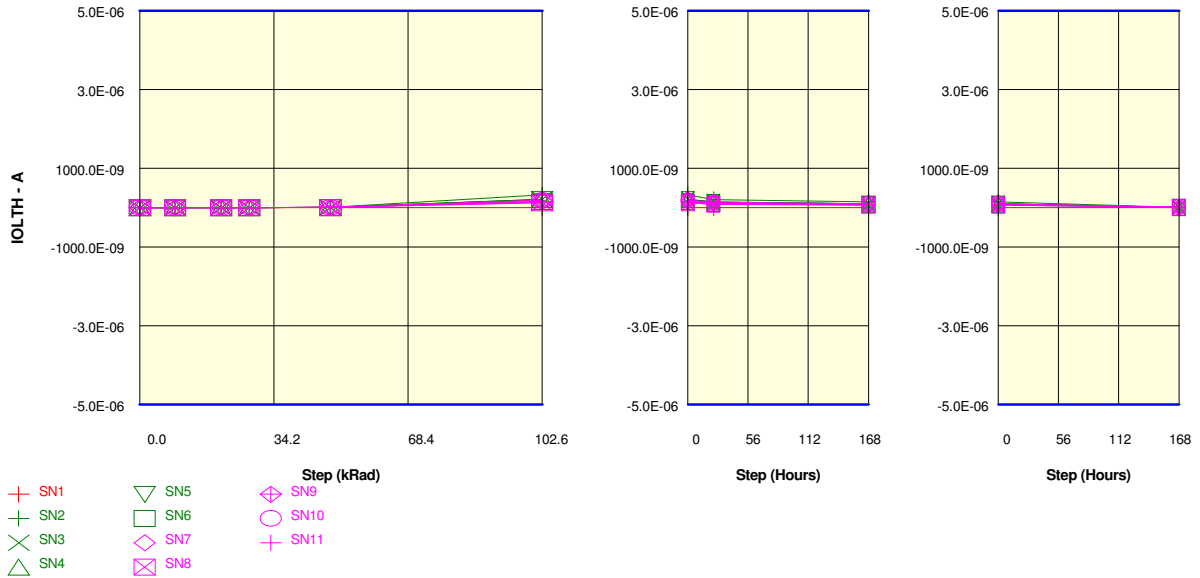
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	1.2E-09	1.3E-09	950.0E-12	1.2E-09	1.2E-09	2.2E-09	1.2E-09	1.3E-09	1.2E-09
ON samples									
SN2	1.2E-09	550.0E-12	400.0E-12	900.0E-12	7.0E-09	325.0E-09	207.0E-09	150.5E-09	6.4E-09
SN3	1.2E-09	600.0E-12	450.0E-12	800.0E-12	6.2E-09	214.5E-09	145.0E-09	100.0E-09	7.3E-09
SN4	1.3E-09	550.0E-12	550.0E-12	800.0E-12	6.1E-09	213.5E-09	146.0E-09	98.5E-09	5.8E-09
SN5	1.1E-09	600.0E-12	500.0E-12	800.0E-12	6.1E-09	206.5E-09	136.5E-09	93.3E-09	8.7E-09
SN6	1.3E-09	650.0E-12	500.0E-12	850.0E-12	5.2E-09	154.0E-09	103.5E-09	70.5E-09	6.2E-09
Statistics									
Min	1.1E-09	550.0E-12	400.0E-12	800.0E-12	5.2E-09	154.0E-09	103.5E-09	70.5E-09	5.8E-09
Max	1.3E-09	650.0E-12	550.0E-12	900.0E-12	7.0E-09	325.0E-09	207.0E-09	150.5E-09	8.7E-09
Average	1.2E-09	590.0E-12	480.0E-12	830.0E-12	6.1E-09	222.7E-09	147.6E-09	102.5E-09	6.9E-09
Sigma	94.9E-12	37.4E-12	51.0E-12	40.0E-12	554.4E-12	55.9E-09	33.5E-09	26.2E-09	1.0E-09

Drift Calculation

IOLTHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-650.0E-12	-800.0E-12	-300.0E-12	5.8E-09	323.8E-09	205.8E-09	149.3E-09	5.2E-09
SN3	-	-550.0E-12	-700.0E-12	-350.0E-12	5.0E-09	213.4E-09	143.9E-09	98.9E-09	6.1E-09
SN4	-	-750.0E-12	-750.0E-12	-500.0E-12	4.8E-09	212.2E-09	144.7E-09	97.2E-09	4.5E-09
SN5	-	-450.0E-12	-550.0E-12	-250.0E-12	5.1E-09	205.5E-09	135.5E-09	92.2E-09	7.7E-09
SN6	-	-650.0E-12	-800.0E-12	-450.0E-12	3.9E-09	152.7E-09	102.2E-09	69.2E-09	4.9E-09
Average	-	-610.0E-12	-720.0E-12	-370.0E-12	4.9E-09	221.5E-09	146.4E-09	101.3E-09	5.7E-09
Sigma	-	102.0E-12	92.7E-12	92.7E-12	596.2E-12	55.9E-09	33.5E-09	26.2E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

IOLTHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.2E-09	1.3E-09	950.0E-12	1.2E-09	1.2E-09	2.2E-09	1.2E-09	1.3E-09	1.2E-09
OFF samples									
SN7	1.2E-09	700.0E-12	450.0E-12	800.0E-12	6.2E-09	190.0E-09	139.5E-09	102.0E-09	7.9E-09
SN8	1.3E-09	650.0E-12	450.0E-12	750.0E-12	4.5E-09	123.0E-09	87.7E-09	68.4E-09	8.9E-09
SN9	1.4E-09	550.0E-12	450.0E-12	700.0E-12	5.3E-09	158.0E-09	113.5E-09	82.9E-09	8.1E-09
SN10	1.2E-09	550.0E-12	500.0E-12	800.0E-12	6.1E-09	183.0E-09	126.5E-09	96.5E-09	8.3E-09
SN11	1.3E-09	550.0E-12	400.0E-12	800.0E-12	4.8E-09	141.0E-09	96.0E-09	80.2E-09	10.5E-09
Statistics									
Min	1.2E-09	550.0E-12	400.0E-12	700.0E-12	4.5E-09	123.0E-09	87.7E-09	68.4E-09	7.9E-09
Max	1.4E-09	700.0E-12	500.0E-12	800.0E-12	6.2E-09	190.0E-09	139.5E-09	102.0E-09	10.5E-09
Average	1.2E-09	600.0E-12	450.0E-12	770.0E-12	5.3E-09	159.0E-09	112.6E-09	86.0E-09	8.7E-09
Sigma	66.3E-12	63.2E-12	31.6E-12	40.0E-12	691.7E-12	25.1E-09	19.1E-09	12.0E-09	955.3E-12

**Drift Calculation**

IOLTHD4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-450.0E-12	-700.0E-12	-350.0E-12	5.1E-09	188.9E-09	138.4E-09	100.9E-09	6.7E-09
SN8	-	-600.0E-12	-800.0E-12	-500.0E-12	3.2E-09	121.8E-09	86.4E-09	67.1E-09	7.7E-09
SN9	-	-800.0E-12	-900.0E-12	-650.0E-12	3.9E-09	156.7E-09	112.2E-09	81.6E-09	6.8E-09
SN10	-	-650.0E-12	-700.0E-12	-400.0E-12	4.9E-09	181.8E-09	125.3E-09	95.3E-09	7.1E-09
SN11	-	-700.0E-12	-850.0E-12	-450.0E-12	3.5E-09	139.8E-09	94.8E-09	79.0E-09	9.3E-09
Average	-	-640.0E-12	-790.0E-12	-470.0E-12	4.1E-09	157.8E-09	111.4E-09	84.8E-09	7.5E-09
Sigma	-	115.8E-12	80.0E-12	103.0E-12	731.4E-12	25.2E-09	19.1E-09	12.0E-09	947.4E-12

Parameter : Three state output leakage : IOLTHD3

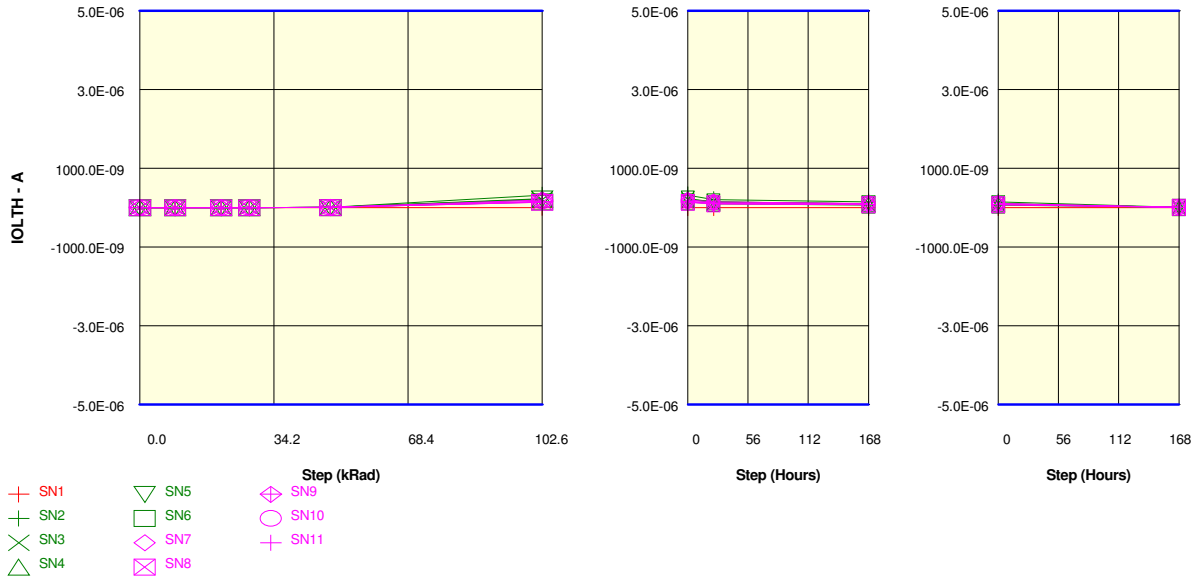
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	550.0E-12	500.0E-12	500.0E-12	600.0E-12	600.0E-12	700.0E-12	500.0E-12	600.0E-12	650.0E-12
ON samples									
SN2	600.0E-12	450.0E-12	600.0E-12	850.0E-12	6.8E-09	323.5E-09	205.0E-09	148.5E-09	7.0E-09
SN3	550.0E-12	400.0E-12	450.0E-12	800.0E-12	6.2E-09	205.5E-09	138.0E-09	95.5E-09	8.1E-09
SN4	700.0E-12	400.0E-12	450.0E-12	900.0E-12	6.4E-09	218.0E-09	149.5E-09	99.0E-09	5.8E-09
SN5	650.0E-12	450.0E-12	500.0E-12	850.0E-12	6.4E-09	226.0E-09	147.5E-09	101.5E-09	8.9E-09
SN6	600.0E-12	450.0E-12	400.0E-12	800.0E-12	5.3E-09	150.0E-09	102.0E-09	67.9E-09	6.5E-09
Statistics									
Min	550.0E-12	400.0E-12	400.0E-12	800.0E-12	5.3E-09	150.0E-09	102.0E-09	67.9E-09	5.8E-09
Max	700.0E-12	450.0E-12	600.0E-12	900.0E-12	6.8E-09	323.5E-09	205.0E-09	148.5E-09	8.9E-09
Average	620.0E-12	430.0E-12	480.0E-12	840.0E-12	6.2E-09	224.6E-09	148.4E-09	102.5E-09	7.2E-09
Sigma	51.0E-12	24.5E-12	67.8E-12	37.4E-12	496.4E-12	56.1E-09	33.1E-09	26.0E-09	1.1E-09

Drift Calculation

IOLTHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-150.0E-12	0.0E+00	250.0E-12	6.2E-09	322.9E-09	204.4E-09	147.9E-09	6.4E-09
SN3	-	-150.0E-12	-100.0E-12	250.0E-12	5.7E-09	205.0E-09	137.5E-09	95.0E-09	7.6E-09
SN4	-	-300.0E-12	-250.0E-12	200.0E-12	5.7E-09	217.3E-09	148.8E-09	98.3E-09	5.1E-09
SN5	-	-200.0E-12	-150.0E-12	200.0E-12	5.8E-09	225.4E-09	146.9E-09	100.9E-09	8.3E-09
SN6	-	-150.0E-12	-200.0E-12	200.0E-12	4.7E-09	149.4E-09	101.4E-09	67.3E-09	5.9E-09
Average	-	-190.0E-12	-140.0E-12	220.0E-12	5.6E-09	224.0E-09	147.8E-09	101.9E-09	6.6E-09
Sigma	-	58.3E-12	86.0E-12	24.5E-12	489.3E-12	56.1E-09	33.1E-09	26.0E-09	1.2E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

IOLTHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	550.0E-12	500.0E-12	500.0E-12	600.0E-12	600.0E-12	700.0E-12	500.0E-12	600.0E-12	650.0E-12
<b>OFF samples</b>									
SN7	700.0E-12	450.0E-12	500.0E-12	900.0E-12	6.5E-09	199.5E-09	146.5E-09	105.5E-09	8.4E-09
SN8	650.0E-12	450.0E-12	500.0E-12	800.0E-12	5.2E-09	136.0E-09	98.5E-09	75.1E-09	9.2E-09
SN9	650.0E-12	500.0E-12	550.0E-12	850.0E-12	5.5E-09	156.5E-09	112.0E-09	85.7E-09	7.7E-09
SN10	600.0E-12	450.0E-12	500.0E-12	850.0E-12	5.9E-09	166.0E-09	124.0E-09	97.5E-09	7.8E-09
SN11	600.0E-12	500.0E-12	550.0E-12	850.0E-12	5.4E-09	145.5E-09	96.5E-09	85.1E-09	10.7E-09
<b>Statistics</b>									
Min	600.0E-12	450.0E-12	500.0E-12	800.0E-12	5.2E-09	136.0E-09	96.5E-09	75.1E-09	7.7E-09
Max	700.0E-12	500.0E-12	550.0E-12	900.0E-12	6.5E-09	199.5E-09	146.5E-09	105.5E-09	10.7E-09
Average	640.0E-12	470.0E-12	520.0E-12	850.0E-12	5.7E-09	160.7E-09	115.5E-09	89.8E-09	8.7E-09
Sigma	37.4E-12	24.5E-12	24.5E-12	31.6E-12	477.9E-12	21.9E-09	18.4E-09	10.6E-09	1.1E-09

**Drift Calculation**

IOLTHD3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-250.0E-12	-200.0E-12	200.0E-12	5.8E-09	198.8E-09	145.8E-09	104.8E-09	7.7E-09
SN8	-	-200.0E-12	-150.0E-12	150.0E-12	4.5E-09	135.4E-09	97.9E-09	74.4E-09	8.5E-09
SN9	-	-150.0E-12	-100.0E-12	200.0E-12	4.8E-09	155.9E-09	111.4E-09	85.0E-09	7.1E-09
SN10	-	-150.0E-12	-100.0E-12	250.0E-12	5.3E-09	165.4E-09	123.4E-09	96.9E-09	7.2E-09
SN11	-	-100.0E-12	-50.0E-12	250.0E-12	4.8E-09	144.9E-09	95.9E-09	84.5E-09	10.1E-09
Average	-	-170.0E-12	-120.0E-12	210.0E-12	5.0E-09	160.1E-09	114.9E-09	89.1E-09	8.1E-09
Sigma	-	51.0E-12	51.0E-12	37.4E-12	458.9E-12	21.9E-09	18.4E-09	10.6E-09	1.1E-09



Parameter : Three state output leakage : IOLTHD2

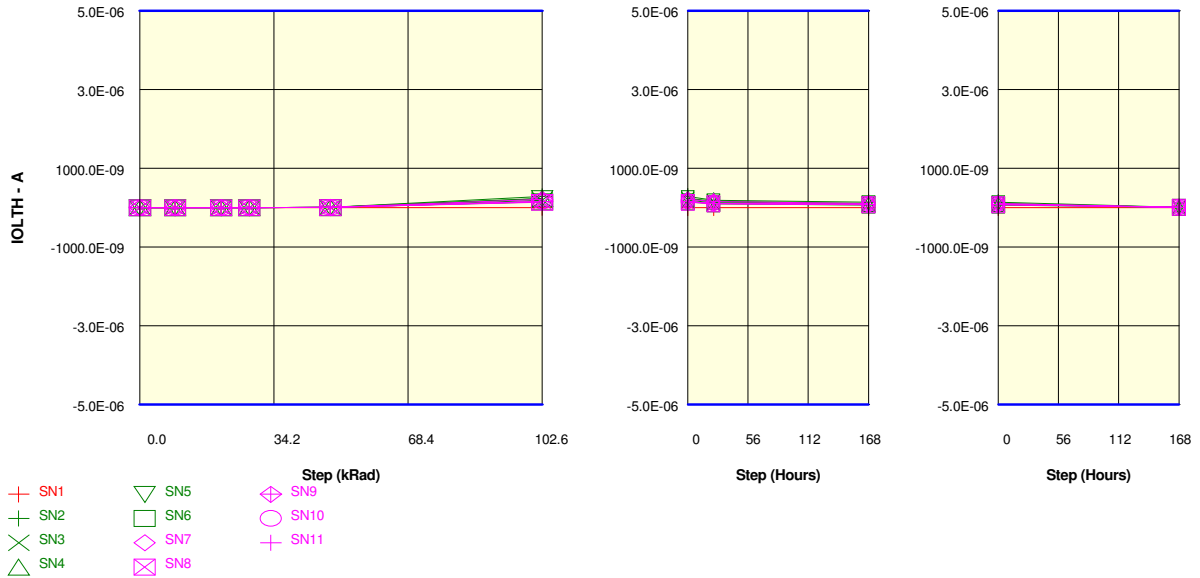
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	500.0E-12	550.0E-12	500.0E-12	650.0E-12	650.0E-12	800.0E-12	550.0E-12	600.0E-12	800.0E-12
ON samples									
SN2	600.0E-12	500.0E-12	550.0E-12	1.0E-09	6.8E-09	290.5E-09	183.5E-09	135.5E-09	6.7E-09
SN3	600.0E-12	500.0E-12	500.0E-12	900.0E-12	6.0E-09	190.5E-09	129.5E-09	88.1E-09	6.9E-09
SN4	800.0E-12	550.0E-12	550.0E-12	950.0E-12	6.5E-09	240.0E-09	161.5E-09	106.5E-09	6.0E-09
SN5	650.0E-12	600.0E-12	550.0E-12	850.0E-12	6.5E-09	229.0E-09	147.5E-09	100.5E-09	9.0E-09
SN6	650.0E-12	550.0E-12	600.0E-12	900.0E-12	5.2E-09	150.0E-09	100.0E-09	66.8E-09	6.4E-09
Statistics									
Min	600.0E-12	500.0E-12	500.0E-12	850.0E-12	5.2E-09	150.0E-09	100.0E-09	66.8E-09	6.0E-09
Max	800.0E-12	600.0E-12	600.0E-12	1.0E-09	6.8E-09	290.5E-09	183.5E-09	135.5E-09	9.0E-09
Average	660.0E-12	540.0E-12	550.0E-12	920.0E-12	6.2E-09	220.0E-09	144.4E-09	99.5E-09	7.0E-09
Sigma	73.5E-12	37.4E-12	31.6E-12	51.0E-12	546.4E-12	47.4E-09	28.4E-09	22.6E-09	1.0E-09

Drift Calculation

IOLTHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-100.0E-12	-50.0E-12	400.0E-12	6.2E-09	289.9E-09	182.9E-09	134.9E-09	6.1E-09
SN3	-	-100.0E-12	-100.0E-12	300.0E-12	5.4E-09	189.9E-09	128.9E-09	87.5E-09	6.3E-09
SN4	-	-250.0E-12	-250.0E-12	150.0E-12	5.7E-09	239.2E-09	160.7E-09	105.7E-09	5.2E-09
SN5	-	-50.0E-12	-100.0E-12	200.0E-12	5.8E-09	228.4E-09	146.9E-09	99.9E-09	8.3E-09
SN6	-	-100.0E-12	-50.0E-12	250.0E-12	4.6E-09	149.4E-09	99.4E-09	66.1E-09	5.8E-09
Average	-	-120.0E-12	-110.0E-12	260.0E-12	5.5E-09	219.3E-09	143.7E-09	98.8E-09	6.3E-09
Sigma	-	67.8E-12	73.5E-12	86.0E-12	540.9E-12	47.4E-09	28.4E-09	22.6E-09	1.1E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	500.0E-12	550.0E-12	500.0E-12	650.0E-12	650.0E-12	800.0E-12	550.0E-12	600.0E-12	800.0E-12
OFF samples									
SN7	800.0E-12	550.0E-12	500.0E-12	850.0E-12	6.4E-09	211.0E-09	155.0E-09	109.5E-09	8.0E-09
SN8	800.0E-12	550.0E-12	600.0E-12	900.0E-12	5.0E-09	137.0E-09	99.0E-09	73.2E-09	9.0E-09
SN9	650.0E-12	500.0E-12	550.0E-12	800.0E-12	5.6E-09	152.0E-09	113.0E-09	82.9E-09	7.5E-09
SN10	650.0E-12	600.0E-12	550.0E-12	900.0E-12	5.9E-09	159.0E-09	108.5E-09	89.4E-09	7.6E-09
SN11	550.0E-12	550.0E-12	650.0E-12	900.0E-12	5.3E-09	152.5E-09	104.0E-09	85.8E-09	10.8E-09
Statistics									
Min	550.0E-12	500.0E-12	500.0E-12	800.0E-12	5.0E-09	137.0E-09	99.0E-09	73.2E-09	7.5E-09
Max	800.0E-12	600.0E-12	650.0E-12	900.0E-12	6.4E-09	211.0E-09	155.0E-09	109.5E-09	10.8E-09
Average	690.0E-12	550.0E-12	570.0E-12	870.0E-12	5.6E-09	162.3E-09	115.9E-09	88.1E-09	8.6E-09
Sigma	97.0E-12	31.6E-12	51.0E-12	40.0E-12	479.2E-12	25.4E-09	20.1E-09	12.0E-09	1.2E-09

**Drift Calculation**

IOLTHD2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-250.0E-12	-300.0E-12	50.0E-12	5.6E-09	210.2E-09	154.2E-09	108.7E-09	7.2E-09
SN8	-	-250.0E-12	-200.0E-12	100.0E-12	4.2E-09	136.2E-09	98.2E-09	72.4E-09	8.2E-09
SN9	-	-150.0E-12	-100.0E-12	150.0E-12	5.0E-09	151.4E-09	112.4E-09	82.2E-09	6.9E-09
SN10	-	-50.0E-12	-100.0E-12	250.0E-12	5.2E-09	158.4E-09	107.9E-09	88.8E-09	7.0E-09
SN11	-	0.0E+00	100.0E-12	350.0E-12	4.8E-09	152.0E-09	103.5E-09	85.3E-09	10.3E-09
Average	-	-140.0E-12	-120.0E-12	180.0E-12	4.9E-09	161.6E-09	115.2E-09	87.5E-09	7.9E-09
Sigma	-	102.0E-12	132.7E-12	107.7E-12	466.3E-12	25.4E-09	20.1E-09	11.9E-09	1.3E-09

Parameter : Three state output leakage : IOLTHD1

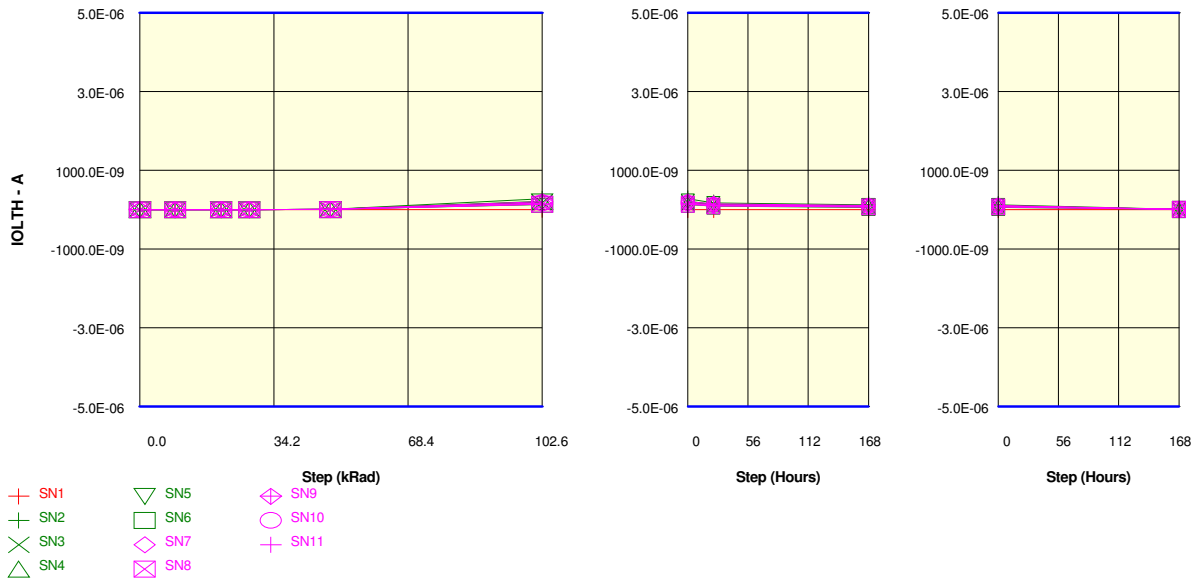
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	800.0E-12	600.0E-12	650.0E-12	700.0E-12	750.0E-12	1.0E-09	550.0E-12	600.0E-12	1.0E-09
ON samples									
SN2	800.0E-12	600.0E-12	550.0E-12	900.0E-12	6.6E-09	275.5E-09	173.5E-09	128.0E-09	5.7E-09
SN3	850.0E-12	550.0E-12	850.0E-12	950.0E-12	6.5E-09	182.5E-09	123.0E-09	84.3E-09	6.9E-09
SN4	950.0E-12	550.0E-12	600.0E-12	900.0E-12	6.1E-09	211.0E-09	143.5E-09	95.5E-09	5.6E-09
SN5	850.0E-12	700.0E-12	700.0E-12	950.0E-12	6.0E-09	200.5E-09	130.5E-09	88.5E-09	8.3E-09
SN6	1.0E-09	600.0E-12	550.0E-12	1.1E-09	5.2E-09	134.0E-09	89.3E-09	60.6E-09	6.2E-09
Statistics									
Min	800.0E-12	550.0E-12	550.0E-12	900.0E-12	5.2E-09	134.0E-09	89.3E-09	60.6E-09	5.6E-09
Max	1.0E-09	700.0E-12	850.0E-12	1.1E-09	6.6E-09	275.5E-09	173.5E-09	128.0E-09	8.3E-09
Average	890.0E-12	600.0E-12	650.0E-12	950.0E-12	6.1E-09	200.7E-09	132.0E-09	91.4E-09	6.5E-09
Sigma	73.5E-12	54.8E-12	114.0E-12	54.8E-12	505.4E-12	45.8E-09	27.4E-09	21.7E-09	999.3E-12

Drift Calculation

IOLTHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-200.0E-12	-250.0E-12	100.0E-12	5.8E-09	274.7E-09	172.7E-09	127.2E-09	4.9E-09
SN3	-	-300.0E-12	0.0E+00	100.0E-12	5.6E-09	181.7E-09	122.2E-09	83.5E-09	6.0E-09
SN4	-	-400.0E-12	-350.0E-12	-50.0E-12	5.2E-09	210.1E-09	142.6E-09	94.6E-09	4.6E-09
SN5	-	-150.0E-12	-150.0E-12	100.0E-12	5.2E-09	199.7E-09	129.7E-09	87.6E-09	7.5E-09
SN6	-	-400.0E-12	-450.0E-12	50.0E-12	4.2E-09	133.0E-09	88.3E-09	59.6E-09	5.2E-09
Average	-	-290.0E-12	-240.0E-12	60.0E-12	5.2E-09	199.8E-09	131.1E-09	90.5E-09	5.6E-09
Sigma	-	102.0E-12	156.2E-12	58.3E-12	569.7E-12	45.8E-09	27.5E-09	21.8E-09	1.0E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

IOLTHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	800.0E-12	600.0E-12	650.0E-12	700.0E-12	750.0E-12	1.0E-09	550.0E-12	600.0E-12	1.0E-09
OFF samples									
SN7	900.0E-12	650.0E-12	550.0E-12	1.0E-09	6.3E-09	203.5E-09	149.5E-09	106.0E-09	8.0E-09
SN8	800.0E-12	600.0E-12	700.0E-12	1.0E-09	5.0E-09	139.0E-09	95.5E-09	69.6E-09	9.0E-09
SN9	950.0E-12	650.0E-12	700.0E-12	850.0E-12	5.4E-09	145.0E-09	105.0E-09	75.5E-09	6.9E-09
SN10	1.0E-09	650.0E-12	700.0E-12	1.1E-09	6.3E-09	171.5E-09	121.0E-09	87.9E-09	7.3E-09
SN11	850.0E-12	650.0E-12	700.0E-12	900.0E-12	5.4E-09	149.5E-09	102.0E-09	89.6E-09	10.3E-09
Statistics									
Min	800.0E-12	600.0E-12	550.0E-12	850.0E-12	5.0E-09	139.0E-09	95.5E-09	69.6E-09	6.9E-09
Max	1.0E-09	650.0E-12	700.0E-12	1.1E-09	6.3E-09	203.5E-09	149.5E-09	106.0E-09	10.3E-09
Average	900.0E-12	640.0E-12	670.0E-12	960.0E-12	5.7E-09	161.7E-09	114.6E-09	85.7E-09	8.3E-09
Sigma	70.7E-12	20.0E-12	60.0E-12	73.5E-12	538.0E-12	23.6E-09	19.4E-09	12.6E-09	1.2E-09

**Drift Calculation**

IOLTHD1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-250.0E-12	-350.0E-12	100.0E-12	5.4E-09	202.6E-09	148.6E-09	105.1E-09	7.1E-09
SN8	-	-200.0E-12	-100.0E-12	200.0E-12	4.2E-09	138.2E-09	94.7E-09	68.8E-09	8.2E-09
SN9	-	-300.0E-12	-250.0E-12	-100.0E-12	4.4E-09	144.1E-09	104.1E-09	74.5E-09	6.0E-09
SN10	-	-350.0E-12	-300.0E-12	50.0E-12	5.3E-09	170.5E-09	120.0E-09	86.9E-09	6.3E-09
SN11	-	-200.0E-12	-150.0E-12	50.0E-12	4.5E-09	148.7E-09	101.2E-09	88.7E-09	9.5E-09
Average	-	-260.0E-12	-230.0E-12	60.0E-12	4.8E-09	160.8E-09	113.7E-09	84.8E-09	7.4E-09
Sigma	-	58.3E-12	92.7E-12	97.0E-12	492.3E-12	23.6E-09	19.3E-09	12.6E-09	1.3E-09

Parameter : Three state output leakage : IOLTHD0

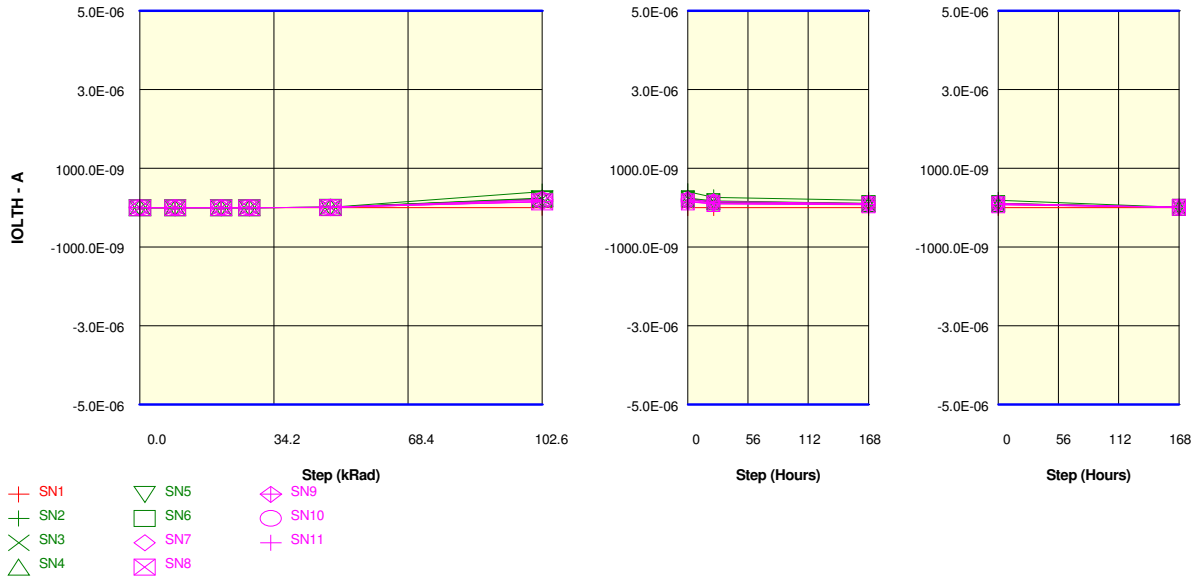
Test conditions :

Unit : A

Spec Limit Min : -5.0E-06

Spec Limit Max : 5.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

IOLTHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.2E-09	850.0E-12	600.0E-12	800.0E-12	1.1E-09	1.5E-09	900.0E-12	850.0E-12	1.4E-09
ON samples									
SN2	1.1E-09	800.0E-12	650.0E-12	1.3E-09	8.1E-09	411.0E-09	258.0E-09	186.0E-09	7.6E-09
SN3	1.7E-09	700.0E-12	750.0E-12	1.2E-09	6.9E-09	231.0E-09	156.0E-09	104.0E-09	7.0E-09
SN4	1.6E-09	750.0E-12	900.0E-12	1.1E-09	6.9E-09	246.0E-09	167.5E-09	109.0E-09	6.2E-09
SN5	1.4E-09	800.0E-12	700.0E-12	1.2E-09	6.9E-09	221.0E-09	145.0E-09	100.0E-09	8.3E-09
SN6	1.5E-09	700.0E-12	850.0E-12	1.3E-09	6.5E-09	221.0E-09	147.0E-09	97.0E-09	6.8E-09
Statistics									
Min	1.1E-09	700.0E-12	650.0E-12	1.1E-09	6.5E-09	221.0E-09	145.0E-09	97.0E-09	6.2E-09
Max	1.7E-09	800.0E-12	900.0E-12	1.3E-09	8.1E-09	411.0E-09	258.0E-09	186.0E-09	8.3E-09
Average	1.5E-09	750.0E-12	770.0E-12	1.2E-09	7.1E-09	266.0E-09	174.7E-09	119.2E-09	7.2E-09
Sigma	204.9E-12	44.7E-12	92.7E-12	73.5E-12	553.2E-12	73.1E-09	42.4E-09	33.6E-09	730.1E-12

Drift Calculation

IOLTHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-300.0E-12	-450.0E-12	200.0E-12	7.0E-09	409.9E-09	256.9E-09	184.9E-09	6.5E-09
SN3	-	-1.0E-09	-950.0E-12	-550.0E-12	5.2E-09	229.3E-09	154.3E-09	102.3E-09	5.3E-09
SN4	-	-850.0E-12	-700.0E-12	-500.0E-12	5.3E-09	244.4E-09	165.9E-09	107.4E-09	4.6E-09
SN5	-	-600.0E-12	-700.0E-12	-250.0E-12	5.5E-09	219.6E-09	143.6E-09	98.6E-09	6.9E-09
SN6	-	-750.0E-12	-600.0E-12	-200.0E-12	5.0E-09	219.6E-09	145.6E-09	95.6E-09	5.3E-09
Average	-	-700.0E-12	-680.0E-12	-260.0E-12	5.6E-09	264.6E-09	173.3E-09	117.8E-09	5.7E-09
Sigma	-	238.7E-12	163.1E-12	267.2E-12	718.3E-12	73.2E-09	42.6E-09	33.8E-09	853.8E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT				Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices		Issue:	02

**Measurements**

IOLTHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.2E-09	850.0E-12	600.0E-12	800.0E-12	1.1E-09	1.5E-09	900.0E-12	850.0E-12	1.4E-09
<b>OFF samples</b>									
SN7	1.5E-09	700.0E-12	650.0E-12	1.1E-09	6.9E-09	219.0E-09	156.5E-09	112.0E-09	8.2E-09
SN8	1.5E-09	750.0E-12	850.0E-12	1.1E-09	5.3E-09	147.0E-09	102.0E-09	76.1E-09	8.8E-09
SN9	1.6E-09	800.0E-12	700.0E-12	1.1E-09	5.7E-09	153.0E-09	113.0E-09	83.6E-09	7.4E-09
SN10	1.5E-09	750.0E-12	900.0E-12	1.2E-09	6.9E-09	183.0E-09	129.0E-09	102.5E-09	8.1E-09
SN11	1.4E-09	800.0E-12	700.0E-12	1.2E-09	5.4E-09	152.0E-09	103.5E-09	83.8E-09	10.3E-09
<b>Statistics</b>									
Min	1.4E-09	700.0E-12	650.0E-12	1.1E-09	5.3E-09	147.0E-09	102.0E-09	76.1E-09	7.4E-09
Max	1.6E-09	800.0E-12	900.0E-12	1.2E-09	6.9E-09	219.0E-09	156.5E-09	112.0E-09	10.3E-09
Average	1.5E-09	760.0E-12	760.0E-12	1.1E-09	6.0E-09	170.8E-09	120.8E-09	91.6E-09	8.5E-09
Sigma	67.8E-12	37.4E-12	97.0E-12	67.8E-12	711.8E-12	27.2E-09	20.3E-09	13.4E-09	976.0E-12

**Drift Calculation**

IOLTHD0	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-750.0E-12	-800.0E-12	-350.0E-12	5.5E-09	217.6E-09	155.1E-09	110.6E-09	6.8E-09
SN8	-	-750.0E-12	-650.0E-12	-450.0E-12	3.8E-09	145.5E-09	100.5E-09	74.6E-09	7.3E-09
SN9	-	-800.0E-12	-900.0E-12	-550.0E-12	4.1E-09	151.4E-09	111.4E-09	82.0E-09	5.8E-09
SN10	-	-700.0E-12	-550.0E-12	-250.0E-12	5.4E-09	181.6E-09	127.6E-09	101.1E-09	6.6E-09
SN11	-	-600.0E-12	-700.0E-12	-200.0E-12	4.0E-09	150.6E-09	102.1E-09	82.4E-09	8.9E-09
Average	-	-720.0E-12	-720.0E-12	-360.0E-12	4.5E-09	169.3E-09	119.3E-09	90.1E-09	7.1E-09
Sigma	-	67.8E-12	120.8E-12	128.1E-12	729.0E-12	27.3E-09	20.3E-09	13.4E-09	1.0E-09

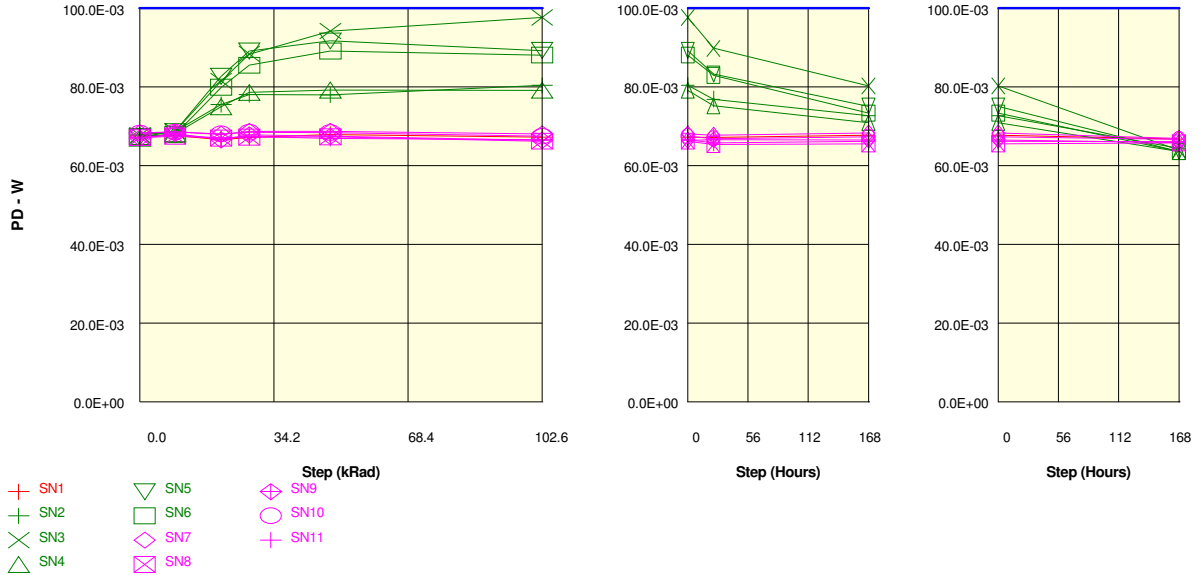
**Parameter : Power dissipation : PD**

**Test conditions :**

Unit : W

Spec Limit Max : 100.0E-03

Spec limits are represented in bold lines on the graphic.



**Measurements**

PD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>SN1_REF</b>	67.6E-03	67.7E-03	66.7E-03	67.2E-03	68.0E-03	67.3E-03	67.2E-03	67.8E-03	66.8E-03
<b>ON samples</b>									
<b>SN2</b>	67.8E-03	68.7E-03	75.6E-03	78.1E-03	78.0E-03	80.4E-03	76.9E-03	72.8E-03	64.4E-03
<b>SN3</b>	67.8E-03	68.8E-03	81.5E-03	88.4E-03	94.2E-03	97.7E-03	89.8E-03	80.3E-03	63.9E-03
<b>SN4</b>	67.0E-03	68.2E-03	75.0E-03	78.6E-03	79.2E-03	79.2E-03	75.2E-03	71.0E-03	63.6E-03
<b>SN5</b>	67.3E-03	68.7E-03	82.7E-03	89.1E-03	91.7E-03	89.3E-03	83.3E-03	75.1E-03	63.6E-03
<b>SN6</b>	67.5E-03	67.9E-03	79.9E-03	85.5E-03	89.1E-03	88.1E-03	83.0E-03	73.4E-03	63.6E-03
<b>Statistics</b>									
<b>Min</b>	67.0E-03	67.9E-03	75.0E-03	78.1E-03	78.0E-03	79.2E-03	75.2E-03	71.0E-03	63.6E-03
<b>Max</b>	67.8E-03	68.8E-03	82.7E-03	89.1E-03	94.2E-03	97.7E-03	89.8E-03	80.3E-03	64.4E-03
<b>Average</b>	67.5E-03	68.4E-03	78.9E-03	83.9E-03	86.4E-03	86.9E-03	81.6E-03	74.5E-03	63.8E-03
<b>Sigma</b>	301.7E-06	341.5E-06	3.1E-03	4.7E-03	6.6E-03	6.7E-03	5.2E-03	3.2E-03	327.1E-06

**Drift Calculation**

PD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>ON samples</b>									
<b>SN2</b>	-	900.0E-06	7.8E-03	10.3E-03	10.2E-03	12.6E-03	9.1E-03	5.0E-03	-3.4E-03
<b>SN3</b>	-	1.0E-03	13.8E-03	20.6E-03	26.5E-03	29.9E-03	22.1E-03	12.5E-03	-3.9E-03
<b>SN4</b>	-	1.2E-03	8.0E-03	11.6E-03	12.2E-03	12.2E-03	8.2E-03	4.0E-03	-3.5E-03
<b>SN5</b>	-	1.4E-03	15.5E-03	21.9E-03	24.5E-03	22.0E-03	16.0E-03	7.9E-03	-3.7E-03
<b>SN6</b>	-	450.0E-06	12.5E-03	18.1E-03	21.7E-03	20.7E-03	15.5E-03	5.9E-03	-3.9E-03
<b>Average</b>	-	980.0E-06	11.5E-03	16.5E-03	19.0E-03	19.5E-03	14.2E-03	7.0E-03	-3.7E-03
<b>Sigma</b>	-	314.0E-06	3.1E-03	4.7E-03	6.6E-03	6.6E-03	5.1E-03	3.0E-03	202.5E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

PD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	67.6E-03	67.7E-03	66.7E-03	67.2E-03	68.0E-03	67.3E-03	67.2E-03	67.8E-03	66.8E-03
<b>OFF samples</b>									
SN7	68.3E-03	68.6E-03	68.0E-03	68.7E-03	68.8E-03	68.1E-03	67.8E-03	68.3E-03	66.9E-03
SN8	67.1E-03	67.5E-03	67.0E-03	67.3E-03	67.4E-03	66.2E-03	65.4E-03	65.5E-03	65.8E-03
SN9	67.0E-03	68.2E-03	66.6E-03	67.8E-03	67.5E-03	66.5E-03	66.6E-03	66.5E-03	65.9E-03
SN10	68.3E-03	68.5E-03	68.1E-03	68.5E-03	68.4E-03	67.5E-03	66.9E-03	67.3E-03	66.7E-03
SN11	67.2E-03	67.9E-03	67.1E-03	67.4E-03	66.9E-03	66.6E-03	65.8E-03	66.2E-03	66.1E-03
<b>Statistics</b>									
Min	67.0E-03	67.5E-03	66.6E-03	67.3E-03	66.9E-03	66.2E-03	65.4E-03	65.5E-03	65.8E-03
Max	68.3E-03	68.6E-03	68.1E-03	68.7E-03	68.8E-03	68.1E-03	67.8E-03	68.3E-03	66.9E-03
Average	67.6E-03	68.1E-03	67.3E-03	67.9E-03	67.8E-03	66.9E-03	66.5E-03	66.8E-03	66.3E-03
Sigma	579.3E-06	408.2E-06	582.8E-06	569.7E-06	691.8E-06	697.4E-06	823.8E-06	962.5E-06	449.0E-06

**Drift Calculation**

PD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	300.0E-06	-350.0E-06	400.0E-06	450.0E-06	-250.0E-06	-550.0E-06	0.0E+00	-1.4E-03
SN8	-	400.0E-06	-100.0E-06	150.0E-06	250.0E-06	-900.0E-06	-1.7E-03	-1.6E-03	-1.3E-03
SN9	-	1.2E-03	-450.0E-06	800.0E-06	450.0E-06	-550.0E-06	-400.0E-06	-500.0E-06	-1.2E-03
SN10	-	250.0E-06	-200.0E-06	200.0E-06	150.0E-06	-800.0E-06	-1.4E-03	-950.0E-06	-1.6E-03
SN11	-	650.0E-06	-150.0E-06	200.0E-06	-300.0E-06	-650.0E-06	-1.4E-03	-1.0E-03	-1.1E-03
Average	-	550.0E-06	-250.0E-06	350.0E-06	200.0E-06	-630.0E-06	-1.1E-03	-810.0E-06	-1.3E-03
Sigma	-	330.2E-06	130.4E-06	240.8E-06	275.7E-06	224.9E-06	516.1E-06	535.2E-06	164.3E-06



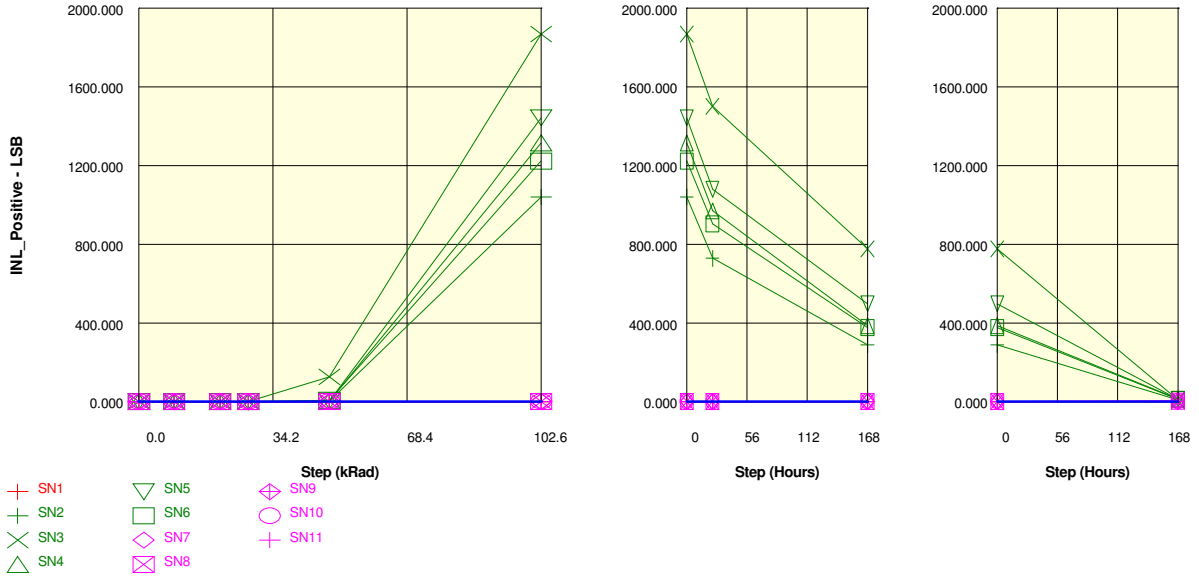
Parameter : Integral nonlinearity Positive : INL\_Positive

Test conditions : All codes

Unit : LSB

Spec Limit Max : 2.500

Spec limits are represented in bold lines on the graphic.



Measurements

INL_Positive	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.293	1.169	1.435	1.350	1.170	1.461	1.592	1.238	1.246
ON samples									
SN2	1.373	1.349	1.336	1.409	4.365	1041.263	729.547	290.908	9.968
SN3	1.337	1.314	1.579	2.331	127.746	1867.891	1501.044	777.391	10.120
SN4	1.276	1.177	1.264	1.232	4.665	1316.099	970.860	387.273	14.769
SN5	1.984	1.212	1.639	2.114	4.378	1443.334	1079.714	498.567	12.506
SN6	1.426	1.373	1.689	1.922	8.381	1223.818	904.530	378.026	13.158
Statistics									
Min	1.276	1.177	1.264	1.232	4.365	1041.263	729.547	290.908	9.968
Max	1.984	1.373	1.689	2.331	127.746	1867.891	1501.044	777.391	14.769
Average	1.479	1.285	1.501	1.802	29.907	1378.481	1037.139	466.433	12.104
Sigma	0.257	0.077	0.170	0.417	48.943	277.581	258.307	168.890	1.837

Drift Calculation

INL_Positive	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-24.0E-03	-37.0E-03	36.0E-03	3.0E+00	1.0E+03	728.2E+00	289.5E+00	8.6E+00
SN3	-	-23.0E-03	242.0E-03	994.0E-03	126.4E+00	1.9E+03	1.5E+03	776.1E+00	8.8E+00
SN4	-	-99.0E-03	-12.0E-03	-44.0E-03	3.4E+00	1.3E+03	969.6E+00	386.0E+00	13.5E+00
SN5	-	-772.0E-03	-345.0E-03	130.0E-03	2.4E+00	1.4E+03	1.1E+03	496.6E+00	10.5E+00
SN6	-	-53.0E-03	263.0E-03	496.0E-03	7.0E+00	1.2E+03	903.1E+00	376.6E+00	11.7E+00
Average	-	-194.2E-03	22.2E-03	322.4E-03	28.4E+00	1.4E+03	1.0E+03	465.0E+00	10.6E+00
Sigma	-	290.2E-03	221.7E-03	383.3E-03	49.0E+00	277.6E+00	258.3E+00	168.9E+00	1.8E+00

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

INL_Positive	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.293	1.169	1.435	1.350	1.170	1.461	1.592	1.238	1.246
<b>OFF samples</b>									
SN7	1.846	1.391	1.499	1.130	1.792	1.933	1.965	2.216	4.175
SN8	1.243	1.218	1.187	1.225	1.348	1.870	2.182	1.725	3.672
SN9	1.309	1.224	1.722	1.109	1.303	2.049	1.898	2.018	3.599
SN10	1.507	1.432	1.303	1.339	1.581	2.262	2.123	2.460	3.758
SN11	1.372	1.262	1.320	1.301	1.354	2.007	1.733	1.852	3.780
<b>Statistics</b>									
Min	1.243	1.218	1.187	1.109	1.303	1.870	1.733	1.725	3.599
Max	1.846	1.432	1.722	1.339	1.792	2.262	2.182	2.460	4.175
Average	1.455	1.305	1.406	1.221	1.476	2.024	1.980	2.054	3.797
Sigma	0.214	0.089	0.187	0.091	0.186	0.134	0.161	0.261	0.200

**Drift Calculation**

INL_Positive	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-455.0E-03	-347.0E-03	-716.0E-03	-54.0E-03	87.0E-03	119.0E-03	370.0E-03	2.3E+00
SN8	-	-25.0E-03	-56.0E-03	-18.0E-03	105.0E-03	627.0E-03	939.0E-03	482.0E-03	2.4E+00
SN9	-	-85.0E-03	413.0E-03	-200.0E-03	-6.0E-03	740.0E-03	589.0E-03	709.0E-03	2.3E+00
SN10	-	-75.0E-03	-204.0E-03	-168.0E-03	74.0E-03	755.0E-03	616.0E-03	953.0E-03	2.3E+00
SN11	-	-110.0E-03	-52.0E-03	-71.0E-03	-18.0E-03	635.0E-03	361.0E-03	480.0E-03	2.4E+00
Average	-	-150.0E-03	-49.2E-03	-234.6E-03	20.2E-03	568.8E-03	524.8E-03	598.8E-03	2.3E+00
Sigma	-	155.0E-03	255.5E-03	249.4E-03	59.6E-03	246.5E-03	274.0E-03	208.7E-03	67.9E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

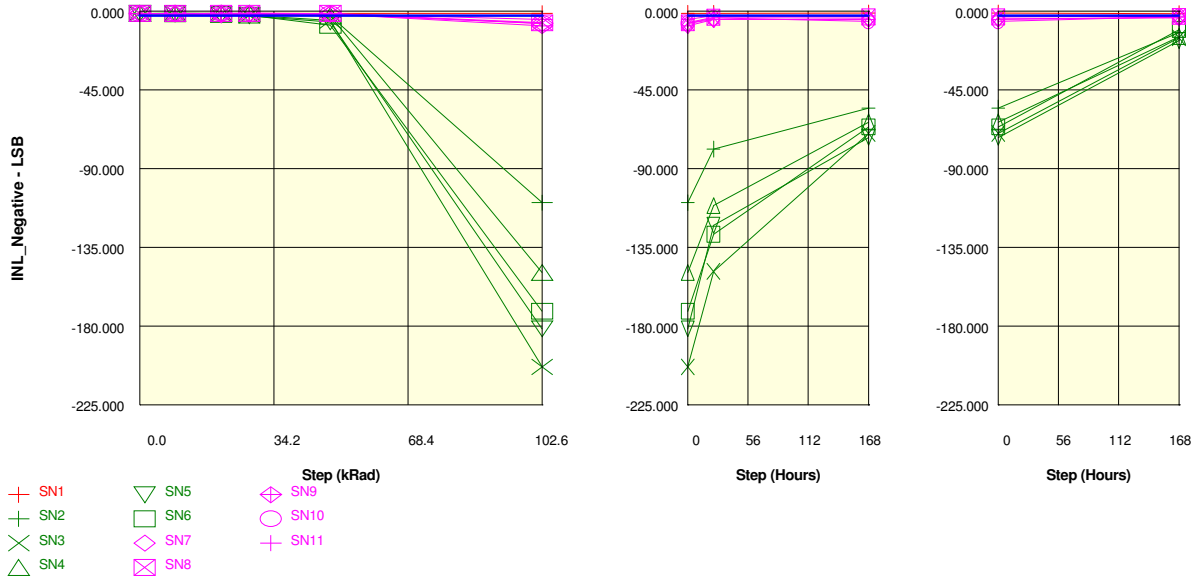
Parameter : Integral nonlinearity Negative : INL\_Negative

Test conditions : All codes

Unit : LSB

Spec Limit Min : -2.500

Spec limits are represented in bold lines on the graphic.



Measurements

INL_Negative	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-1.222	-1.453	-1.694	-1.226	-1.264	-1.303	-1.270	-1.135	-1.382
ON samples									
SN2	-1.478	-1.472	-1.396	-1.396	-2.782	-109.447	-78.856	-55.436	-12.152
SN3	-1.252	-1.317	-1.639	-2.354	-5.239	-203.263	-148.642	-69.813	-15.180
SN4	-1.349	-1.163	-1.293	-1.258	-2.793	-149.328	-111.065	-63.363	-14.469
SN5	-1.341	-1.456	-1.919	-2.685	-6.111	-181.567	-122.340	-72.095	-16.871
SN6	-1.401	-1.404	-1.875	-2.306	-7.982	-171.462	-127.481	-66.103	-10.463
Statistics									
Min	-1.478	-1.472	-1.919	-2.685	-7.982	-203.263	-148.642	-72.095	-16.871
Max	-1.252	-1.163	-1.293	-1.258	-2.782	-109.447	-78.856	-55.436	-10.463
Average	-1.364	-1.362	-1.624	-2.000	-4.981	-163.013	-117.677	-65.362	-13.827
Sigma	0.074	0.113	0.250	0.566	1.999	31.913	22.924	5.800	2.264

Drift Calculation

INL_Negative	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	6.0E-03	82.0E-03	82.0E-03	-1.3E+00	-108.0E+00	-77.4E+00	-54.0E+00	-10.7E+00
SN3	-	-65.0E-03	-387.0E-03	-1.1E+00	-4.0E+00	-202.0E+00	-147.4E+00	-68.6E+00	-13.9E+00
SN4	-	186.0E-03	56.0E-03	91.0E-03	-1.4E+00	-148.0E+00	-109.7E+00	-62.0E+00	-13.1E+00
SN5	-	-115.0E-03	-578.0E-03	-1.3E+00	-4.8E+00	-180.2E+00	-121.0E+00	-70.8E+00	-15.5E+00
SN6	-	-3.0E-03	-474.0E-03	-905.0E-03	-6.6E+00	-170.1E+00	-126.1E+00	-64.7E+00	-9.1E+00
Average	-	1.8E-03	-260.2E-03	-635.6E-03	-3.6E+00	-161.6E+00	-116.3E+00	-64.0E+00	-12.5E+00
Sigma	-	102.1E-03	275.6E-03	605.8E-03	2.0E+00	32.0E+00	23.0E+00	5.9E+00	2.3E+00

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

INL_Negative	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-1.222	-1.453	-1.694	-1.226	-1.264	-1.303	-1.270	-1.135	-1.382
<b>OFF samples</b>									
SN7	-1.274	-1.489	-1.266	-1.476	-1.691	-6.980	-4.794	-4.323	-3.821
SN8	-1.316	-1.355	-1.297	-1.187	-1.340	-6.641	-3.448	-3.322	-2.924
SN9	-1.424	-1.517	-2.094	-1.351	-1.595	-8.322	-4.730	-4.691	-3.346
SN10	-1.441	-1.326	-1.224	-1.748	-1.533	-7.062	-3.926	-5.720	-3.188
SN11	-1.378	-1.434	-1.249	-1.361	-1.352	-4.835	-2.504	-2.653	-2.885
<b>Statistics</b>									
Min	-1.441	-1.517	-2.094	-1.748	-1.691	-8.322	-4.794	-5.720	-3.821
Max	-1.274	-1.326	-1.224	-1.187	-1.340	-4.835	-2.504	-2.653	-2.885
Average	-1.367	-1.424	-1.426	-1.425	-1.502	-6.768	-3.880	-4.142	-3.233
Sigma	0.063	0.074	0.335	0.186	0.137	1.122	0.853	1.069	0.340

**Drift Calculation**

INL_Negative	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-215.0E-03	8.0E-03	-202.0E-03	-417.0E-03	-5.7E+00	-3.5E+00	-3.0E+00	-2.5E+00
SN8	-	-39.0E-03	19.0E-03	129.0E-03	-24.0E-03	-5.3E+00	-2.1E+00	-2.0E+00	-1.6E+00
SN9	-	-93.0E-03	-670.0E-03	73.0E-03	-171.0E-03	-6.9E+00	-3.3E+00	-3.3E+00	-1.9E+00
SN10	-	115.0E-03	217.0E-03	-307.0E-03	-92.0E-03	-5.6E+00	-2.5E+00	-4.3E+00	-1.7E+00
SN11	-	-56.0E-03	129.0E-03	17.0E-03	26.0E-03	-3.5E+00	-1.1E+00	-1.3E+00	-1.5E+00
Average	-	-57.6E-03	-59.4E-03	-58.0E-03	-135.6E-03	-5.4E+00	-2.5E+00	-2.8E+00	-1.9E+00
Sigma	-	106.0E-03	314.8E-03	167.6E-03	155.5E-03	1.1E+00	861.7E-03	1.0E+00	367.8E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

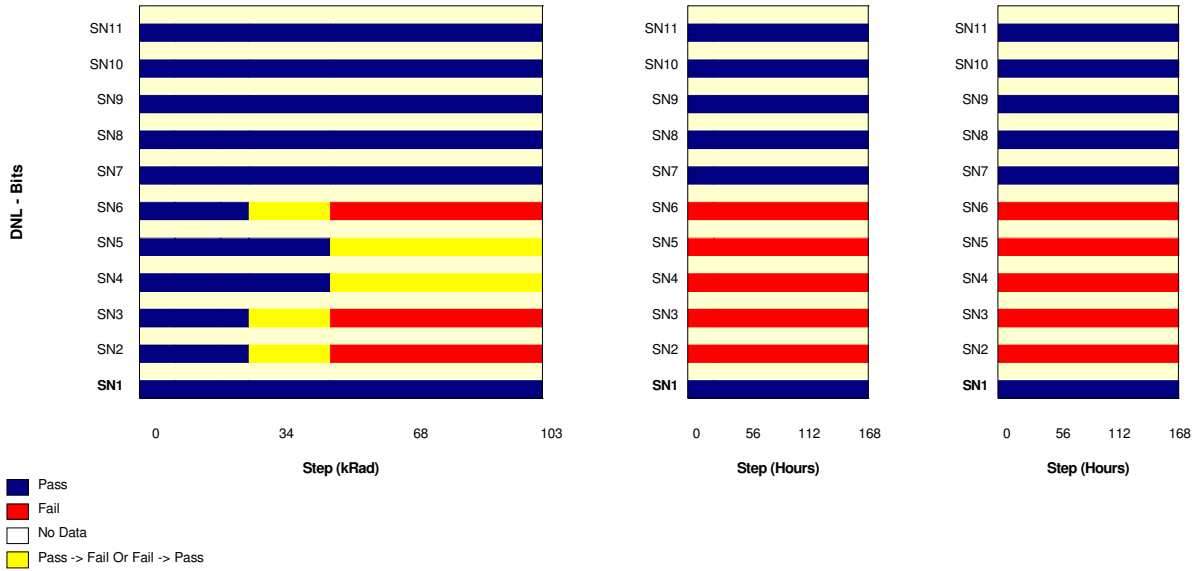
Parameter : Differential nonlinearity : DNL

Test conditions : All codes? Minimum resolution for which "no missing codes" is guaranteed.

Unit : Bits

Spec Limit Min : 16

Spec limits are represented in bold lines on the graphic.



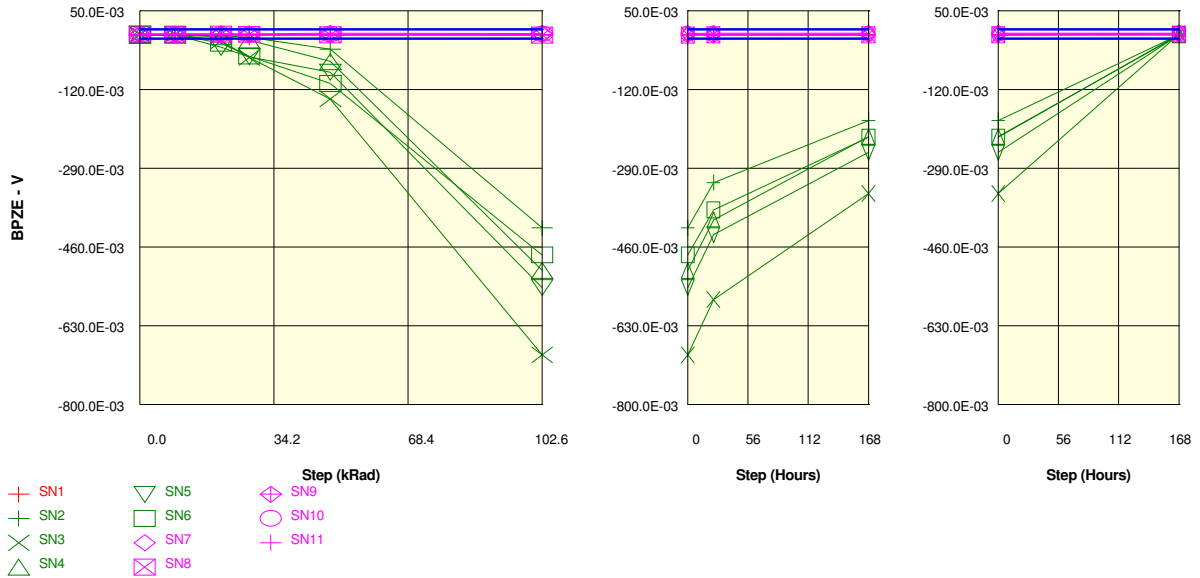
Measurements

DNL	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
ON samples									
SN2	PASS	PASS	PASS	PASS	FAIL	FAIL	FAIL	FAIL	FAIL
SN3	PASS	PASS	PASS	PASS	FAIL	FAIL	FAIL	FAIL	FAIL
SN4	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	FAIL	FAIL
SN5	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	FAIL	FAIL
SN6	PASS	PASS	PASS	PASS	FAIL	FAIL	FAIL	FAIL	FAIL

Measurements

DNL	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
OFF samples									
SN7	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN8	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN9	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN10	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN11	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS

Parameter : Bipolar zero error : BPZE  
 Test conditions : Code = 32767.5. Ta=+25°C  
 Unit : V  
 Spec Limit Min : -10.0E-03  
 Spec Limit Max : 10.0E-03  
 Spec limits are represented in bold lines on the graphic.



Measurements

BPZE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	-2.2E-03	-2.3E-03	-2.0E-03	-2.2E-03	-2.2E-03	-2.3E-03	-2.5E-03	-2.5E-03	-2.5E-03
ON samples									
SN2	-1.7E-03	-2.3E-03	-4.2E-03	-7.2E-03	-32.7E-03	-418.7E-03	-320.9E-03	-187.1E-03	-1.7E-03
SN3	-2.1E-03	-1.3E-03	-15.1E-03	-50.8E-03	-140.2E-03	-692.8E-03	-573.0E-03	-344.4E-03	-371.1E-06
SN4	-2.9E-03	-2.5E-03	-6.0E-03	-13.9E-03	-59.6E-03	-510.5E-03	-401.5E-03	-221.8E-03	-2.1E-03
SN5	-1.2E-03	-1.9E-03	-28.7E-03	-49.1E-03	-82.7E-03	-547.4E-03	-433.0E-03	-255.4E-03	-1.6E-03
SN6	-1.2E-03	-1.8E-03	-19.8E-03	-47.7E-03	-106.7E-03	-476.8E-03	-379.5E-03	-222.6E-03	-859.4E-06
Statistics									
Min	-2.9E-03	-2.5E-03	-28.7E-03	-50.8E-03	-140.2E-03	-692.8E-03	-573.0E-03	-344.4E-03	-2.1E-03
Max	-1.2E-03	-1.3E-03	-4.2E-03	-7.2E-03	-32.7E-03	-418.7E-03	-320.9E-03	-187.1E-03	-371.1E-06
Average	-1.8E-03	-2.0E-03	-14.8E-03	-33.7E-03	-84.4E-03	-529.2E-03	-421.6E-03	-246.3E-03	-1.3E-03
Sigma	632.2E-06	422.8E-06	9.0E-03	19.1E-03	37.1E-03	92.1E-03	84.1E-03	53.6E-03	614.5E-06

Drift Calculation

BPZE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-527.3E-06	-2.4E-03	-5.5E-03	-31.0E-03	-417.0E-03	-319.1E-03	-185.4E-03	48.8E-06
SN3	-	791.0E-06	-13.1E-03	-48.8E-03	-138.1E-03	-690.7E-03	-570.9E-03	-342.3E-03	1.7E-03
SN4	-	400.4E-06	-3.1E-03	-11.0E-03	-56.7E-03	-507.6E-03	-398.6E-03	-218.9E-03	839.8E-06
SN5	-	-654.3E-06	-27.5E-03	-47.8E-03	-81.4E-03	-546.2E-03	-431.8E-03	-254.2E-03	-351.6E-06
SN6	-	-615.2E-06	-18.6E-03	-46.5E-03	-105.5E-03	-475.6E-03	-378.3E-03	-221.4E-03	332.0E-06
Average	-	-121.1E-06	-12.9E-03	-31.9E-03	-82.6E-03	-527.4E-03	-419.7E-03	-244.4E-03	513.7E-06
Sigma	-	599.6E-06	9.5E-03	19.4E-03	37.3E-03	92.0E-03	84.0E-03	53.6E-03	708.5E-06

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT				Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices		Issue:	02

**Measurements**

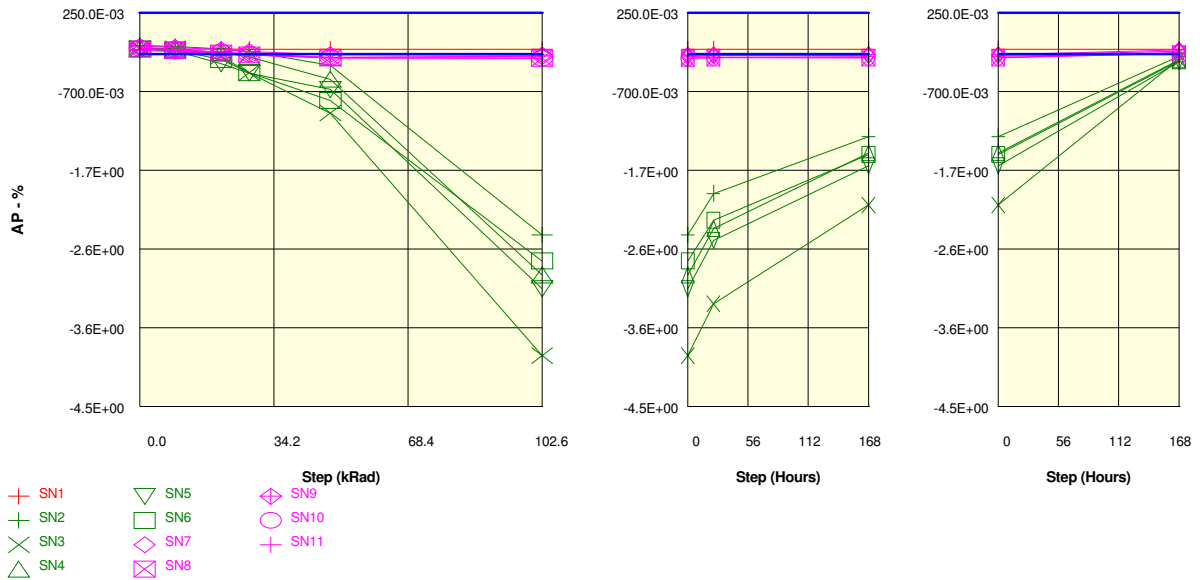
BPZE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-2.2E-03	-2.3E-03	-2.0E-03	-2.2E-03	-2.2E-03	-2.3E-03	-2.5E-03	-2.5E-03	-2.5E-03
<b>OFF samples</b>									
SN7	-361.3E-06	-136.7E-06	527.3E-06	351.6E-06	1.2E-03	1.1E-03	1.4E-03	1.6E-03	1.8E-03
SN8	322.3E-06	-127.0E-06	-322.3E-06	-849.6E-06	-1.4E-03	-2.5E-03	-1.9E-03	-2.0E-03	78.1E-06
SN9	-2.1E-03	-1.7E-03	-1.3E-03	-1.7E-03	-1.6E-03	-957.0E-06	-810.5E-06	-1.1E-03	146.5E-06
SN10	-1.4E-03	-1.5E-03	-849.6E-06	-1.5E-03	-556.6E-06	-332.0E-06	-498.0E-06	-117.2E-06	576.2E-06
SN11	-1.4E-03	-1.1E-03	-1.5E-03	-2.0E-03	-1.6E-03	-1.9E-03	-1.9E-03	-2.0E-03	-136.7E-06
<b>Statistics</b>									
Min	-2.1E-03	-1.7E-03	-1.5E-03	-2.0E-03	-1.6E-03	-2.5E-03	-1.9E-03	-2.0E-03	-136.7E-06
Max	322.3E-06	-127.0E-06	527.3E-06	351.6E-06	1.2E-03	1.1E-03	1.4E-03	1.6E-03	1.8E-03
Average	-1.0E-03	-919.9E-06	-697.3E-06	-1.1E-03	-794.9E-06	-923.8E-06	-740.2E-06	-716.8E-06	502.0E-06
Sigma	868.5E-06	672.8E-06	740.4E-06	828.7E-06	1.1E-03	1.2E-03	1.2E-03	1.4E-03	710.6E-06

**Drift Calculation**

BPZE	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	224.6E-06	888.7E-06	712.9E-06	1.5E-03	1.4E-03	1.8E-03	2.0E-03	2.2E-03
SN8	-	-449.2E-06	-644.5E-06	-1.2E-03	-1.8E-03	-2.8E-03	-2.2E-03	-2.4E-03	-244.1E-06
SN9	-	390.6E-06	820.3E-06	468.8E-06	546.9E-06	1.2E-03	1.3E-03	1.1E-03	2.3E-03
SN10	-	-68.4E-06	576.2E-06	-39.1E-06	869.1E-06	1.1E-03	927.7E-06	1.3E-03	2.0E-03
SN11	-	312.5E-06	-117.2E-06	-585.9E-06	-146.5E-06	-498.0E-06	-468.8E-06	-556.6E-06	1.3E-03
Average	-	82.0E-06	304.7E-06	-123.0E-06	207.0E-06	78.1E-06	261.7E-06	285.2E-06	1.5E-03
Sigma	-	307.7E-06	593.2E-06	688.5E-06	1.1E-03	1.6E-03	1.5E-03	1.6E-03	940.7E-06

Parameter : Positive full scale error : AP  
 Test conditions : Code=65535.5. Ta=+25°C

Unit : %  
 Spec Limit Min : -250.0E-03  
 Spec Limit Max : 250.0E-03  
 Spec limits are represented in bold lines on the graphic.



Measurements

AP	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-188.5E-03	-188.9E-03	-187.3E-03	-189.1E-03	-189.2E-03	-190.2E-03	-188.9E-03	-190.3E-03	-189.5E-03
ON samples									
SN2	-140.6E-03	-154.2E-03	-185.8E-03	-217.2E-03	<b>-383.7E-03</b>	<b>-2.4E+00</b>	<b>-1.9E+00</b>	<b>-1.2E+00</b>	<b>-275.5E-03</b>
SN3	-174.1E-03	-180.1E-03	<b>-276.0E-03</b>	<b>-472.8E-03</b>	<b>-960.4E-03</b>	<b>-3.9E+00</b>	<b>-3.3E+00</b>	<b>-2.1E+00</b>	<b>-311.6E-03</b>
SN4	-178.0E-03	-186.6E-03	-228.3E-03	<b>-283.0E-03</b>	<b>-551.2E-03</b>	<b>-2.9E+00</b>	<b>-2.4E+00</b>	<b>-1.4E+00</b>	<b>-317.1E-03</b>
SN5	-193.5E-03	-208.1E-03	<b>-364.7E-03</b>	<b>-478.6E-03</b>	<b>-673.9E-03</b>	<b>-3.1E+00</b>	<b>-2.5E+00</b>	<b>-1.6E+00</b>	<b>-337.9E-03</b>
SN6	-185.3E-03	-197.7E-03	<b>-312.8E-03</b>	<b>-471.5E-03</b>	<b>-806.8E-03</b>	<b>-2.7E+00</b>	<b>-2.3E+00</b>	<b>-1.5E+00</b>	<b>-328.8E-03</b>
Statistics									
Min	-193.5E-03	-208.1E-03	-364.7E-03	-478.6E-03	-960.4E-03	-3.9E+00	-3.3E+00	-2.1E+00	-337.9E-03
Max	-140.6E-03	-154.2E-03	-185.8E-03	-217.2E-03	-383.7E-03	-2.4E+00	-1.9E+00	-1.2E+00	-275.5E-03
Average	-174.3E-03	-185.3E-03	-273.5E-03	-384.6E-03	-675.2E-03	-3.0E+00	-2.5E+00	-1.6E+00	-314.2E-03
Sigma	18.1E-03	18.3E-03	62.6E-03	111.8E-03	199.5E-03	487.2E-03	442.2E-03	277.1E-03	21.4E-03

Drift Calculation

AP	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-13.6E-03	-45.2E-03	-76.6E-03	-243.1E-03	-2.3E+00	-1.8E+00	-1.1E+00	-134.9E-03
SN3	-	-5.9E-03	-101.9E-03	-298.6E-03	-786.3E-03	-3.7E+00	-3.1E+00	-1.9E+00	-137.5E-03
SN4	-	-8.6E-03	-50.3E-03	-105.0E-03	-373.2E-03	-2.7E+00	-2.2E+00	-1.3E+00	-139.1E-03
SN5	-	-14.6E-03	-171.2E-03	-285.0E-03	-480.4E-03	-2.9E+00	-2.3E+00	-1.4E+00	-144.3E-03
SN6	-	-12.4E-03	-127.5E-03	-286.2E-03	-621.5E-03	-2.6E+00	-2.1E+00	-1.3E+00	-143.5E-03
Average	-	-11.0E-03	-99.2E-03	-210.3E-03	-500.9E-03	-2.8E+00	-2.3E+00	-1.4E+00	-139.9E-03
Sigma	-	3.3E-03	47.5E-03	98.1E-03	189.3E-03	480.3E-03	435.4E-03	270.6E-03	3.6E-03



Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT					Ref.:	HRX/TID/1197
	AD976SD/883		Analog Devices			Issue:	02

**Measurements**

AP	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-188.5E-03	-188.9E-03	-187.3E-03	-189.1E-03	-189.2E-03	-190.2E-03	-188.9E-03	-190.3E-03	-189.5E-03
OFF samples									
SN7	-177.2E-03	-194.2E-03	-225.6E-03	-245.8E-03	-286.2E-03	-278.3E-03	-269.2E-03	-264.4E-03	-213.1E-03
SN8	-187.5E-03	-204.5E-03	-236.0E-03	-257.7E-03	-293.3E-03	-296.7E-03	-291.7E-03	-292.7E-03	-241.9E-03
SN9	-151.3E-03	-165.5E-03	-194.0E-03	-216.7E-03	-255.1E-03	-257.9E-03	-252.2E-03	-253.6E-03	-196.4E-03
SN10	-179.7E-03	-196.2E-03	-226.1E-03	-251.6E-03	-292.8E-03	-299.2E-03	-291.2E-03	-290.3E-03	-228.4E-03
SN11	-204.2E-03	-216.7E-03	-244.8E-03	-260.1E-03	-288.8E-03	-271.8E-03	-265.8E-03	-275.1E-03	-244.3E-03
Statistics									
Min	-204.2E-03	-216.7E-03	-244.8E-03	-260.1E-03	-293.3E-03	-299.2E-03	-291.7E-03	-292.7E-03	-244.3E-03
Max	-151.3E-03	-165.5E-03	-194.0E-03	-216.7E-03	-255.1E-03	-257.9E-03	-252.2E-03	-253.6E-03	-196.4E-03
Average	-180.0E-03	-195.4E-03	-225.3E-03	-246.4E-03	-283.2E-03	-280.8E-03	-274.0E-03	-275.2E-03	-224.8E-03
Sigma	17.2E-03	16.9E-03	17.2E-03	15.7E-03	14.3E-03	15.5E-03	15.4E-03	14.9E-03	18.1E-03

**Drift Calculation**

AP	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-17.0E-03	-48.4E-03	-68.6E-03	-109.0E-03	-101.1E-03	-92.0E-03	-87.2E-03	-35.9E-03
SN8	-	-17.0E-03	-48.5E-03	-70.3E-03	-105.9E-03	-109.3E-03	-104.2E-03	-105.2E-03	-54.5E-03
SN9	-	-14.2E-03	-42.7E-03	-65.4E-03	-103.8E-03	-106.6E-03	-100.9E-03	-102.3E-03	-45.1E-03
SN10	-	-16.5E-03	-46.4E-03	-71.9E-03	-113.1E-03	-119.5E-03	-111.5E-03	-110.6E-03	-48.7E-03
SN11	-	-12.5E-03	-40.7E-03	-55.9E-03	-84.6E-03	-67.6E-03	-61.6E-03	-71.0E-03	-40.1E-03
Average	-	-15.5E-03	-45.4E-03	-66.4E-03	-103.3E-03	-100.8E-03	-94.1E-03	-95.2E-03	-44.9E-03
Sigma	-	1.8E-03	3.1E-03	5.7E-03	9.8E-03	17.6E-03	17.4E-03	14.4E-03	6.5E-03

Parameter : Negative full scale error : AN

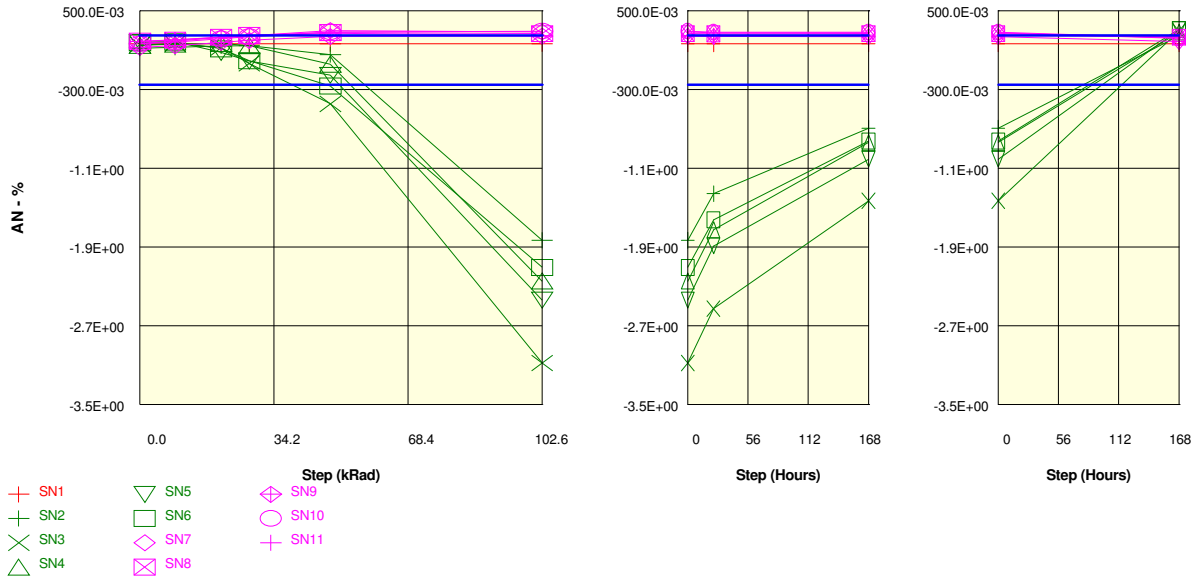
Test conditions : Code=0.5. Ta=+25°C

Unit : %

Spec Limit Min : -250.0E-03

Spec Limit Max : 250.0E-03

Spec limits are represented in bold lines on the graphic.



AN	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	166.2E-03	164.8E-03	164.5E-03	164.9E-03	165.5E-03	165.4E-03	164.2E-03	165.3E-03	164.7E-03
ON samples									
SN2	120.2E-03	129.8E-03	142.3E-03	144.3E-03	55.0E-03	-1.8E+00	-1.4E+00	-692.2E-03	245.6E-03
SN3	154.2E-03	167.7E-03	126.2E-03	-35.3E-03	-444.6E-03	-3.1E+00	-2.5E+00	-1.4E+00	294.3E-03
SN4	148.6E-03	161.9E-03	167.5E-03	145.4E-03	-43.7E-03	-2.2E+00	-1.7E+00	-838.1E-03	284.0E-03
SN5	180.5E-03	186.1E-03	78.5E-03	-11.3E-03	-154.4E-03	-2.4E+00	-1.9E+00	-1.0E+00	307.2E-03
SN6	173.2E-03	179.6E-03	115.3E-03	-6.7E-03	-263.4E-03	-2.1E+00	-1.6E+00	-823.9E-03	311.3E-03
Statistics									
Min	120.2E-03	129.8E-03	78.5E-03	-35.3E-03	-444.6E-03	-3.1E+00	-2.5E+00	-1.4E+00	245.6E-03
Max	180.5E-03	186.1E-03	167.5E-03	145.4E-03	55.0E-03	-1.8E+00	-1.4E+00	-692.2E-03	311.3E-03
Average	155.3E-03	165.0E-03	126.0E-03	47.3E-03	-170.2E-03	-2.3E+00	-1.8E+00	-958.1E-03	288.5E-03
Sigma	21.1E-03	19.6E-03	29.5E-03	80.3E-03	173.8E-03	419.0E-03	390.7E-03	256.0E-03	23.5E-03

AN	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	9.6E-03	22.1E-03	24.1E-03	-65.1E-03	-2.0E+00	-1.5E+00	-812.3E-03	125.4E-03
SN3	-	13.6E-03	-28.0E-03	-189.4E-03	-598.8E-03	-3.2E+00	-2.7E+00	-1.6E+00	140.1E-03
SN4	-	13.3E-03	18.9E-03	-3.3E-03	-192.4E-03	-2.4E+00	-1.9E+00	-986.7E-03	135.4E-03
SN5	-	5.6E-03	-102.0E-03	-191.8E-03	-334.9E-03	-2.6E+00	-2.1E+00	-1.2E+00	126.8E-03
SN6	-	6.4E-03	-57.9E-03	-179.9E-03	-436.7E-03	-2.3E+00	-1.8E+00	-997.1E-03	138.1E-03
Average	-	9.7E-03	-29.4E-03	-108.1E-03	-325.6E-03	-2.5E+00	-2.0E+00	-1.1E+00	133.2E-03
Sigma	-	3.3E-03	47.1E-03	97.2E-03	185.8E-03	427.1E-03	398.5E-03	263.3E-03	6.0E-03

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

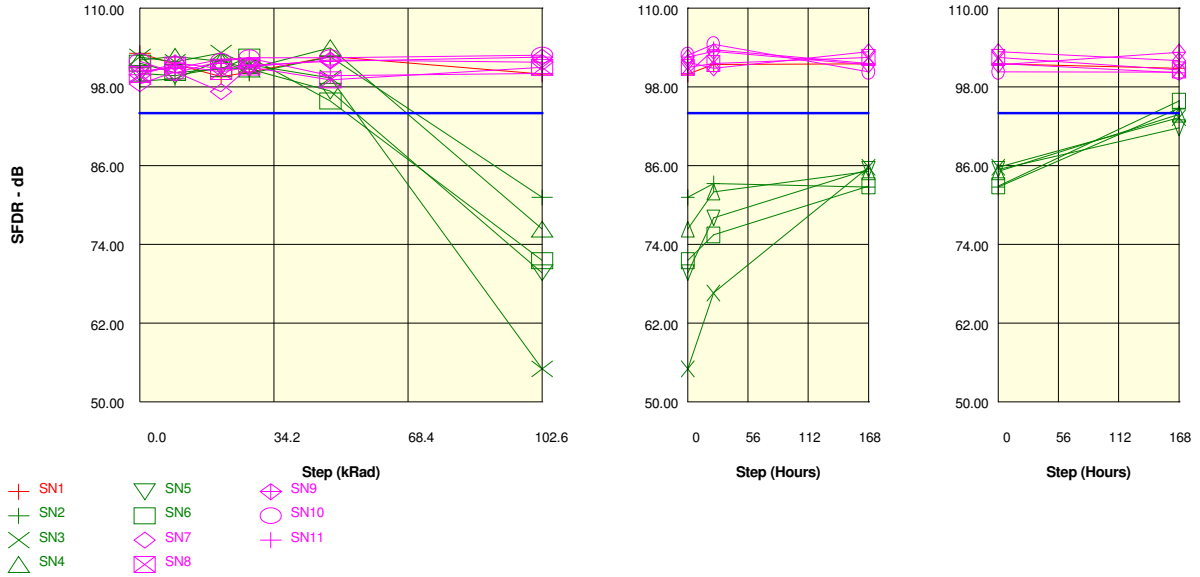
**Measurements**

AN	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	166.2E-03	164.8E-03	164.5E-03	164.9E-03	165.5E-03	165.4E-03	164.2E-03	165.3E-03	164.7E-03
<b>OFF samples</b>									
SN7	170.5E-03	190.5E-03	228.6E-03	248.7E-03	297.9E-03	286.3E-03	278.6E-03	274.7E-03	220.9E-03
SN8	190.6E-03	203.6E-03	232.4E-03	249.3E-03	279.0E-03	269.2E-03	266.4E-03	268.4E-03	232.8E-03
SN9	129.2E-03	146.1E-03	179.7E-03	199.4E-03	239.6E-03	242.9E-03	238.8E-03	238.3E-03	187.3E-03
SN10	163.2E-03	180.1E-03	215.7E-03	237.3E-03	285.5E-03	292.1E-03	282.7E-03	283.5E-03	223.6E-03
SN11	189.7E-03	204.5E-03	228.7E-03	240.8E-03	273.0E-03	248.6E-03	242.6E-03	251.4E-03	232.9E-03
<b>Statistics</b>									
Min	129.2E-03	146.1E-03	179.7E-03	199.4E-03	239.6E-03	242.9E-03	238.8E-03	238.3E-03	187.3E-03
Max	190.6E-03	204.5E-03	232.4E-03	249.3E-03	297.9E-03	292.1E-03	282.7E-03	283.5E-03	232.9E-03
Average	168.6E-03	185.0E-03	217.0E-03	235.1E-03	275.0E-03	267.8E-03	261.8E-03	263.3E-03	219.5E-03
Sigma	22.4E-03	21.4E-03	19.5E-03	18.4E-03	19.5E-03	19.6E-03	18.1E-03	16.3E-03	16.8E-03

**Drift Calculation**

AN	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	20.0E-03	58.1E-03	78.2E-03	127.4E-03	115.8E-03	108.1E-03	104.1E-03	50.4E-03
SN8	-	13.0E-03	41.8E-03	58.7E-03	88.4E-03	78.6E-03	75.8E-03	77.8E-03	42.2E-03
SN9	-	16.8E-03	50.4E-03	70.2E-03	110.3E-03	113.7E-03	109.6E-03	109.1E-03	58.0E-03
SN10	-	16.9E-03	52.6E-03	74.2E-03	122.3E-03	128.9E-03	119.6E-03	120.4E-03	60.4E-03
SN11	-	14.8E-03	39.0E-03	51.0E-03	83.2E-03	58.9E-03	52.9E-03	61.7E-03	43.2E-03
Average	-	16.3E-03	48.4E-03	66.5E-03	106.3E-03	99.2E-03	93.2E-03	94.6E-03	50.8E-03
Sigma	-	2.3E-03	7.0E-03	10.1E-03	17.7E-03	26.2E-03	25.0E-03	21.6E-03	7.4E-03

Parameter : Spurious free dynamic range : SFDR  
 Test conditions : Fin=45KHz  
 Unit : dB  
 Spec Limit Min : 94.00  
 Spec limits are represented in bold lines on the graphic.



Measurements

SFDR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	103.12	101.45	99.57	100.22	102.66	99.94	101.42	101.54	100.87
ON samples									
SN2	98.92	99.25	102.09	100.06	102.59	81.16	83.24	82.75	94.73
SN3	102.58	101.81	103.18	101.41	99.38	55.04	66.63	85.77	93.31
SN4	102.13	102.64	101.95	100.76	103.96	76.34	82.02	85.11	93.84
SN5	100.06	99.69	100.96	100.74	97.36	69.69	78.05	85.45	91.76
SN6	101.62	100.17	100.76	102.54	95.86	71.54	75.45	82.92	95.85
Statistics									
Min	98.92	99.25	100.76	100.06	95.86	55.04	66.63	82.75	91.76
Max	102.58	102.64	103.18	102.54	103.96	81.16	83.24	85.77	95.85
Average	101.06	100.71	101.79	101.10	99.83	70.76	77.08	84.40	93.90
Sigma	1.37	1.30	0.87	0.83	3.06	8.81	5.92	1.29	1.37

Drift Calculation

SFDR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	335.0E-03	3.2E+00	1.1E+00	3.7E+00	-17.8E+00	-15.7E+00	-16.2E+00	-4.2E+00
SN3	-	-770.0E-03	603.0E-03	-1.2E+00	-3.2E+00	-47.5E+00	-36.0E+00	-16.8E+00	-9.3E+00
SN4	-	508.0E-03	-187.0E-03	-1.4E+00	1.8E+00	-25.8E+00	-20.1E+00	-17.0E+00	-8.3E+00
SN5	-	-369.0E-03	901.0E-03	679.0E-03	-2.7E+00	-30.4E+00	-22.0E+00	-14.6E+00	-8.3E+00
SN6	-	-1.4E+00	-856.0E-03	916.0E-03	-5.8E+00	-30.1E+00	-26.2E+00	-18.7E+00	-5.8E+00
Average	-	-349.0E-03	727.8E-03	40.2E-03	-1.2E+00	-30.3E+00	-24.0E+00	-16.7E+00	-7.2E+00
Sigma	-	719.7E-03	1.4E+00	1.1E+00	3.5E+00	9.7E+00	6.9E+00	1.3E+00	1.9E+00

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

SFDR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	103.12	101.45	99.57	100.22	102.66	99.94	101.42	101.54	100.87
<b>OFF samples</b>									
SN7	98.46	100.29	97.28	101.08	102.09	101.74	100.86	103.40	102.02
SN8	99.93	101.34	100.33	101.04	99.07	100.99	101.57	102.49	100.60
SN9	99.84	101.67	100.78	101.28	101.94	102.54	103.40	101.36	103.29
SN10	101.90	100.16	101.92	102.45	102.45	102.84	104.48	100.30	100.26
SN11	100.43	100.87	102.22	102.41	99.68	100.07	103.66	101.56	100.15
<b>Statistics</b>									
Min	98.46	100.16	97.28	101.04	99.07	100.07	100.86	100.30	100.15
Max	101.90	101.67	102.22	102.45	102.45	102.84	104.48	103.40	103.29
Average	100.11	100.86	100.51	101.65	101.05	101.64	102.79	101.82	101.26
Sigma	1.11	0.58	1.76	0.64	1.39	1.02	1.36	1.05	1.21

**Drift Calculation**

SFDR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	1.8E+00	-1.2E+00	2.6E+00	3.6E+00	3.3E+00	2.4E+00	4.9E+00	3.6E+00
SN8	-	1.4E+00	405.0E-03	1.1E+00	-855.0E-03	1.1E+00	1.6E+00	2.6E+00	672.0E-03
SN9	-	1.8E+00	948.0E-03	1.4E+00	2.1E+00	2.7E+00	3.6E+00	1.5E+00	3.5E+00
SN10	-	-1.7E+00	14.0E-03	544.0E-03	550.0E-03	941.0E-03	2.6E+00	-1.6E+00	-1.6E+00
SN11	-	433.0E-03	1.8E+00	2.0E+00	-757.0E-03	-367.0E-03	3.2E+00	1.1E+00	-287.0E-03
Average	-	752.2E-03	394.2E-03	1.5E+00	935.0E-03	1.5E+00	2.7E+00	1.7E+00	1.2E+00
Sigma	-	1.3E+00	986.0E-03	710.9E-03	1.7E+00	1.3E+00	669.2E-03	2.1E+00	2.1E+00

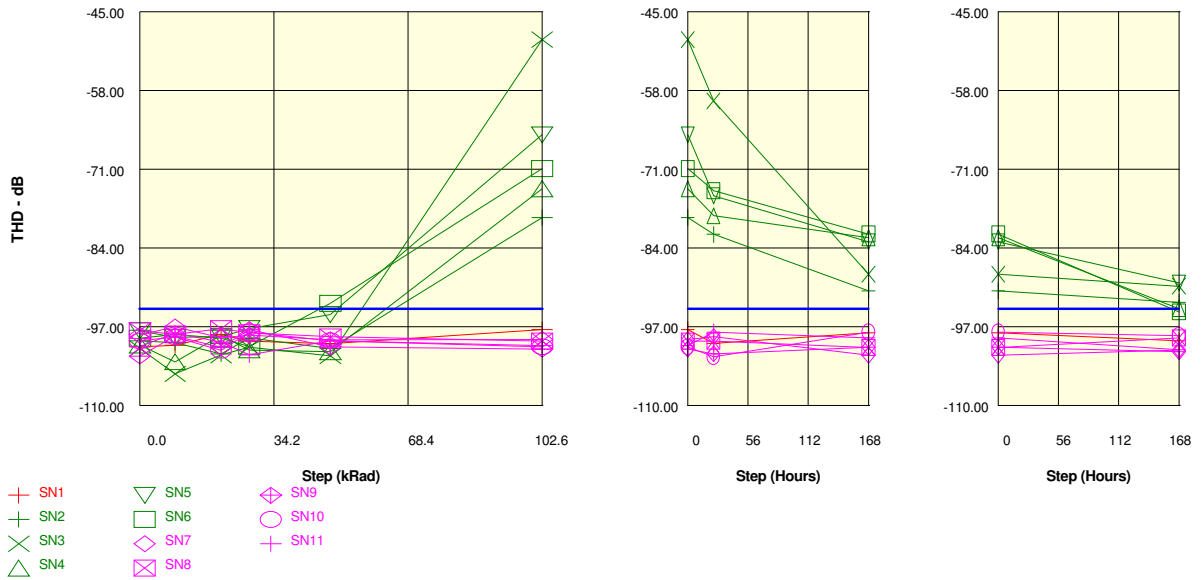
**Parameter : Total Harmonic Distorsion : THD**

**Test conditions : Fin=45KHz. Vin=-0.5dB. Fin=45KHz. all measurement referred to a 0dB (20Vpp) input signal. THD includes first six harmonics. Bandwidth =50kHz**

Unit : dB

Spec Limit Max : -94.00

Spec limits are represented in bold lines on the graphic.



Measurements									
THD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-100.31	-100.06	-98.24	-99.37	-99.81	-97.47	-99.73	-97.99	-99.35
ON samples									
SN2	-99.31	-99.65	-101.48	-98.81	-100.61	-78.98	-81.74	-91.07	-92.97
SN3	-100.58	-104.77	-101.66	-100.34	-101.78	-49.60	-59.72	-88.31	-90.30
SN4	-99.99	-102.79	-98.42	-100.82	-101.11	-74.23	-78.67	-82.30	-93.99
SN5	-97.68	-98.73	-98.63	-97.28	-94.99	-65.30	-75.36	-82.96	-89.77
SN6	-98.89	-98.26	-98.87	-100.24	-93.14	-70.88	-74.54	-81.69	-94.54
Statistics									
Min	-100.58	-104.77	-101.66	-100.82	-101.78	-78.98	-81.74	-91.07	-94.54
Max	-97.68	-98.26	-98.42	-97.28	-93.14	-49.60	-59.72	-81.69	-89.77
Average	-99.29	-100.84	-99.81	-99.50	-98.32	-67.80	-74.01	-85.27	-92.31
Sigma	0.99	2.52	1.44	1.30	3.55	10.13	7.59	3.74	1.93

Drift Calculation									
THD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-344.0E-03	-2.2E+00	496.0E-03	-1.3E+00	20.3E+00	17.6E+00	8.2E+00	6.3E+00
SN3	-	-4.2E+00	-1.1E+00	234.0E-03	-1.2E+00	51.0E+00	40.9E+00	12.3E+00	10.3E+00
SN4	-	-2.8E+00	1.6E+00	-831.0E-03	-1.1E+00	25.8E+00	21.3E+00	17.7E+00	6.0E+00
SN5	-	-1.1E+00	-950.0E-03	397.0E-03	2.7E+00	32.4E+00	22.3E+00	14.7E+00	7.9E+00
SN6	-	634.0E-03	20.0E-03	-1.4E+00	5.8E+00	28.0E+00	24.4E+00	17.2E+00	4.4E+00
Average	-	-1.6E+00	-522.8E-03	-211.2E-03	964.8E-03	31.5E+00	25.3E+00	14.0E+00	7.0E+00
Sigma	-	1.7E+00	1.3E+00	742.1E-03	2.8E+00	10.5E+00	8.1E+00	3.5E+00	2.0E+00

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

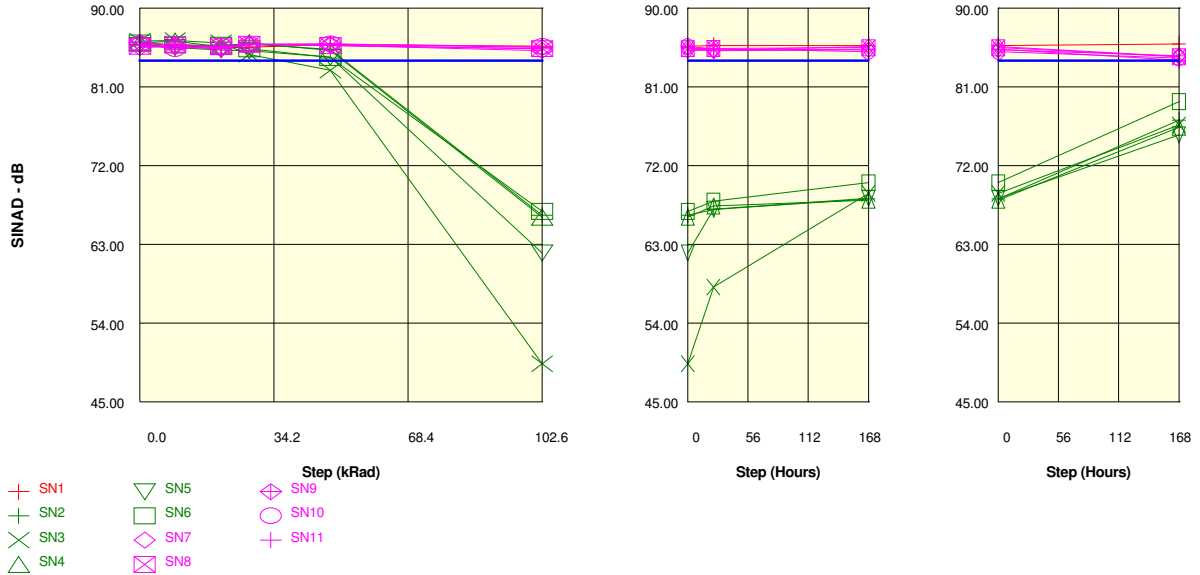
**Measurements**

THD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-100.31	-100.06	-98.24	-99.37	-99.81	-97.47	-99.73	-97.99	-99.35
<b>OFF samples</b>									
SN7	-98.39	-97.01	-98.81	-98.38	-99.14	-99.08	-98.64	-101.70	-100.83
SN8	-97.61	-98.22	-97.30	-97.99	-98.66	-99.35	-99.38	-100.41	-98.82
SN9	-101.82	-98.50	-100.43	-97.48	-100.30	-100.69	-101.44	-100.38	-101.11
SN10	-99.34	-98.67	-100.88	-97.85	-99.30	-100.30	-101.94	-97.86	-98.43
SN11	-100.27	-98.04	-99.54	-101.63	-99.34	-100.11	-97.85	-98.86	-100.79
<b>Statistics</b>									
Min	-101.82	-98.67	-100.88	-101.63	-100.30	-100.69	-101.94	-101.70	-101.11
Max	-97.61	-97.01	-97.30	-97.48	-98.66	-99.08	-97.85	-97.86	-98.43
Average	-99.49	-98.09	-99.39	-98.66	-99.35	-99.90	-99.85	-99.84	-100.00
Sigma	1.47	0.58	1.27	1.51	0.54	0.60	1.58	1.34	1.13

**Drift Calculation**

THD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	1.4E+00	-425.0E-03	8.0E-03	-755.0E-03	-688.0E-03	-255.0E-03	-3.3E+00	-2.4E+00
SN8	-	-609.0E-03	317.0E-03	-379.0E-03	-1.0E+00	-1.7E+00	-1.8E+00	-2.8E+00	-1.2E+00
SN9	-	3.3E+00	1.4E+00	4.3E+00	1.5E+00	1.1E+00	383.0E-03	1.4E+00	713.0E-03
SN10	-	671.0E-03	-1.5E+00	1.5E+00	36.0E-03	-958.0E-03	-2.6E+00	1.5E+00	906.0E-03
SN11	-	2.2E+00	733.0E-03	-1.4E+00	929.0E-03	160.0E-03	2.4E+00	1.4E+00	-523.0E-03
Average	-	1.4E+00	95.4E-03	820.8E-03	136.0E-03	-419.4E-03	-362.2E-03	-355.6E-03	-510.6E-03
Sigma	-	1.3E+00	1.0E+00	2.0E+00	972.0E-03	983.8E-03	1.7E+00	2.2E+00	1.2E+00

Parameter : Signal-to-noise + distortion : SINAD  
 Test conditions : Fin=45KHz. Vin=-0.5dB. Fin=45KHz. all measurement referred to a 0dB (20Vpp) input signal  
 Unit : dB  
 Spec Limit Min : 84.00  
 Spec limits are represented in bold lines on the graphic.



Measurements

SINAD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	85.79	85.81	85.47	85.55	85.81	85.66	85.71	85.72	85.91
ON samples									
SN2	85.87	85.52	85.75	85.89	85.30	66.33	67.02	68.20	77.22
SN3	86.25	86.31	86.04	84.72	82.91	49.38	58.13	68.83	76.67
SN4	86.03	86.22	85.58	86.04	85.19	66.12	67.40	68.07	76.39
SN5	85.72	85.49	85.23	85.15	84.41	62.02	67.04	68.29	75.51
SN6	86.02	85.78	85.76	85.36	84.36	66.78	67.95	70.05	79.33
Statistics									
Min	85.72	85.49	85.23	84.72	82.91	49.38	58.13	68.07	75.51
Max	86.25	86.31	86.04	86.04	85.30	66.78	67.95	70.05	79.33
Average	85.98	85.86	85.67	85.43	84.44	62.13	65.51	68.69	77.02
Sigma	0.18	0.34	0.27	0.48	0.85	6.60	3.71	0.73	1.28

Drift Calculation

SINAD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-344.9E-03	-118.5E-03	20.0E-03	-563.9E-03	-19.5E+00	-18.9E+00	-17.7E+00	-8.6E+00
SN3	-	53.1E-03	-211.3E-03	-1.5E+00	-3.3E+00	-36.9E+00	-28.1E+00	-17.4E+00	-9.6E+00
SN4	-	190.3E-03	-451.6E-03	3.5E-03	-844.3E-03	-19.9E+00	-18.6E+00	-18.0E+00	-9.6E+00
SN5	-	-230.1E-03	-492.3E-03	-567.6E-03	-1.3E+00	-23.7E+00	-18.7E+00	-17.4E+00	-10.2E+00
SN6	-	-240.5E-03	-262.2E-03	-659.2E-03	-1.7E+00	-19.2E+00	-18.1E+00	-16.0E+00	-6.7E+00
Average	-	-114.4E-03	-307.2E-03	-547.7E-03	-1.5E+00	-23.9E+00	-20.5E+00	-17.3E+00	-9.0E+00
Sigma	-	201.7E-03	142.8E-03	568.1E-03	973.3E-03	6.7E+00	3.8E+00	691.6E-03	1.2E+00



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**Measurements**

SINAD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	85.79	85.81	85.47	85.55	85.81	85.66	85.71	85.72	85.91
<b>OFF samples</b>									
SN7	85.50	85.60	85.35	85.82	85.77	85.16	85.23	85.62	84.48
SN8	85.63	85.88	85.59	85.87	85.74	85.37	85.39	85.48	84.44
SN9	86.07	85.80	85.48	85.89	85.88	85.50	85.13	85.26	84.57
SN10	85.93	85.33	85.68	85.85	85.91	85.63	85.35	85.02	84.29
SN11	85.73	85.59	85.34	85.90	85.73	85.34	85.20	85.33	84.05
<b>Statistics</b>									
Min	85.50	85.33	85.34	85.82	85.73	85.16	85.13	85.02	84.05
Max	86.07	85.88	85.68	85.90	85.91	85.63	85.39	85.62	84.57
Average	85.77	85.64	85.49	85.87	85.80	85.40	85.26	85.34	84.37
Sigma	0.20	0.19	0.13	0.03	0.07	0.16	0.10	0.20	0.18

**Drift Calculation**

SINAD	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	102.1E-03	-148.0E-03	315.7E-03	266.0E-03	-344.4E-03	-267.4E-03	113.0E-03	-1.0E+00
SN8	-	247.4E-03	-44.1E-03	237.4E-03	101.9E-03	-264.7E-03	-238.7E-03	-152.5E-03	-1.2E+00
SN9	-	-269.3E-03	-588.2E-03	-174.6E-03	-189.5E-03	-562.6E-03	-936.8E-03	-806.6E-03	-1.5E+00
SN10	-	-593.7E-03	-250.5E-03	-80.1E-03	-16.0E-03	-300.2E-03	-572.9E-03	-903.6E-03	-1.6E+00
SN11	-	-143.7E-03	-390.0E-03	169.7E-03	3.0E-03	-391.8E-03	-527.5E-03	-400.6E-03	-1.7E+00
Average	-	-131.5E-03	-284.2E-03	93.6E-03	33.1E-03	-372.7E-03	-508.7E-03	-430.0E-03	-1.4E+00
Sigma	-	293.6E-03	190.2E-03	188.6E-03	149.6E-03	104.1E-03	252.6E-03	384.4E-03	253.8E-03

Parameter : Voltage reference output : VREF

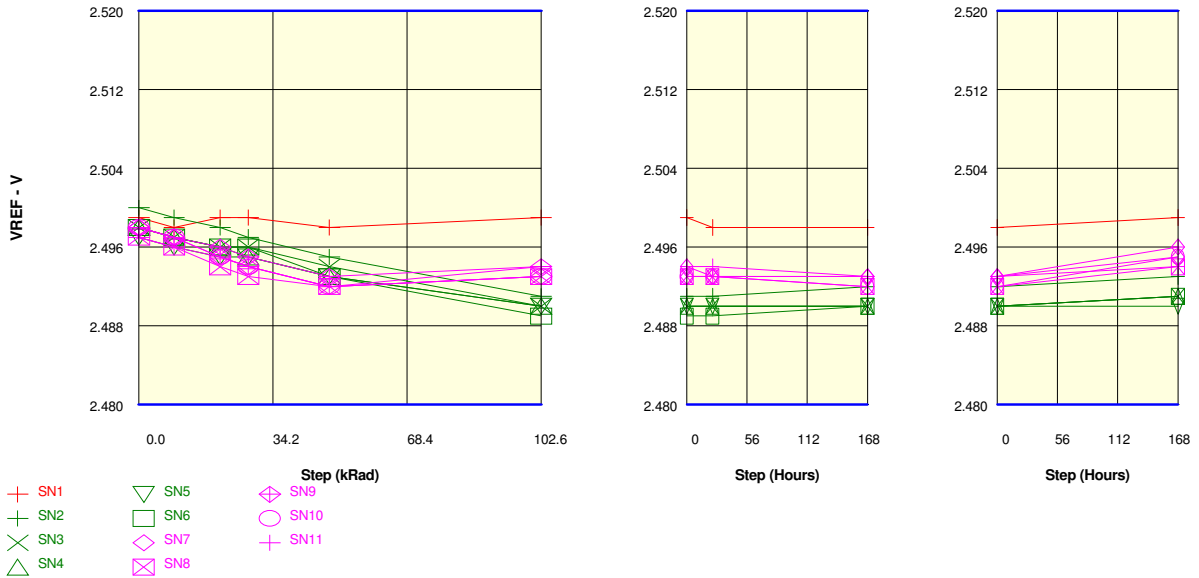
Test conditions : Ta=+25°C

Unit : V

Spec Limit Min : 2.480

Spec Limit Max : 2.520

Spec limits are represented in bold lines on the graphic.



Measurements

VREF	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	2.499	2.498	2.499	2.499	2.498	2.499	2.498	2.498	2.499
ON samples									
SN2	2.500	2.499	2.498	2.497	2.495	2.491	2.491	2.492	2.493
SN3	2.498	2.497	2.496	2.496	2.494	2.490	2.490	2.490	2.491
SN4	2.498	2.497	2.496	2.495	2.493	2.490	2.490	2.490	2.491
SN5	2.497	2.496	2.495	2.495	2.493	2.490	2.490	2.490	2.490
SN6	2.498	2.497	2.496	2.496	2.493	2.489	2.489	2.490	2.491
Statistics									
Min	2.497	2.496	2.495	2.495	2.493	2.489	2.489	2.490	2.490
Max	2.500	2.499	2.498	2.497	2.495	2.491	2.491	2.492	2.493
Average	2.498	2.497	2.496	2.496	2.494	2.490	2.490	2.490	2.491
Sigma	0.001	0.001	0.001	0.001	0.001	0.001	0.001	0.001	0.001

Drift Calculation

VREF	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-1000.0E-06	-2.0E-03	-3.0E-03	-5.0E-03	-9.0E-03	-9.0E-03	-8.0E-03	-7.0E-03
SN3	-	-1.0E-03	-2.0E-03	-2.0E-03	-4.0E-03	-8.0E-03	-8.0E-03	-8.0E-03	-7.0E-03
SN4	-	-1.0E-03	-2.0E-03	-3.0E-03	-5.0E-03	-8.0E-03	-8.0E-03	-8.0E-03	-7.0E-03
SN5	-	-1000.0E-06	-2.0E-03	-2.0E-03	-4.0E-03	-7.0E-03	-7.0E-03	-7.0E-03	-7.0E-03
SN6	-	-1.0E-03	-2.0E-03	-2.0E-03	-5.0E-03	-9.0E-03	-9.0E-03	-8.0E-03	-7.0E-03
Average	-	-1.0E-03	-2.0E-03	-2.4E-03	-4.6E-03	-8.2E-03	-8.2E-03	-7.8E-03	-7.0E-03
Sigma	-	9.2E-12	41.2E-12	489.9E-06	489.9E-06	748.3E-06	748.3E-06	400.0E-06	73.6E-12

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**Measurements**

VREF	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	2.499	2.498	2.499	2.499	2.498	2.499	2.498	2.498	2.499
OFF samples									
SN7	2.498	2.497	2.495	2.494	2.492	2.493	2.493	2.493	2.495
SN8	2.497	2.496	2.494	2.493	2.492	2.493	2.493	2.492	2.494
SN9	2.498	2.497	2.496	2.495	2.493	2.494	2.493	2.493	2.496
SN10	2.498	2.497	2.495	2.494	2.492	2.493	2.493	2.492	2.495
SN11	2.497	2.496	2.495	2.494	2.492	2.494	2.494	2.493	2.494
Statistics									
Min	2.497	2.496	2.494	2.493	2.492	2.493	2.493	2.492	2.494
Max	2.498	2.497	2.496	2.495	2.493	2.494	2.494	2.493	2.496
Average	2.498	2.497	2.495	2.494	2.492	2.493	2.493	2.493	2.495
Sigma	0.000	0.000	0.001	0.001	0.000	0.000	0.000	0.000	0.001

**Drift Calculation**

VREF	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-1.0E-03	-3.0E-03	-4.0E-03	-6.0E-03	-5.0E-03	-5.0E-03	-5.0E-03	-3.0E-03
SN8	-	-1000.0E-06	-3.0E-03	-4.0E-03	-5.0E-03	-4.0E-03	-4.0E-03	-5.0E-03	-3.0E-03
SN9	-	-1.0E-03	-2.0E-03	-3.0E-03	-5.0E-03	-4.0E-03	-5.0E-03	-5.0E-03	-2.0E-03
SN10	-	-1.0E-03	-3.0E-03	-4.0E-03	-6.0E-03	-5.0E-03	-5.0E-03	-6.0E-03	-3.0E-03
SN11	-	-1000.0E-06	-2.0E-03	-3.0E-03	-5.0E-03	-3.0E-03	-3.0E-03	-4.0E-03	-3.0E-03
Average	-	-1.0E-03	-2.6E-03	-3.6E-03	-5.4E-03	-4.2E-03	-4.4E-03	-5.0E-03	-2.8E-03
Sigma	-	9.2E-12	489.9E-06	489.9E-06	489.9E-06	748.3E-06	800.0E-06	632.5E-06	400.0E-06

**Parameter : Power supply rejection : PSR**

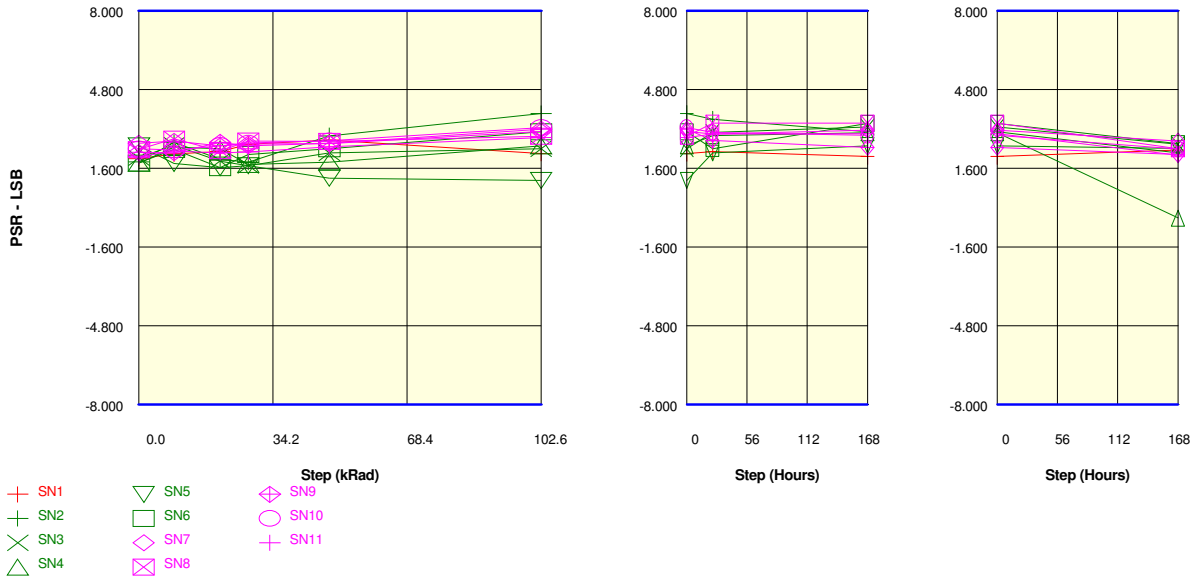
**Test conditions : Vdig=Vana=5V +/-5%**

Unit : LSB

Spec Limit Min : -8.000

Spec Limit Max : 8.000

Spec limits are represented in bold lines on the graphic.



**Measurements**

PSR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>SN1_REF</b>	1.991	2.188	2.282	2.585	2.743	2.209	2.282	2.083	2.337
<b>ON samples</b>									
SN2	1.862	2.655	1.974	1.850	2.925	3.828	3.596	3.086	2.220
SN3	2.029	2.539	1.897	1.713	2.226	2.397	3.063	3.279	2.579
SN4	1.807	2.470	2.390	1.756	1.854	2.513	2.930	3.046	-0.420
SN5	2.513	1.795	1.622	1.705	1.203	1.110	2.222	2.520	2.411
SN6	1.816	2.371	1.622	2.157	2.397	3.083	2.403	3.425	2.608
<b>Statistics</b>									
Min	1.807	1.795	1.622	1.705	1.203	1.110	2.222	2.520	-0.420
Max	2.513	2.655	2.390	2.157	2.925	3.828	3.596	3.425	2.608
Average	2.005	2.366	1.901	1.836	2.121	2.586	2.843	3.071	1.880
Sigma	0.266	0.300	0.283	0.168	0.574	0.895	0.490	0.308	1.158

**Drift Calculation**

PSR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>ON samples</b>									
SN2	-	793.0E-03	112.0E-03	-12.0E-03	1.1E+00	2.0E+00	1.7E+00	1.2E+00	358.0E-03
SN3	-	510.0E-03	-132.0E-03	-316.0E-03	197.0E-03	368.0E-03	1.0E+00	1.3E+00	550.0E-03
SN4	-	663.0E-03	583.0E-03	-51.0E-03	47.0E-03	706.0E-03	1.1E+00	1.2E+00	-2.2E+00
SN5	-	-718.0E-03	-891.0E-03	-808.0E-03	-1.3E+00	-1.4E+00	-291.0E-03	7.0E-03	-102.0E-03
SN6	-	555.0E-03	-194.0E-03	341.0E-03	581.0E-03	1.3E+00	587.0E-03	1.6E+00	792.0E-03
Average	-	360.6E-03	-104.4E-03	-169.2E-03	115.6E-03	580.8E-03	837.4E-03	1.1E+00	-125.8E-03
Sigma	-	548.1E-03	478.9E-03	381.7E-03	794.7E-03	1.1E+00	672.3E-03	548.6E-03	1.1E+00

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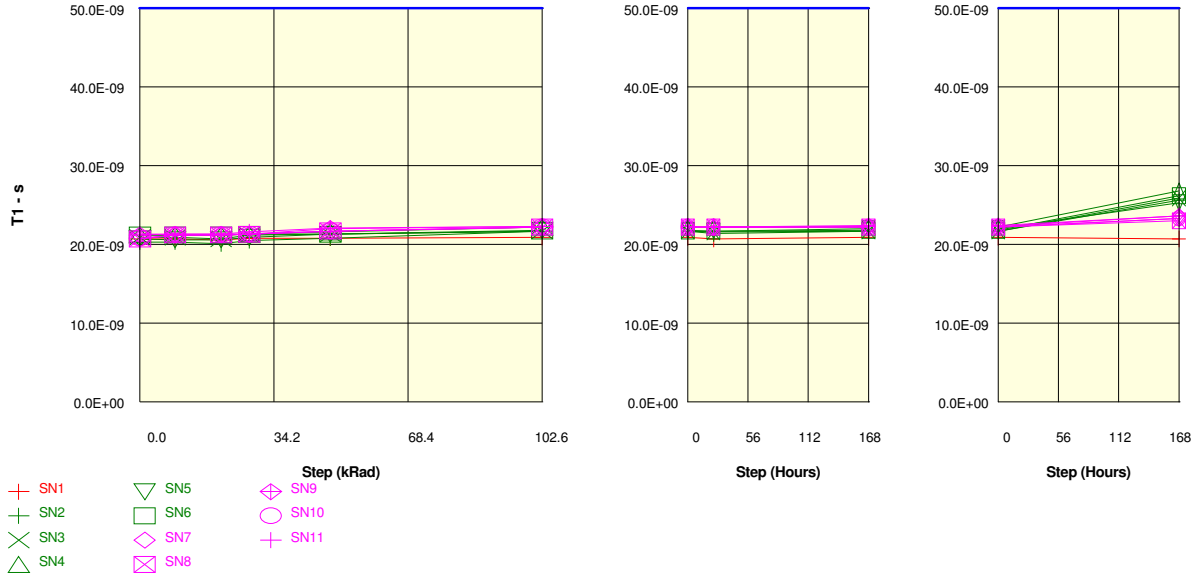
**Measurements**

PSR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	1.991	2.188	2.282	2.585	2.743	2.209	2.282	2.083	2.337
<b>OFF samples</b>									
SN7	2.618	2.702	2.512	2.596	2.610	3.100	2.986	3.150	2.711
SN8	2.363	2.791	2.310	2.713	2.695	2.903	3.441	3.435	2.397
SN9	2.246	2.235	2.659	2.510	2.617	3.189	2.738	2.452	2.157
SN10	2.390	2.346	2.521	2.624	2.716	3.254	3.054	2.934	2.380
SN11	2.072	2.309	2.235	2.265	2.471	2.850	2.999	3.008	2.140
<b>Statistics</b>									
Min	2.072	2.235	2.235	2.265	2.471	2.850	2.738	2.452	2.140
Max	2.618	2.791	2.659	2.713	2.716	3.254	3.441	3.435	2.711
Average	2.338	2.477	2.447	2.542	2.622	3.059	3.044	2.996	2.357
Sigma	0.179	0.225	0.154	0.153	0.086	0.158	0.227	0.321	0.207

**Drift Calculation**

PSR	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	84.0E-03	-106.0E-03	-22.0E-03	-8.0E-03	482.0E-03	368.0E-03	532.0E-03	93.0E-03
SN8	-	428.0E-03	-53.0E-03	350.0E-03	332.0E-03	540.0E-03	1.1E+00	1.1E+00	34.0E-03
SN9	-	-11.0E-03	413.0E-03	264.0E-03	371.0E-03	943.0E-03	492.0E-03	206.0E-03	-89.0E-03
SN10	-	-44.0E-03	131.0E-03	234.0E-03	326.0E-03	864.0E-03	664.0E-03	544.0E-03	-10.0E-03
SN11	-	237.0E-03	163.0E-03	193.0E-03	399.0E-03	778.0E-03	927.0E-03	936.0E-03	68.0E-03
Average	-	138.8E-03	109.6E-03	203.8E-03	284.0E-03	721.4E-03	705.8E-03	658.0E-03	19.2E-03
Sigma	-	174.4E-03	183.5E-03	124.1E-03	148.4E-03	180.5E-03	264.2E-03	310.4E-03	64.2E-03

Parameter : Convert pulse width : T1  
 Test conditions : Iol=1.6mA; loh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V  
 Unit : s  
 Spec Limit Max : 50.0E-09  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

T1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	20.7E-09	20.7E-09	20.6E-09	20.8E-09	20.8E-09	20.9E-09	20.7E-09	20.9E-09	20.7E-09
ON samples									
SN2	20.3E-09	20.3E-09	20.1E-09	20.5E-09	20.8E-09	21.7E-09	21.4E-09	21.7E-09	25.6E-09
SN3	20.9E-09	20.9E-09	20.7E-09	21.2E-09	21.3E-09	21.7E-09	21.6E-09	21.7E-09	25.9E-09
SN4	21.2E-09	21.2E-09	21.2E-09	21.3E-09	21.6E-09	22.2E-09	22.2E-09	22.2E-09	26.8E-09
SN5	20.7E-09	20.6E-09	20.6E-09	20.9E-09	21.3E-09	21.8E-09	21.7E-09	22.0E-09	25.3E-09
SN6	21.2E-09	21.2E-09	21.2E-09	21.3E-09	21.3E-09	21.7E-09	21.7E-09	21.8E-09	26.2E-09
Statistics									
Min	20.3E-09	20.3E-09	20.1E-09	20.5E-09	20.8E-09	21.7E-09	21.4E-09	21.7E-09	25.3E-09
Max	21.2E-09	21.2E-09	21.2E-09	21.3E-09	21.6E-09	22.2E-09	22.2E-09	22.2E-09	26.8E-09
Average	20.9E-09	20.8E-09	20.8E-09	21.0E-09	21.3E-09	21.8E-09	21.7E-09	21.9E-09	26.0E-09
Sigma	338.2E-12	349.9E-12	412.8E-12	307.2E-12	257.7E-12	193.9E-12	263.8E-12	193.9E-12	516.1E-12

**Drift Calculation**

T1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-200.0E-12	200.0E-12	500.0E-12	1.4E-09	1.1E-09	1.4E-09	5.3E-09
SN3	-	0.0E+00	-200.0E-12	300.0E-12	400.0E-12	800.0E-12	700.0E-12	800.0E-12	5.0E-09
SN4	-	0.0E+00	0.0E+00	100.0E-12	400.0E-12	1000.0E-12	1000.0E-12	1000.0E-12	5.6E-09
SN5	-	-100.0E-12	-100.0E-12	200.0E-12	600.0E-12	1.1E-09	1000.0E-12	1.3E-09	4.6E-09
SN6	-	0.0E+00	0.0E+00	100.0E-12	100.0E-12	500.0E-12	500.0E-12	600.0E-12	5.0E-09
Average	-	-20.0E-12	-100.0E-12	180.0E-12	400.0E-12	960.0E-12	860.0E-12	1.0E-09	5.1E-09
Sigma	-	40.0E-12	89.4E-12	74.8E-12	167.3E-12	300.7E-12	224.5E-12	299.3E-12	334.7E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

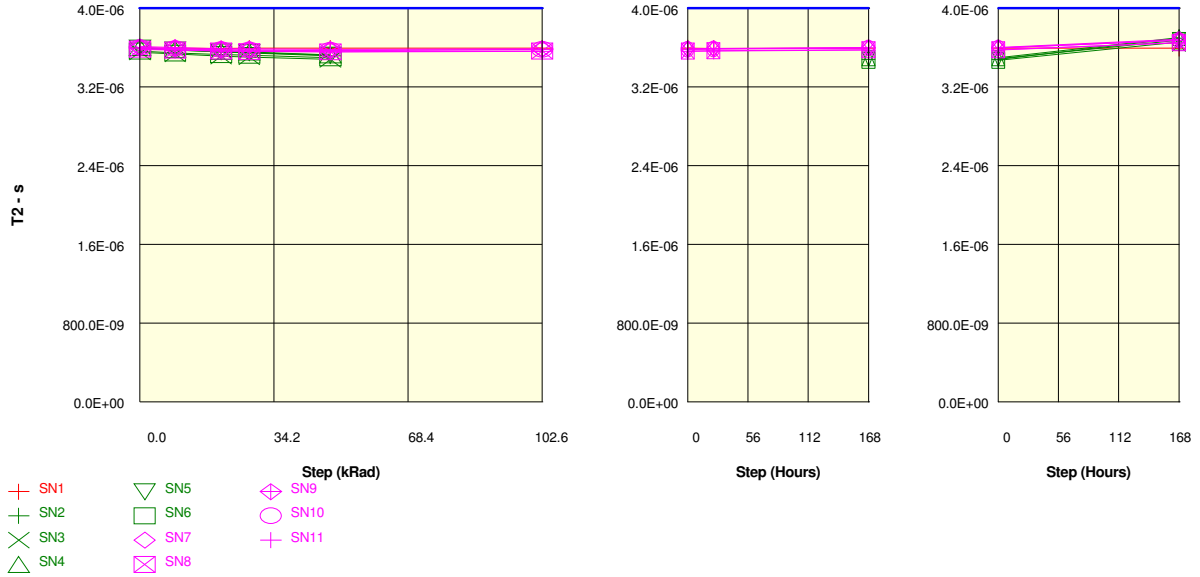
**Measurements**

T1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	20.7E-09	20.7E-09	20.6E-09	20.8E-09	20.8E-09	20.9E-09	20.7E-09	20.9E-09	20.7E-09
OFF samples									
SN7	20.7E-09	21.2E-09	21.2E-09	21.3E-09	21.7E-09	22.2E-09	22.2E-09	22.2E-09	23.3E-09
SN8	20.7E-09	21.2E-09	21.2E-09	21.3E-09	21.7E-09	22.2E-09	22.2E-09	22.2E-09	23.0E-09
SN9	21.2E-09	21.3E-09	21.3E-09	21.3E-09	22.0E-09	22.3E-09	22.2E-09	22.3E-09	23.6E-09
SN10	20.8E-09	21.2E-09	21.2E-09	21.3E-09	21.7E-09	22.2E-09	22.2E-09	22.2E-09	23.3E-09
SN11	21.3E-09	21.3E-09	21.3E-09	21.6E-09	22.1E-09	22.3E-09	22.2E-09	22.4E-09	23.6E-09
Statistics									
Min	20.7E-09	21.2E-09	21.2E-09	21.3E-09	21.7E-09	22.2E-09	22.2E-09	22.2E-09	23.0E-09
Max	21.3E-09	21.3E-09	21.3E-09	21.6E-09	22.1E-09	22.3E-09	22.2E-09	22.4E-09	23.6E-09
Average	20.9E-09	21.2E-09	21.2E-09	21.4E-09	21.8E-09	22.2E-09	22.2E-09	22.3E-09	23.4E-09
Sigma	257.7E-12	49.0E-12	49.0E-12	120.0E-12	174.4E-12	49.0E-12	140.4E-18	80.0E-12	224.5E-12

**Drift Calculation**

T1	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	500.0E-12	500.0E-12	600.0E-12	1000.0E-12	1.5E-09	1.5E-09	1.5E-09	2.6E-09
SN8	-	500.0E-12	500.0E-12	600.0E-12	1000.0E-12	1.5E-09	1.5E-09	1.5E-09	2.3E-09
SN9	-	100.0E-12	100.0E-12	100.0E-12	800.0E-12	1.1E-09	1000.0E-12	1.1E-09	2.4E-09
SN10	-	400.0E-12	400.0E-12	500.0E-12	900.0E-12	1.4E-09	1.4E-09	1.4E-09	2.5E-09
SN11	-	0.0E+00	0.0E+00	300.0E-12	800.0E-12	1.0E-09	900.0E-12	1.1E-09	2.3E-09
Average	-	300.0E-12	300.0E-12	420.0E-12	900.0E-12	1.3E-09	1.3E-09	1.3E-09	2.4E-09
Sigma	-	209.8E-12	209.8E-12	193.9E-12	89.4E-12	209.8E-12	257.7E-12	183.3E-12	116.6E-12

Parameter : Data valid after R//C low : T2  
 Test conditions : Iol=1.6mA; Ioh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V  
 Unit : s  
 Spec Limit Max : 4.0E-06  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

T2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06
ON samples									
SN2	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06			3.5E-06	3.7E-06
SN3	3.6E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06				3.6E-06
SN4	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06			3.5E-06	3.7E-06
SN5	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06			3.5E-06	3.7E-06
SN6	3.6E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06			3.5E-06	3.7E-06
Statistics									
Min	3.6E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	-	-	3.5E-06	3.6E-06
Max	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	-	-	3.5E-06	3.7E-06
Average	3.6E-06	3.6E-06	3.5E-06	3.5E-06	3.5E-06	-	-	3.5E-06	3.7E-06
Sigma	19.3E-09	19.1E-09	18.9E-09	18.6E-09	17.4E-09	-	-	9.6E-09	22.3E-09

**Drift Calculation**

T2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-20.3E-09	-42.5E-09	-51.2E-09	-82.4E-09			-118.0E-09	96.7E-09
SN3	-	-18.1E-09	-39.8E-09	-47.7E-09	-74.0E-09				88.0E-09
SN4	-	-18.6E-09	-38.5E-09	-46.4E-09	-74.5E-09			-104.4E-09	100.6E-09
SN5	-	-19.1E-09	-38.0E-09	-46.3E-09	-73.1E-09			-107.6E-09	79.4E-09
SN6	-	-19.9E-09	-36.4E-09	-43.1E-09	-68.0E-09			-94.3E-09	92.4E-09
Average	-	-19.2E-09	-39.0E-09	-46.9E-09	-74.4E-09			-106.1E-09	91.4E-09
Sigma	-	809.9E-12	2.0E-09	2.6E-09	4.6E-09			8.5E-09	7.3E-09



Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

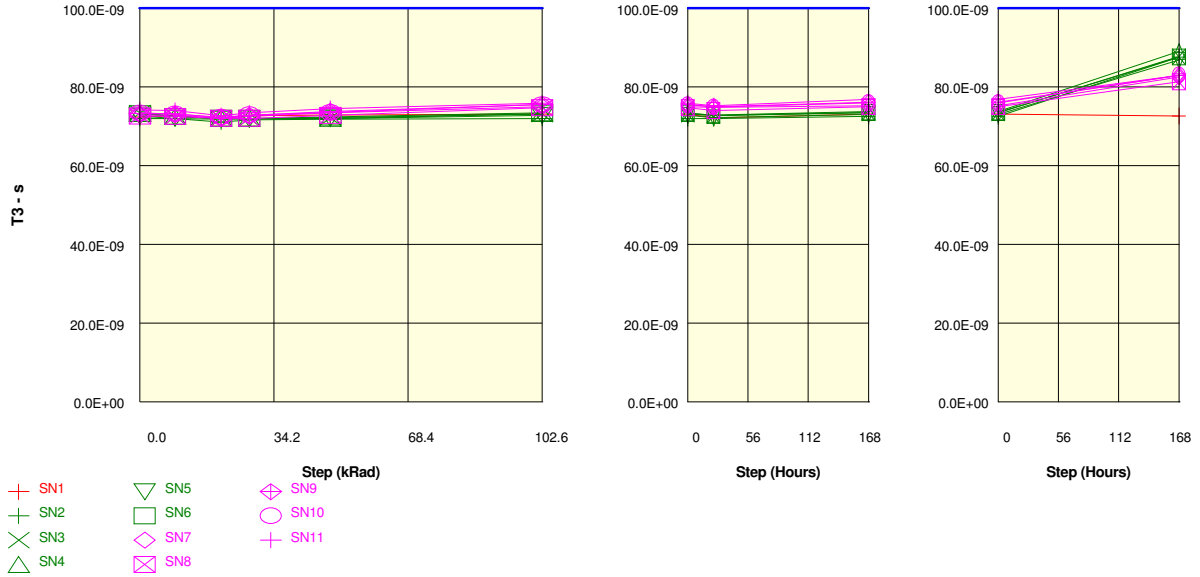
T2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06
OFF samples									
SN7	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06
SN8	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06
SN9	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06
SN10	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06
SN11	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06
Statistics									
Min	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06
Max	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06
Average	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06
Sigma	9.6E-09	9.5E-09	9.2E-09	9.5E-09	9.5E-09	10.3E-09	10.2E-09	9.4E-09	14.5E-09

**Drift Calculation**

T2	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-8.3E-09	-20.4E-09	-23.3E-09	-28.7E-09	-21.4E-09	-18.9E-09	-10.3E-09	76.3E-09
SN8	-	-7.9E-09	-18.7E-09	-21.7E-09	-25.7E-09	-17.9E-09	-14.3E-09	-4.9E-09	65.9E-09
SN9	-	-8.8E-09	-21.7E-09	-22.7E-09	-26.1E-09	-15.0E-09	-11.7E-09	-2.0E-09	74.8E-09
SN10	-	-8.4E-09	-21.3E-09	-23.6E-09	-28.3E-09	-17.8E-09	-14.4E-09	-4.7E-09	75.9E-09
SN11	-	-8.3E-09	-21.2E-09	-24.3E-09	-30.2E-09	-23.8E-09	-21.0E-09	-8.8E-09	64.5E-09
Average	-	-8.3E-09	-20.7E-09	-23.1E-09	-27.8E-09	-19.2E-09	-16.1E-09	-6.1E-09	71.5E-09
Sigma	-	287.1E-12	1.1E-09	877.3E-12	1.7E-09	3.1E-09	3.4E-09	3.0E-09	5.2E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

Parameter : /BUSY low delay : T3  
 Test conditions : Iol=1.6mA; Ioh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V  
 Unit : s  
 Spec Limit Max : 100.0E-09  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

T3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	72.4E-09	72.7E-09	72.0E-09	72.7E-09	72.9E-09	73.1E-09	72.1E-09	73.1E-09	72.6E-09
ON samples									
SN2	72.0E-09	72.0E-09	71.1E-09	71.6E-09	71.8E-09	72.0E-09	72.0E-09	72.5E-09	87.6E-09
SN3	73.4E-09	72.5E-09	72.0E-09	72.0E-09	72.2E-09	73.1E-09	72.7E-09	73.4E-09	87.7E-09
SN4	73.3E-09	72.5E-09	72.0E-09	72.0E-09	72.0E-09	73.2E-09	72.9E-09	73.7E-09	89.0E-09
SN5	72.6E-09	72.0E-09	71.8E-09	71.9E-09	72.0E-09	72.8E-09	72.2E-09	73.0E-09	86.8E-09
SN6	73.2E-09	72.5E-09	72.0E-09	72.0E-09	72.4E-09	73.4E-09	72.8E-09	73.5E-09	87.6E-09
Statistics									
Min	72.0E-09	72.0E-09	71.1E-09	71.6E-09	71.8E-09	72.0E-09	72.0E-09	72.5E-09	86.8E-09
Max	73.4E-09	72.5E-09	72.0E-09	72.0E-09	72.4E-09	73.4E-09	72.9E-09	73.7E-09	89.0E-09
Average	72.9E-09	72.3E-09	71.8E-09	71.9E-09	72.1E-09	72.9E-09	72.5E-09	73.2E-09	87.7E-09
Sigma	529.2E-12	244.9E-12	348.7E-12	154.9E-12	204.0E-12	489.9E-12	354.4E-12	426.1E-12	708.8E-12

**Drift Calculation**

T3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	-900.0E-12	-400.0E-12	-200.0E-12	0.0E+00	0.0E+00	500.0E-12	15.6E-09
SN3	-	-900.0E-12	-1.4E-09	-1.4E-09	-1.2E-09	-300.0E-12	-700.0E-12	0.0E+00	14.3E-09
SN4	-	-800.0E-12	-1.3E-09	-1.3E-09	-1.3E-09	-100.0E-12	-400.0E-12	400.0E-12	15.7E-09
SN5	-	-600.0E-12	-800.0E-12	-700.0E-12	-600.0E-12	200.0E-12	-400.0E-12	400.0E-12	14.2E-09
SN6	-	-700.0E-12	-1.2E-09	-1.2E-09	-800.0E-12	200.0E-12	-400.0E-12	300.0E-12	14.4E-09
Average	-	-600.0E-12	-1.1E-09	-1000.0E-12	-820.0E-12	0.0E+00	-380.0E-12	320.0E-12	14.8E-09
Sigma	-	316.2E-12	231.5E-12	384.7E-12	402.0E-12	189.7E-12	222.7E-12	172.0E-12	665.1E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197	
	AD976SD/883			Analog Devices			Issue:	02	

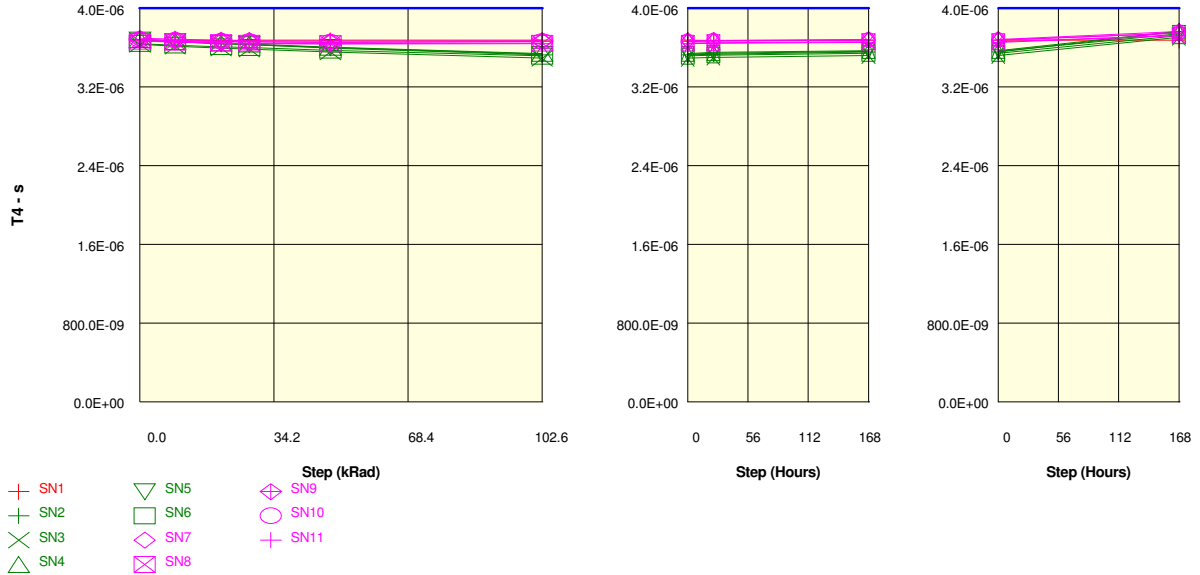
**Measurements**

T3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	72.4E-09	72.7E-09	72.0E-09	72.7E-09	72.9E-09	73.1E-09	72.1E-09	73.1E-09	72.6E-09
<b>OFF samples</b>									
SN7	72.9E-09	72.9E-09	72.0E-09	72.5E-09	73.4E-09	75.0E-09	74.8E-09	75.2E-09	82.5E-09
SN8	72.6E-09	72.5E-09	72.0E-09	72.0E-09	72.8E-09	74.7E-09	74.0E-09	75.0E-09	81.3E-09
SN9	73.3E-09	73.2E-09	72.1E-09	72.8E-09	73.8E-09	75.5E-09	75.0E-09	76.1E-09	83.0E-09
SN10	73.4E-09	73.1E-09	72.3E-09	72.9E-09	73.5E-09	75.5E-09	74.9E-09	76.0E-09	83.0E-09
SN11	74.2E-09	74.0E-09	72.7E-09	73.4E-09	74.5E-09	75.9E-09	75.2E-09	76.9E-09	82.9E-09
<b>Statistics</b>									
Min	72.6E-09	72.5E-09	72.0E-09	72.0E-09	72.8E-09	74.7E-09	74.0E-09	75.0E-09	81.3E-09
Max	74.2E-09	74.0E-09	72.7E-09	73.4E-09	74.5E-09	75.9E-09	75.2E-09	76.9E-09	83.0E-09
Average	73.3E-09	73.1E-09	72.2E-09	72.7E-09	73.6E-09	75.3E-09	74.8E-09	75.8E-09	82.5E-09
Sigma	541.8E-12	492.3E-12	263.8E-12	462.2E-12	555.0E-12	421.4E-12	411.8E-12	682.9E-12	646.8E-12

**Drift Calculation**

T3	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	0.0E+00	-900.0E-12	-400.0E-12	500.0E-12	2.1E-09	1.9E-09	2.3E-09	9.6E-09
SN8	-	-100.0E-12	-600.0E-12	-600.0E-12	200.0E-12	2.1E-09	1.4E-09	2.4E-09	8.7E-09
SN9	-	-100.0E-12	-1.2E-09	-500.0E-12	500.0E-12	2.2E-09	1.7E-09	2.8E-09	9.7E-09
SN10	-	-300.0E-12	-1.1E-09	-500.0E-12	100.0E-12	2.1E-09	1.5E-09	2.6E-09	9.6E-09
SN11	-	-200.0E-12	-1.5E-09	-800.0E-12	300.0E-12	1.7E-09	1000.0E-12	2.7E-09	8.7E-09
Average	-	-140.0E-12	-1.1E-09	-560.0E-12	320.0E-12	2.0E-09	1.5E-09	2.6E-09	9.3E-09
Sigma	-	102.0E-12	300.7E-12	135.6E-12	160.0E-12	174.4E-12	303.3E-12	185.5E-12	458.7E-12

Parameter : /BUSY low time : T4  
 Test conditions : Iol=1.6mA; loh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V  
 Unit : s  
 Spec Limit Max : 4.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

T4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06
ON samples									
SN2	3.7E-06	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06	3.6E-06	3.8E-06
SN3	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06	3.5E-06	3.7E-06
SN4	3.7E-06	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.6E-06	3.6E-06	3.8E-06
SN5	3.7E-06	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06	3.6E-06	3.7E-06
SN6	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06	3.5E-06	3.7E-06
Statistics									
Min	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06	3.5E-06	3.7E-06
Max	3.7E-06	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.6E-06	3.6E-06	3.8E-06
Average	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.5E-06	3.5E-06	3.5E-06	3.7E-06
Sigma	21.2E-09	20.4E-09	20.3E-09	20.1E-09	18.9E-09	16.9E-09	17.1E-09	17.9E-09	23.7E-09

Drift Calculation

T4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-20.6E-09	-41.6E-09	-52.5E-09	-86.1E-09	-156.5E-09	-146.8E-09	-126.5E-09	82.6E-09
SN3	-	-17.4E-09	-38.2E-09	-47.7E-09	-77.3E-09	-140.8E-09	-131.3E-09	-113.3E-09	73.8E-09
SN4	-	-18.1E-09	-37.1E-09	-45.8E-09	-77.0E-09	-140.8E-09	-131.0E-09	-111.3E-09	85.8E-09
SN5	-	-18.7E-09	-37.1E-09	-46.7E-09	-76.5E-09	-145.6E-09	-134.6E-09	-115.1E-09	65.5E-09
SN6	-	-17.3E-09	-34.3E-09	-42.7E-09	-69.6E-09	-127.5E-09	-117.7E-09	-100.1E-09	79.7E-09
Average	-	-18.4E-09	-37.7E-09	-47.1E-09	-77.3E-09	-142.2E-09	-132.3E-09	-113.3E-09	77.5E-09
Sigma	-	1.2E-09	2.4E-09	3.2E-09	5.2E-09	9.3E-09	9.3E-09	8.4E-09	7.2E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

T4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06
<b>OFF samples</b>									
SN7	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.8E-06
SN8	3.7E-06	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06	3.7E-06
SN9	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06
SN10	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06
SN11	3.7E-06	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06	3.7E-06
<b>Statistics</b>									
Min	3.7E-06	3.7E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.6E-06	3.7E-06	3.7E-06
Max	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.8E-06
Average	3.7E-06	3.7E-06	3.7E-06	3.7E-06	3.6E-06	3.7E-06	3.7E-06	3.7E-06	3.7E-06
Sigma	11.0E-09	10.9E-09	10.7E-09	10.8E-09	10.7E-09	11.6E-09	11.4E-09	11.0E-09	15.8E-09

**Drift Calculation**

T4	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-8.2E-09	-18.7E-09	-22.3E-09	-29.9E-09	-24.7E-09	-21.2E-09	-12.4E-09	68.8E-09
SN8	-	-7.7E-09	-16.6E-09	-20.0E-09	-24.8E-09	-18.9E-09	-14.1E-09	-5.8E-09	59.1E-09
SN9	-	-8.5E-09	-18.3E-09	-20.9E-09	-25.8E-09	-16.4E-09	-11.8E-09	-3.5E-09	67.0E-09
SN10	-	-7.9E-09	-17.9E-09	-21.6E-09	-27.7E-09	-19.0E-09	-14.2E-09	-5.7E-09	68.8E-09
SN11	-	-8.3E-09	-19.2E-09	-23.4E-09	-31.1E-09	-26.8E-09	-22.4E-09	-12.2E-09	56.4E-09
Average	-	-8.1E-09	-18.1E-09	-21.6E-09	-27.9E-09	-21.2E-09	-16.7E-09	-7.9E-09	64.0E-09
Sigma	-	285.7E-12	882.3E-12	1.2E-09	2.4E-09	3.9E-09	4.2E-09	3.7E-09	5.2E-09

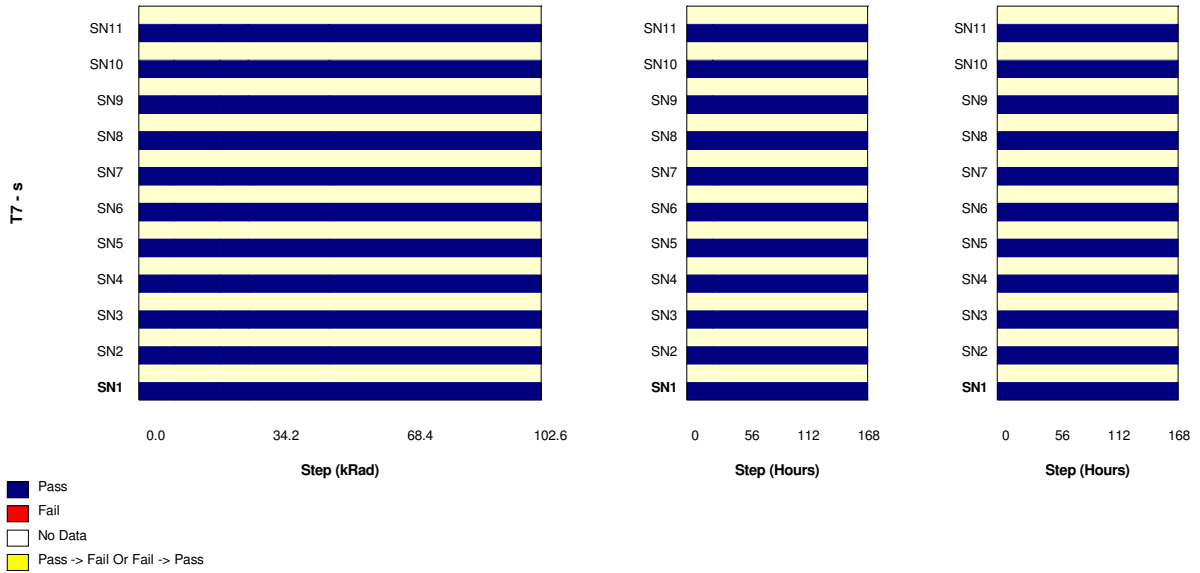
Parameter : Conversion time : T7

Test conditions : GO NOGO

Unit : s

Spec Limit Max : 4.0E-06

Spec limits are represented in bold lines on the graphic.



Measurements

T7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
ON samples									
SN2	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN3	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN4	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN5	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN6	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS

Measurements

T7	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
OFF samples									
SN7	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN8	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN9	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN10	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN11	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS

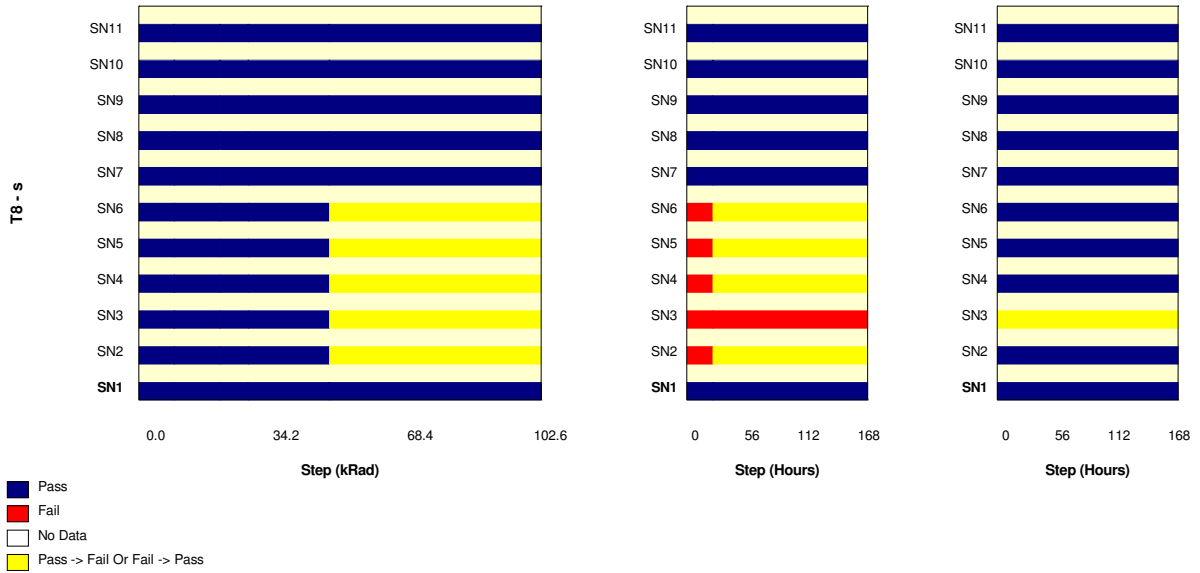
Parameter : Acquisition time : T8

Test conditions : GO NOGO

Unit : s

Spec Limit Max : 1.0E-06

Spec limits are represented in bold lines on the graphic.



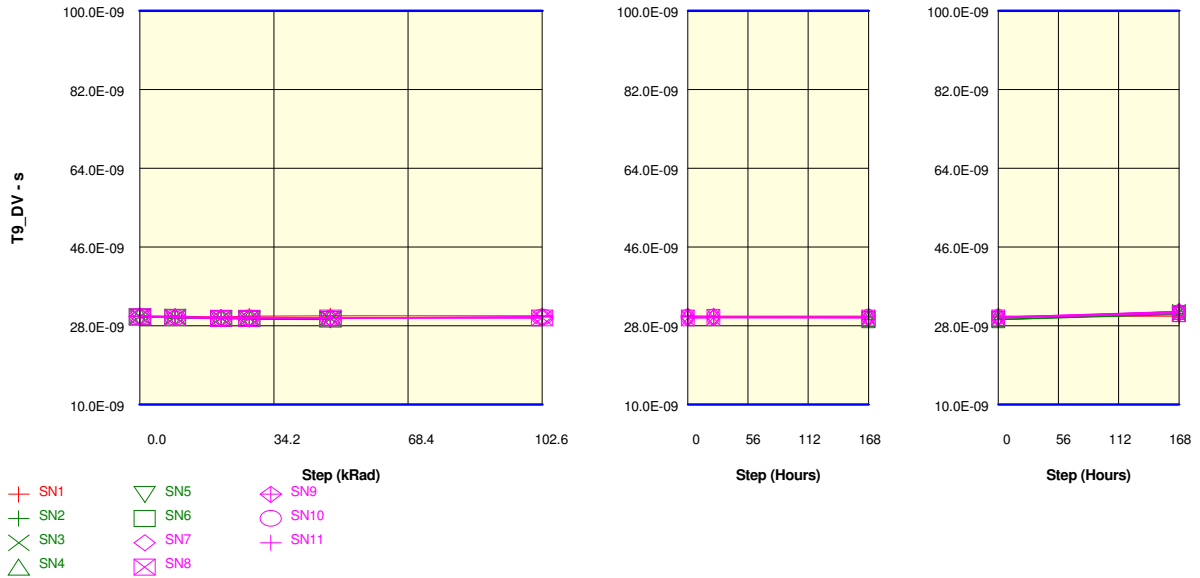
Measurements

T8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
ON samples									
SN2	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS
SN3	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	FAIL	PASS
SN4	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS
SN5	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS
SN6	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS

Measurements

T8	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
OFF samples									
SN7	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN8	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN9	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN10	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN11	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS

Parameter : Bus relinquish : T9\_DV  
 Test conditions : Iol=1.6mA; Ioh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V. all data valid  
 Unit : s  
 Spec Limit Min : 10.0E-09  
 Spec Limit Max : 100.0E-09  
 Spec limits are represented in bold lines on the graphic.



Measurements

T9 DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	30.2E-09	30.2E-09	30.0E-09	30.2E-09	30.3E-09	30.3E-09	30.2E-09	30.2E-09	30.2E-09
ON samples									
SN2	30.1E-09	29.8E-09	29.7E-09	29.7E-09	29.7E-09			29.5E-09	30.8E-09
SN3	30.2E-09	30.1E-09	29.8E-09	29.7E-09	29.6E-09				31.1E-09
SN4	30.2E-09	30.0E-09	29.8E-09	29.7E-09	29.8E-09			29.7E-09	31.3E-09
SN5	30.0E-09	29.9E-09	29.6E-09	29.5E-09	29.4E-09			29.4E-09	30.6E-09
SN6	30.0E-09	29.9E-09	29.7E-09	29.7E-09	29.5E-09			29.4E-09	30.8E-09
Statistics									
Min	30.0E-09	29.8E-09	29.6E-09	29.5E-09	29.4E-09	-	-	29.4E-09	30.6E-09
Max	30.2E-09	30.1E-09	29.8E-09	29.7E-09	29.8E-09	-	-	29.7E-09	31.3E-09
Average	30.1E-09	29.9E-09	29.7E-09	29.7E-09	29.6E-09	-	-	29.5E-09	30.9E-09
Sigma	89.4E-12	102.0E-12	74.8E-12	80.0E-12	141.4E-12	-	-	122.5E-12	248.2E-12

Drift Calculation

T9 DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-300.0E-12	-400.0E-12	-400.0E-12	-400.0E-12			-600.0E-12	700.0E-12
SN3	-	-100.0E-12	-400.0E-12	-500.0E-12	-600.0E-12				900.0E-12
SN4	-	-200.0E-12	-400.0E-12	-500.0E-12	-400.0E-12			-500.0E-12	1.1E-09
SN5	-	-100.0E-12	-400.0E-12	-500.0E-12	-600.0E-12			-600.0E-12	600.0E-12
SN6	-	-100.0E-12	-300.0E-12	-300.0E-12	-500.0E-12			-600.0E-12	800.0E-12
Average	-	-160.0E-12	-380.0E-12	-440.0E-12	-500.0E-12			-575.0E-12	820.0E-12
Sigma	-	80.0E-12	40.0E-12	80.0E-12	89.4E-12			43.3E-12	172.0E-12



Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

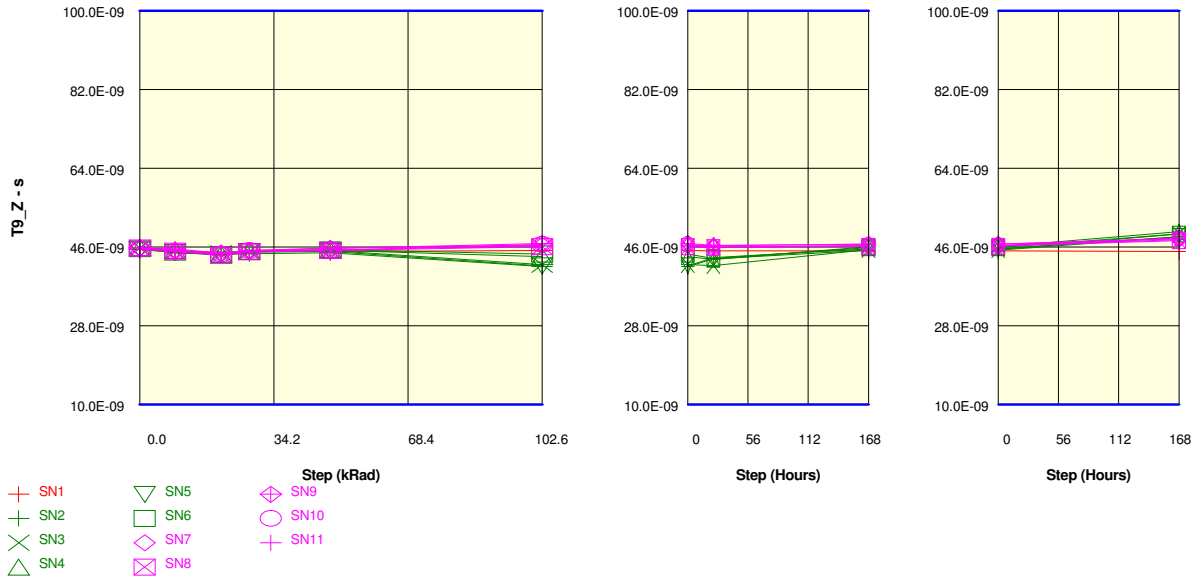
**Measurements**

T9_DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	30.2E-09	30.2E-09	30.0E-09	30.2E-09	30.3E-09	30.3E-09	30.2E-09	30.2E-09	30.2E-09
<b>OFF samples</b>									
SN7	30.2E-09	30.0E-09	29.8E-09	29.7E-09	29.8E-09	29.8E-09	29.9E-09	29.9E-09	31.0E-09
SN8	30.1E-09	29.9E-09	29.7E-09	29.7E-09	29.8E-09	29.8E-09	29.9E-09	29.8E-09	30.8E-09
SN9	30.1E-09	30.0E-09	29.7E-09	29.8E-09	29.8E-09	30.1E-09	30.0E-09	30.0E-09	31.3E-09
SN10	30.1E-09	29.9E-09	29.7E-09	29.8E-09	29.7E-09	30.0E-09	30.0E-09	30.0E-09	31.0E-09
SN11	30.2E-09	30.1E-09	30.0E-09	30.0E-09	29.9E-09	30.0E-09	30.0E-09	30.0E-09	31.2E-09
<b>Statistics</b>									
Min	30.1E-09	29.9E-09	29.7E-09	29.7E-09	29.7E-09	29.8E-09	29.9E-09	29.8E-09	30.8E-09
Max	30.2E-09	30.1E-09	30.0E-09	30.0E-09	29.9E-09	30.1E-09	30.0E-09	30.0E-09	31.3E-09
Average	30.1E-09	30.0E-09	29.8E-09	29.8E-09	29.8E-09	29.9E-09	30.0E-09	29.9E-09	31.1E-09
Sigma	49.0E-12	74.8E-12	116.6E-12	109.5E-12	63.2E-12	120.0E-12	49.0E-12	80.0E-12	174.4E-12

**Drift Calculation**

T9_DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-200.0E-12	-400.0E-12	-500.0E-12	-400.0E-12	-400.0E-12	-300.0E-12	-300.0E-12	800.0E-12
SN8	-	-200.0E-12	-400.0E-12	-400.0E-12	-300.0E-12	-300.0E-12	-200.0E-12	-300.0E-12	700.0E-12
SN9	-	-100.0E-12	-400.0E-12	-300.0E-12	-300.0E-12	0.0E+00	-100.0E-12	-100.0E-12	1.2E-09
SN10	-	-200.0E-12	-400.0E-12	-300.0E-12	-400.0E-12	-100.0E-12	-100.0E-12	-100.0E-12	900.0E-12
SN11	-	-100.0E-12	-200.0E-12	-200.0E-12	-300.0E-12	-200.0E-12	-200.0E-12	-200.0E-12	1.0E-09
Average	-	-160.0E-12	-360.0E-12	-340.0E-12	-340.0E-12	-200.0E-12	-180.0E-12	-200.0E-12	920.0E-12
Sigma	-	49.0E-12	80.0E-12	102.0E-12	49.0E-12	141.4E-12	74.8E-12	89.4E-12	172.0E-12

Parameter : Bus relinquish : T9\_Z  
 Test conditions : Iol=1.6mA; loh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V. all data Z  
 Unit : s  
 Spec Limit Min : 10.0E-09  
 Spec Limit Max : 100.0E-09  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

T9_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	45.4E-09	45.2E-09	44.8E-09	45.1E-09	45.0E-09	45.2E-09	45.1E-09	45.1E-09	45.0E-09
<b>ON samples</b>									
SN2	45.8E-09	44.7E-09	44.3E-09	44.5E-09	44.7E-09	41.5E-09	43.3E-09	45.3E-09	48.4E-09
SN3	45.8E-09	45.1E-09	44.6E-09	45.1E-09	45.2E-09	42.0E-09	41.8E-09	45.4E-09	49.0E-09
SN4	45.9E-09	45.2E-09	44.4E-09	45.1E-09	45.3E-09	43.8E-09	43.2E-09	46.1E-09	49.5E-09
SN5	45.4E-09	44.8E-09	44.2E-09	44.9E-09	45.0E-09	41.7E-09	43.6E-09	45.6E-09	48.4E-09
SN6	45.6E-09	44.8E-09	44.3E-09	45.0E-09	45.4E-09	44.4E-09	43.4E-09	45.9E-09	49.0E-09
<b>Statistics</b>									
Min	45.4E-09	44.7E-09	44.2E-09	44.5E-09	44.7E-09	41.5E-09	41.8E-09	45.3E-09	48.4E-09
Max	45.9E-09	45.2E-09	44.6E-09	45.1E-09	45.4E-09	44.4E-09	43.6E-09	46.1E-09	49.5E-09
Average	45.7E-09	44.9E-09	44.4E-09	44.9E-09	45.1E-09	42.7E-09	43.1E-09	45.7E-09	48.9E-09
Sigma	178.9E-12	193.9E-12	135.6E-12	222.7E-12	248.2E-12	1.2E-09	643.7E-12	300.7E-12	417.6E-12

**Drift Calculation**

T9_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>ON samples</b>									
SN2	-	-1.1E-09	-1.5E-09	-1.3E-09	-1.1E-09	-4.3E-09	-2.5E-09	-500.0E-12	2.6E-09
SN3	-	-700.0E-12	-1.2E-09	-700.0E-12	-600.0E-12	-3.8E-09	-4.0E-09	-400.0E-12	3.2E-09
SN4	-	-700.0E-12	-1.5E-09	-800.0E-12	-600.0E-12	-2.1E-09	-2.7E-09	200.0E-12	3.6E-09
SN5	-	-600.0E-12	-1.2E-09	-500.0E-12	-400.0E-12	-3.7E-09	-1.8E-09	200.0E-12	3.0E-09
SN6	-	-800.0E-12	-1.3E-09	-600.0E-12	-200.0E-12	-1.2E-09	-2.2E-09	300.0E-12	3.4E-09
Average	-	-780.0E-12	-1.3E-09	-780.0E-12	-580.0E-12	-3.0E-09	-2.6E-09	-40.0E-12	3.2E-09
Sigma	-	172.0E-12	135.6E-12	278.6E-12	299.3E-12	1.2E-09	744.6E-12	338.2E-12	344.1E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197	
	AD976SD/883			Analog Devices			Issue:	02	

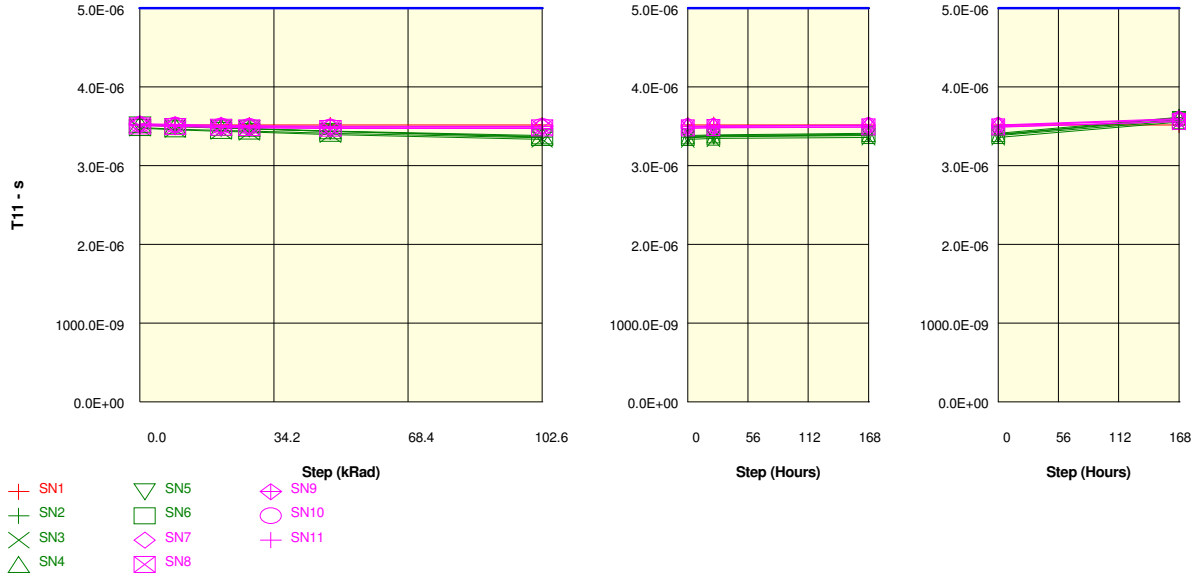
**Measurements**

T9_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	45.4E-09	45.2E-09	44.8E-09	45.1E-09	45.0E-09	45.2E-09	45.1E-09	45.1E-09	45.0E-09
<b>OFF samples</b>									
SN7	45.9E-09	45.0E-09	44.5E-09	45.1E-09	45.3E-09	46.4E-09	46.0E-09	46.3E-09	47.7E-09
SN8	45.8E-09	45.1E-09	44.1E-09	44.9E-09	45.2E-09	46.1E-09	45.9E-09	46.2E-09	47.5E-09
SN9	45.8E-09	45.3E-09	44.6E-09	45.2E-09	45.7E-09	46.8E-09	46.4E-09	46.7E-09	48.0E-09
SN10	45.5E-09	45.0E-09	44.4E-09	45.2E-09	45.3E-09	46.6E-09	45.9E-09	46.4E-09	48.0E-09
SN11	45.8E-09	45.6E-09	44.6E-09	45.2E-09	45.8E-09	46.5E-09	46.3E-09	46.7E-09	47.9E-09
<b>Statistics</b>									
Min	45.5E-09	45.0E-09	44.1E-09	44.9E-09	45.2E-09	46.1E-09	45.9E-09	46.2E-09	47.5E-09
Max	45.9E-09	45.6E-09	44.6E-09	45.2E-09	45.8E-09	46.8E-09	46.4E-09	46.7E-09	48.0E-09
Average	45.8E-09	45.2E-09	44.4E-09	45.1E-09	45.5E-09	46.5E-09	46.1E-09	46.5E-09	47.8E-09
Sigma	135.6E-12	228.0E-12	185.5E-12	116.6E-12	241.7E-12	231.5E-12	209.8E-12	205.9E-12	193.9E-12

**Drift Calculation**

T9_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-900.0E-12	-1.4E-09	-800.0E-12	-600.0E-12	500.0E-12	100.0E-12	400.0E-12	1.8E-09
SN8	-	-700.0E-12	-1.7E-09	-900.0E-12	-600.0E-12	300.0E-12	100.0E-12	400.0E-12	1.7E-09
SN9	-	-500.0E-12	-1.2E-09	-600.0E-12	-100.0E-12	1.0E-09	600.0E-12	900.0E-12	2.2E-09
SN10	-	-500.0E-12	-1.1E-09	-300.0E-12	-200.0E-12	1.1E-09	400.0E-12	900.0E-12	2.5E-09
SN11	-	-200.0E-12	-1.2E-09	-600.0E-12	0.0E+00	700.0E-12	500.0E-12	900.0E-12	2.1E-09
Average	-	-560.0E-12	-1.3E-09	-640.0E-12	-300.0E-12	720.0E-12	340.0E-12	700.0E-12	2.1E-09
Sigma	-	233.2E-12	213.5E-12	205.9E-12	253.0E-12	299.3E-12	205.9E-12	244.9E-12	287.1E-12

Parameter : Throughput time : T11  
 Test conditions : Iol=1.6mA; Ioh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V  
 Unit : s  
 Spec Limit Max : 5.0E-06  
 Spec limits are represented in bold lines on the graphic.



Measurements

T11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06
ON samples									
SN2	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.6E-06
SN3	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.3E-06	3.3E-06	3.4E-06	3.6E-06
SN4	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.6E-06
SN5	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.6E-06
SN6	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.6E-06
Statistics									
Min	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.3E-06	3.3E-06	3.4E-06	3.6E-06
Max	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.6E-06
Average	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.4E-06	3.4E-06	3.4E-06	3.4E-06	3.6E-06
Sigma	19.9E-09	19.2E-09	19.2E-09	19.0E-09	17.5E-09	16.2E-09	15.7E-09	16.4E-09	22.5E-09

Drift Calculation

T11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-20.8E-09	-43.9E-09	-54.1E-09	-88.1E-09	-157.9E-09	-148.0E-09	-128.8E-09	87.5E-09
SN3	-	-19.0E-09	-41.5E-09	-51.3E-09	-81.0E-09	-143.9E-09	-132.5E-09	-115.5E-09	79.0E-09
SN4	-	-19.6E-09	-39.1E-09	-49.8E-09	-81.0E-09	-143.3E-09	-132.9E-09	-114.4E-09	91.5E-09
SN5	-	-20.0E-09	-40.7E-09	-49.9E-09	-81.0E-09	-145.8E-09	-137.5E-09	-119.4E-09	69.4E-09
SN6	-	-18.5E-09	-36.7E-09	-46.0E-09	-73.0E-09	-129.0E-09	-119.9E-09	-103.8E-09	84.8E-09
Average	-	-19.6E-09	-40.4E-09	-50.2E-09	-80.8E-09	-144.0E-09	-134.2E-09	-116.4E-09	82.4E-09
Sigma	-	796.0E-12	2.4E-09	2.6E-09	4.8E-09	9.2E-09	9.1E-09	8.1E-09	7.7E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

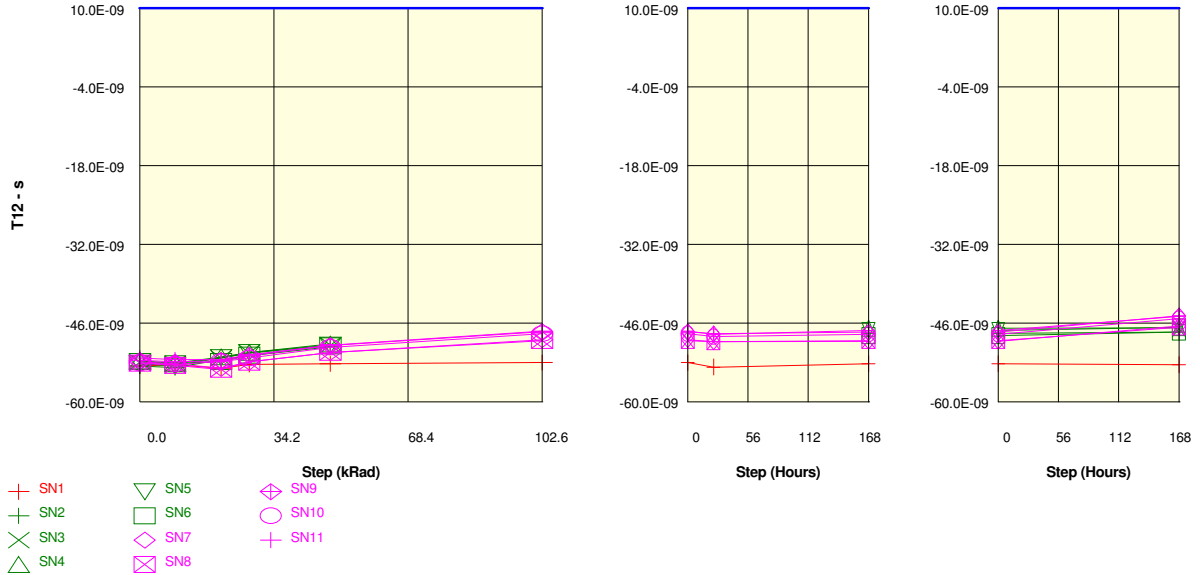
T11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06
OFF samples									
SN7	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
SN8	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
SN9	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
SN10	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
SN11	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
Statistics									
Min	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
Max	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
Average	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.5E-06	3.6E-06
Sigma	9.9E-09	9.4E-09	9.6E-09	9.5E-09	9.9E-09	10.6E-09	10.5E-09	9.9E-09	14.9E-09

**Drift Calculation**

T11	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
OFF samples									
SN7	-	-10.1E-09	-21.4E-09	-26.3E-09	-33.6E-09	-30.7E-09	-26.8E-09	-18.5E-09	64.9E-09
SN8	-	-8.4E-09	-19.9E-09	-23.3E-09	-30.9E-09	-26.5E-09	-21.7E-09	-13.2E-09	54.8E-09
SN9	-	-9.4E-09	-21.0E-09	-24.6E-09	-31.5E-09	-24.4E-09	-19.9E-09	-11.0E-09	63.6E-09
SN10	-	-9.2E-09	-20.9E-09	-25.3E-09	-33.6E-09	-26.9E-09	-22.2E-09	-13.7E-09	65.2E-09
SN11	-	-8.7E-09	-21.2E-09	-26.2E-09	-34.8E-09	-32.6E-09	-28.3E-09	-17.6E-09	53.3E-09
Average	-	-9.2E-09	-20.9E-09	-25.1E-09	-32.9E-09	-28.2E-09	-23.8E-09	-14.8E-09	60.4E-09
Sigma	-	588.6E-12	519.2E-12	1.1E-09	1.5E-09	3.0E-09	3.2E-09	2.8E-09	5.2E-09

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT		Ref.:	HRX/TID/1197
	AD976SD/883	Analog Devices	Issue:	02

Parameter : R//C to /CS setup : T12  
 Test conditions : Iol=1.6mA; loh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V  
 Unit : s  
 Spec Limit Max : 10.0E-09  
 Spec limits are represented in bold lines on the graphic.



**Measurements**

T12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-53.6E-09	-53.4E-09	-54.0E-09	-53.3E-09	-53.2E-09	-53.0E-09	-53.8E-09	-53.2E-09	-53.4E-09
ON samples									
SN2	-53.6E-09	-53.9E-09	-52.5E-09	-51.8E-09	-50.2E-09			-47.8E-09	-47.6E-09
SN3	-52.9E-09	-53.2E-09	-52.2E-09	-51.3E-09	-49.9E-09				-47.0E-09
SN4	-52.7E-09	-53.1E-09	-52.0E-09	-51.2E-09	-49.7E-09			-46.9E-09	-46.8E-09
SN5	-53.2E-09	-53.6E-09	-52.1E-09	-51.2E-09	-49.9E-09			-47.3E-09	-46.7E-09
SN6	-52.8E-09	-53.2E-09	-52.8E-09	-51.7E-09	-50.0E-09			-48.2E-09	-47.6E-09
Statistics									
Min	-53.6E-09	-53.9E-09	-52.8E-09	-51.8E-09	-50.2E-09	-	-	-48.2E-09	-47.6E-09
Max	-52.7E-09	-53.1E-09	-52.0E-09	-51.2E-09	-49.7E-09	-	-	-46.9E-09	-46.7E-09
Average	-53.0E-09	-53.4E-09	-52.3E-09	-51.4E-09	-49.9E-09	-	-	-47.6E-09	-47.1E-09
Sigma	326.2E-12	303.3E-12	292.6E-12	257.7E-12	162.6E-12	-	-	492.4E-12	387.8E-12

**Drift Calculation**

T12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-300.0E-12	1.1E-09	1.8E-09	3.4E-09			5.8E-09	6.0E-09
SN3	-	-300.0E-12	700.0E-12	1.6E-09	3.0E-09				5.9E-09
SN4	-	-400.0E-12	700.0E-12	1.5E-09	3.0E-09			5.8E-09	5.9E-09
SN5	-	-400.0E-12	1.1E-09	2.0E-09	3.3E-09			5.9E-09	6.5E-09
SN6	-	-400.0E-12	0.0E+00	1.1E-09	2.8E-09			4.6E-09	5.2E-09
Average	-	-360.0E-12	720.0E-12	1.6E-09	3.1E-09			5.5E-09	5.9E-09
Sigma	-	49.0E-12	402.0E-12	303.3E-12	219.1E-12			535.6E-12	414.7E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

T12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	-53.6E-09	-53.4E-09	-54.0E-09	-53.3E-09	-53.2E-09	-53.0E-09	-53.8E-09	-53.2E-09	-53.4E-09
<b>OFF samples</b>									
SN7	-52.9E-09	-53.2E-09	-54.0E-09	-52.9E-09	-51.2E-09	-48.9E-09	-49.3E-09	-49.2E-09	-46.5E-09
SN8	-53.1E-09	-53.5E-09	-54.2E-09	-52.9E-09	-51.2E-09	-49.1E-09	-49.3E-09	-49.1E-09	-46.7E-09
SN9	-52.6E-09	-52.9E-09	-52.7E-09	-51.8E-09	-50.0E-09	-47.5E-09	-47.9E-09	-47.6E-09	-44.7E-09
SN10	-53.1E-09	-53.3E-09	-52.8E-09	-52.2E-09	-50.3E-09	-47.9E-09	-48.4E-09	-48.0E-09	-45.2E-09
SN11	-52.2E-09	-52.5E-09	-52.5E-09	-51.6E-09	-49.9E-09	-47.4E-09	-48.0E-09	-47.3E-09	-44.8E-09
<b>Statistics</b>									
Min	-53.1E-09	-53.5E-09	-54.2E-09	-52.9E-09	-51.2E-09	-49.1E-09	-49.3E-09	-49.2E-09	-46.7E-09
Max	-52.2E-09	-52.5E-09	-52.5E-09	-51.6E-09	-49.9E-09	-47.4E-09	-47.9E-09	-47.3E-09	-44.7E-09
Average	-52.8E-09	-53.1E-09	-53.2E-09	-52.3E-09	-50.5E-09	-48.2E-09	-48.6E-09	-48.2E-09	-45.6E-09
Sigma	342.9E-12	348.7E-12	711.6E-12	541.8E-12	570.6E-12	708.8E-12	611.2E-12	776.1E-12	851.8E-12

**Drift Calculation**

T12	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-300.0E-12	-1.1E-09	0.0E+00	1.7E-09	4.0E-09	3.6E-09	3.7E-09	6.4E-09
SN8	-	-400.0E-12	-1.1E-09	200.0E-12	1.9E-09	4.0E-09	3.8E-09	4.0E-09	6.4E-09
SN9	-	-300.0E-12	-100.0E-12	800.0E-12	2.6E-09	5.1E-09	4.7E-09	5.0E-09	7.9E-09
SN10	-	-200.0E-12	300.0E-12	900.0E-12	2.8E-09	5.2E-09	4.7E-09	5.1E-09	7.9E-09
SN11	-	-300.0E-12	-300.0E-12	600.0E-12	2.3E-09	4.8E-09	4.2E-09	4.9E-09	7.4E-09
Average	-	-300.0E-12	-460.0E-12	500.0E-12	2.3E-09	4.6E-09	4.2E-09	4.5E-09	7.2E-09
Sigma	-	63.2E-12	557.1E-12	346.4E-12	412.8E-12	523.1E-12	451.7E-12	574.8E-12	678.2E-12

Parameter : Time between conversions : T13

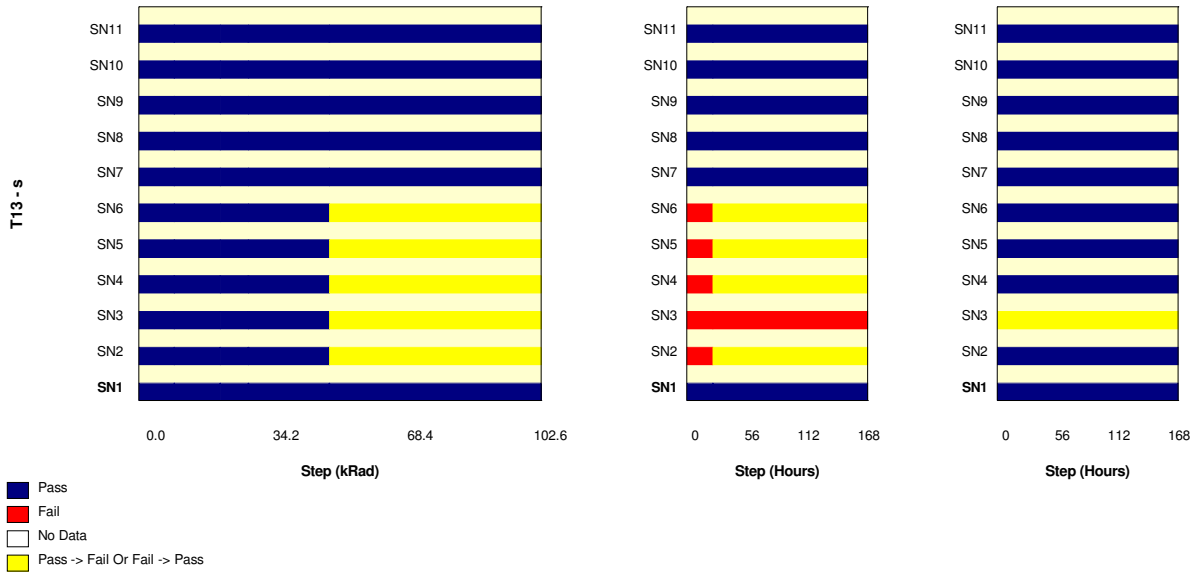
Test conditions : GO NOGO Functionality tested for the two extreme values of T13

Unit : s

Spec Limit Min : 5.0E-06

Spec Limit Max : 1.0E-03

Spec limits are represented in bold lines on the graphic.



Measurements

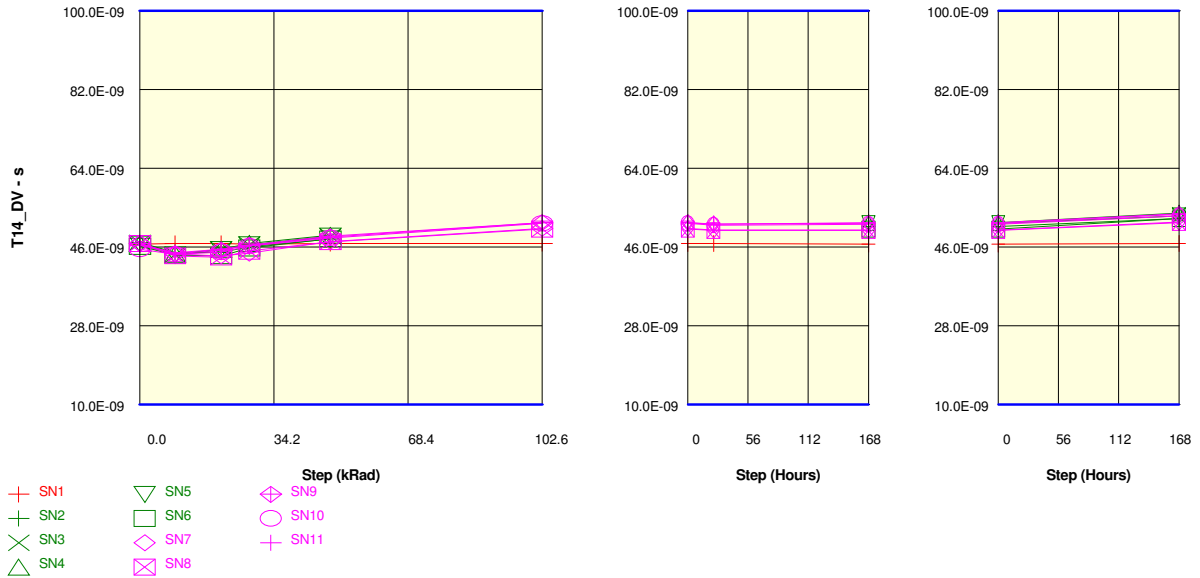
T13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
ON samples									
SN2	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS
SN3	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	FAIL	PASS
SN4	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS
SN5	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS
SN6	PASS	PASS	PASS	PASS	PASS	FAIL	FAIL	PASS	PASS

Measurements

T13	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
OFF samples									
SN7	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN8	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN9	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN10	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS
SN11	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS	PASS



Parameter : Bus access and byte delay : T14\_DV  
 Test conditions : Iol=1.6mA; Ioh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V. all data valid  
 Unit : s  
 Spec Limit Min : 10.0E-09  
 Spec Limit Max : 100.0E-09  
 Spec limits are represented in bold lines on the graphic.



Measurements

T14_DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	46.7E-09	46.8E-09	46.8E-09	46.7E-09	46.8E-09	46.8E-09	46.8E-09	46.7E-09	46.8E-09
ON samples									
SN2	47.0E-09	44.8E-09	44.8E-09	46.1E-09	47.8E-09			50.7E-09	52.5E-09
SN3	47.0E-09	44.3E-09	45.4E-09	46.5E-09	48.4E-09				53.3E-09
SN4	46.8E-09	44.4E-09	45.5E-09	46.8E-09	48.7E-09			51.6E-09	53.8E-09
SN5	46.7E-09	44.1E-09	45.5E-09	46.5E-09	48.5E-09			51.4E-09	53.1E-09
SN6	46.2E-09	44.2E-09	44.0E-09	45.8E-09	47.9E-09			50.1E-09	52.5E-09
Statistics									
Min	46.2E-09	44.1E-09	44.0E-09	45.8E-09	47.8E-09	-	-	50.1E-09	52.5E-09
Max	47.0E-09	44.8E-09	45.5E-09	46.8E-09	48.7E-09	-	-	51.6E-09	53.8E-09
Average	46.7E-09	44.4E-09	45.0E-09	46.3E-09	48.3E-09	-	-	51.0E-09	53.0E-09
Sigma	293.9E-12	241.7E-12	581.7E-12	349.9E-12	349.9E-12	-	-	593.7E-12	496.4E-12

Drift Calculation

T14_DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	-2.2E-09	-2.2E-09	-900.0E-12	800.0E-12			3.7E-09	5.5E-09
SN3	-	-2.7E-09	-1.6E-09	-500.0E-12	1.4E-09				6.3E-09
SN4	-	-2.4E-09	-1.3E-09	0.0E+00	1.9E-09			4.8E-09	7.0E-09
SN5	-	-2.6E-09	-1.2E-09	-200.0E-12	1.8E-09			4.7E-09	6.4E-09
SN6	-	-2.0E-09	-2.2E-09	-400.0E-12	1.7E-09			3.9E-09	6.3E-09
Average	-	-2.4E-09	-1.7E-09	-400.0E-12	1.5E-09			4.3E-09	6.3E-09
Sigma	-	256.1E-12	429.0E-12	303.3E-12	397.0E-12			481.5E-12	477.5E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

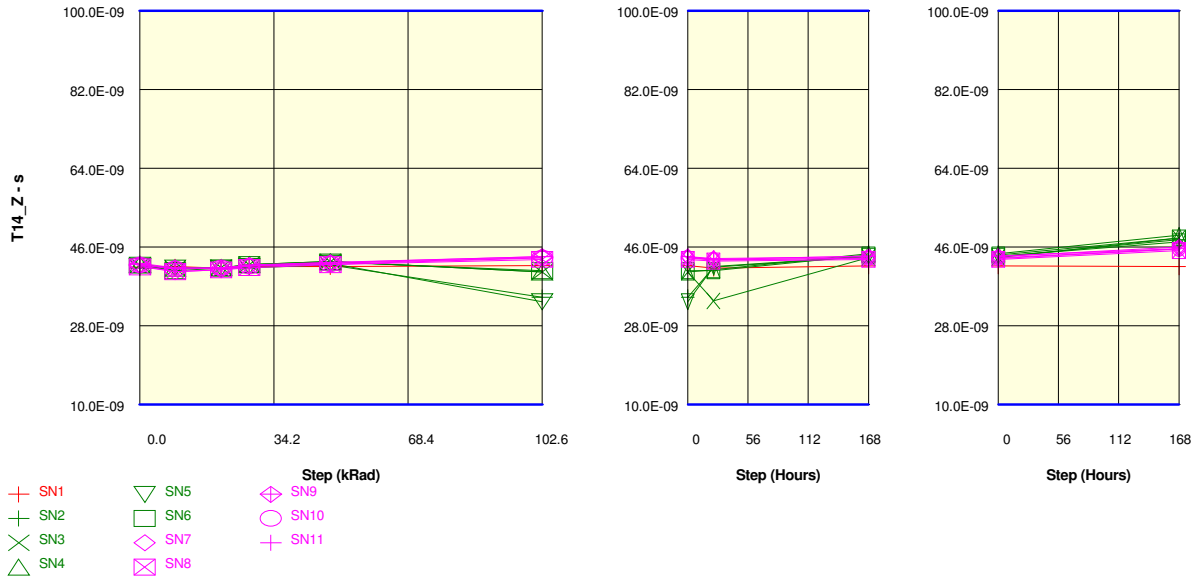
**Measurements**

T14_DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	46.7E-09	46.8E-09	46.8E-09	46.7E-09	46.8E-09	46.8E-09	46.8E-09	46.7E-09	46.8E-09
<b>OFF samples</b>									
SN7	46.8E-09	44.4E-09	44.0E-09	44.6E-09	47.3E-09	50.3E-09	49.9E-09	49.9E-09	51.7E-09
SN8	46.8E-09	44.0E-09	43.7E-09	45.1E-09	47.2E-09	50.1E-09	49.8E-09	49.8E-09	51.6E-09
SN9	46.8E-09	44.5E-09	45.3E-09	46.4E-09	48.3E-09	51.6E-09	51.3E-09	51.4E-09	53.5E-09
SN10	45.5E-09	44.3E-09	44.9E-09	46.2E-09	48.1E-09	51.4E-09	51.0E-09	51.2E-09	53.1E-09
SN11	46.4E-09	44.7E-09	45.5E-09	46.5E-09	48.5E-09	51.6E-09	51.2E-09	51.6E-09	53.6E-09
<b>Statistics</b>									
Min	45.5E-09	44.0E-09	43.7E-09	44.6E-09	47.2E-09	50.1E-09	49.8E-09	49.8E-09	51.6E-09
Max	46.8E-09	44.7E-09	45.5E-09	46.5E-09	48.5E-09	51.6E-09	51.3E-09	51.6E-09	53.6E-09
Average	46.5E-09	44.4E-09	44.7E-09	45.8E-09	47.9E-09	51.0E-09	50.6E-09	50.8E-09	52.7E-09
Sigma	504.4E-12	231.5E-12	711.1E-12	765.8E-12	530.7E-12	660.3E-12	653.0E-12	770.5E-12	874.1E-12

**Drift Calculation**

T14_DV	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-2.4E-09	-2.8E-09	-2.2E-09	500.0E-12	3.5E-09	3.1E-09	3.1E-09	4.9E-09
SN8	-	-2.8E-09	-3.1E-09	-1.7E-09	400.0E-12	3.3E-09	3.0E-09	3.0E-09	4.8E-09
SN9	-	-2.3E-09	-1.5E-09	-400.0E-12	1.5E-09	4.8E-09	4.5E-09	4.6E-09	6.7E-09
SN10	-	-1.2E-09	-600.0E-12	700.0E-12	2.6E-09	5.9E-09	5.5E-09	5.7E-09	7.6E-09
SN11	-	-1.7E-09	-900.0E-12	100.0E-12	2.1E-09	5.2E-09	4.8E-09	5.2E-09	7.2E-09
Average	-	-2.1E-09	-1.8E-09	-700.0E-12	1.4E-09	4.5E-09	4.2E-09	4.3E-09	6.2E-09
Sigma	-	563.6E-12	1.0E-09	1.1E-09	865.8E-12	997.2E-12	978.6E-12	1.1E-09	1.2E-09

Parameter : Bus access and byte delay : T14\_Z  
 Test conditions : Iol=1.6mA; loh=500uA. Vcrossover 2.1V. Vol=0.4V. Voh=4V. all data Z  
 Unit : s  
 Spec Limit Min : 10.0E-09  
 Spec Limit Max : 100.0E-09  
 Spec limits are represented in bold lines on the graphic.



Measurements

T14_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1 REF	41.4E-09	41.5E-09	41.2E-09	41.5E-09	41.5E-09	41.8E-09	41.2E-09	41.7E-09	41.5E-09
ON samples									
SN2	41.2E-09	41.2E-09	41.2E-09	41.3E-09	41.9E-09	34.5E-09	41.4E-09	43.8E-09	47.7E-09
SN3	41.9E-09	41.1E-09	41.3E-09	42.0E-09	42.7E-09	40.3E-09	33.7E-09	43.6E-09	48.1E-09
SN4	42.0E-09	41.2E-09	41.3E-09	42.0E-09	42.7E-09	40.3E-09	40.8E-09	44.5E-09	48.7E-09
SN5	41.6E-09	41.2E-09	41.2E-09	41.6E-09	42.3E-09	33.5E-09	41.5E-09	43.9E-09	47.2E-09
SN6	41.9E-09	40.6E-09	41.2E-09	42.0E-09	42.6E-09	40.6E-09	40.6E-09	44.2E-09	48.1E-09
Statistics									
Min	41.2E-09	40.6E-09	41.2E-09	41.3E-09	41.9E-09	33.5E-09	33.7E-09	43.6E-09	47.2E-09
Max	42.0E-09	41.2E-09	41.3E-09	42.0E-09	42.7E-09	40.6E-09	41.5E-09	44.5E-09	48.7E-09
Average	41.7E-09	41.1E-09	41.2E-09	41.8E-09	42.4E-09	37.8E-09	39.6E-09	44.0E-09	48.0E-09
Sigma	292.6E-12	233.2E-12	49.0E-12	285.7E-12	307.2E-12	3.2E-09	3.0E-09	316.2E-12	496.4E-12

Drift Calculation

T14_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
ON samples									
SN2	-	0.0E+00	0.0E+00	100.0E-12	700.0E-12	-6.7E-09	200.0E-12	2.6E-09	6.5E-09
SN3	-	-800.0E-12	-600.0E-12	100.0E-12	800.0E-12	-1.6E-09	-8.2E-09	1.7E-09	6.2E-09
SN4	-	-800.0E-12	-700.0E-12	0.0E+00	700.0E-12	-1.7E-09	-1.2E-09	2.5E-09	6.7E-09
SN5	-	-400.0E-12	-400.0E-12	0.0E+00	700.0E-12	-8.1E-09	-100.0E-12	2.3E-09	5.6E-09
SN6	-	-1.3E-09	-700.0E-12	100.0E-12	700.0E-12	-1.3E-09	-1.3E-09	2.3E-09	6.2E-09
Average	-	-660.0E-12	-480.0E-12	60.0E-12	720.0E-12	-3.9E-09	-2.1E-09	2.3E-09	6.2E-09
Sigma	-	436.3E-12	263.8E-12	49.0E-12	40.0E-12	2.9E-09	3.1E-09	312.4E-12	372.0E-12

Hirex Engineering	TOTAL IONIZING DOSE TEST REPORT						Ref.:	HRX/TID/1197
	AD976SD/883			Analog Devices			Issue:	02

**Measurements**

T14_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
SN1_REF	41.4E-09	41.5E-09	41.2E-09	41.5E-09	41.5E-09	41.8E-09	41.2E-09	41.7E-09	41.5E-09
<b>OFF samples</b>									
SN7	41.8E-09	40.4E-09	40.8E-09	41.7E-09	42.3E-09	43.6E-09	43.2E-09	43.4E-09	45.6E-09
SN8	41.5E-09	40.4E-09	40.8E-09	41.3E-09	42.0E-09	43.2E-09	42.8E-09	43.2E-09	45.2E-09
SN9	42.0E-09	41.2E-09	41.2E-09	41.8E-09	42.4E-09	43.8E-09	43.4E-09	43.8E-09	46.0E-09
SN10	41.9E-09	41.0E-09	41.2E-09	41.6E-09	42.1E-09	43.5E-09	43.0E-09	43.5E-09	45.6E-09
SN11	42.3E-09	41.3E-09	41.3E-09	41.9E-09	42.5E-09	43.8E-09	43.2E-09	44.0E-09	45.7E-09
<b>Statistics</b>									
Min	41.5E-09	40.4E-09	40.8E-09	41.3E-09	42.0E-09	43.2E-09	42.8E-09	43.2E-09	45.2E-09
Max	42.3E-09	41.3E-09	41.3E-09	41.9E-09	42.5E-09	43.8E-09	43.4E-09	44.0E-09	46.0E-09
Average	41.9E-09	40.9E-09	41.1E-09	41.7E-09	42.3E-09	43.6E-09	43.1E-09	43.6E-09	45.6E-09
Sigma	260.8E-12	387.8E-12	215.4E-12	205.9E-12	185.5E-12	222.7E-12	204.0E-12	285.7E-12	256.1E-12

**Drift Calculation**

T14_Z	0 kRad	9 kRad	20.7 kRad	27.9 kRad	48.6 kRad	102.6 kRad	24 Hours	168 Hours	168 Hours
<b>OFF samples</b>									
SN7	-	-1.4E-09	-1000.0E-12	-100.0E-12	500.0E-12	1.8E-09	1.4E-09	1.6E-09	3.8E-09
SN8	-	-1.1E-09	-700.0E-12	-200.0E-12	500.0E-12	1.7E-09	1.3E-09	1.7E-09	3.7E-09
SN9	-	-800.0E-12	-800.0E-12	-200.0E-12	400.0E-12	1.8E-09	1.4E-09	1.8E-09	4.0E-09
SN10	-	-900.0E-12	-700.0E-12	-300.0E-12	200.0E-12	1.6E-09	1.1E-09	1.6E-09	3.7E-09
SN11	-	-1.0E-09	-1.0E-09	-400.0E-12	200.0E-12	1.5E-09	900.0E-12	1.7E-09	3.4E-09
Average	-	-1.0E-09	-840.0E-12	-240.0E-12	360.0E-12	1.7E-09	1.2E-09	1.7E-09	3.7E-09
Sigma	-	205.9E-12	135.6E-12	102.0E-12	135.6E-12	116.6E-12	193.9E-12	74.8E-12	193.9E-12